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-: HAND WRITTEN NOTES:-

OF

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ELECTRICAL ENGINEERING

-: SUBJECT:-

ANALOG ELECTRONICS

(2)

Topic →

1) Semiconductor physics. (3)

2) P N junction diode.

Special diodes

✓ Zener diode

✓ Tunnel diode

→ Schottky diode

→ Photo diode

Applications →

- Rectifiers

- filters

Diode CKTs →

- Ideal diode problems.

- Practical diode problems

- clippers

- clampers.

BJT -

- BJT device analysis

- BJT biasing (DC)

Analog CKTs -

- Small signal analysis

- low freq Analysis

- High freq Analysis

- freq response of an amplifier.

- large Signal Amplifiers. (power amplifiers)

- multistage amplifiers

Feedback -

- Feedback amplifiers

- oscillators

FET / MOSFET :-

- FET biasing
- Small signal analysis
- low freq analysis
- High freq analysis

(4)

} Problems.

OP-Amps -

- Differential amplifiers.
- OP amp applications.
- 555 timer.
- Active filters

Some conductor properties

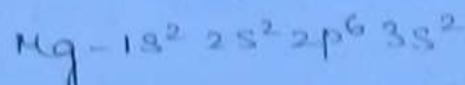
Introduction :-



Cu - 29

(3)

valence shell
((3)) unstable atom.



conductors

((1))

Al - 13

((1))

Li - 10

F - 14

Q. The max no. of e^- that can be filled in the valence shell of an atom will be

- a) $4e^-$, b) $6e^-$ c) $13e^-$ d) None [$8e^-$]

Aus: Acc. to Aufbau principle, s, p, d, f, s, p

Si - 14

Ge - 32

T = OK \rightarrow Insulators } \rightarrow S.C.

((1)), T \neq OK \rightarrow conductors }

As - 33

((1))

Br - 35

((1))

Ne - 10 $1s^2 \ 2s^2 \ 2p^6$

((1)) \rightarrow stable atom

Insulators

so the no. of e⁻ may van be filled in the valence shell of a semiconductor will be —

Ans. 4 e⁻

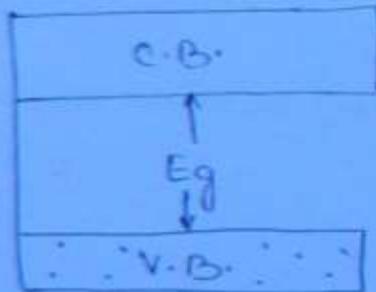
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Examples of Semiconductors :-

Si, Ge, GaAs [Gallium Arsenic]
Single compound
crystalline semi conductors

Q. Why Si and Ge are generally preferred compare to Gallium Arsenic (GaAs) ?

Ans.



C.B. \rightarrow conduction band
Eg \rightarrow en. gap
V.B. \rightarrow valence band.

* At t=0K,

Ego

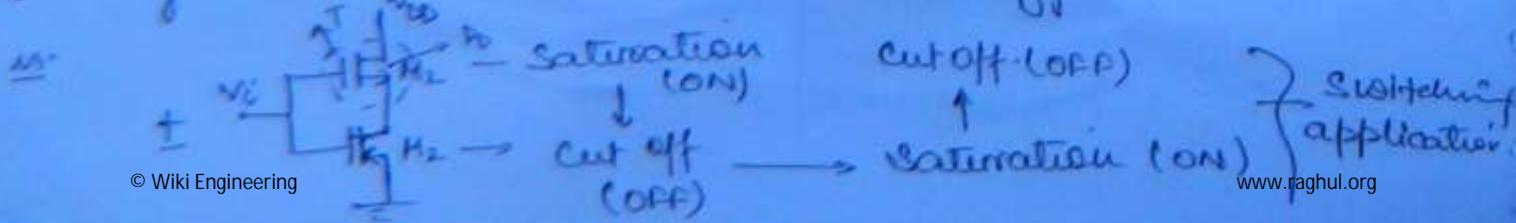
Ge - 0.785 ev

Si - 1.11 ev

GaAs - 1.58 ev.

As the en. gap value for silicon and germanium is less compare to gall GaAs, we expect more conduction is possible in case of Silicon and Germanium.

Q. Why GaAs is used in 'CMOS' technology ?



Movement of carrier (majority) is called mobility - -
↳ The mobility of charge carriers in case of GaAs >
Si and Ge.

2) The temp with standing capability is more for GaAs
(Eg is more)

→ Typical Values of temp. for which the device can work with :-

Ge \rightarrow 100°C

Si \rightarrow 200°C

GaAs $> 200^\circ\text{C}$

Q. Why $\text{H}_e > \text{H}_n$ $\text{H} \rightarrow \text{mobility}$

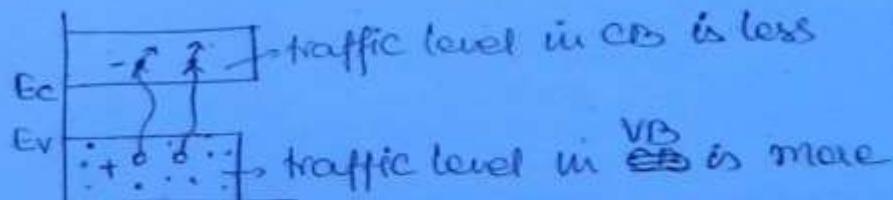
a) The traffic level in CB < in VB.

b) The traffic level in CB > VB

c) The traffic level in CB = VB

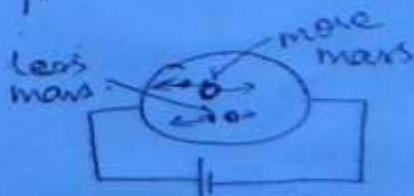
d) None

Ans:



2nd reason, when things are in motion

The effective mass of a hole is always greater than effective mass of an e-.



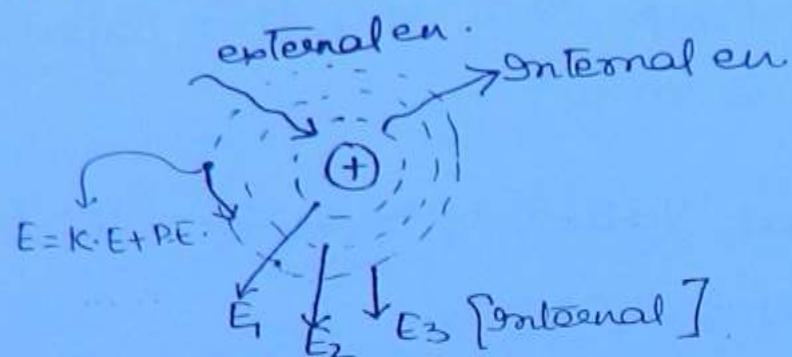
Traffic level is more in Ge, Si compare to GaAs.
mobility of Ge, Si < mobility of GaAs.

Atomic structure of an atom :-

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Q. What is the relation b/w E_1, E_2, E_3 ?

- a) $E_1 < E_2 < E_3$
 b) $E_1 > E_2 > E_3$.
 c) $E_1 = E_2 = E_3$
 d) none.



Ans: E_1, E_2 and E_3 are internal orbit energies.

Int. en.

$E_n \rightarrow e^-$ revolving around the ~~nucleus~~ ^{nucleus}.

$$= -\frac{13.56}{n^2} \text{ ev}$$

$$E_1 = -\frac{13.56}{1^2} = -13.56 \text{ ev}$$

$$E_2 = -\frac{13.56}{2^2} = -3.5 \text{ ev}$$

$$\vdots$$

$$E_{\infty} = -\frac{13.56}{\infty^2} = 0 \text{ ev}$$

$$n = \infty \quad \dots \quad \dots \quad \dots \quad \dots \quad 0 \text{ ev}$$

$$n = 3 \quad \dots \quad \dots \quad \dots \quad \dots \quad -1.5 \text{ ev}$$

$$n = 2 \quad \dots \quad \dots \quad \dots \quad \dots \quad -3.5 \text{ ev}$$

$$n = 1 \quad \dots \quad \dots \quad \dots \quad \dots \quad -13.56 \text{ ev}$$

en. diagram for an isolated atom

- * The valence cell of an atom will have the highest en. level.

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Fows →

There are two types of ions :-

- 1> five lions
 - 2> -ive lions

Five ions \rightarrow

Five ions → When the atom loses an e^- , the atom is characterised as five ion.

-ive ion : —

-ive ion :—
When the atom gains an e⁻, the atom is characterised as -ive ion.

NOTE -

Ions are indirectly atoms which are immobile in nature.

Energy band diagram concept :-

Ex.:- Si material

Si → Crystal lattice

Si : Si : Si : Si

↓ Covalent Bond ↓
Sharing of e^-

Interatomic Spacing

ignore E_{11}, E_{21}, E_{31} .

$$E_{g12}, E_{g21}, E_{g2} =$$

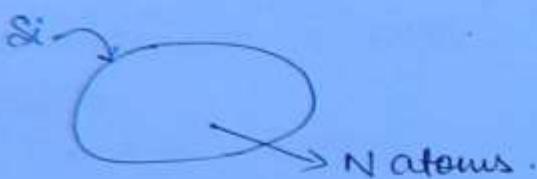
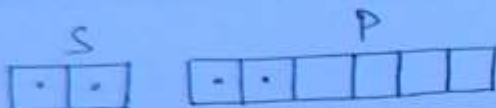
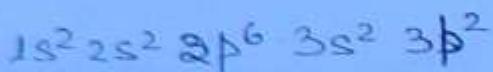
because outer levels interact with each other.

Conclusions:

- 1) The above en. diagram is valid for isolated atoms.
2) This type of diagram is not valid for material concept because the interatomic spacing b/w the atoms is very less.

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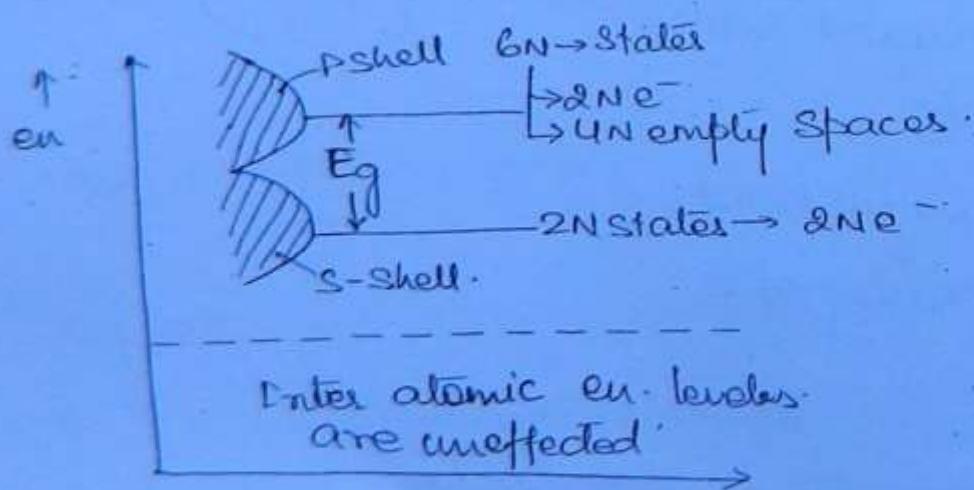
Si = 14



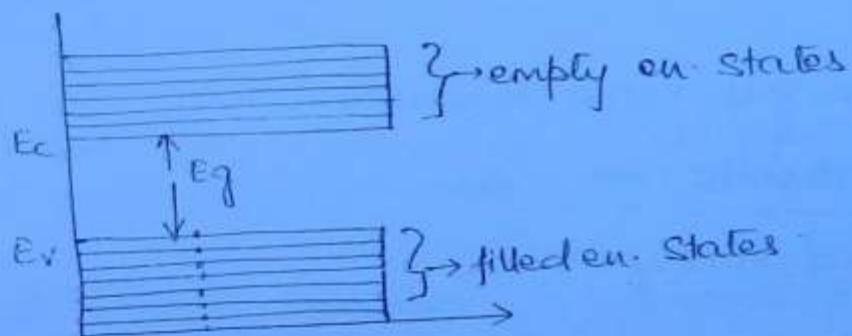
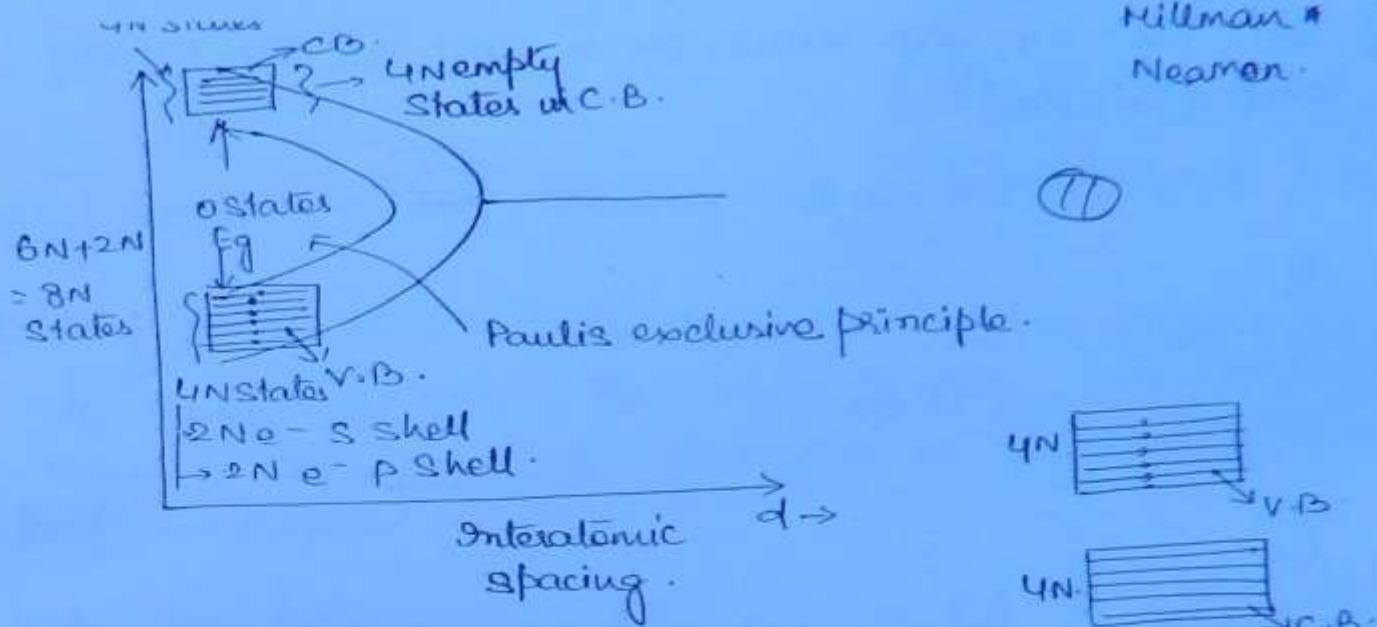
$2N$ states $\rightarrow 2Ne^-$
(S shell)

$6N$ states $\rightarrow 2Ne^-$
(P shell)

$\rightarrow 4N$ empty states



Inter atomic spacing (d) \rightarrow
Large



$E_C \rightarrow$ lowest en. level in C.B.

$E_V \rightarrow$ highest en. level in V.B.

$E_g \rightarrow$ forbidden gap or en. gap.

energy gap vs temp :-

$$E_g(\text{at any temp in K}) = E_{g0} - \beta T$$

↓ en. gap at any temp in K.

↓ en. gap at 0K.

$\beta \rightarrow$ const for a material

$$\begin{aligned} E_{g0} &= 0.78 \text{ eV.} & \beta(\text{Si}) &= 3.6 \times 10^{-4} \\ & & \beta &= 1.21 \text{ eV.} & \beta(\text{Ge}) &= 2.23 \times 10^{-4} \end{aligned}$$

$T \rightarrow$ temp in K.

Q: Cal. the en. gap value for Si and Ge at 300K
temp. [T=27°C] (12)

Ans: T = 273 + 27 = 300 K.

Si
 $E_g(300K) = 1.21 - 3.6 \times 10^{-4} \times 300$
 $= 1.12 \text{ eV}$

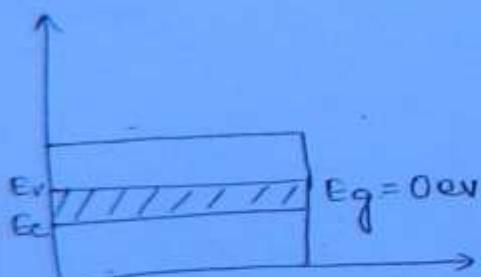
Ge
 $E_g(300K) = 0.785 - 2.23 \times 10^{-4} \times 300$
 $= 0.72 \text{ eV}$

NOTE →

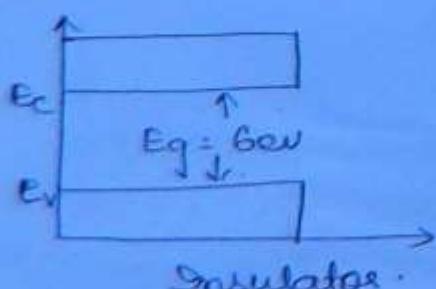
As temp increases, en. gap value decreases.

Classification of materials :-

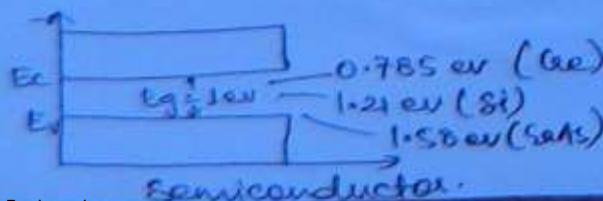
- based on en. band theory.



Conductor.

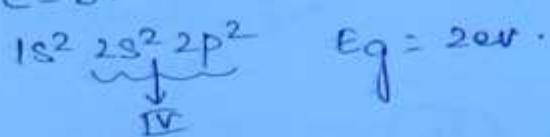


Insulator.



Semiconductor.

$C \rightarrow 0 \text{ eV}$ going toward Insulator.



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Q: Why Carbon is not behaving like a semiconductor?

A: Eg for carbon = 2eV.

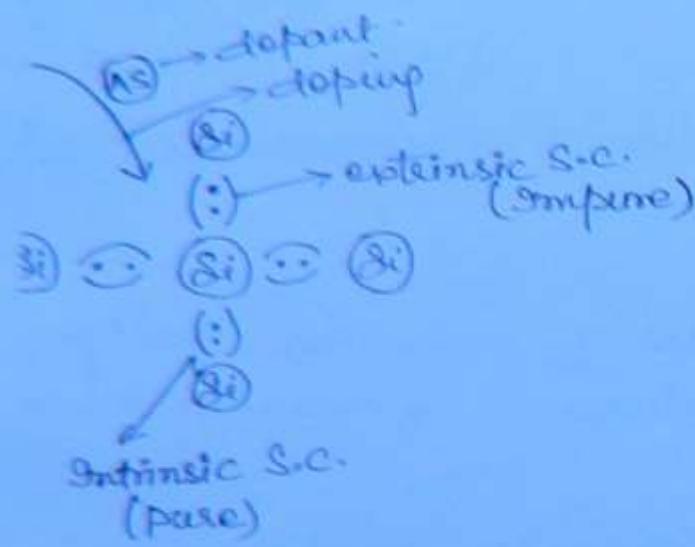
As energy gap value for carbon is more than the typical value of semiconductor. Sometimes it is behaving like a perfect insulator.

Differences between conductors, insulators and semiconductors

Property	Conductors	Insulators	Semiconductors
1) Resistivity	less $10^{-8} \Omega \text{cm}$	Highest $10^{12} \Omega \text{cm}$	10^{-4} to $10^3 \Omega \text{cm}$
2) type of bonding	Metallic (free)	ionic & covalent	covalent
3) Energy gap	0eV	6eV	1eV
4) Temp coeff of resistance	positive	—	negative
5) Charge carriers	e^-	—	electron & holes

Properties of semiconductors →

- 1) Resistivity of a semiconductor is more than that of a conductor but less than of an insulator.
- 2) It is having -ive temp co-eff. of Resistance property.
- 3) Doping is possible in it.



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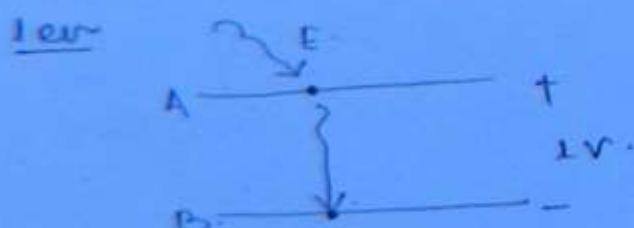
When an impurity is added to an intrinsic Sc., its conductivity property changes.

Note → Doping is a process which improves the conductivity of a semiconductor.

Unit of en: —

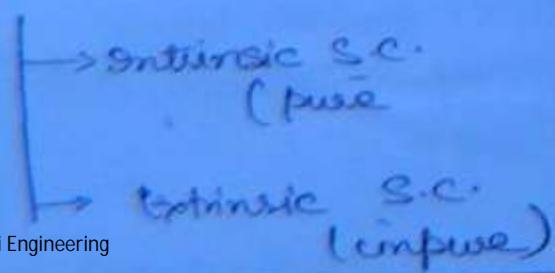
$$1\text{ev} = 1.6 \times 10^{-19} \text{ J} \times 1\text{V}$$

$$= 1.6 \times 10^{-19} \text{ J.}$$



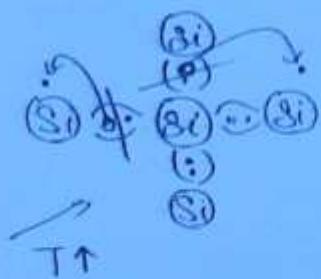
The amount of en. required for an e- to fall through a pt diff. of 1v is called as '1ev'

Semiconductors →

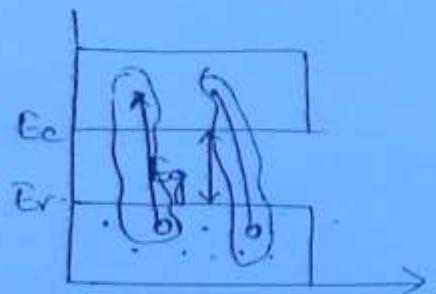


Intrinsic S.C.

(pure)



(B)



$$n = P$$

$$n = \text{conc. of } e^-/\text{cm}^3$$

$$P = \text{conc. of } e^- \text{ holes}/\text{cm}^3$$

$$n = P = n_i$$

$$n_i \rightarrow \text{Intrinsic conc. } (e-h)/\text{cm}^3$$

Extrinsic S.C.

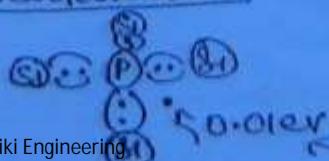
(impure)

Intrinsic S.C. + Other material = Extrinsic S.C.

Other material \rightarrow dopants

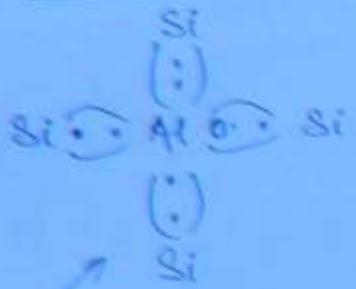
- \rightarrow Pentavalent impurity -
Arsenic, Antimony, Bismuth, Phosphorus etc.
- \rightarrow Trivalent Impurity -
eg - Gallium, Boron, Al, Indium.

Pentavalent



major carriers $\rightarrow e^-$
minority carriers \rightarrow holes
 n type S.C.

Bivalent -

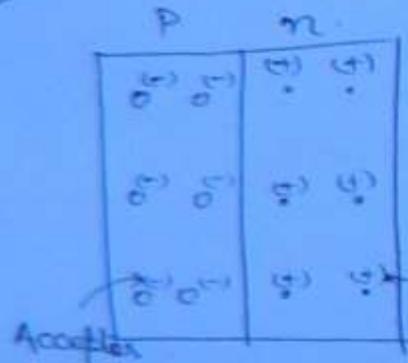


major carriers - holes

minor carriers - e^-

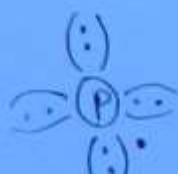
P type s.c.

28/12/11

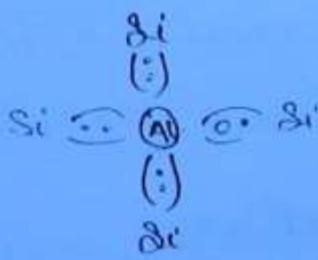


donor [pentavalent]

Pentavalent



Trivalent



[Bivalent]

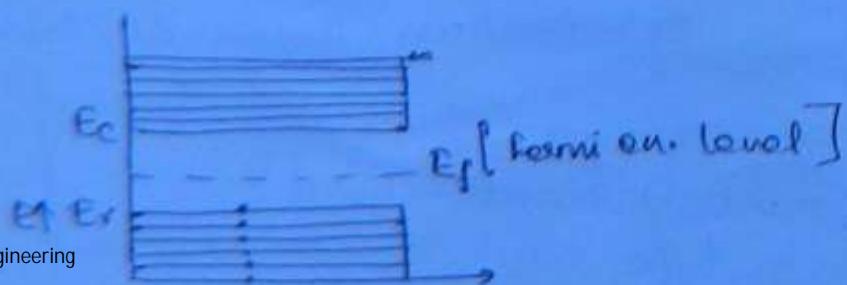
En. band diagram in a Semiconductor :-

Fermi Dirac probability f^{\pm} :-

"In energy band diagram, the probability that the en. level of e^- is given by a f^{\pm} called as fermi f^{\pm} defined as

$$F(E) = \frac{1}{1 + e^{(E-E_F)/kT}}$$

At $T=0K$,



$T = \text{OK}$,

$$F(E) = 1$$

$$E < E_f$$

$$= 0$$

$$E > E_f$$

$$= x$$

$$E = E_f$$

↓
indeterminate

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$$F(E) = \frac{1}{1 + e^{(E - E_f)/kT}}$$

At $E = E_f$,

$L = \text{OK}$.

$$F(E) = \frac{1}{1 + e^{0/0}} \rightarrow \text{Indeterminate}$$

empty states

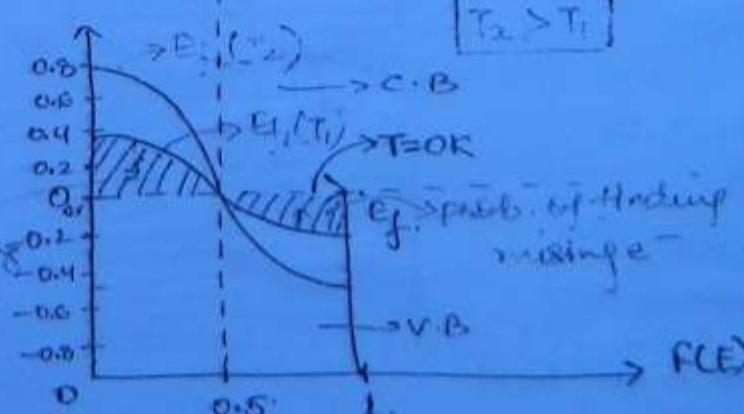
→ E_f

filled states

Fermi level : →

It is the ref. en. level which separates filled states and empty states at OK.

P.N.S.Q.



$T \neq \text{OK}$,

$$F(E) = 0.5 \quad E = E_f$$

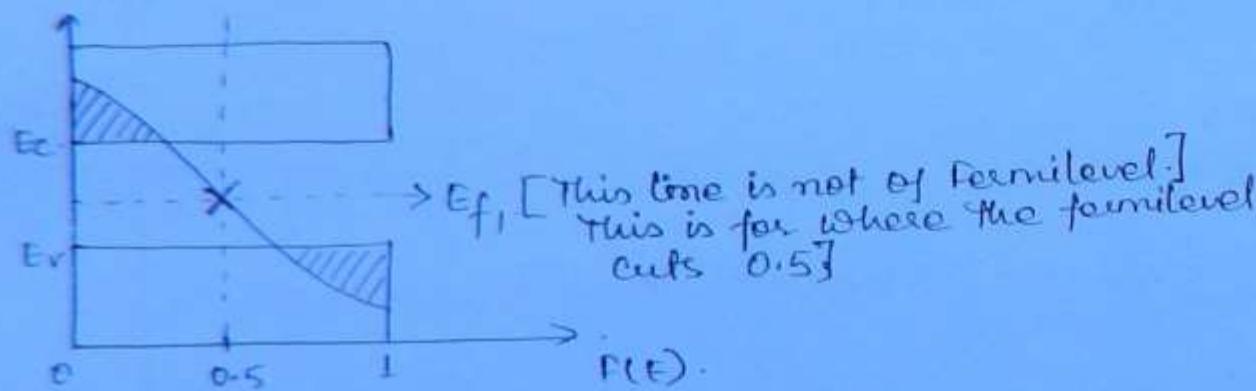
$$\begin{aligned} F(E) &= \frac{1}{1 + e^{(E - E_f)/kT}} \\ &= \frac{1}{1 + 1} \\ &= 0.5 \end{aligned}$$

- At $T=0K$, the Fermilevel line will be shown like a flat line.
- At $T \neq 0K$, the Fermilevel will be represented like a curvature nature.
- Fermilevel is not a const level and depends on doping.

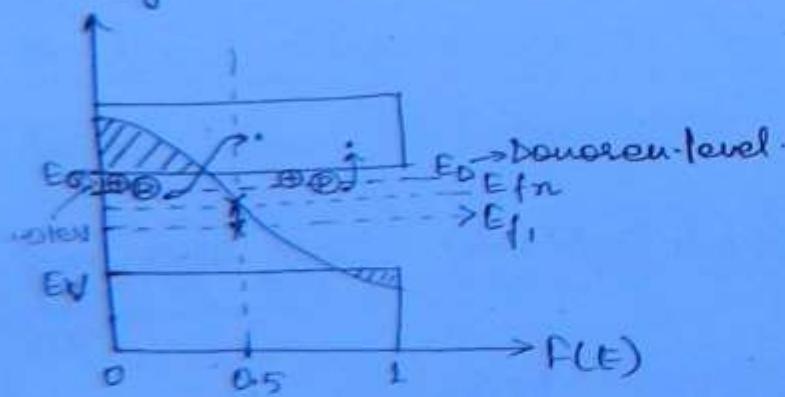
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Energy band diagrams:-

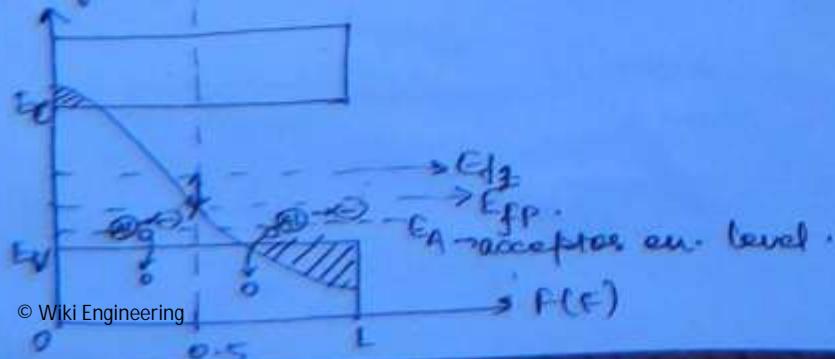
Intrinsic S.C. →



N-type



P-type →



Mathematical Analysis \rightarrow

$$n = N_c e^{-(E_c - E_f)/kT} \quad p = N_v e^{-(E_f - E_v)/kT}$$

} Fermi Dirac prob. fn.

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$n \rightarrow$ conc. of e^-

$p \rightarrow$ conc. of holes

$N_c \rightarrow$ effective density of states in C.B.

$N_v \rightarrow$ eff. density of states in V.B.

$E_c \rightarrow$ lowest en. level in C.B.

$E_v \rightarrow$ highest en. level in V.B.

$E_f \rightarrow$ Fermi level

$k \rightarrow$ Boltzmann const. $= 1.38 \times 10^{-23} \text{ J/K}$

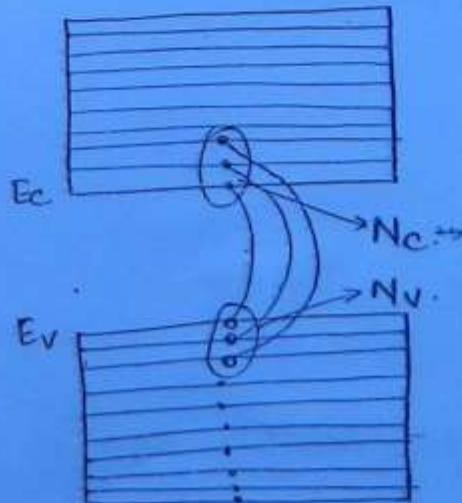
$T \rightarrow$ Temp in Kelvin.

$$\frac{k}{q} = \frac{1.38 \times 10^{-23} \text{ J/K}}{1.6 \times 10^{-19} \text{ C}}$$

$$\frac{k}{q} = 8.65 \times 10^{-5} \text{ ev/K}$$

N_c & N_v \rightarrow

$T \neq 0 \text{ K}$.



$N_c \rightarrow$ The density of en. states where the e^- are filled.

$N_v \rightarrow$ The density of en. states where the e^- are missing

$N_c \approx N_v \rightarrow$ intrinsic S.C.
[material perfect]

$N_c \neq N_v \rightarrow$ intrinsic S.C.
[material imperfect]

$N_c = N_v \rightarrow$ ideal condition

$$N_C = 4.82 \times 10^{15} \left(\frac{m_n}{m} \right)^{1/2} T^{3/2} / \text{cm}^3$$

$$N_V = 4.82 \times 10^{15} \left(\frac{m_p}{m} \right)^{3/2} T^{3/2} / \text{cm}^3.$$

If $m_n = m_p \Rightarrow N_C = N_V$

$m_n \rightarrow$ Effective mass of e^- in C.B.

$m_p \rightarrow$ Effective mass of proton [i.e holes]

$m \rightarrow$ Rest mass of an e^-

$$= 9.18 \times 10^{-31} \text{ kg}$$

Expression for fermilevel in case of Intrinsic Semiconductor

$$n = p \\ + N_C e^{-(E_C - E_F)/kT} = N_V e^{-(E_F - E_V)/kT}$$

$$\Rightarrow kT \ln \frac{N_C}{N_V} = E_C + E_V - 2E_F$$

$$\Rightarrow E_F = \frac{E_C + E_V}{2} - kT \ln \left(\frac{N_C}{N_V} \right) \Rightarrow N_C \neq N_V \text{ [Imperfect]}$$

$$E_F = \frac{E_C + E_V}{2} \Rightarrow N_C \approx N_V \text{ [Perfect]}$$

if $N_C > N_V$, $E_F' < E_F$ [0.5].

if $N_C < N_V$, $E_F' > E_F$.

Expression for fermilevel in Extrinsic S.C. : →

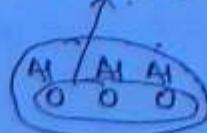
N type →

$$n = N_D \text{ [Donor conc]}$$



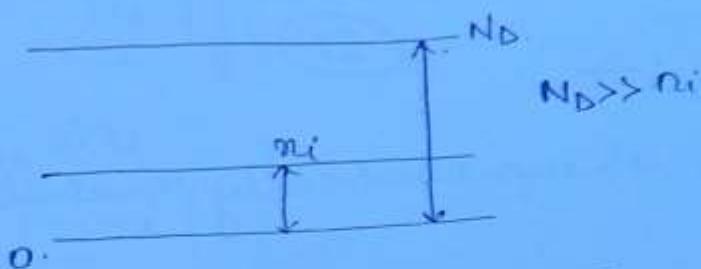
P type →

$$n = p = N_A \text{ [Acceptor conc]}$$



mini conc. level in S.C. = $n = P = n_i$ (intrinsic S.C.).

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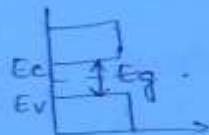


Law of mass Action : \rightarrow [Applied for all type of S.C.]

$$n \cdot P = \text{const}$$

$$n = N_c e^{-(E_c - E_f)/kT}$$

$$P = N_v e^{-(E_f - E_v)/kT}$$



$$\begin{aligned} n \cdot P_0 &= N_c N_v e^{-E_{q0}/kT} \\ &= N_c N_v e^{-E_q/kT} \\ &= n_i^2 \end{aligned}$$

$$\begin{aligned} N_c N_v e^{-E_q/kT} &= \underbrace{4.82 \times 10^{15}}_{c.} \left(\frac{m_p}{m} \right)^{3/2} T^{3/2} \underbrace{4.82 \times 10^{15}}_{c.} \left(\frac{m_p}{m} \right)^{3/2} T^{3/2} \\ &\quad \times e^{-E_{q0}/kT} e^{P/kT} \\ &= A_0 T^3 e^{-E_{q0}/kT} \\ &= n_i^2. \end{aligned}$$

Intrinsic S.C. :-

$$n \cdot P = n_i^2$$

$$n = P$$

n type \rightarrow

$$n \cdot P = n_i^2$$

↓
majority minority

P type

$$n \cdot P = n_i^2$$

↓
minority \rightarrow Majority

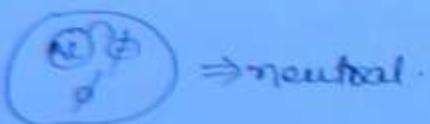
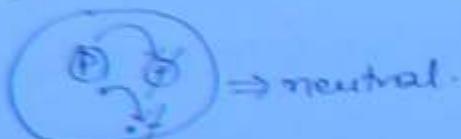
LOW OF MEAN ACCURACY IS USED FOR THE APPROXIMATE

[subimic, n-type, P-type]

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Charge neutrality equation : →

"Any part of a s.c. bar is always electrically neutral"



Net charge density = 0

Total the charge density = total -ve charge densities

H_2 P N_D N_A
- + \oplus \ominus

$$P + N_D = n + N_A$$

N-type →

$$P + N_D = n + N_A$$

$$n \gg p ; N_A \approx 0$$

$$\frac{m^2}{n} + N_D = m + 0.$$

$$\Rightarrow n^2 - N_D n - n^2 = 0$$

$$\Rightarrow n = \frac{N_D}{2} \pm \sqrt{\left(\frac{N_D}{2}\right)^2 + n^2}$$

$$n = \frac{ND}{2} + \sqrt{\left(\frac{ND}{2}\right)^2 + n^2}$$

$$N_D \gg n_c \Rightarrow n \propto N_D$$

Similarly, for P-type \rightarrow

$$P = \frac{N_A}{2} + \sqrt{\left(\frac{N_A}{2}\right)^2 + n_i^2}$$

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$N_A \gg n_i$

$$P \approx N_A$$

N-type

$$n = N_c e^{-(E_c - E_f)/kT}$$

\downarrow

$$N_D$$

$$kT \ln \frac{N_c}{N_D} = E_c - E_{fn}$$

$$E_{fn} = E_c - kT \ln \left(\frac{N_c}{N_D} \right)$$

P-type

$$P = N_V e^{-(E_f - E_V)/kT}$$

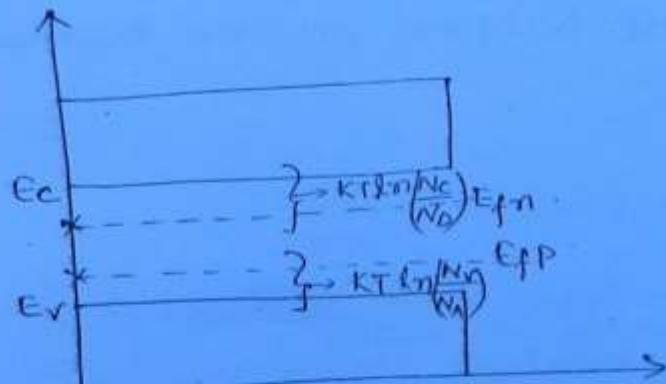
\downarrow

$$N_A$$

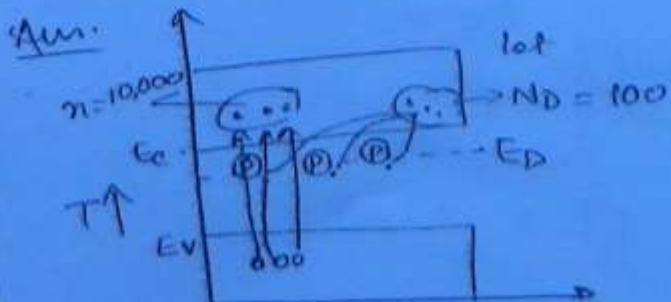
$$N_A = N_V e^{-(E_f - E_V)/kT}$$

$$kT \ln \left(\frac{N_V}{N_A} \right) = E_{fp} - E_V$$

$$E_{fp} = E_V + kT \ln \frac{N_V}{N_A}$$



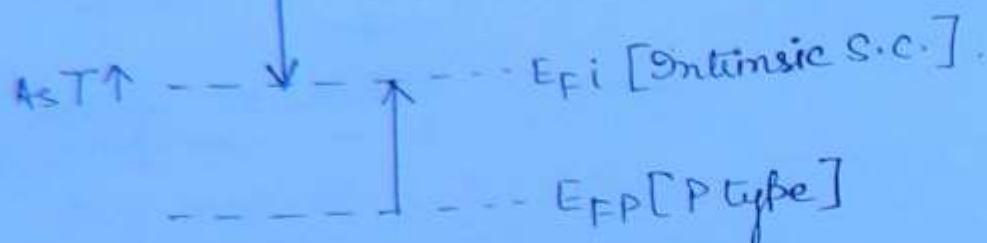
Q1. As temp inc. a in an extrinsic S.C. what happens to the position of fermilevel?



As temp inc., n also increases but on N_D , temp has no effect so, at high temp, extrinsic S.C. behaves as intrinsic S.C.

E_{Fn} [n type]

(24)



The fermilevel moves toward the intrinsic S.C. in case of n-type and P-type.

At very very high temp, extrinsic S.C. will behave like an intrinsic S.C.

Q2 As doping conc. increases, in an extrinsic S.C. what happens to fermi level?

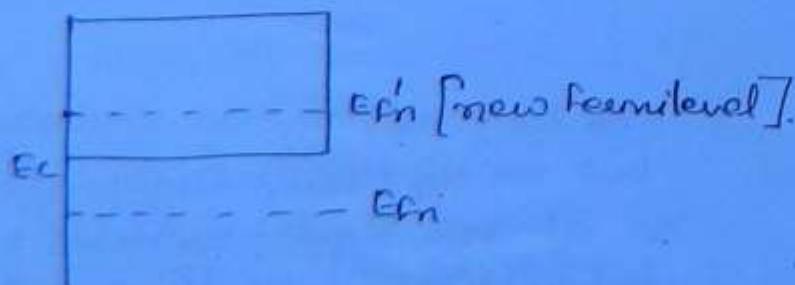
Ans Fermilevel moves towards the CB in case of n-type and moves towards the V.B. in case of P-type.

Q3 If $N_D \gg N_C$ in n type what happens to the position of fermilevel?

$$E_{Fn} = E_C - KT \ln\left(\frac{N_C}{N_D}\right)$$

$N_D \gg N_C$.

$$E_{Fn} = E_C + KT \ln N_D.$$



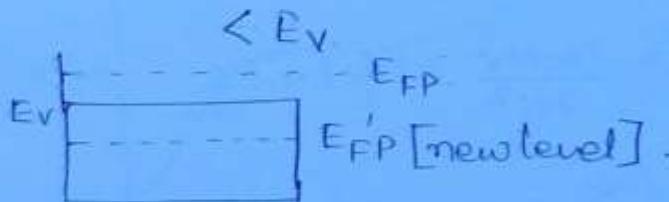
If $N_A \gg N_V$ in p-type, what happens to the fermilevel?

(Q3)

$$\text{Ans. } E_{FP} = E_V \pm KT \ln \left(\frac{N_V}{N_A} \right)$$

$$N_A \gg N_V$$

$$E_{FP} = E_V - KT \ln \frac{N_A}{N_V}$$



Conclusion :-

$$E'_{Fn} \cdot (N_D \gg N_C)$$

$$E_C$$

$$E_{Fn}$$

$$E_F$$

$$E_{FP}$$

$$E_V$$

$$E'_{FP} (N_A \gg N_V)$$

tunnel diode [heavily doped diode]

Shift in the fermilevel in case of n-type :-
w.r.t. intrinsic fermilevel.

$$\{E_{Fn} - E_F\}$$

$$= E_C - KT \ln \left(\frac{N_C}{N_D} \right) - \left\{ \frac{E_C + E_V}{2} - \frac{KT}{2} \ln \frac{N_C}{N_V} \right\}$$

$$= E_C - KT \ln \left(\frac{N_C}{N_D} \right) - \left\{ \frac{E_C + E_C - E_g}{2} - \frac{KT}{2} \ln \frac{N_C}{N_V} \right\}$$

$$= -KT \ln \frac{N_C}{N_D} + \frac{E_g}{2} + \frac{KT}{2} \ln \left(\frac{N_C}{N_V} \right) \quad (1)$$

$$m \cdot D = m_i^2 - (E_F - E_0)/kT$$

$$m_i^2 = N_c N_V e^{-\frac{E_0}{kT}}$$

(26)

$$E_F = kT \ln \frac{N_c N_V}{m_i^2}$$

From (1)

$$= -kT \ln \frac{N_c}{N_D} + \frac{kT}{2} \ln \frac{N_c N_V}{N_i^2} + \frac{kT}{2} \ln \frac{N_c}{N_V}$$

$$= kT \ln \frac{N_D}{N_c} \frac{\sqrt{N_c N_V}}{m_i} \frac{\sqrt{N_c}}{\sqrt{N_V}}$$

$$E_{ph} - E_F = kT \ln \left(\frac{N_D}{N_i} \right)$$

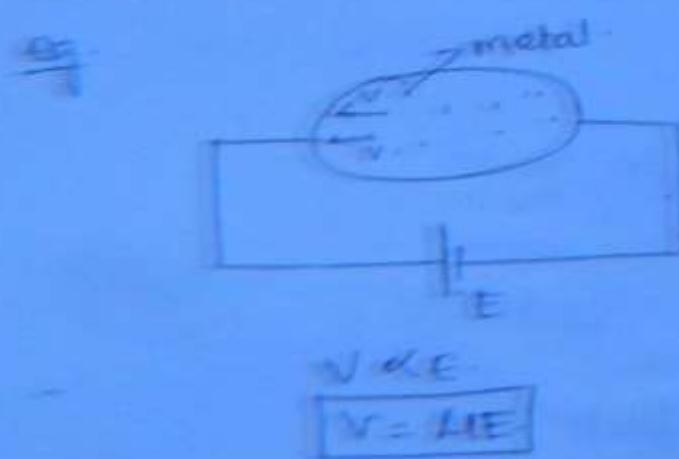
Similarly,

$$E_A - E_{pp} = kT \ln \left(\frac{N_A}{N_i} \right)$$

For P-type

Drift current \rightarrow

Drift current in metals and S.C.



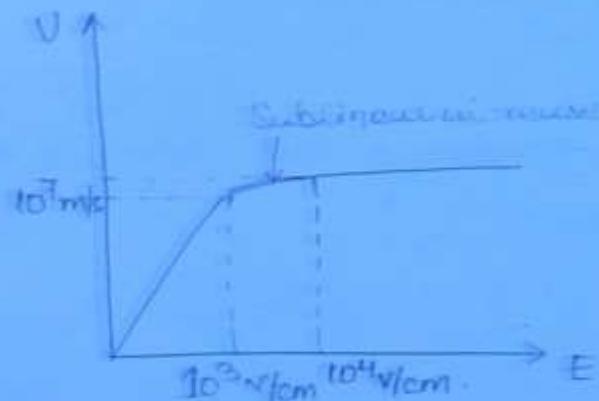
$$\text{Mobility} = \frac{\text{Drift velo}}{\text{Electric field}} = \frac{m/\text{Sec.}}{\text{V/m}} = \frac{m^2}{\text{V-sec.}}$$

The current is produced due to the drifting of gasee
is called as drift current [drifting means movement]

Mobility →

(Q7)

Effect of E-fd on mobility : —

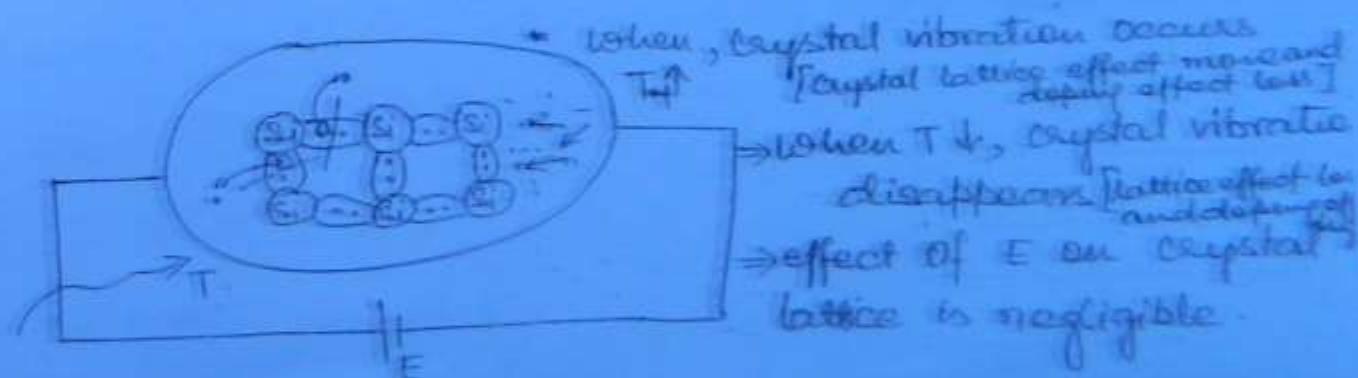


$$\mu = \text{const} \rightarrow E < 10^3 \text{ V/cm}$$

$$\mu \propto \frac{1}{\sqrt{E}} \rightarrow 10^3 < E < 10^4 \text{ V/cm}$$

$$\mu \propto \frac{1}{E} \left[= \frac{V}{E} \right] \rightarrow E > 10^4 \text{ V/cm}$$

Effect of temp and impurity on mobility : —



The e⁻ and hole mobility are influenced by two scattering phenomena. One is lattice scattering effect and other is impurity scattering.

Lattice scattering :→

As temp increases, there will be vibration in the crystal lattice which produces the mobility.

(28)

$$M \propto T^{-m}$$

Impurity scattering :→

As temp decreases, impurity scattering will become more dominant then mobility reduces.

$$M \propto T^m$$

Current density :→

$$J = \frac{I}{A}$$

$$I = \frac{N \cdot e}{T} \quad T \rightarrow \text{time}$$

$$J = \frac{N \cdot e}{T \cdot A}$$

$$\text{Time} = \frac{\text{dist}}{\text{velo}}$$

$$T = \frac{L}{V}$$



$N \rightarrow \text{no. of } e^-$

$$J = \frac{Nev}{LA}$$

$$\eta_1 = \frac{N}{LA}$$

$$J = \frac{nev}{\eta_1}$$

$\eta_1 = nxe$ = charge density

$$J = fV$$

metals

$$J = \frac{NeV}{L}$$

$$V = LE$$

$$J = \frac{n}{\tau} e L E$$

(29)

$$\boxed{J = \sigma E} \quad \boxed{\sigma \rightarrow \text{conductivity}}$$

$$\boxed{\sigma = n e \tau L}$$

S.C.

$$J_{SC} = J_n + J_p$$

$$J_n = n q L_n E$$

$$J_p = P q L_p E$$

$$J_{SC} = n q L_n E + P q L_p E$$

$$\boxed{J_{SC} = (n L_n + P L_p) q E}$$

↓
 σ_{SC}

$$\text{where } \sigma_{SC} = (n L_n + P L_p) q$$

Expression for conductivity in case of extra intrinsic S.C. :-

$$\sigma_{SC} = (n L_n + P L_p) q$$

$$n = P = n_i$$

$$\sigma_{SC} = n_i (L_n + L_p) q$$

$$\text{where } n_i^2 = A_0 T^3 e^{-E_g / kT}$$

$$\boxed{n_i \propto T^{3/2}}$$

For n-type :-

$$J_{SC} = (n L_n + P L_p) q = n L_n q$$

$P L_p q \rightarrow \text{can be neglect}$

$$n_{N\text{-type}} \approx n_{\text{free}} \\ \approx N_D n_q$$

(30)

For P-type \rightarrow

$$n_{P\text{-type}} \approx n_{\text{free}} \\ \approx N_A n_q$$

9/12/11

Parameter	Ge	Si
1) Eg at 0K	0.785 eV	1.21 eV
2) Eg at 300K	0.72 eV	1.12 eV
3) n_i/cm^3 at 300K	$2.5 \times 10^{13}/\text{cm}^3$	$1.5 \times 10^{10}/\text{cm}^3$
4) $k_{\text{tr}} \text{ cm}^2/\text{Vsec}$	3,800	1300
5) $k_{\text{tr}} \text{ cm}^2/\text{Vsec}$	1800	500
6) no. of atoms/ cm^3	$4.4 \times 10^{22}/\text{cm}^3$	$5.0 \times 10^{22}/\text{cm}^3$

Diffusion current : \rightarrow

It occurs in a non uniformly doped S.C.

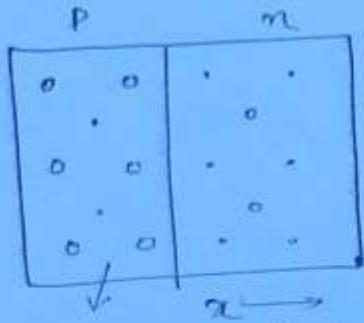
g:



uniformly doped S.C.
diffusion $I = 0$.



non uniformly doped S.C.
 $I_{\text{diff}} \neq 0$.



(3)

The best eg of non uniformly doped s.c. is $p-n-j^2$.

The rate of change of conc. w.r.t. dist. x is called as diffusion current.

NOTE →

Diffusion current mechanism can also be called as conc. gradient $\left[\frac{dn}{dx} \right]$.

Shift current mechanism can also be called as pot. gradient $\left[\frac{dv}{dx} \right]$.

$$J_n \propto q D_n \frac{dn}{dx}$$

$$J_n = q D_n \frac{dn}{dx}$$

D_n → diffusion const of e^-

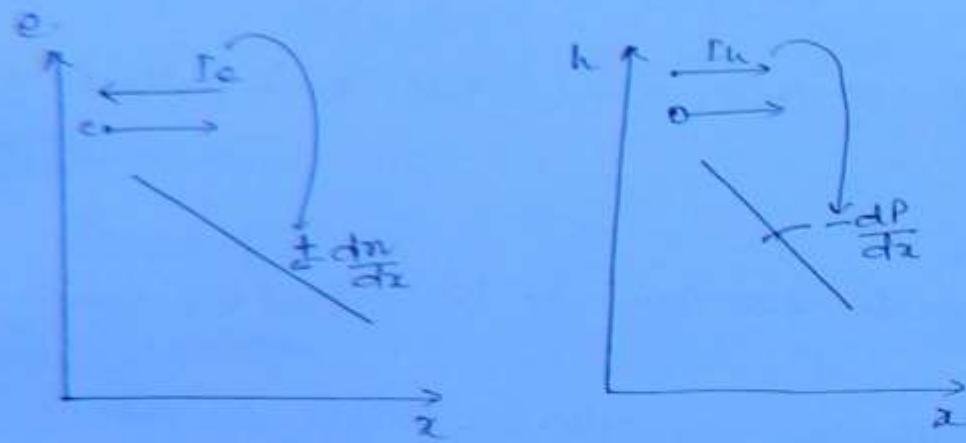
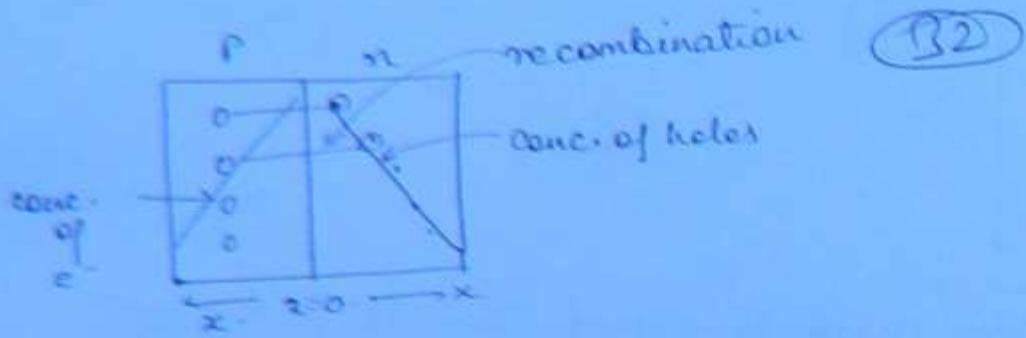
$$I_n = A q D_n \frac{dn}{dx}$$

$$J_p \propto q D_p \frac{dp}{dx}$$

$$\boxed{J_p = q D_p \frac{dp}{dx}} \rightarrow X$$

D_p → Diffusion const of holes

$$\boxed{I_p = A q D_p \frac{dp}{dx}} \rightarrow X$$



$$\Rightarrow I_p = -q D_p \frac{dP}{dx}$$

$$\Rightarrow I_p = -A q D_p \frac{dP}{dx}$$

Total current in a S.C. :-

$$I_{SC} = I_{drift} + I_{diff}$$

$$= n q \mu_n E_A + P q \mu_p E_A + A q D_n \frac{dn}{dx} - A q D_p \frac{dP}{dx}$$

There is an imp. relation b/w diffusion \propto const. and mobility

$D \propto \mu$.

$$D = V_T \mu$$

$V_T \rightarrow$ volt equivalent temp or Thermal voltage.

$$V_T = \frac{kT}{q} = \bar{k}T = \frac{T}{11600}$$

$$1.38 \times 10^{-23} \text{ J/K} \quad 8.65 \times 10^{-5} \text{ eV/K}$$

Q. Calculate the value of V_T across a 1 cm^2 area at 27°C.

Ans. $T = 27^\circ\text{C}$

$$= 300\text{ K}$$

(P3)

$$V_T = \frac{T}{11600}$$

$$= 0.026\text{ V}$$

OR

$$V_T = 26\text{ mV}$$

Units

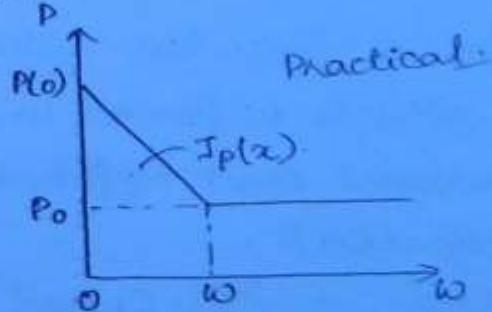
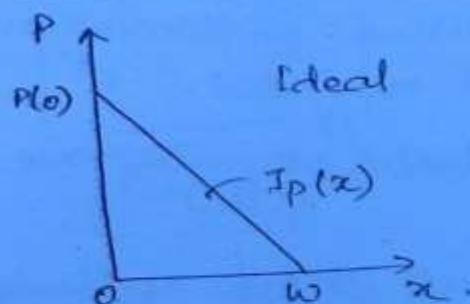
$$\mu \rightarrow \text{m}^2/\text{N-sec.}$$

$$V_T \rightarrow \text{V.}$$

$$D \rightarrow \text{m}^2/\text{sec}$$

$$\boxed{\frac{D_n}{\mu_n} = \frac{D_p}{\mu_p} = V_T} \rightarrow \text{Einstein relation}$$

Problems based on diffusion current :-



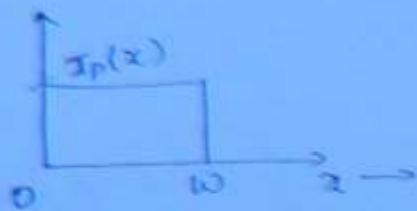
$$\begin{aligned} J_p(x) &= -q D_p \frac{dP(x)}{dx} \\ &= -q D_p \left(\frac{P(0) - 0}{0 - w} \right) \\ &= q D_p \frac{P(0)}{w}. \end{aligned}$$

$$\begin{aligned} J_p(x) &= -q D_p \frac{dP(x)}{dx} \\ &= -q D_p \left(\frac{P(0) - P_0}{0 - w} \right) \\ &= \frac{q D_p (P(0) - P_0)}{w}. \end{aligned}$$

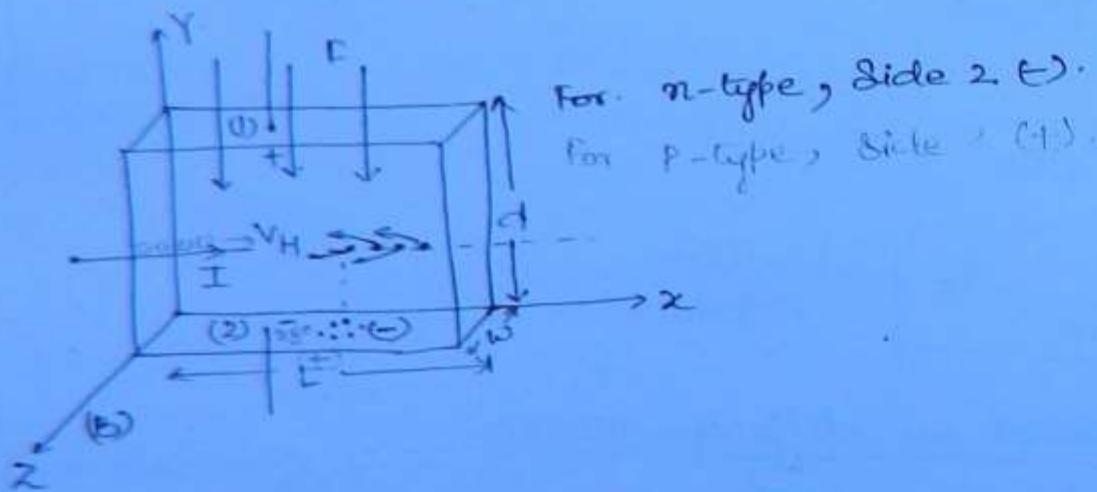
$$J_p(x) = \frac{qD_p \{ P(0) - P_0 \}}{W} \quad 0 < x < W$$

(34)

$= 0$ else



Hall effect →



- 1) let us consider a S.C. bar whose current is flowing in the direcⁿ x-dirⁿ which is placed in a \vec{B} mag. fld.
- 2) Due to the current and M-fld, an Electro magnetic force (EMF) exist in the Y-dirⁿ.
- 3) Due to the EMF, a P.d. called as hall voltage is developed in the Y-dirⁿ

The main application of hall effect is to find the s.c. bar whether it is n-type or p-type.

Side (2) " " \rightarrow n type

" + " \rightarrow p type

Other application of Hall effect :-

(25)

- 1) We can determine the mobility of charge carriers in a S.C. bar.
- 2) We can also determine the conductivity of charge carriers.
- 3) It can be used as a voltage multiplier $[V_H \propto B \times I]$.

Expression for hall voltage (V_H), hall coefficient (R_H), mobility (μ), conductivity (σ) :-

$$F_E = F_B$$

$F_E \rightarrow$ force due to $E-fld.$

$$F_B \rightarrow " " " M-fld.$$

$v \rightarrow$ velo.

$$\frac{V'}{d} = BV$$

$$v' \rightarrow v_{all} = V_H$$

$$v' = Bvd$$

$$= \frac{BI}{A} d \quad [I = fv]$$

$$= \frac{BI}{Af} d$$

$$= \frac{BI}{wgd} d$$

$$V_H = \frac{BI}{wgd}$$

$$R_H = \frac{1}{f}$$

$f \rightarrow$ charge density

$$V_H = \frac{BI}{W} R_H$$

$$R_H = \frac{V_H W}{BI}$$

$$\sigma = \frac{n \times e \times I}{\rho}$$

$$\sigma = f \mu$$

$$\mu = \frac{\sigma}{f} = \sigma R_H$$

Generation and Recombination of charge carriers :-

eq.

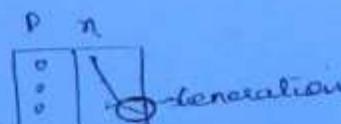
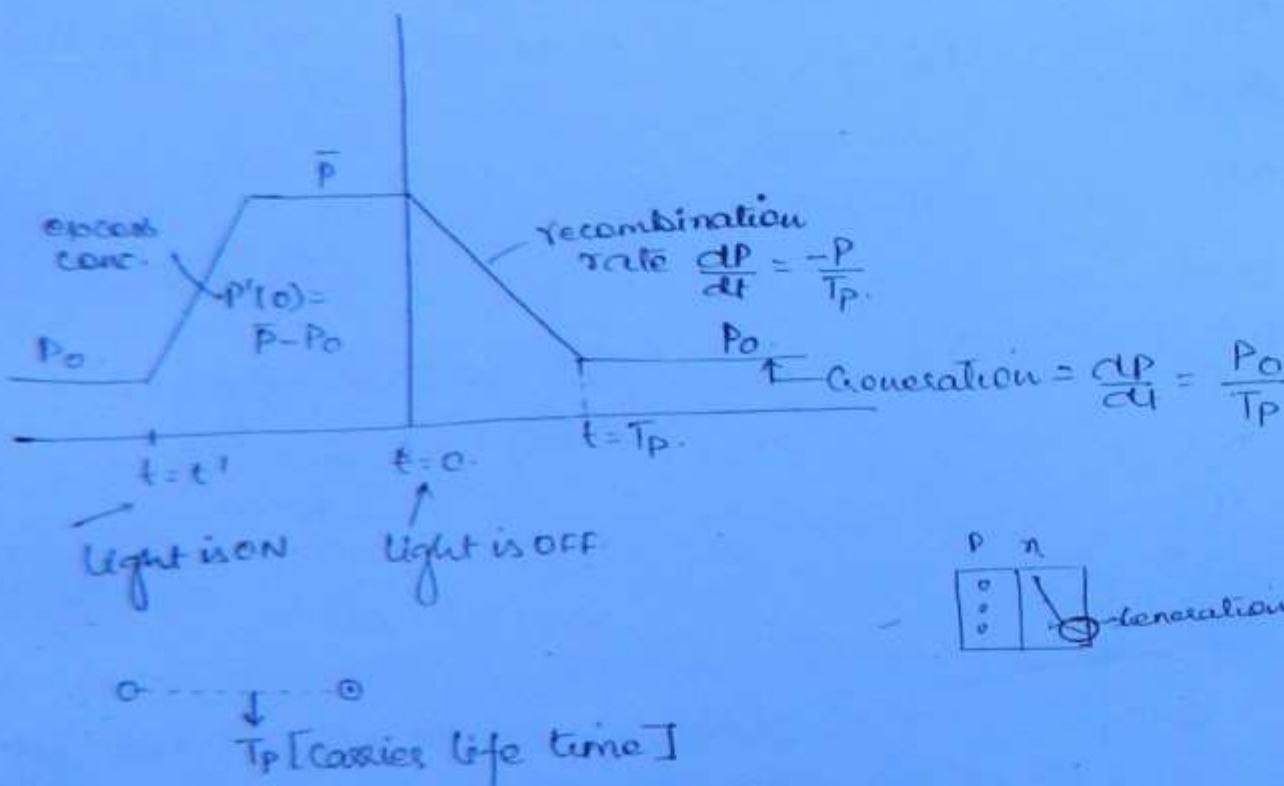
$$n = 1000 + 50e$$

$$P = 20 + 50e$$

rate of increase of e^- is less as compared to rate of increase of holes. $\Rightarrow 250\%$.

For the analysis of S.C. bar, we have to conc. on minority carriers but not majority carrier.

(36)



$T_p \rightarrow$ carrier life time for holes.

It is a time taken for a hole to exist before recombination is called as carrier life time for holes.

- When light radiation is applied to a S.C. bar, two mechanism will be happen.

Recombination rate \rightarrow

$$\frac{dP}{dt} = -\frac{P}{T_p}$$

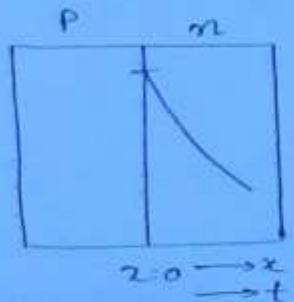
Generation rate \rightarrow

$$\frac{dP}{dt} = \frac{P_0}{T_p}$$

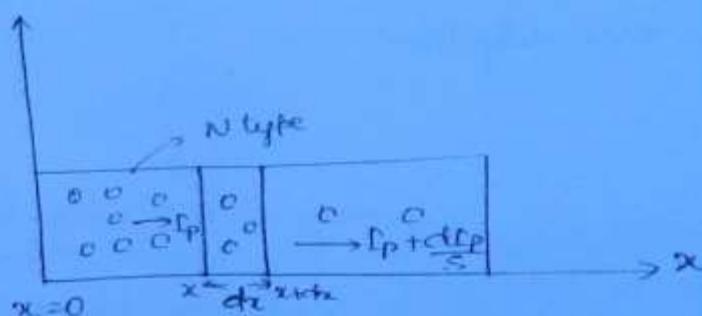
- Generation rate always occurs after recombination rate.

continuity equation →

- 1) For the analysis of a diode or a transistor we have to determine the conc. of charge carriers w.r.t. time and space
- 2) For such analysis, we have a mathematical eqn called as continuity eqn?



(Q7)



Factors affecting the conc. P of thin slice of thickness dx and area of $x \text{ sec } A$ is

1) Diffusion →

$$\frac{dP}{dt} = \frac{\text{charge taken away}}{\text{Unit charge} \times \text{Vol.}}$$

$$= -\frac{dP}{q \times A \times dx} \quad \text{(1)}$$

2) When light radiation is applied →

$$G_i = \frac{dP}{dt} = \frac{P_0}{\tau_p} \quad \text{(2)}$$

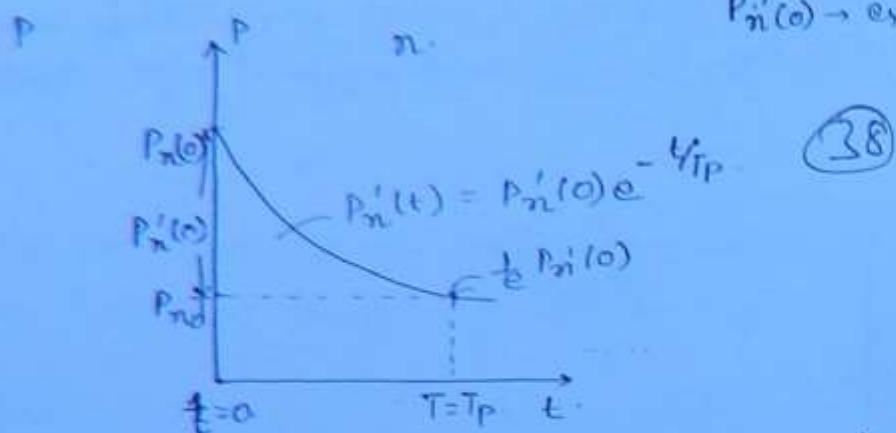
$$R = \frac{dP}{dt} = -\frac{P}{\tau_p} \quad \text{(3)}$$

$$(1) + (2) + (3) \Rightarrow$$

$$\frac{dP}{dt} = -\frac{dP}{q \times A \times dx} + \frac{P_0}{\tau_p} - \frac{P}{\tau_p}$$

Case 1. →

w.r.t time →



P_{no} → Thermal equilibrium
 $P_n'(0)$ → excess charge carriers.

$P_n(0)$ → Injected minority carrier conc. [on the jth always e⁻ or hole
→ minority]

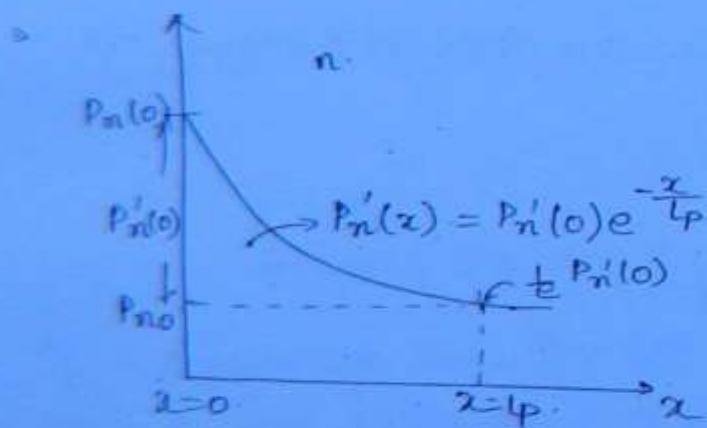
P_{no} → Thermal equilibrium minority conc.

$P_n'(0)$ → Excess conc.

Case 2. →

w.r.t Space →

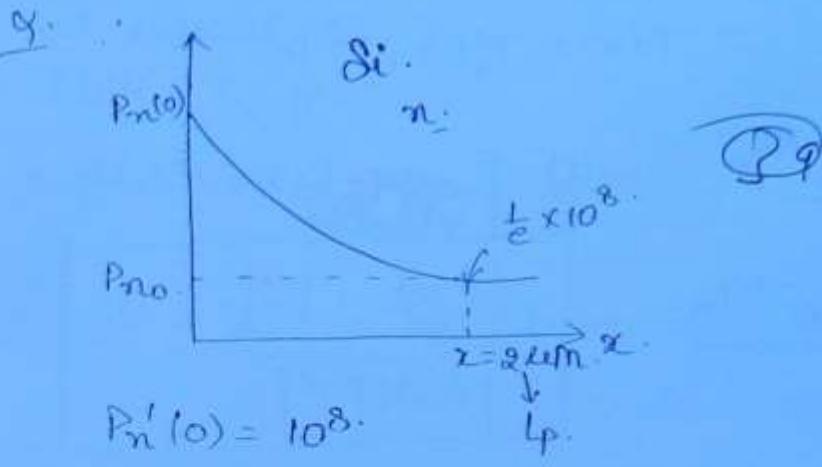
$\uparrow l_p$ → mini dist travelled by
hole before recombination.
= diffusion length for
holes.



$\uparrow l_p \rightarrow$

l_p is the mini distance travelled by a hole before recombination is called as diffusion length for a hole. [l_p]

$$l_p^2 = D_p T_p$$



$$P_n'(0) = 10^8.$$

$$P_{n0}(0) = 1 \times 10^8.$$

$$P_n(0) = 2 \times 10^8.$$

Cal.

a) e⁻ conc.

$$\Rightarrow L_p = 2 \mu m$$

$$c) T_p = \frac{L_p^2}{D_p} = 9$$

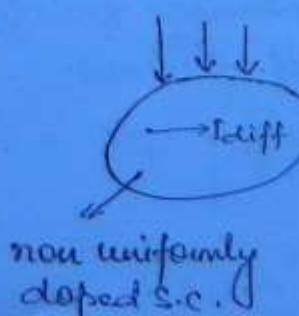
$$Am. a) n = \frac{n_i^2}{P_{n0}} = \frac{(1.5 \times 10^{10})^2}{1 \times 10^8}$$

$$b) L_p = 2 \mu m = 2 \times 10^{-6} m$$

$$c) T_p = \frac{L_p^2}{D_p} =$$

$$D_p = L_p V_f = 0.05 \times 0.026.$$

Total current in an illuminated O.C. S.c. bar :-



$$I_n(x) + I_p(x)$$

$$I_p(x) = -Aq D_p \frac{d P_n(x)}{dx} \quad P(x) = P_n(0) e^{-x/l_p}$$

$$= \frac{-Aq D_p P_n'(0) e^{-x/l_p}}{l_p} \quad -(1) \quad \textcircled{40}$$

$$I_n(x) = -\frac{Aq D_n n P_n'(0) e^{-x/l_n}}{l_n} \quad -(2)$$

When light is ON.

$$1) P_n'(0) = n P'(0)$$

$$2) l_p = l_n$$

$$\therefore I_n(x) = -\frac{Aq D_n P_n'(0) e^{-x/l_p}}{l_p} \quad -(3)$$

$$(1) + (3) \Rightarrow$$

$$I_{diff} = \frac{Aq D_p \left(1 - \frac{D_n}{D_p}\right) P_n'(0) e^{-x/l_p}}{l_p}$$

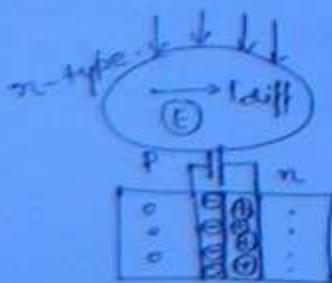
$$= I_p \left[1 - \frac{D_n}{D_p} \right]$$

$$\text{As } D_n > D_p$$

$$I_{diff} = -\text{ive}$$

Inclusion: →

In a O.C. Sc. bar, net current should be equal to 0
 that means there is an E-field generated which produces drift current that cancels the diff. current



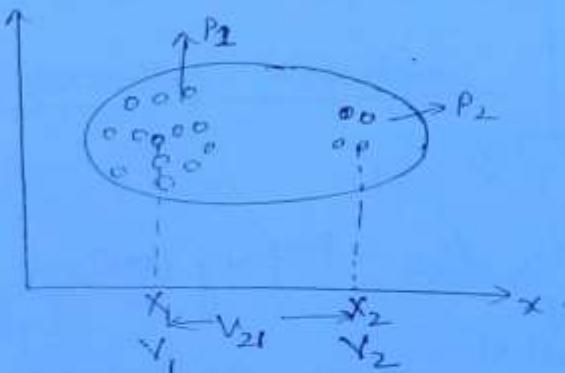
net current = 0.

$I_{drift} + I_{diff} = 0$.

$$nqHnEA + I_p \left[1 - \frac{D_n}{D_p} \right] = 0 \quad (41)$$

$$E = \frac{\left| I_p \left[1 - \frac{D_n}{D_p} \right] \right|}{\left| nqHnA \right|}$$

Potential variation in a o.c. S.c. bar :-



$$\bar{J} = 0$$

$$I_{drift} + I_{diff} = 0.$$

$$I_n + I_p + I_n + I_p = 0$$

$I_p = 0$. we are taking about holes, so, ignore I_n .

$$I_{pdiff} + I_{pdiff} = 0.$$

$$pqM_p E - qD_p \frac{dp}{dx} = 0.$$

$$E = \frac{D_p}{M_p} \frac{1}{P} \frac{dp}{dx}$$

$$-\int_{V_1}^{V_2} \frac{dv}{dx} dx = V_T \int_{P_1}^{P_2} \frac{1}{P} \frac{dp}{dx} dx$$

$$V_2 - V_1 = V_T (-\ln P) \Big|_{P_1}^{P_2}$$

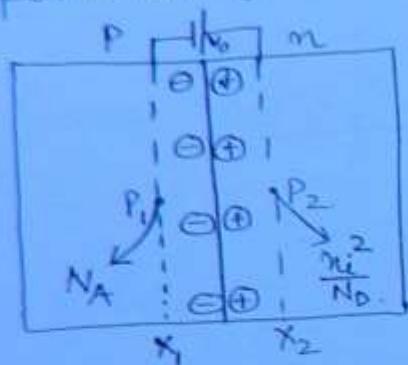
$$V_2 - V_1 = V_T \ln \left(\frac{P_1}{P_2} \right)$$

$$\left. \begin{array}{l} P_1 = P_2 e^{-V_0/N_T} \\ P_2 = P_1 e^{-V_0/N_T} \end{array} \right\} \begin{array}{l} \text{Boltzmann} \\ \text{relation} \end{array}$$

Kinetic gas theory.

(42)

Q10/11
Applying the Boltzmann relation in a o.c. pn junction to find
the barrier potential V_0



$$V_0 = N_T k_B \left[\frac{N_A N_D}{n_i^2} \right] \quad N_A, N_D \rightarrow \text{Doping conc.}$$

$$V_0(\text{Ge}) = 0.1 \text{ to } 0.3 \text{ V}$$

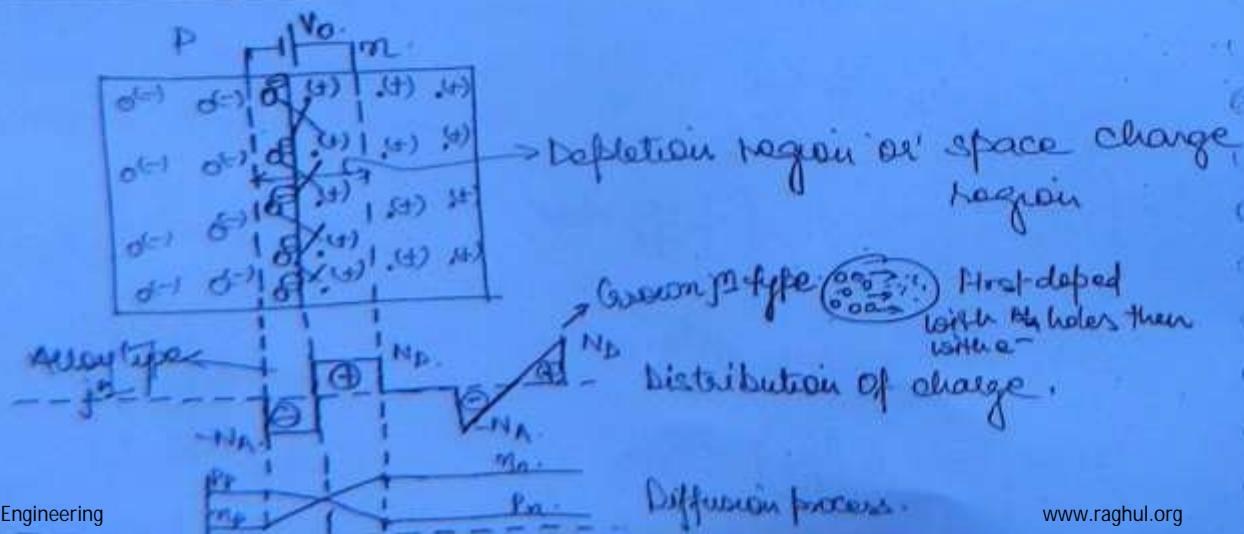
$$V_0(\text{Si}) = 0.5 \text{ to } 0.7 \text{ V}$$

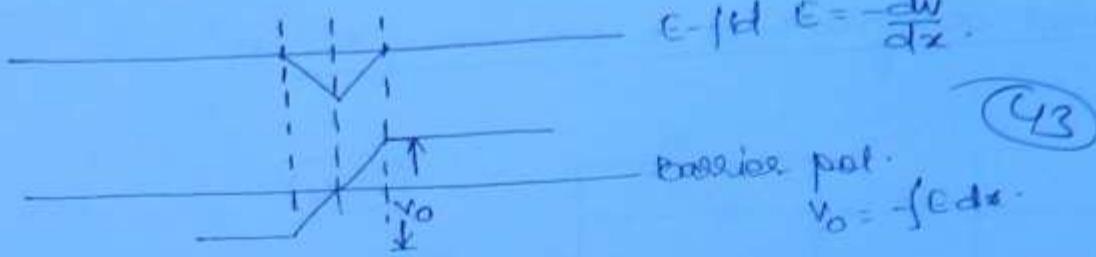
$$n_i(\text{Ge}) = 2 \times 10^{13} / \text{cm}^3$$

$$n_i(\text{Si}) = 1.5 \times 10^{10} / \text{cm}^3$$

P-N Junction Diode :

open ckt P-n junction : →





Barrier pot.
 $V_0 = \int \epsilon dE$

(43)

Mobile charge carriers

e⁻ holes

Immobile charge carriers

donor ions acceptor ions

Pn jⁿ formation techniques

$W \propto \sqrt{V_j}$

Alloy type jⁿ

↓
Step graded jⁿ

↓
Sudden change or
abrupt change.

$W \propto \sqrt[3]{V_j}$

Carrousel jⁿ type

↓
to linearly graded jⁿ

↓
diffused type

V_0 or V_j or V_T →

Barrier potential
'or'

Built in Voltage
'or'

Cut in Voltage
'or'

Contact potential
'or'

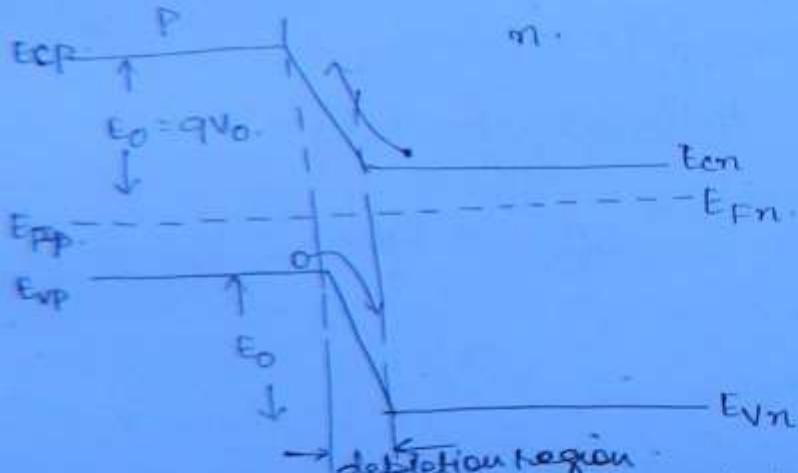
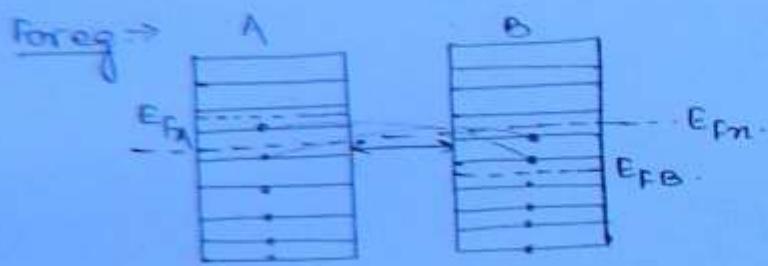
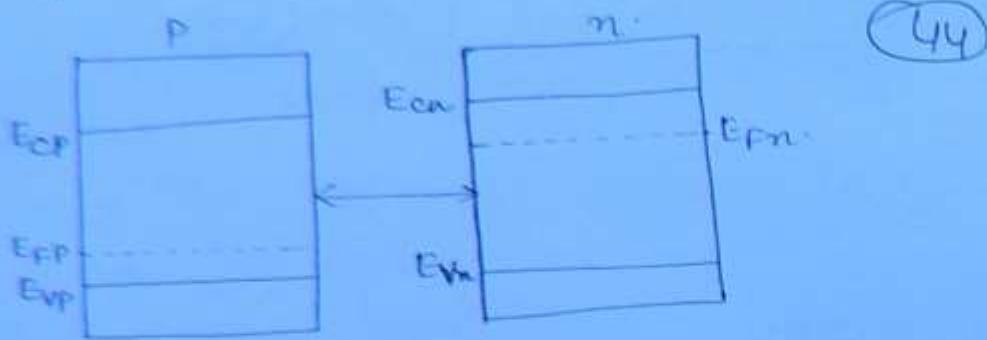
Depletion voltage
'or'

Space charge voltage
'or'

Transition voltage.

* Electric fld will be more conc. on
the jⁿ.

Energy band diagram in a diode $P-n$

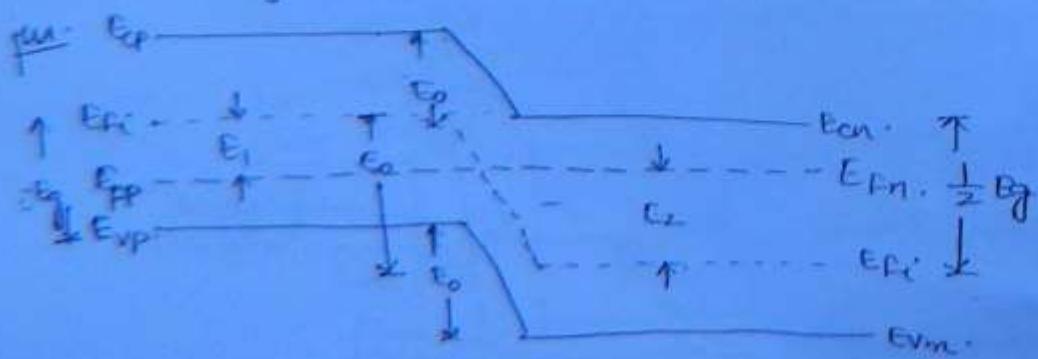


$E_0 \rightarrow$ potential en for an e^-

$V_0 \rightarrow$ Depletion pot.

Note → Any two materials are joined fermi levels will be in aligned position.

{ Derive an expression for pot. en for an e^- , E_0 from En. band theory concept. }



$$E_0 = E_{CP} - E_{CN}$$

"or"

$$= E_{VP} - E_{VN}$$

"or"

$$= E_1 + E_2$$

(45)

$$E_{FP} - E_{VP} = \frac{1}{2} E_g - E_1 \quad \text{---(1)}$$

$$E_{CN} - E_{FN} = \frac{1}{2} E_g - E_2 \quad \text{---(2)}$$

$$E_0 = E_1 + E_2$$

$$= E_g - \{E_{FP} - E_{VP}\} - \{E_{CN} - E_{FN}\}$$

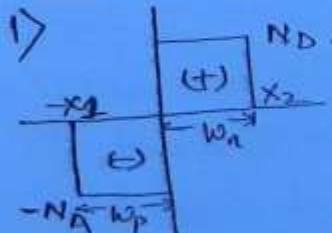
$$= KT \ln \left(\frac{N_c N_V}{m_i^2} \right) - KT \ln \left(\frac{N_V}{N_A} \right) - KT \ln \left(\frac{N_c}{N_D} \right)$$

$$= KT \ln \left(\frac{N_c N_V}{m_i^2} \frac{N_A}{N_V} \frac{N_D}{N_c} \right)$$

$$E_0 = KT \ln \left(\frac{N_A N_D}{m_i^2} \right) \text{ ev.}$$

$$V_0 = \frac{KT}{q} \ln \left(\frac{N_A N_D}{m_i^2} \right) \text{ ev.}$$

Formulas based on o.c. P-N j2.



Net charge densities = 0.

Positive charge densities = -ive charge densities.

$$q N_D w_n = q N_A w_p$$

$$\frac{N_D}{N_A} = \frac{w_p}{w_n}$$

neutrality concept

$$2) \frac{\partial^2 V}{\partial x^2} = -\frac{P}{\epsilon}$$

3) $f : q_{ND} \quad 0 < x < x_2$
 $-q_{NA} \quad -x_1 < x < 0$
 $0 \quad \text{else.}$

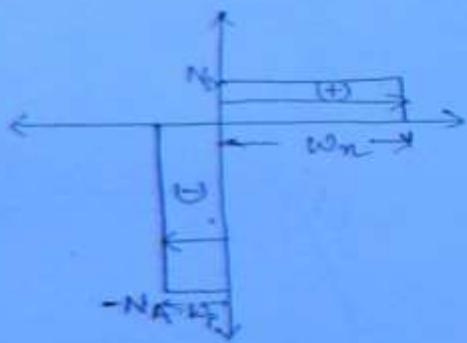
(16)

$$4) E = \left| \frac{q_{ND}\omega}{\epsilon} \right| = \left| \frac{q_{NA}\omega}{\epsilon} \right|$$

$$V_0 = \left| \frac{q_{ND}\omega^2}{2\epsilon} \right| = \left| \frac{q_{NA}\omega^2}{2\epsilon} \right|$$

$$\boxed{\omega \propto \sqrt{V_0}}$$

5) P+N.

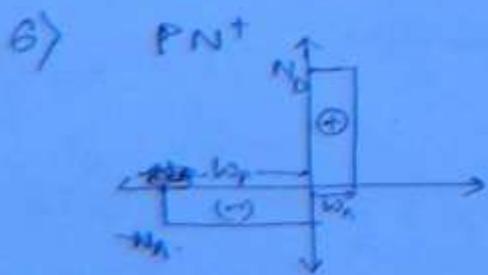


$$\omega_n + \omega_p = \omega$$

$$\omega \approx \omega_n$$

$$E = \left| \frac{q_{ND}\omega}{\epsilon} \right|$$

$$V_0 = \left| \frac{q_{ND}\omega_n^2}{2\epsilon} \right|$$



$$\omega \approx \omega_p$$

$$E = \left| \frac{q_{NA}\omega_p}{\epsilon} \right|$$

$$V_0 = \left| \frac{q_{NA}\omega_p^2}{2\epsilon} \right|$$

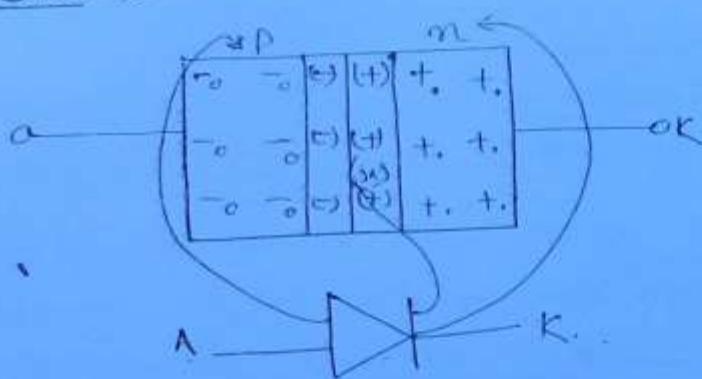
- Note →
- 1) When the material is lightly doped one, the penetration of the depletion region will be more.
- 2) When material is heavily doped, the penetration of the depletion region will be narrower. (Q7)

$$w = \left[\frac{2\epsilon_0 \epsilon_r V_i}{q} \left(\frac{1}{N_A} + \frac{1}{N_D} \right) \right]^{1/2}$$

$$w_n = \left\{ \frac{2\epsilon_0 \epsilon_r V_i}{q} \frac{1}{N_D} \right\}^{1/2}$$

$$w_p = \left\{ \frac{2\epsilon_0 \epsilon_r V_i}{q} \frac{1}{N_A} \right\}^{1/2}$$

Bias →



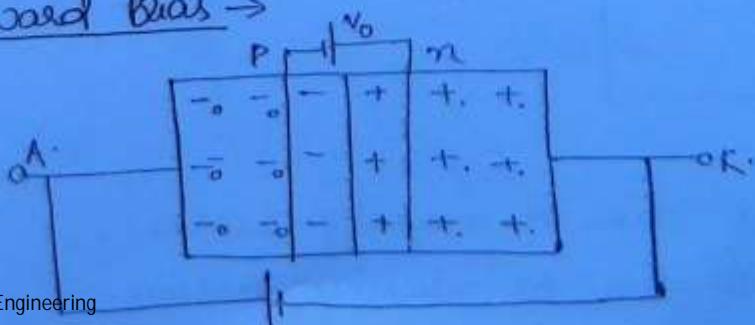
→ Guru Adding an ext dc Voltage to a P-n j^o diode is called 'Bias'

→ There are two types of Bias —

1) Forward bias

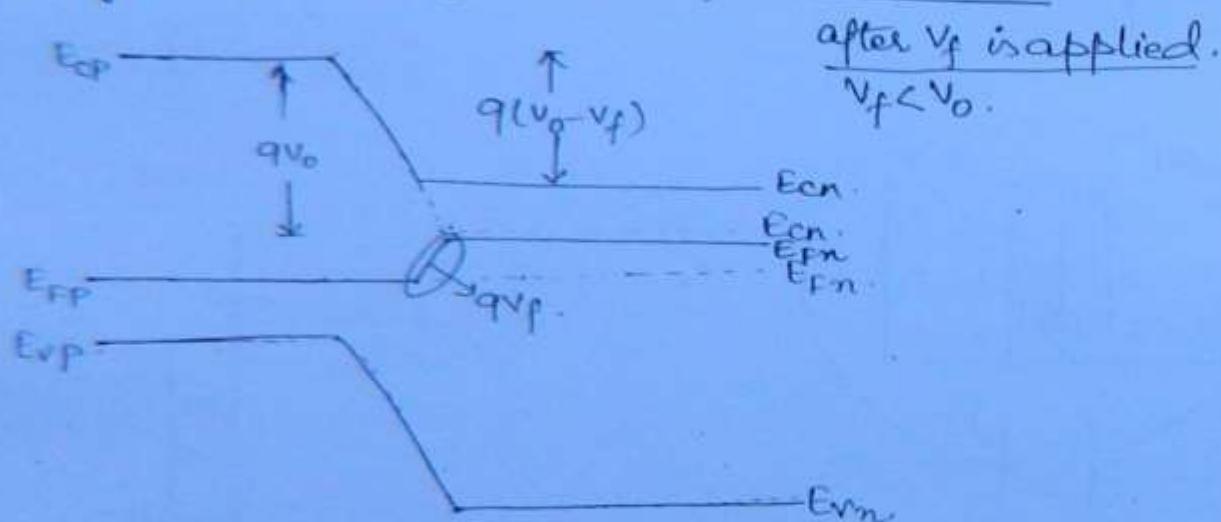
2) Reverse bias.

Forward Bias →

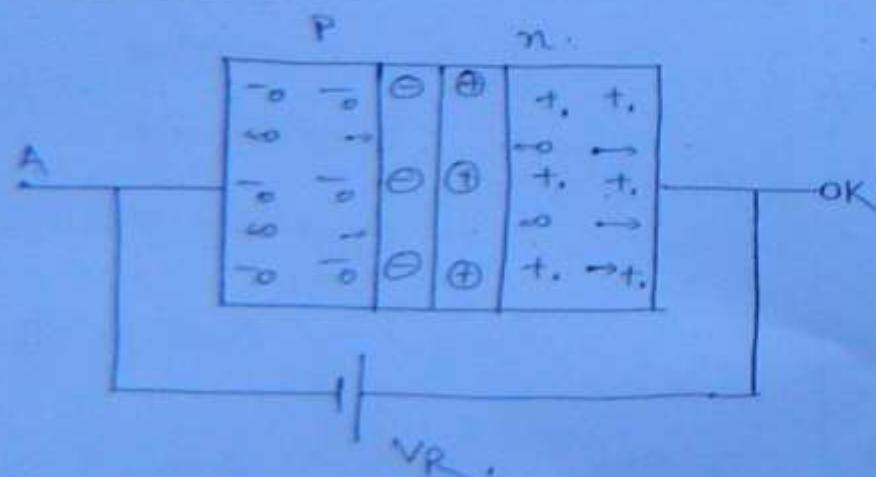


- 1) If $V_f > V_0$, current conduction is possible. (48)
- 2) The current is possible due to majority carriers and that majority current is represented by $I_f = mA$.
- 3) The current will be zero due to minority carriers.
- 4) The depletion region becomes narrower or negligible.
- 5) In $\text{en}-\text{v}$ band diagram, barrier height decreases.
- 6) Resistance offered by the diode is very less.

Energy band diagram in forward bias:



Reverse bias →



- 1) The current will be 0 due to majority carriers.
- 2) The current is possible due to minority carriers.

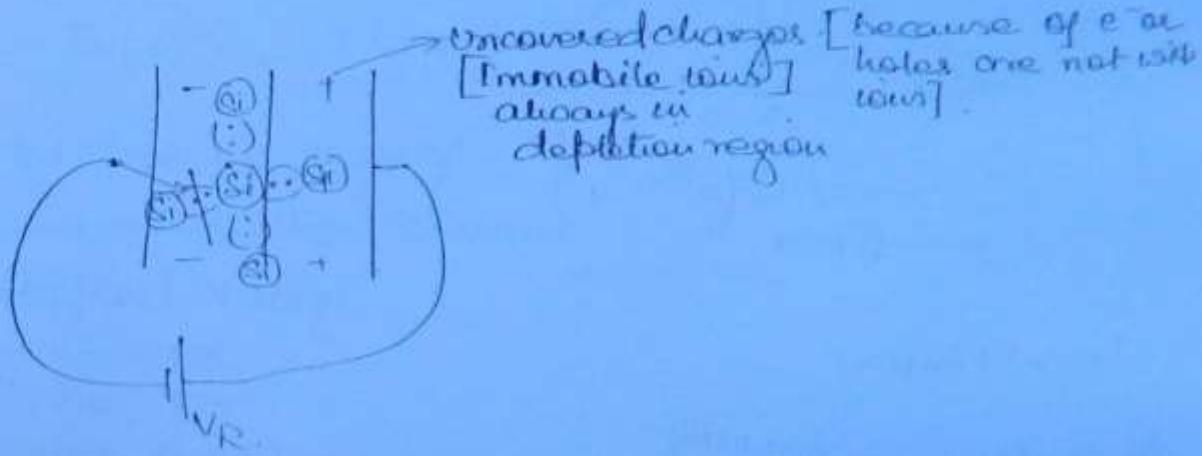
3) Minority carrier can move in reverse as reverse saturation current. [I_0 or I_s]

$$\begin{matrix} I_{OA} \\ (Be) \end{matrix} \quad \begin{matrix} I_{SA} \\ (Si) \end{matrix}$$

(49)

Q: Why the reverse saturation current for Be is in 'mA' and for Si it is in 'nA'?

A:



→ In the depletion region, there will be some stable atoms along with uncovered charges.

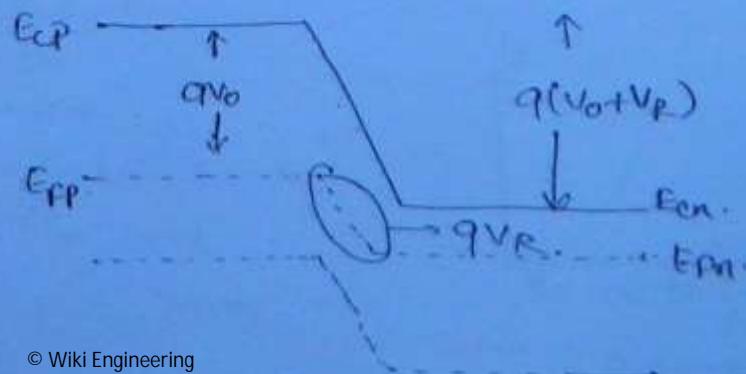
→ As the reverse bias voltage increases, the velo. of the minority charge carrier increases which collides with the stable atom in the depletion region.

→ As the en. gap value for Be is less compare to Silicon we expect I_0 to will be in mA for Be and nano amp. in Silicon.

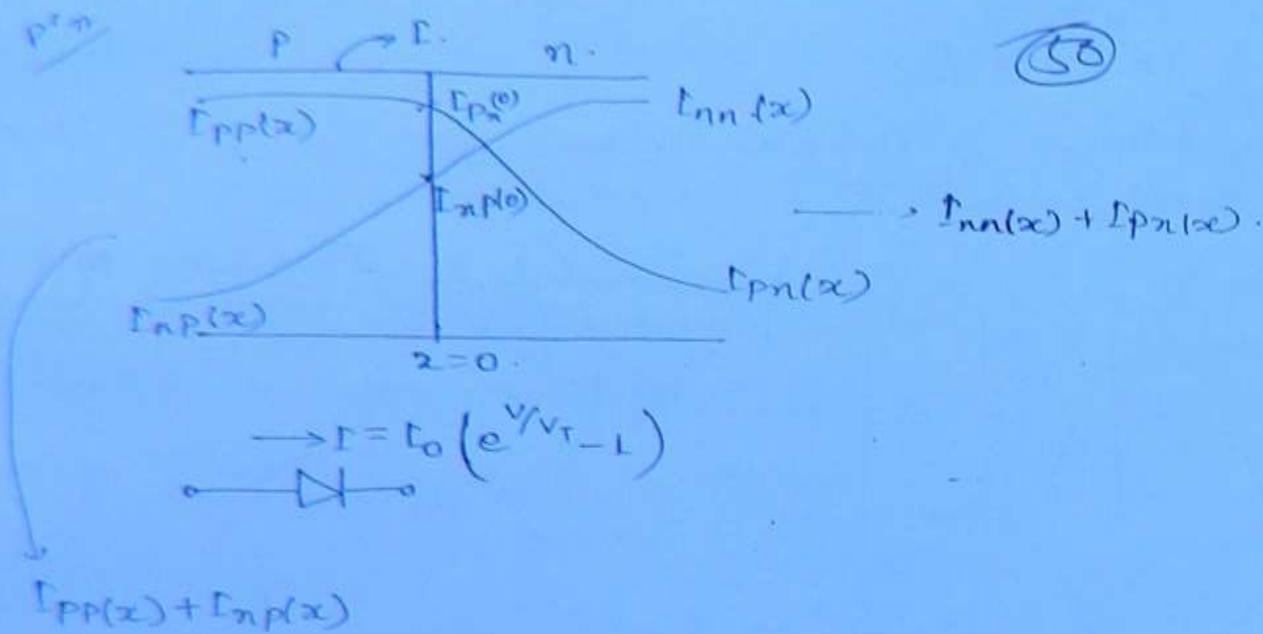
→ Depletion region becomes wider in reverse bias.

→ In en. band diagram, barrier height increases.

→ Resistance offered is very high in the order of M Ω .



Current components in p-n diode :-



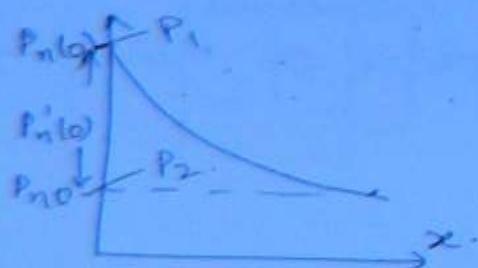
At $x=0$, minority minority

$$I = I_{pn}(0) + I_{np}(0)$$

$$\begin{aligned} I_{pn}(x) &= -Aq D_p \frac{dP(x)}{dx} \rightarrow P_n'(0) e^{-x/L_p} \\ &= \frac{-Aq D_p P_n'(0) e^{-x/L_p}}{-L_p} \end{aligned}$$

at $x=0$,

$$I_{pn}(0) = \frac{Aq D_p P_n'(0)}{L_p} = Aq D_p P_{n0} (e^{V/V_T - 1})$$



$$P_n(0) = P_{n0} e^{V/V_T} \rightarrow \text{Law of JN}$$

$$P_n'(0) = P_n(0) - P_{n0}$$

$$= P_{n0} (e^{V/V_T - 1})$$

$$P_1 = P_2 e^{V_{21}/V_T}$$

$$I = \left[\frac{AqD_p P_n(0)}{L_p} + \frac{Aq D_n n_p(0)}{L_n} \right] (e^{\frac{V}{V_T}} - 1)$$

\downarrow
 I_0

(S)

3/12/11

Diode current equation :-

$$I = I_0 (e^{\frac{V}{nV_T}} - 1)$$

I → Total current through diode

I_0 → Reverse saturation current

V → Applied Voltage.

→ +ve FB

→ -ve RB

n → Idealised factor

= 1 (ce)

= 2 (si).

V_T → Volt eq temp.

$$= \frac{T}{11,600}$$

At 300K, $V_T \rightarrow 26mV$.

Diode current eq: can also be called as V-I char. eq:.

VI characteristics of P-n diode :-

$$I = I_0 (e^{\frac{V}{nV_T}} - 1)$$

Case 1 →

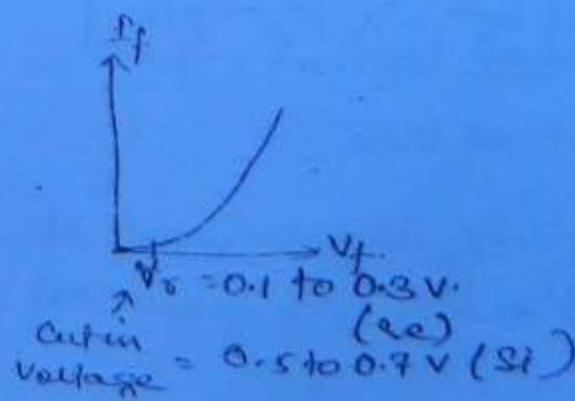
F.B.

$V \rightarrow$ +ve

$$I = I_0 (e^{\frac{V}{nV_T}} - 1)$$

$$e^{\frac{V}{nV_T}} \gg 1$$

$$I = I_0 e^{\frac{V}{nV_T}}$$



Case 2:

RB.

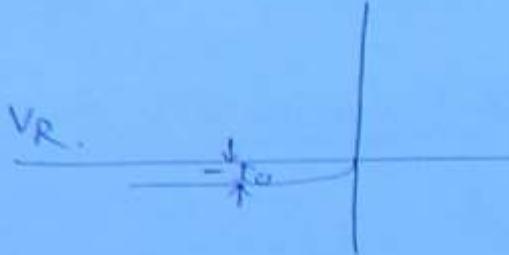
$V \rightarrow -V_T$

$$I = I_0 \left(e^{-\frac{V}{nV_T}} - 1 \right)$$

$$e^{-\frac{V}{nV_T}} \ll 1$$

$$I \approx -I_0$$

(52)



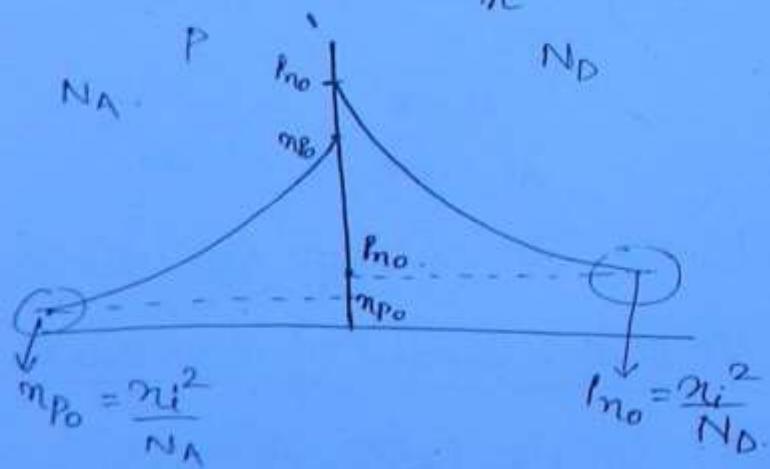
Temp dependence on VI char. of P-n diode : \rightarrow

$$I = I_0 \left(\frac{V}{e^{nV_T}} - 1 \right)$$

$I_0 \propto T^{\beta}$ \rightarrow

$$\begin{aligned} I_0 &= \left[\frac{AqD_p P_{n0}}{L_p} + \frac{Aq D_n n_p o}{L_n} \right] \\ &= \left[\frac{D_p}{L_p N_D} + \frac{D_n}{L_n N_A} \right] Aq n_i^2 \end{aligned}$$

$$= \frac{D_p}{L_p N_D} + \Delta$$



Property \rightarrow

$\frac{dI}{dV}$

$$I_0 \propto n_i$$

I_0

$$D \propto \frac{1}{T}$$

$$n_i^2 = A_0 T^3 e^{-E_g / kT}$$

For $\frac{dI}{dV}$ \rightarrow

$$I_0 = k_1 T^{3/2} e^{-\frac{E_g}{2kT}}$$

For I_0 ,

$$I_0 = K_2 T^2 e^{-\frac{E_{g0}}{kT}}$$

(53)

$$I_0 = K' T^m e^{-\frac{E_{g0}}{nKT}}$$

	m	E_{g0}	n
Si	1.5	1.21	2
Ge	2	0.785	1

Relative temp co-eff of I_0

$$\frac{\partial I_0}{I_0} / \partial T$$

$$\ln I_0 = \ln K' + m \ln T - \frac{E_{g0}}{nKT}$$

diff w.r.t ΔT

$$\frac{1}{I_0} \frac{dI_0}{dT} = 0 + \frac{m}{T} + \frac{E_{g0}}{nKT^2}$$

Q.E.D.

$$\frac{\partial I_0}{I_0} / \partial T = \left[\frac{2}{300} + \frac{0.785}{2 \cdot 0.026 \times 300} \right] = 10.7\% / {}^\circ C \quad \rightarrow 7\% / {}^\circ C$$

Si,

$$\frac{\partial I_0}{I_0} / \partial T = \frac{1.5}{300} + \frac{1.21}{2 \cdot 0.026 \cdot 300} = 8.27 / {}^\circ C$$

$$(1.07)^{10} = 2$$

→ for every $10^\circ C$ rise in temp, I_0 will be double

→ for every $1^\circ C$ " " " , I_0 will be 7%.

∴ I_0 increases by 7% for every degree centigrade rise in temp. or I_0 doubles for every $10^\circ C$ rise in temp.

Applied Voltage V/S Temp :-

$$\frac{dV}{dT} = -2.5 \text{ mV}/^\circ\text{C}$$

(54)

$$I = I_0 (e^{\frac{V}{nV_T}} - 1)$$

$$F.B. \frac{V}{nV_T}$$

$$I = I_0 e^{\frac{V}{nV_T}}$$

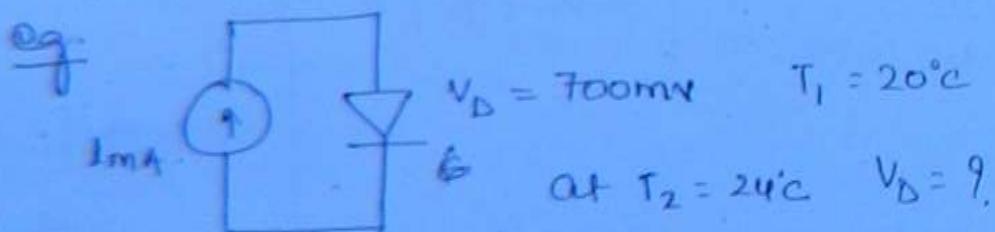
$$\Rightarrow V = nV_T \ln\left(\frac{I}{I_0}\right)$$

diff. w.r.t T.

$$\begin{aligned} \frac{dV}{dT} &= -0.0019 \text{ V}, -0.0017 \text{ V} \xrightarrow{-2 \text{ mV}/^\circ\text{C}} \\ &= -1.9 \text{ mV}, -1.7 \text{ mV} \xrightarrow{0.5 \text{ mV}} \\ &\quad \downarrow \qquad \downarrow \\ &\quad \text{Si} \qquad \text{Ge} \end{aligned}$$

$$\frac{dV_D}{dT} = \frac{k \cdot P_D}{T} = -2.5 \text{ mV}/^\circ\text{C}, -2 \text{ mV}/^\circ\text{C}$$

↓ ↓
on 0.7 mV on 0.5 mV



Ans. $\frac{dV}{dT} = -2.5 \text{ mV}/^\circ\text{C}$

$$\begin{aligned} \therefore V_D &= 0.7 \text{ V} - 4 \times 2.5 \\ &= 0.700 \text{ mV} - 10 \text{ mV} \\ &= 630 \text{ mV} \end{aligned}$$

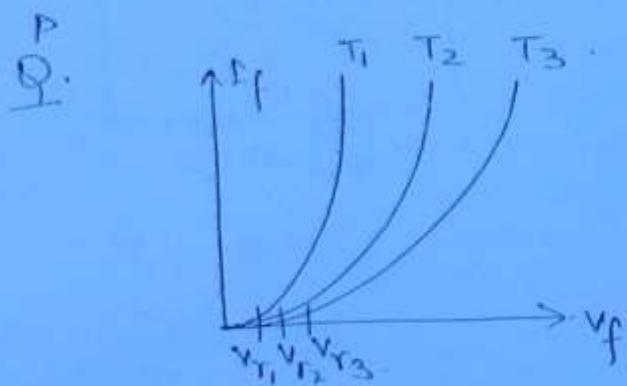
As $T \uparrow$, $v_T \uparrow$ and $v_D \downarrow$

v_T vs Temp. \rightarrow

$$v_T = \frac{T}{11600}$$

(S)

$T \uparrow, v_T \uparrow$



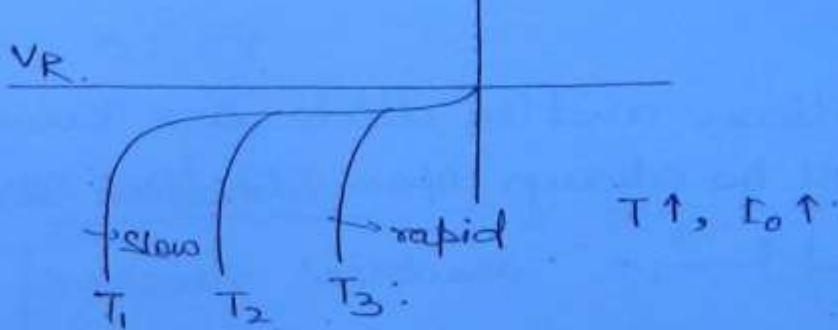
a) $T_1 < T_2 < T_3$

~~b)~~ $T_1 > T_2 > T_3$

c) $T_1 = T_2 = T_3$

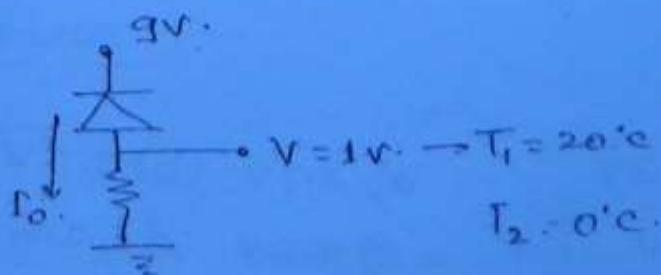
d) None.

Q.



$T_3 > T_2 > T_1$

Q



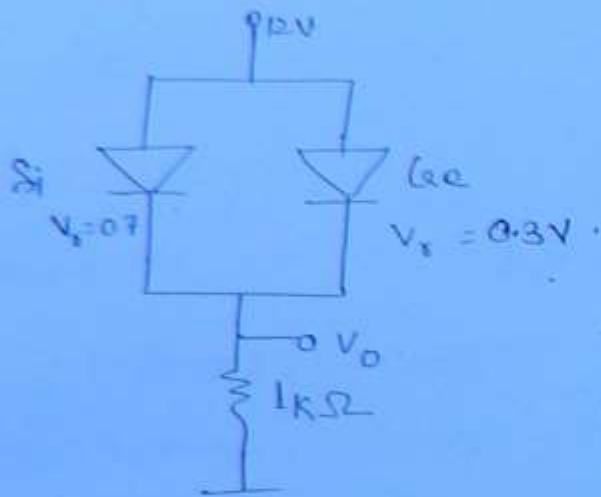
$$0^\circ C \quad I_0 \quad 10^\circ C \quad 20^\circ C \quad 30^\circ \quad 40^\circ$$

$$\frac{I_0}{4} \quad \frac{I_0}{2} \quad I_0 \quad 2I_0 \quad 4I_0$$

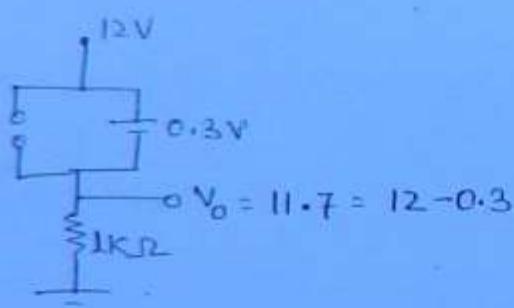
(56)

at $T_2 = 0^\circ C$, $V_t = 0.25 V$

Q.

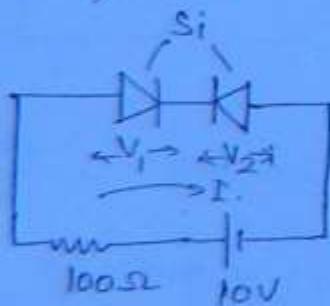


Ans:



- When a practical Silicon and Ge diode are connected in parallel, Silicon will be always open circuit (OFF state).

Q



$$V_1 =$$

- ~~a) 0.7~~ b) 9.3V
c) 8.6V d) 2.6V

$$V_2 =$$

- a) 0.7V ~~b) 9.3V~~
c) 8.6V d) 2.6V

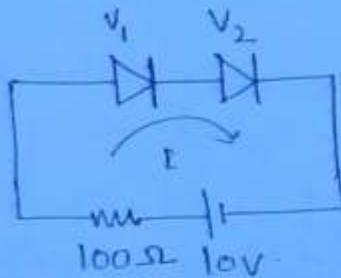
$$I = .$$

a) 3mA b) $\frac{3}{2}\text{mA}$

c) 6.2mA and I_0

(57)

2)

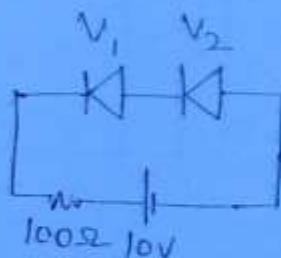


$$V_1 = 0.7$$

$$V_2 = 0.7$$

$$V = 8.6\text{mV} = \frac{10 - 0.7 - 0.7}{100} = 8.6 \times 10^{-3}\text{A}$$

3)



$$V_1 = 5\text{V}$$

$$V_2 = 5\text{V}$$

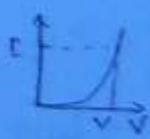
$$I = I_0$$

Diode resistance →

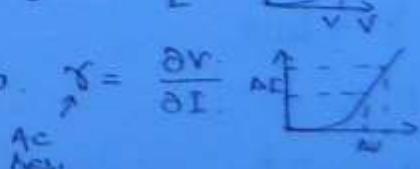
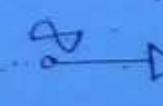
→ Static Resistance



$$R = \frac{V}{I}$$



→ Dynamic Resistance



Static resistance : →

$$R = \frac{V}{I}$$

F.B.

$$R = \frac{V}{I} = \frac{0.7\text{V}}{100\text{mA}} = 7\Omega$$

RB →

$$R = \frac{V}{I} = \frac{10V}{1mA} = 10 M\Omega$$

Dynamic resistance →

(58)

$$\lambda = \frac{\partial V}{\partial I}$$

$$g = \frac{\partial I}{\partial V} \\ = \frac{\partial I_0(e^{\frac{V}{nV_T}} - 1)}{\partial V} \\ = \frac{I_0 e^{\frac{V}{nV_T}}}{nV_T}$$

$$I = I_0(e^{\frac{V}{nV_T}} - 1)$$

$$\frac{V_T}{T} \text{ V/S temp}$$

$$V_T = \frac{T}{11600}$$

#

$$g = \frac{I + I_0}{nV_T}$$

for F.B. →

$$g = \frac{I}{nV_T}$$

typically

$$\eta = 1, I = 100mA, V_T = 26mV$$

$$g \approx > 1.$$

$\gamma \rightarrow \text{less}$

for R.B. →

$$g = \frac{2I_0}{nV_T} < 1$$

$\gamma \rightarrow \text{high}$

Junction capacitance :→

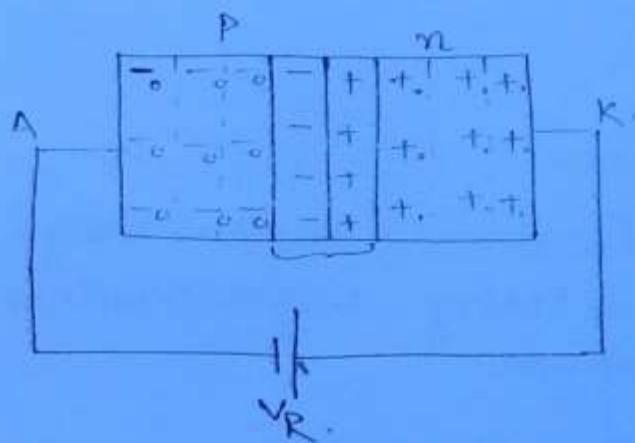
- transition capacitance → R.B.
- Diffusion capacitance → F.B.

(59)

Transition means depletion region. Depletion region exist only in R.B.

Diffusion is a process occurs in Forward Bias because of negligible depletion region.

Transition capacitance :— C_T → space charge
(C_T)



The rate of change of charge with the applied Voltage
—capacitance

The rate of change of immobile charge in the depletion region with the applied R.B. Voltage is a capacitive effect called as transition capacitance.

$$C = \frac{EA}{d}$$

$$C_T = \frac{EA}{w}$$

$$w \propto \sqrt{V_j} \quad w \propto \sqrt[3]{V} \quad \left. \begin{array}{l} \\ \end{array} \right\} \rightarrow \text{open circuit}$$

↓ ↓

(Alloy type) (Copper \int^n)

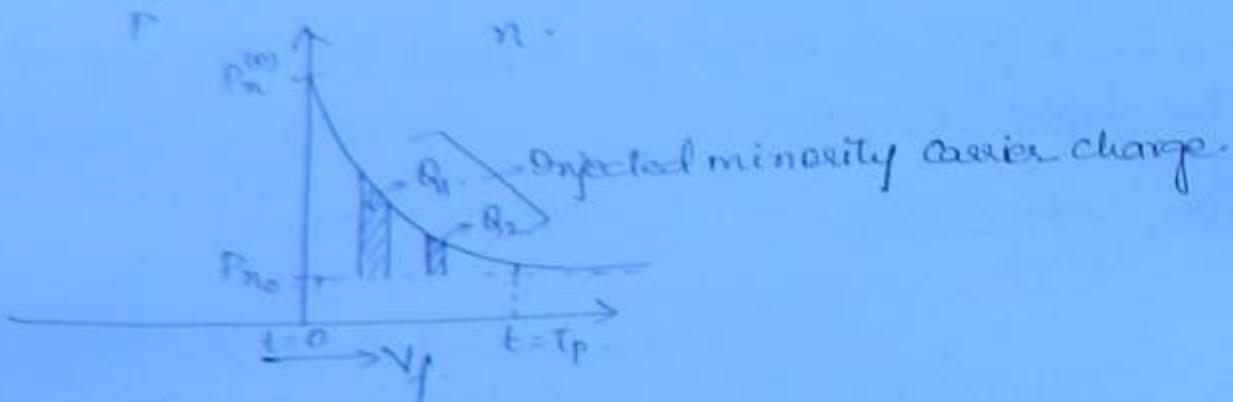
$$w \propto \sqrt{V_j + V_R} \quad \left. \begin{array}{l} \\ \end{array} \right\} \rightarrow \text{R.B.}$$

$$w \propto \sqrt[3]{V_j + V_R}$$

$C_d \propto \frac{1}{V_R}$ → nay type

$C_d \propto \frac{1}{\sqrt{V_R}}$ → brown type (68)

Diffusion Capacitance →



$P_n^{(in)}$ → Injected minority carrier conc.

The rate of change of injected minority carrier charge with the applied forward bias voltage is a capacitive effect called as diffusion capacitance.

$$Q = I_p t_p$$

$$C_D = \frac{dQ}{dV} = T_p \frac{\partial I_p}{\partial V} \rightarrow \frac{I_p + R_0}{\eta V_T}$$

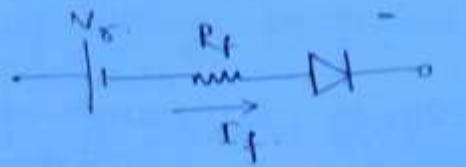
$$C_D = \frac{T_p \partial I_p / I_p}{V_T}$$

2/01/12 Diode equivalent models →

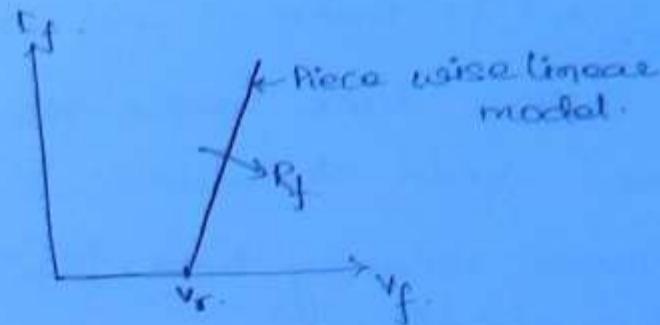
$$V_f \geq V_x + I_f R_f$$

Case 1 →

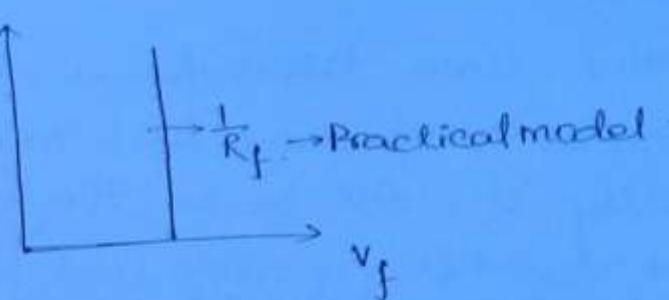
$$R_f = \text{const.}$$



(61)



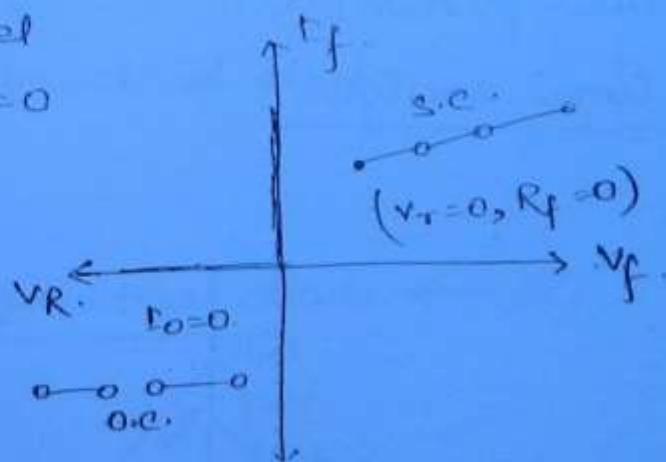
Case 2 →



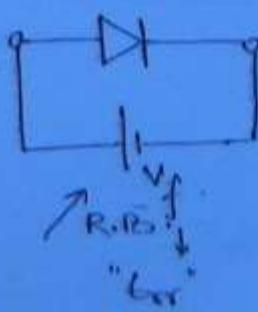
Cause 3 →

Ideal model

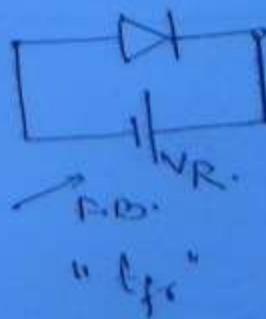
$$\cdot v_T = 0, R_f = 0$$



Diode Switching times :→



reverse Recovery time



forward Recovery time

t_f :-

It is the time taken for a diode to change forward biased mode to reverse biased mode.

Reverse recovery time practically, it will be in the order of μs. (62)

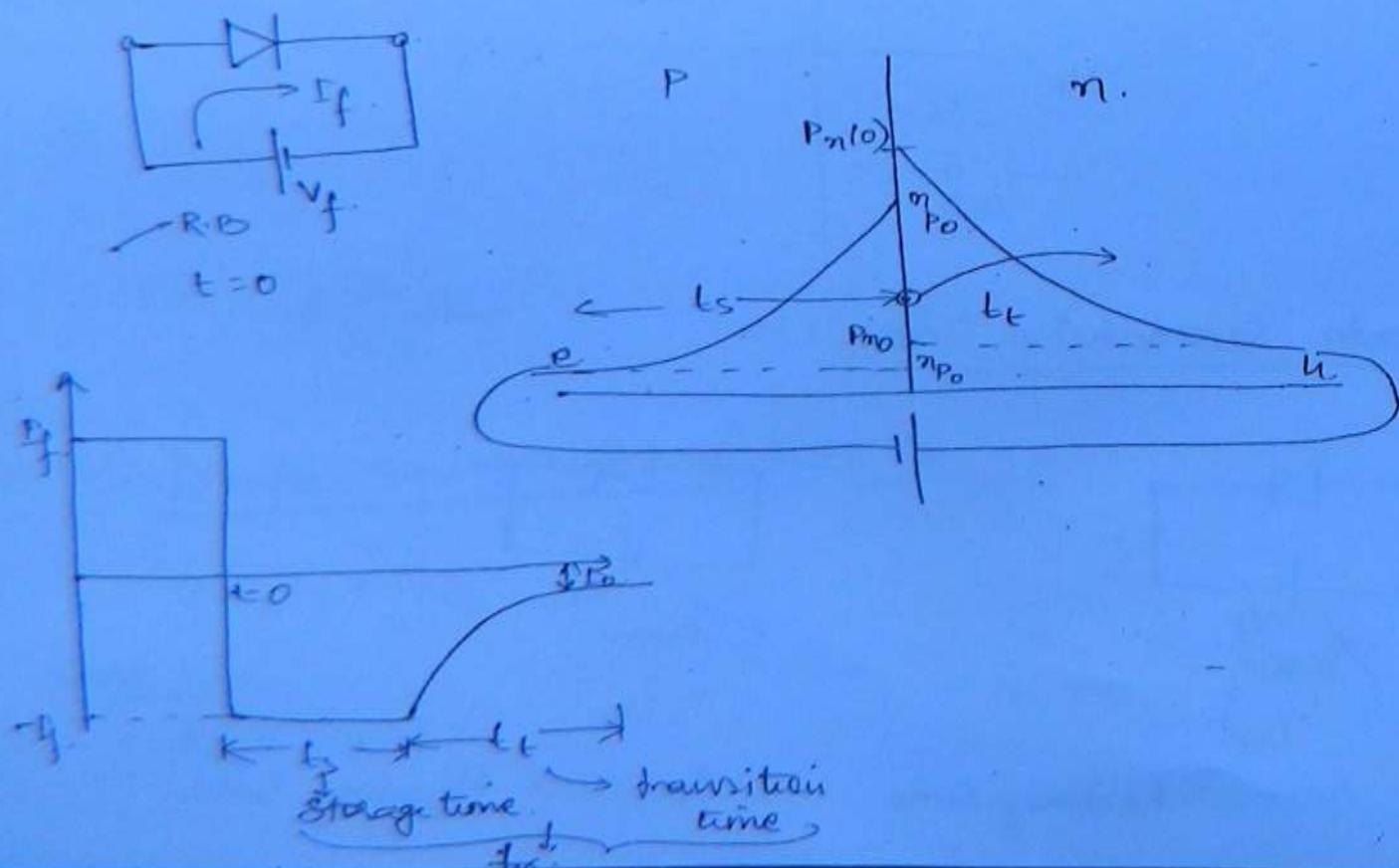
t_{fr} :-

It is the time taken for a diode to change reverse bias mode to forward bias mode.

Practically it will be in the order of Pico sec.

In high freq. applications, forward recovery time is neglected in the analysis (Pico sec) but reverse recovery time becomes a serious problem (μs)

Reverse Recovery time analysis :-



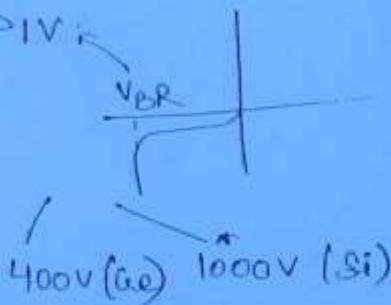
Q Why Si is preferred over Ge in most of the applications?

Ans) Temp

200°C (Si)

100°C (Ge)

2) PIV



(63)

PIV (Peak Inverse Voltage) →

It is the max reverse bias voltage applied to a diode.

The main drawback of silicon is cut-in voltage.

Diode problems →

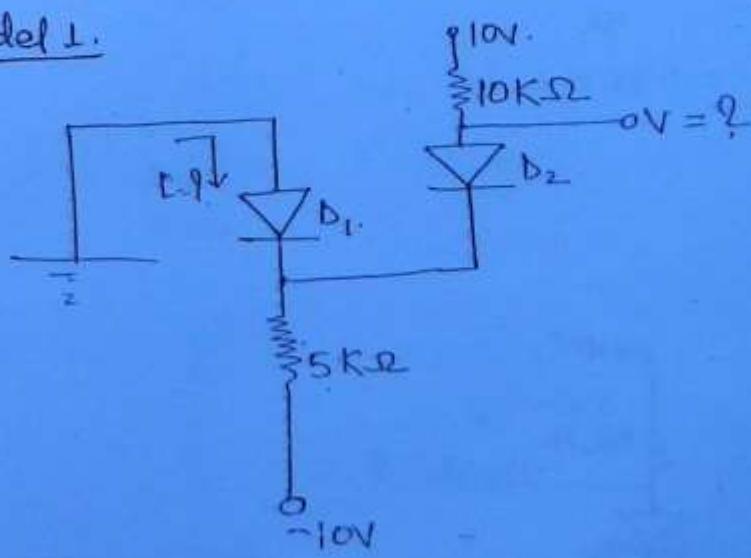
→ Ideal and practical diode

→ clippers

→ clampers.

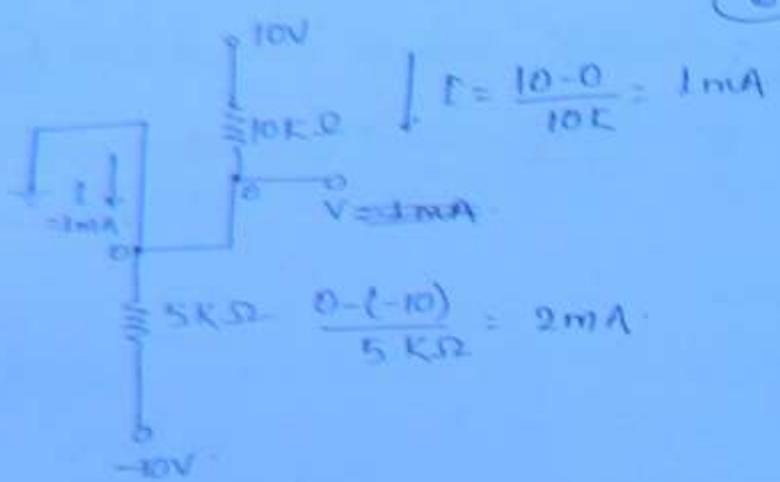
Ideal and practical diode :—

Model 1.



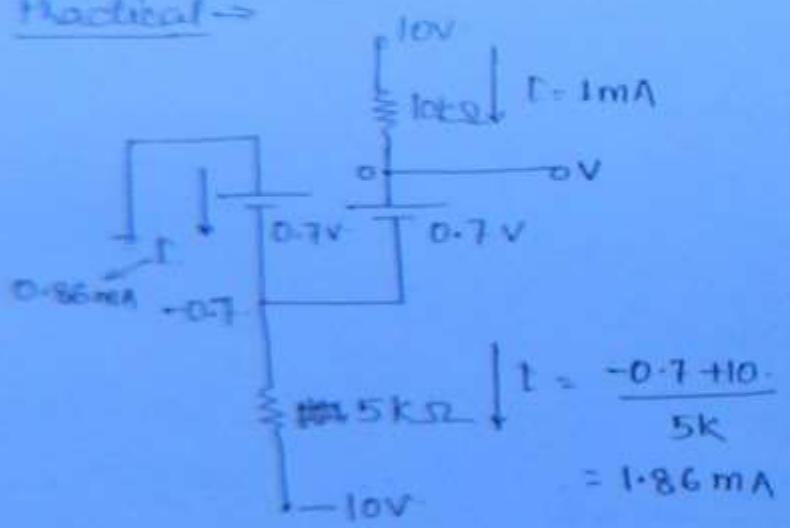
Assume D_1 and D_2 FB.

(64)



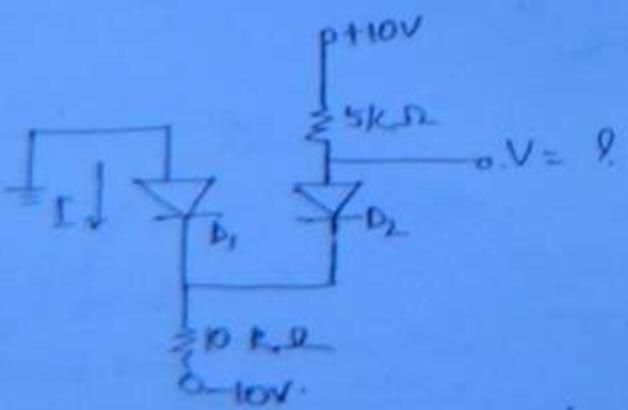
$$V = 0V$$
$$I = 1 \text{ mA}$$

Practical \rightarrow



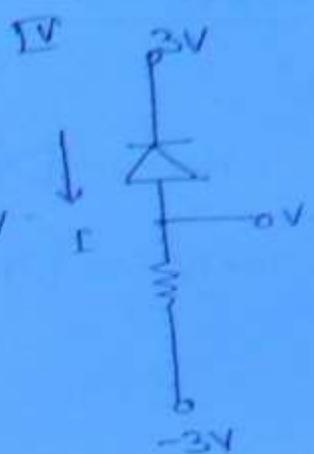
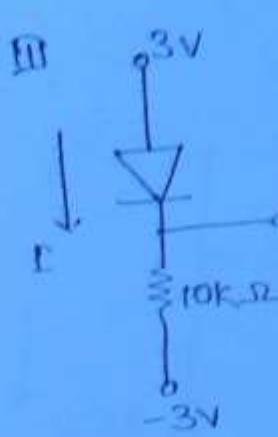
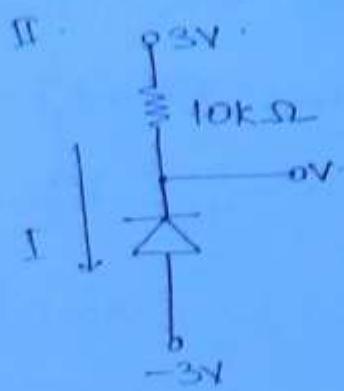
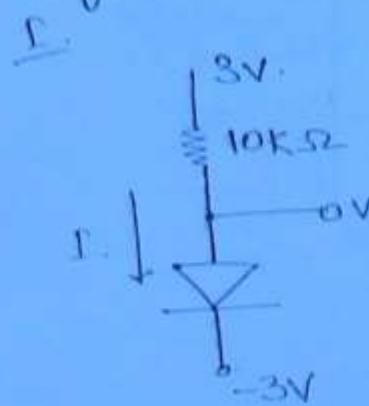
$$V = 0V$$
$$I = 0.86 \text{ mA}$$

model 2

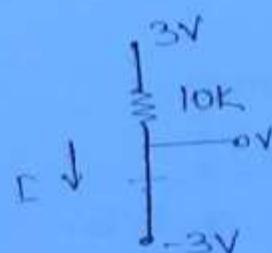


Single source problem →

Model - 1



V.



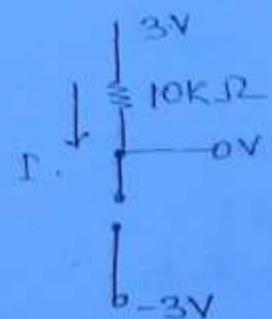
$$I = \frac{3 - (-3)}{10k} \text{ A}$$

$$= 0.6 \text{ mA}$$

$$V = -3 \text{ V}$$

(65)

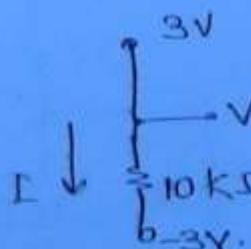
VI.



$$I = 0$$

$$V = 3 \text{ V}$$

VII.



$$V = 3 \text{ V}$$

$$I = 0.6 \text{ mA}$$

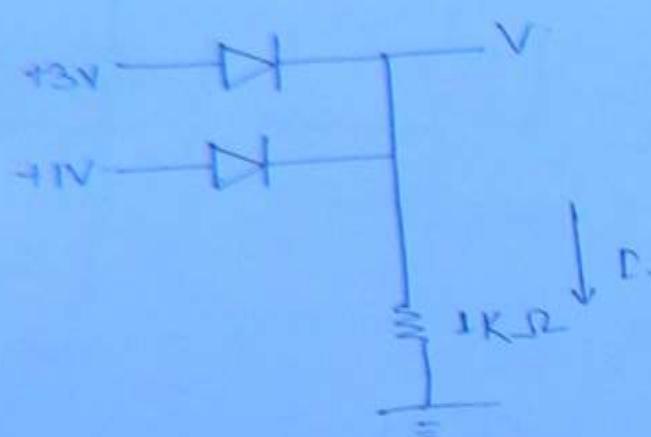
IV.



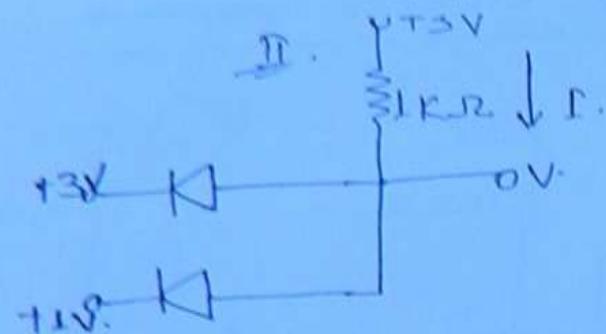
$$V = -3 \text{ V}$$

$$I = 0$$

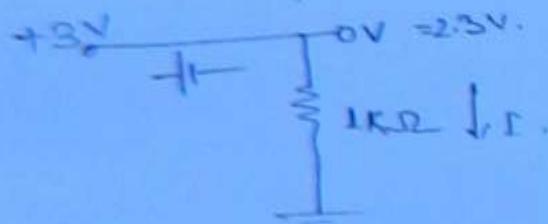
model - 3. \rightarrow



Q6



\Downarrow OR-logic.

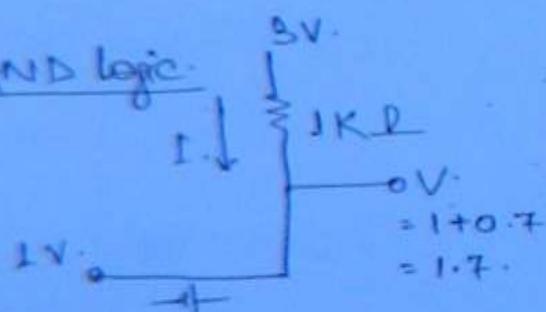


highest voltage is F.B.

$$V = 3V$$

$$I = 3mA$$

II. AND logic.



lowest voltage is F.B.

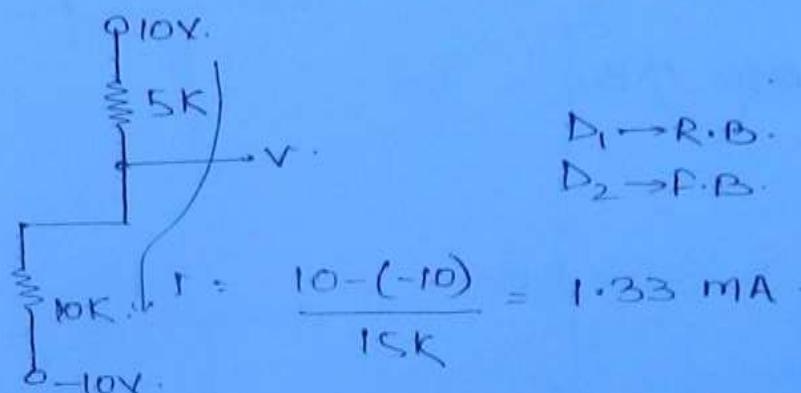
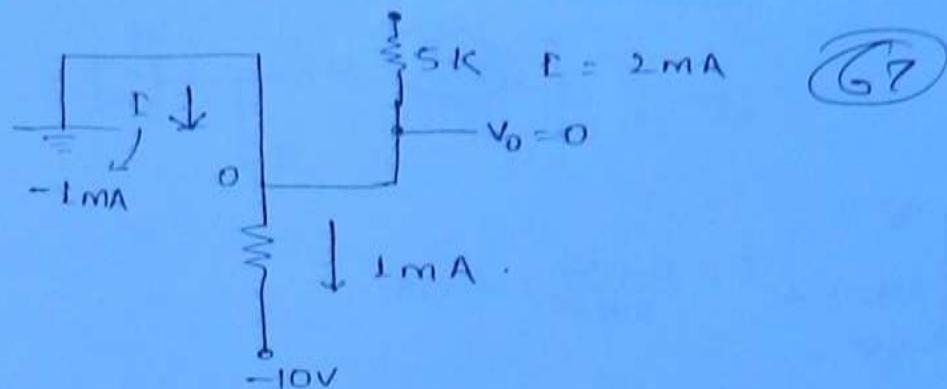
$$I = 2mA$$

$$V = 1V$$

- On OR logic problems highest I/P voltage applied to the diode will be the O/P.
- On AND logic problems, lowest I/P voltage applied to the diode will be the O/P.

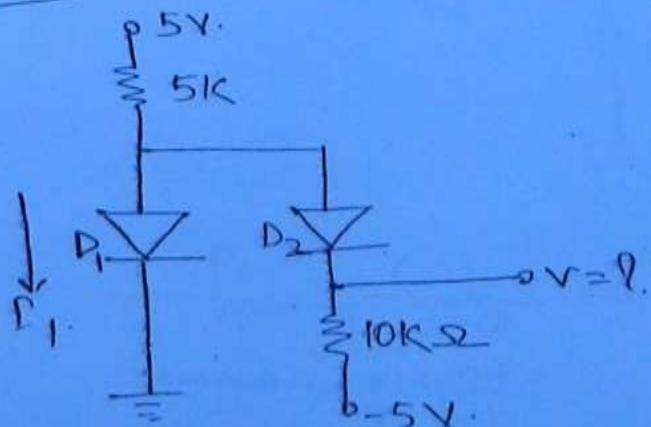
ideal ->

Assume D_1 and D_2 are P.B.

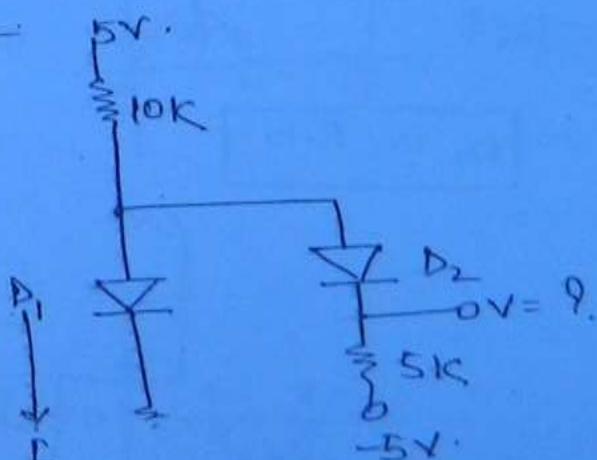


$$\begin{aligned} V &= 10k \times 1.33 \text{ mA} - 10 \\ &= 13.3 - 10 \\ &= 3.3 \text{ V} \end{aligned}$$

Ckt-1

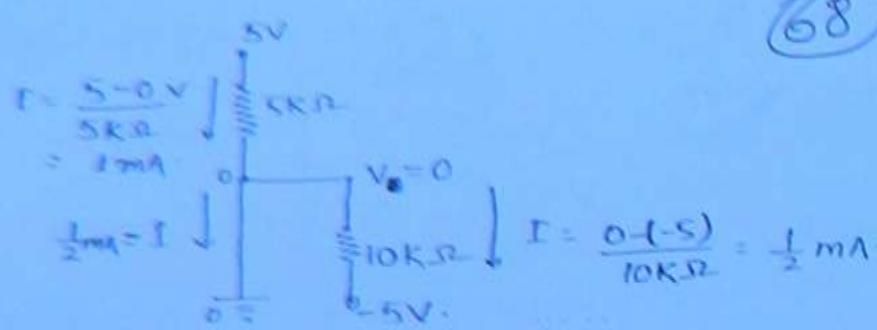


Ckt-2



Ckt 1: Assume D_1 and D_2 are F.B.

(68)

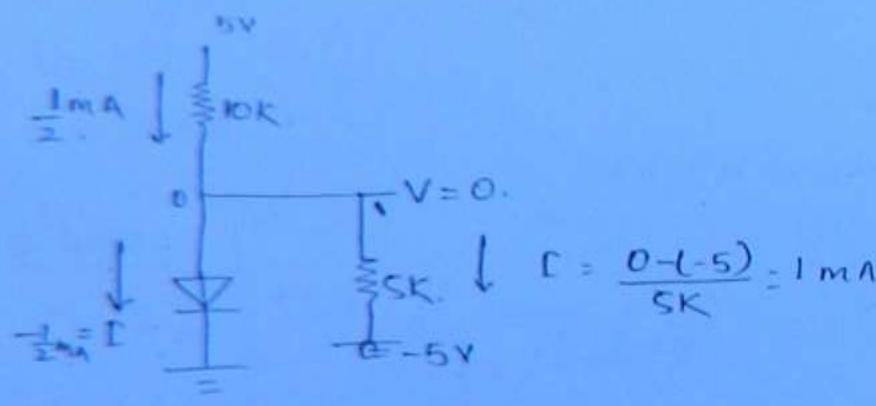


Assumption is true.

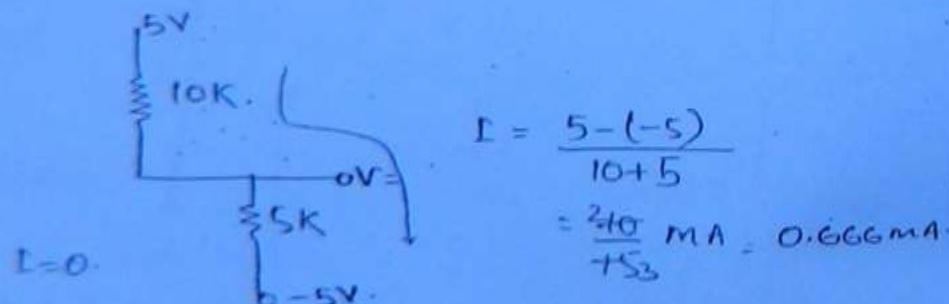
$\therefore D_1$ and D_2 are F.B.

Ckt 2:

Assume D_1 and D_2 are F.B.



D_1 is R.B.

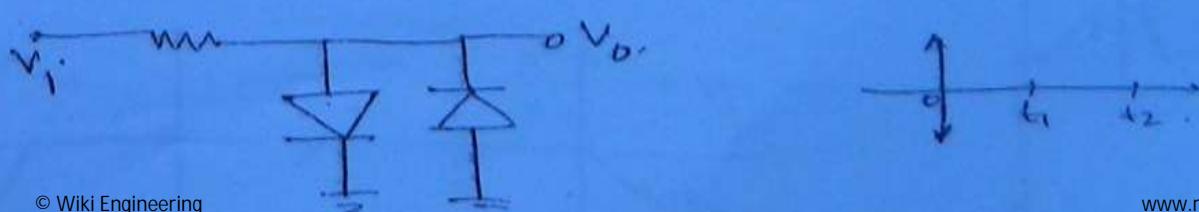
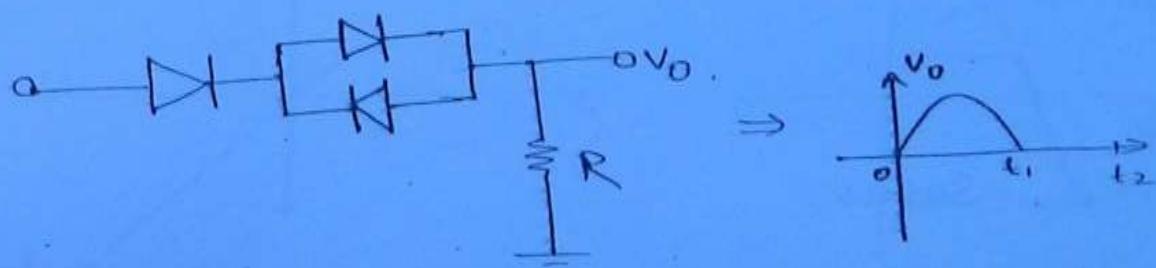
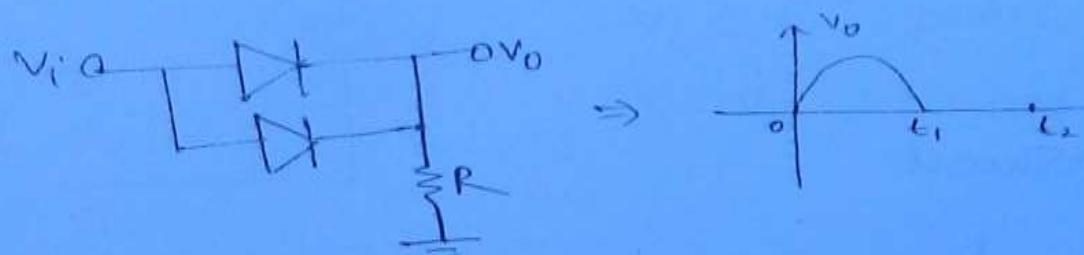
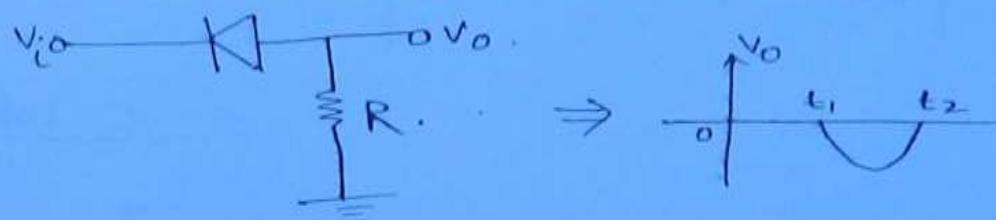
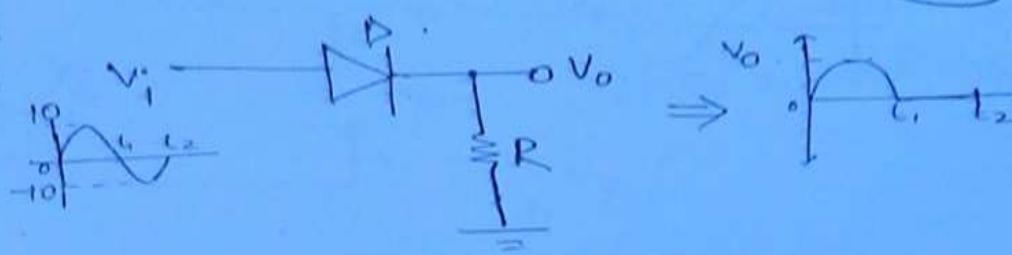


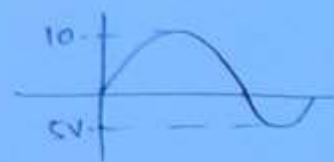
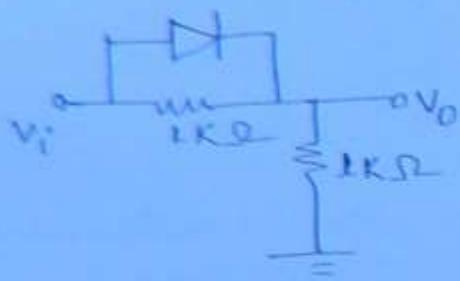
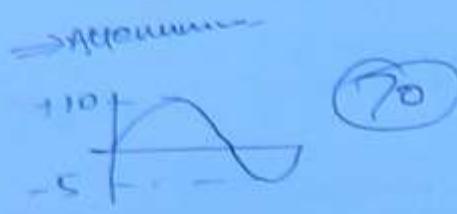
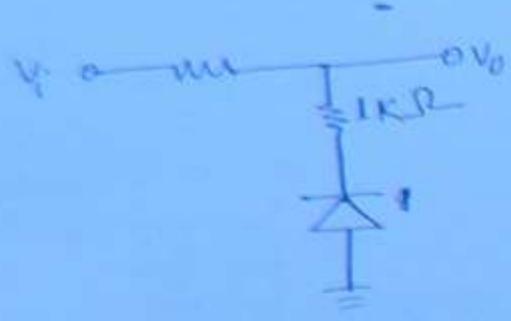
$$V = 5 - 10\text{k}\Omega \times 0.666\text{mA} \\ = -1.67\text{V}$$

Model 4:

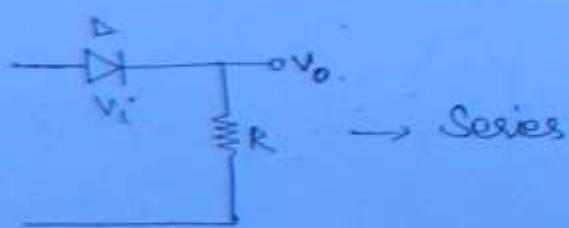
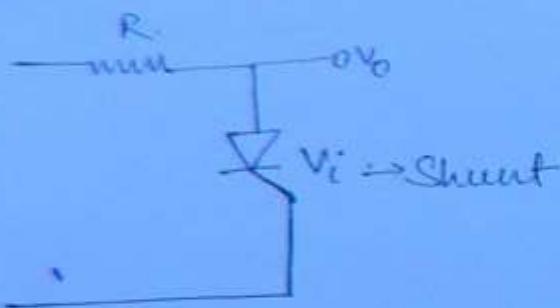
AC Analysis.

(69)

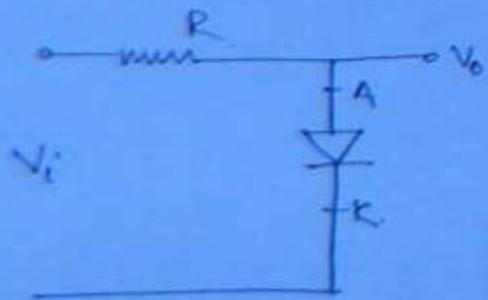




Clippers →

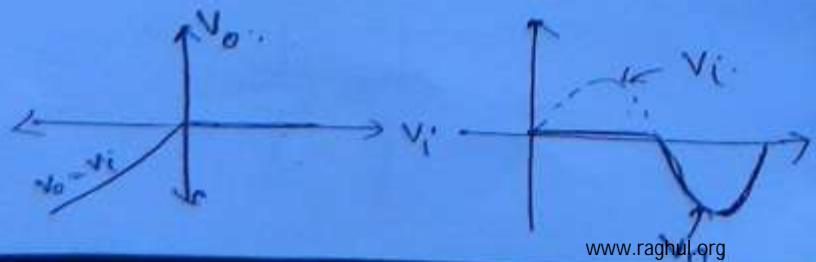


Shunt clippers →

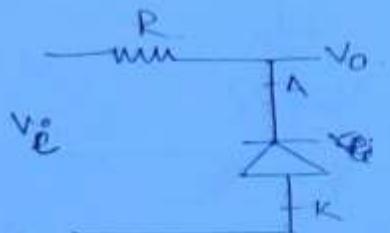


$V_i < 0 \rightarrow D \text{ off} \quad V_o = V_i$

$V_i > 0 \rightarrow D \text{ on} \quad V_o = 0.$

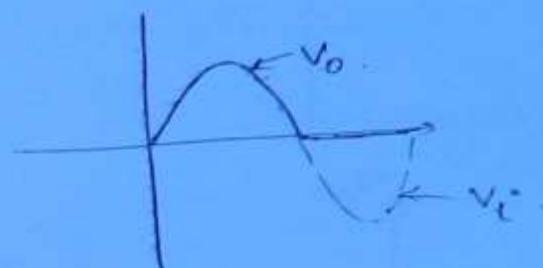
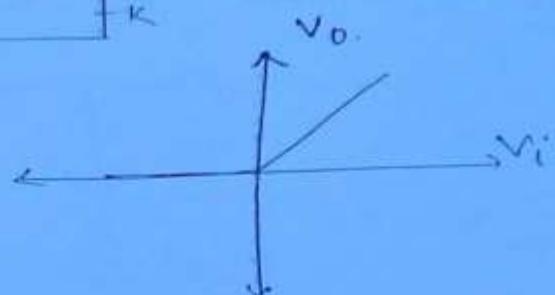


Model 1. →

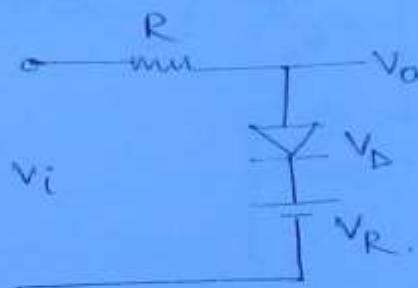


$V_i < 0$, D-ON $V_o \rightarrow 0$.
 $V_i > 0$, D-OFF $V_o = V_i$

(Q1)

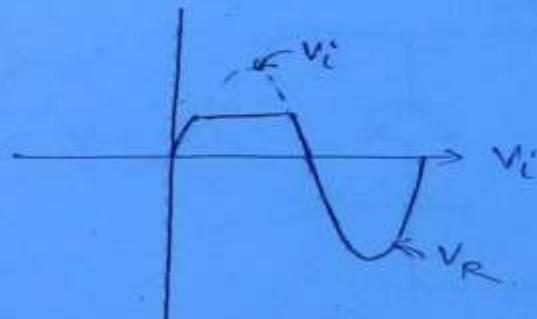
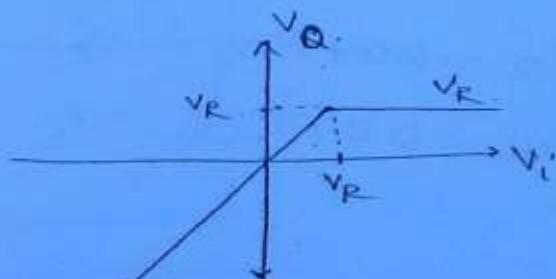


Model - 3. →

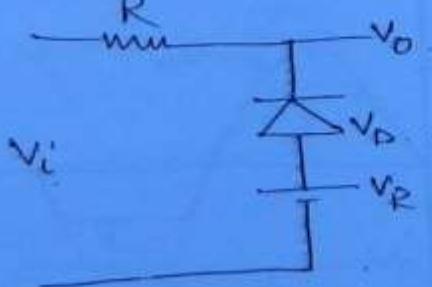


$V_i < V_R \rightarrow D\text{-OFF}, V_o = V_i$

$V_i > V_R \rightarrow D\text{-ON}, V_o = V_R + V_i$

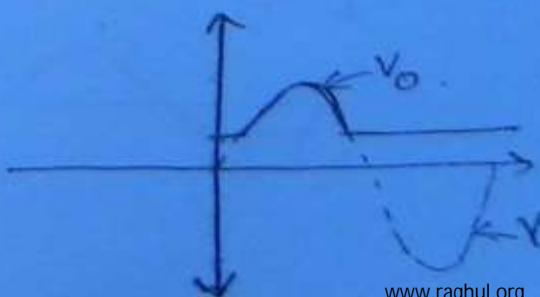
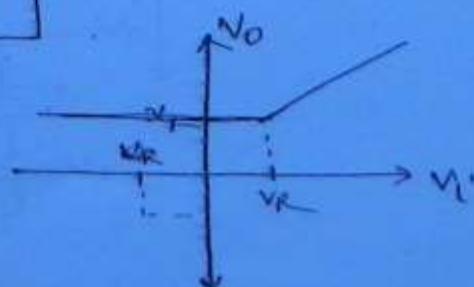


model - 4. →

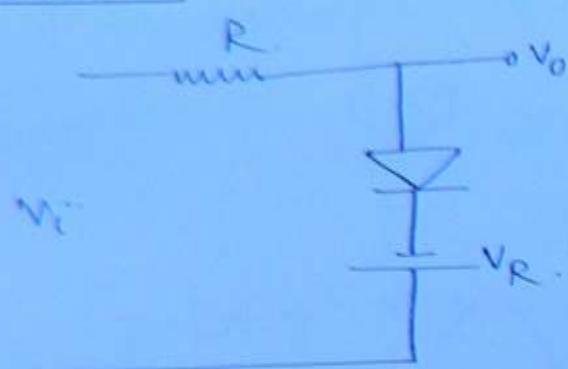


$V_i < V_R, D\text{-ON}, V_o = V_R$

$V_i > V_R, D\text{-OFF}, V_o = V_i$

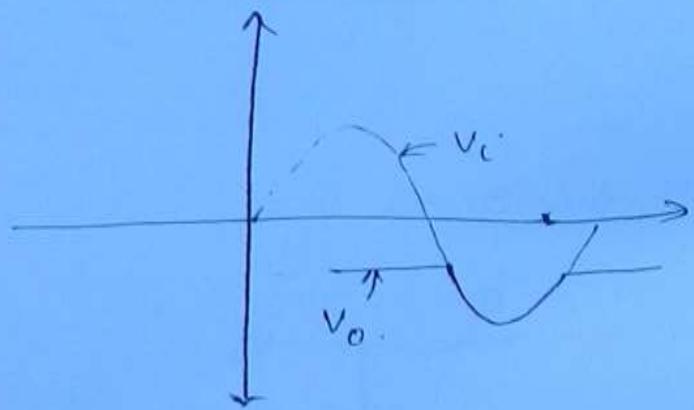
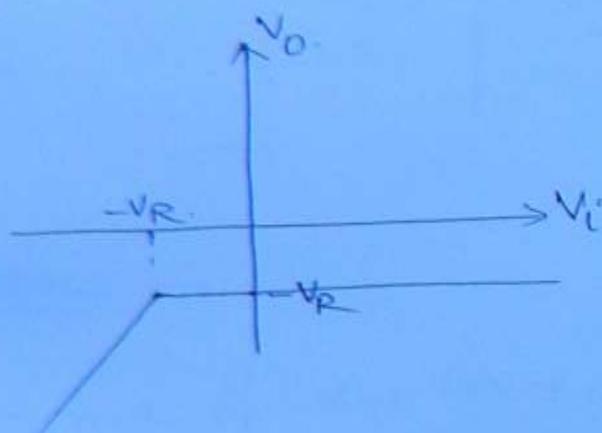


model 5 →

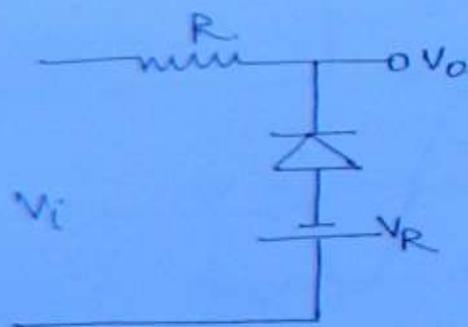


②

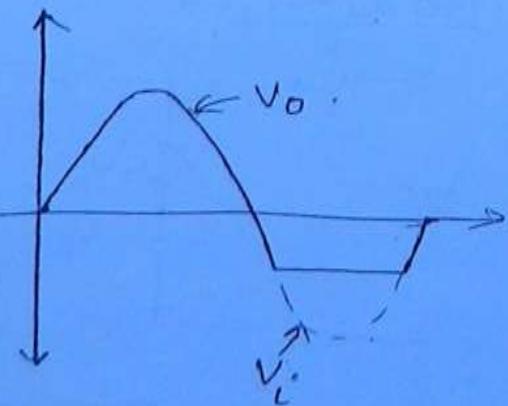
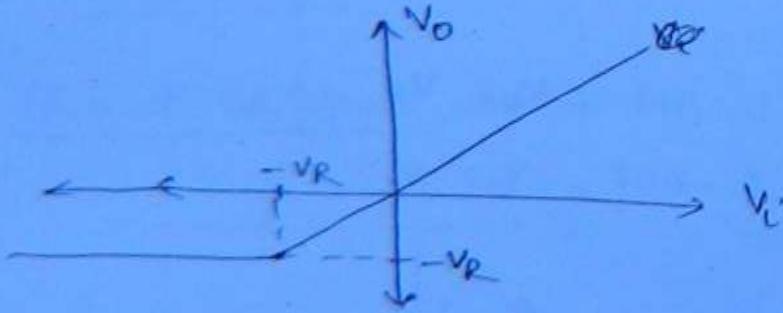
$$\begin{aligned} V_i < -V_R &\rightarrow \text{D OFF} & V_o = V_i \\ V_i \geq -V_R &\rightarrow \text{D ON} & V_o = -V_R \end{aligned}$$

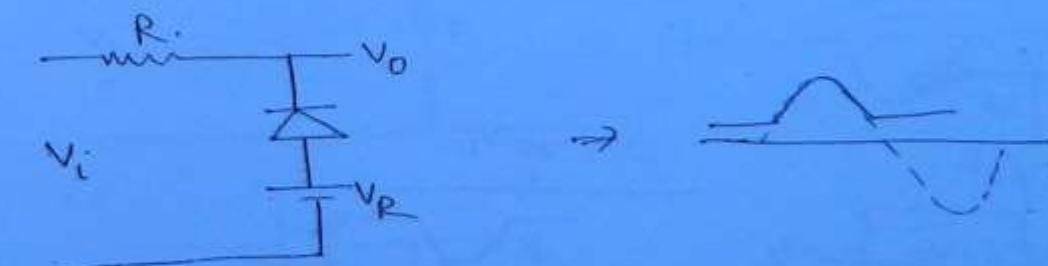
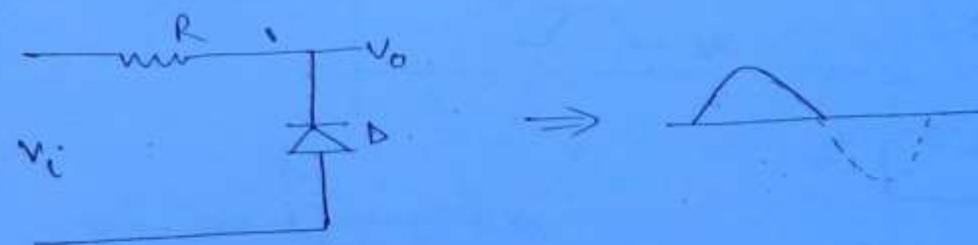
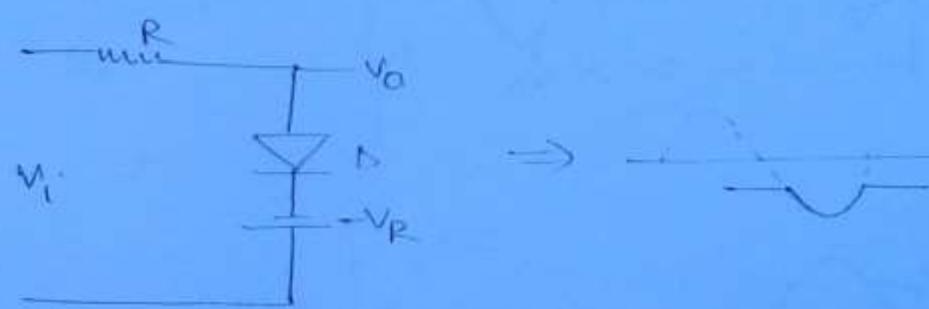
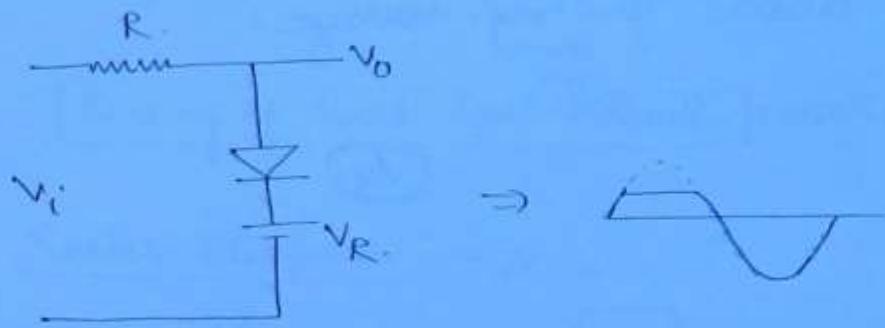
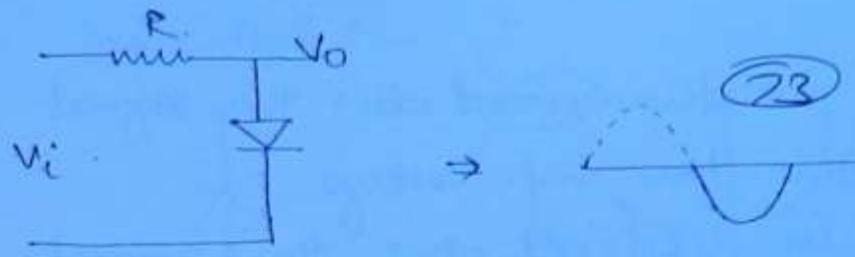


model 6 →



$$\begin{aligned} V_i < -V_R &\rightarrow \text{D OFF} & V_o = -V_R \\ V_i \geq -V_R &\rightarrow \text{D ON} & V_o = V_i \end{aligned}$$



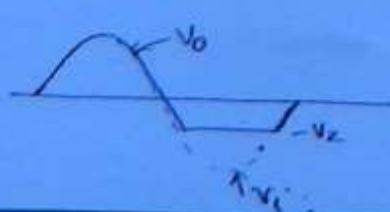
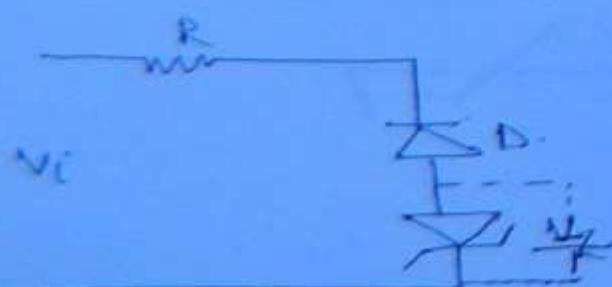
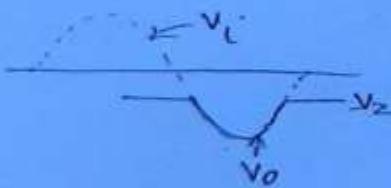
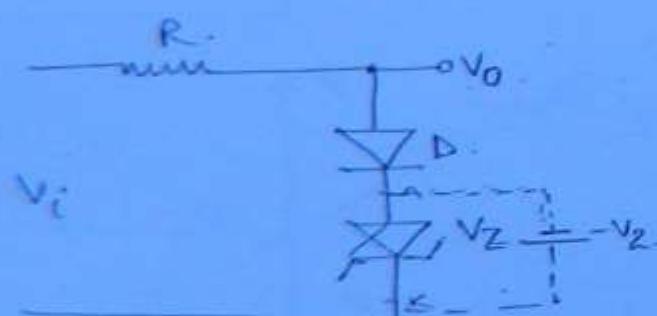
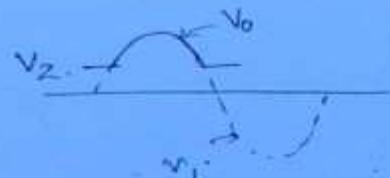
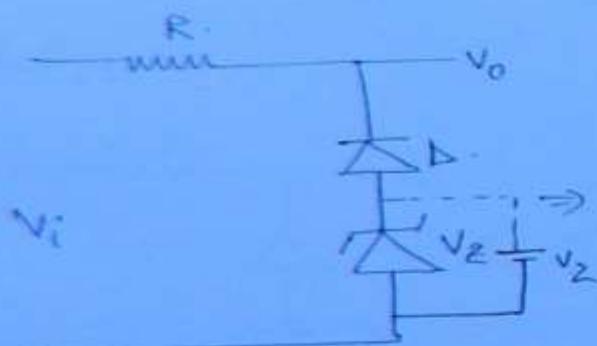
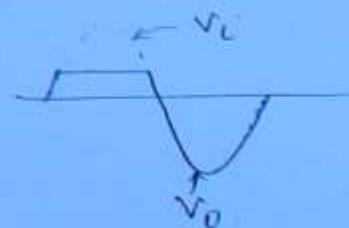
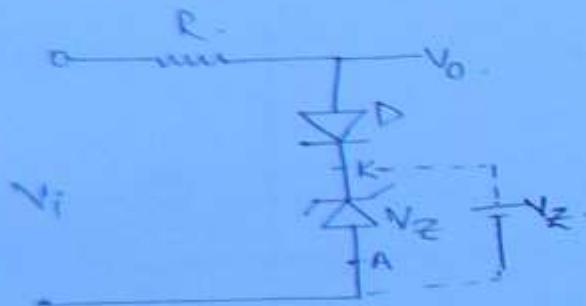


Conclusion :-

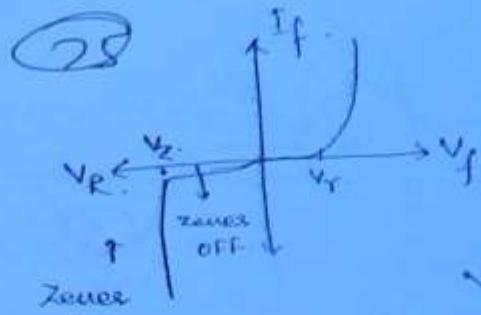
- 1) When the diode is in downward dirⁿ, the signal will be transmitted below the ref. voltage.
- 2) When the diode is in upward dirⁿ, the signal will be transmitted above the ref. voltage.

Typical models \rightarrow * Zener is ON.

(74)



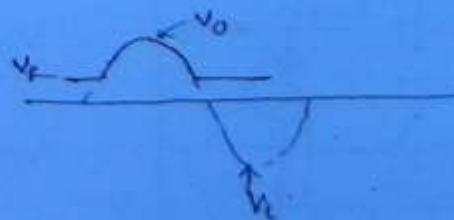
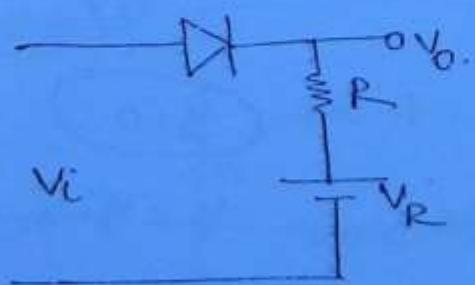
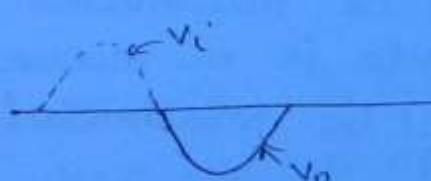
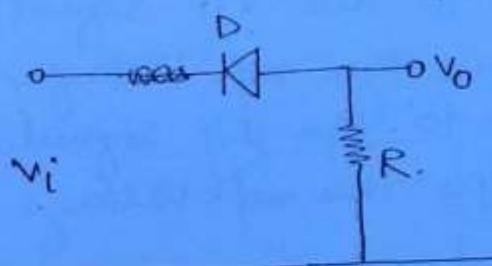
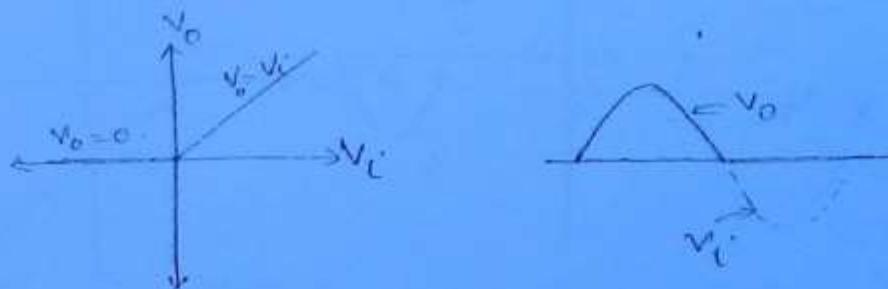
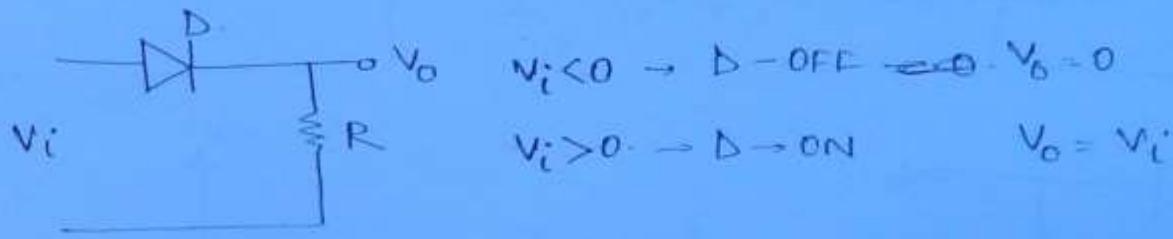
Zener diode →

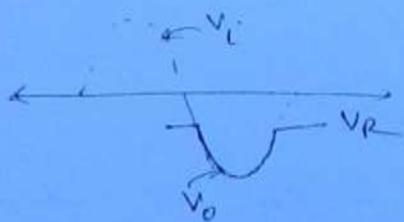
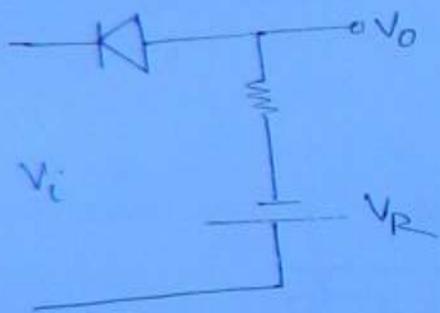
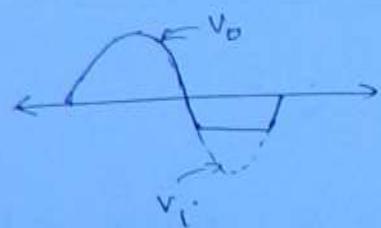
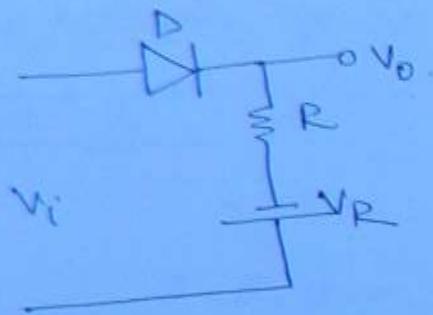
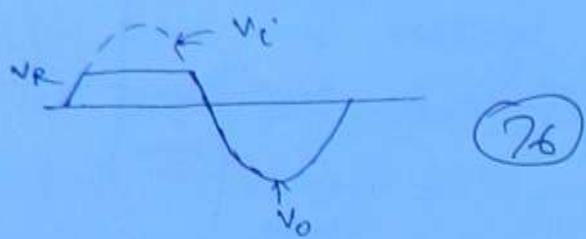
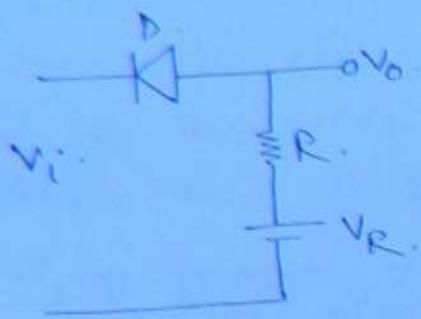


[Best eq of const Volt. Source]

$V > V_Z \rightarrow \text{ON}$ $V < V_Z \rightarrow \text{OFF}$ $V = V_f \rightarrow \text{FB}$

Series Clippers →

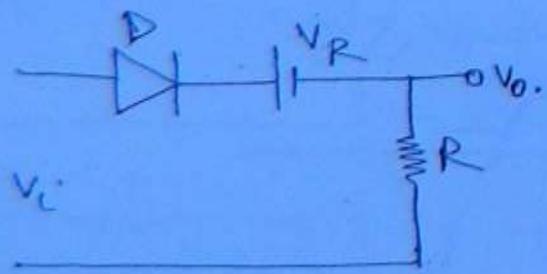




conclusions →

- When the diode is in forward dirⁿ to the I/P signal, the signal will be transmitted above the ref. Voltage
- When the diode is in reverse dirⁿ to the I/P signal, the signal will be transmitted below the ref. Voltage

Output following I/P ckt's →

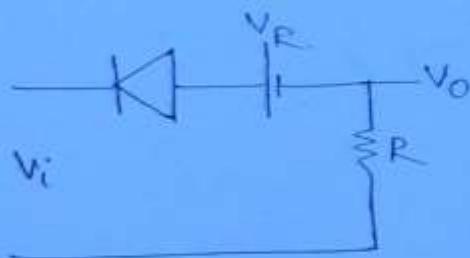
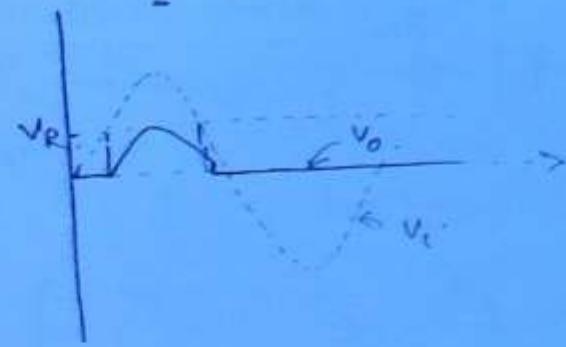
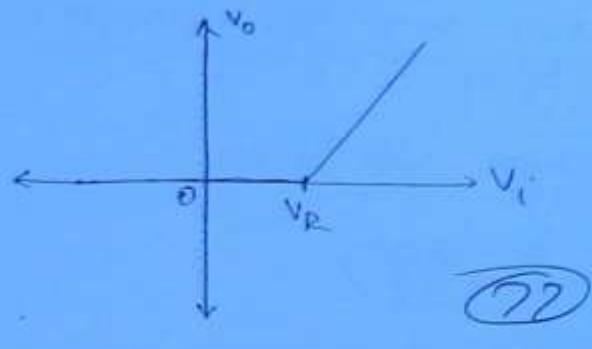


$V_i < V_R \cdot D \text{ OFF}$

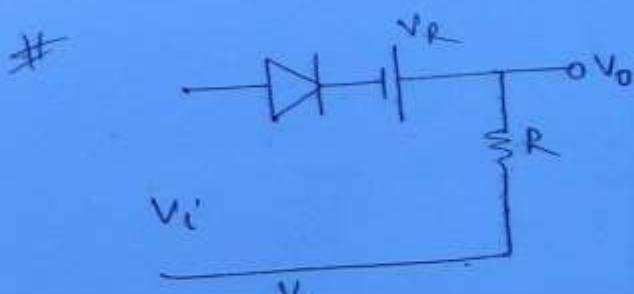
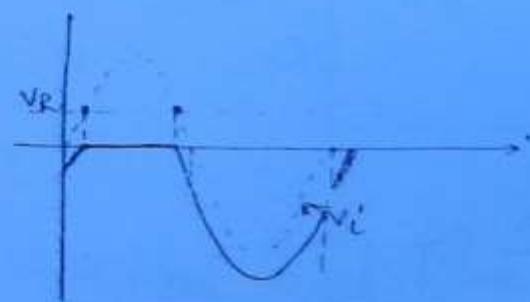
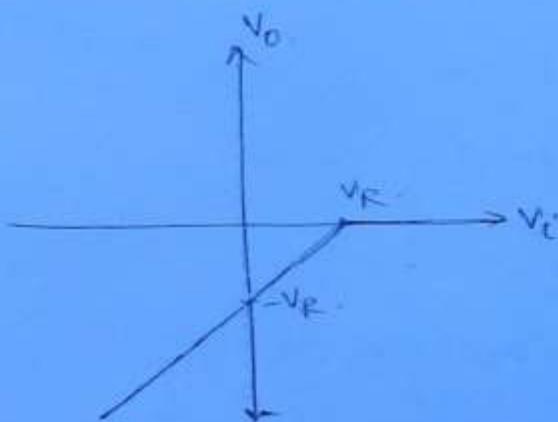
$$V_o = 0.$$

$V_i > V_R \cdot D \text{ ON}$

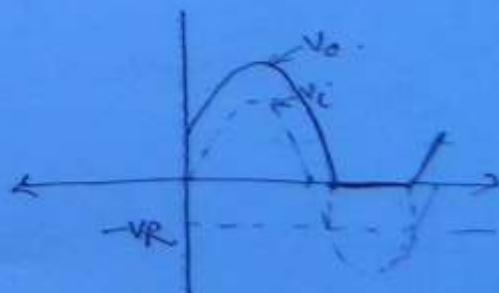
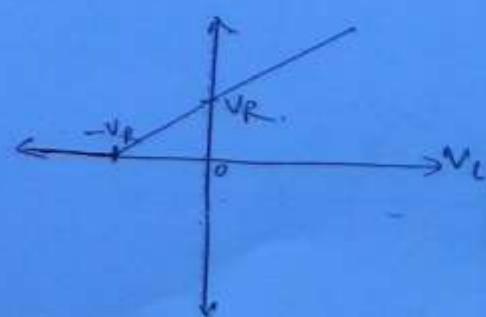
$$V_o = V_i - V_R$$

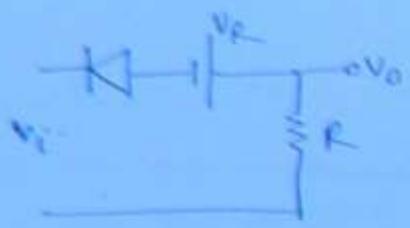


$V_i < V_R$, D-ON, $V_o = V_i - V_R$
 $V_i > V_R$, D-OFF, $V_o = 0$

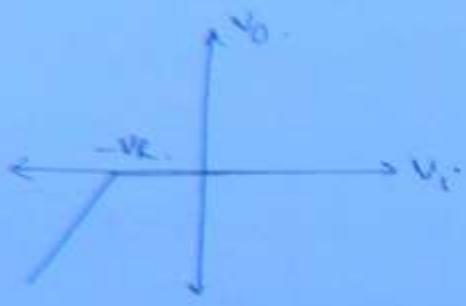


$V_i > V_R$ D ON $V_o = V_i + V_R$
 $V_i < -V_R$ D OFF $V_o = 0$

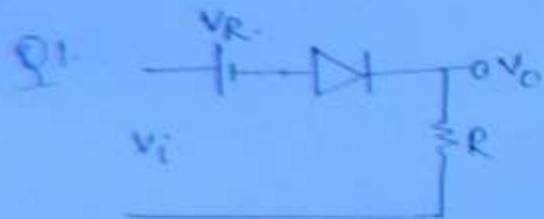
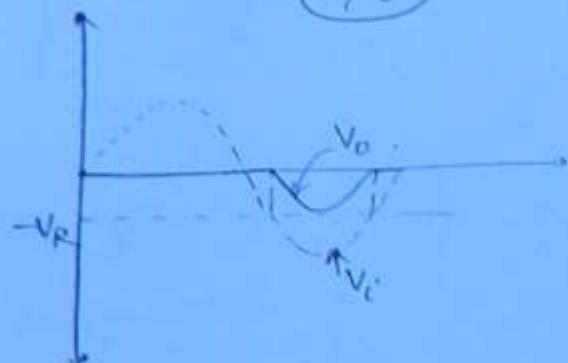




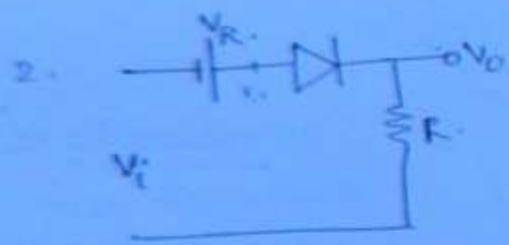
$v_i > -v_R$, D OFF. $v_o = 0$
 $v_i < -v_R$ D ON $v_o = v_i + v_R$



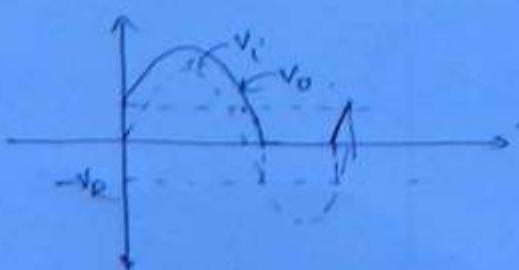
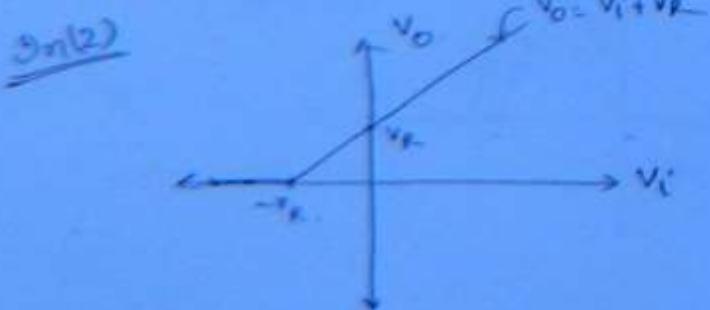
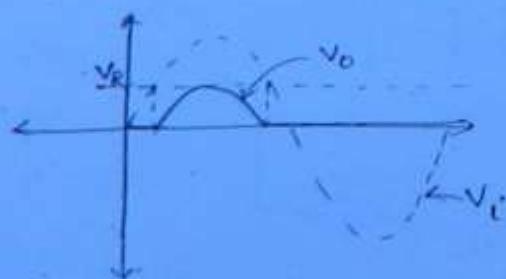
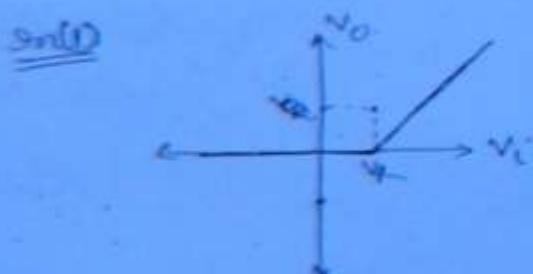
(78)



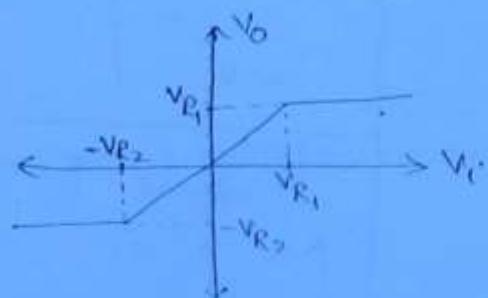
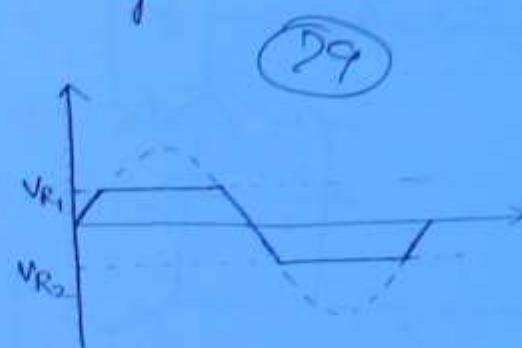
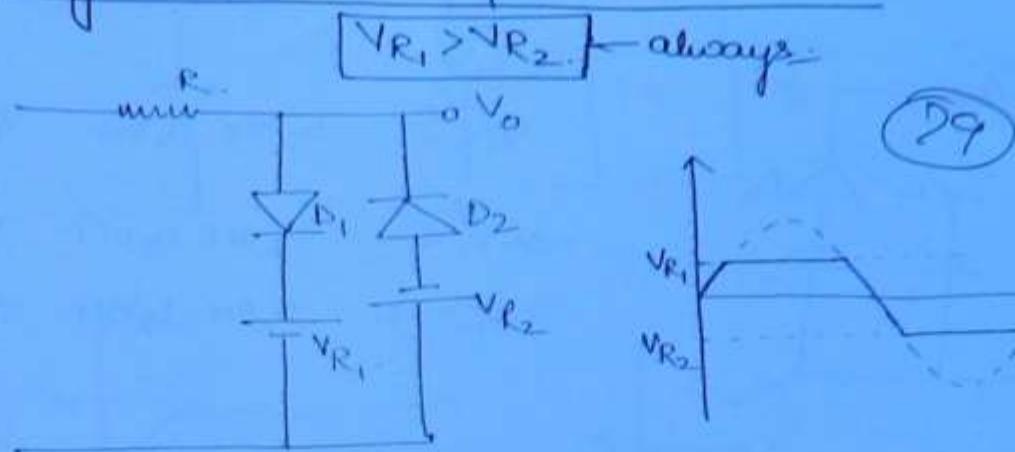
$v_i > v_R$ D ON $v_o = v_i - v_R$
 $v_i < v_R$ D OFF $v_o = 0$



$v_i > -v_R$ D ON $v_o = v_i + v_R$,
 $v_i < -v_R$ D OFF $v_o = 0$.



Climbing at two independent levels :-

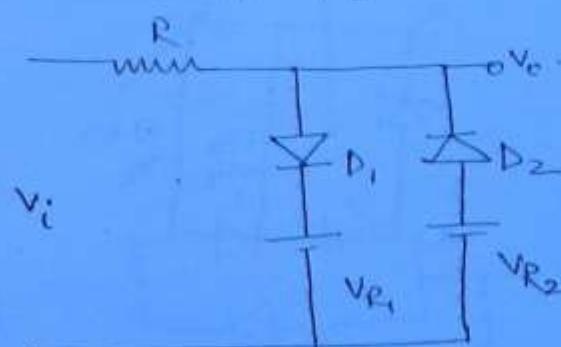


$$V_i < -V_{R_2} \quad D_1 \text{ OFF} \quad D_2 \text{ ON} \quad V_o = -V_{R_2}$$

$$-V_{R_2} < V_i < V_{R_1} \quad D_1 \text{ OFF} \quad D_2 \text{ OFF} \quad V_o = V_i$$

$$V_i > V_{R_1} \quad D_1 \text{ ON} \quad D_2 \text{ OFF} \quad V_o = V_{R_1}$$

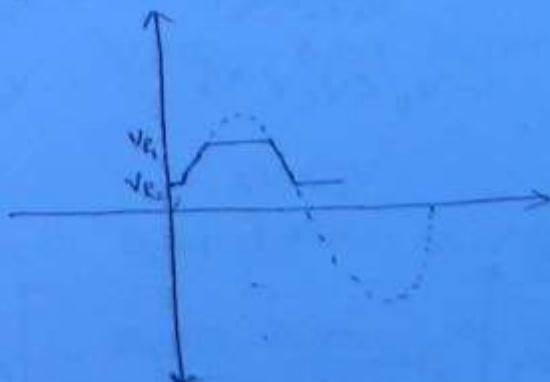
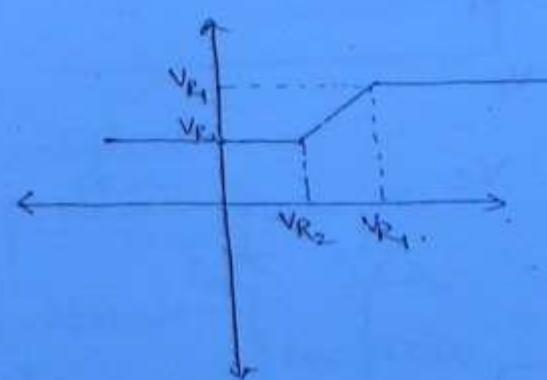
3/02/12

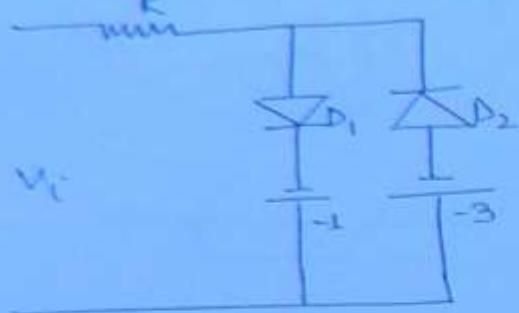


$$V_i < V_{R_2} \quad D_1 \text{ OFF} \quad D_2 \text{ ON} \quad V_o = V_{R_2}$$

$$V_{R_2} < V_i < V_{R_1} \quad D_1 \text{ OFF} \quad D_2 \text{ OFF} \quad V_o = V_i$$

$$V_i > V_{R_1} \quad D_1 \text{ ON} \quad D_2 \text{ OFF} \quad V_o = V_{R_1}$$



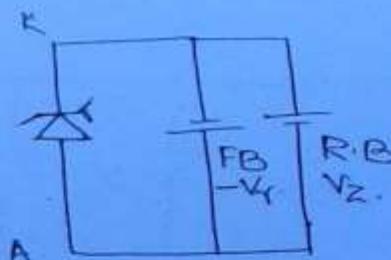
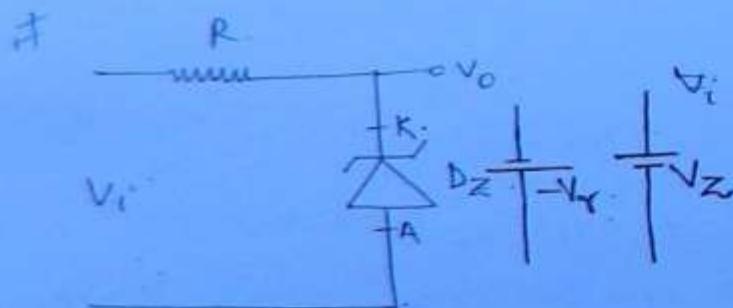
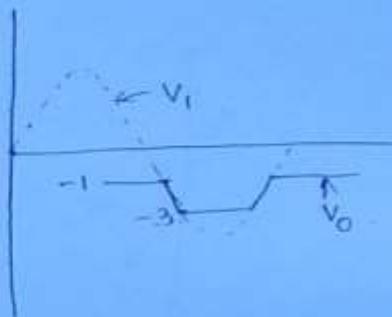
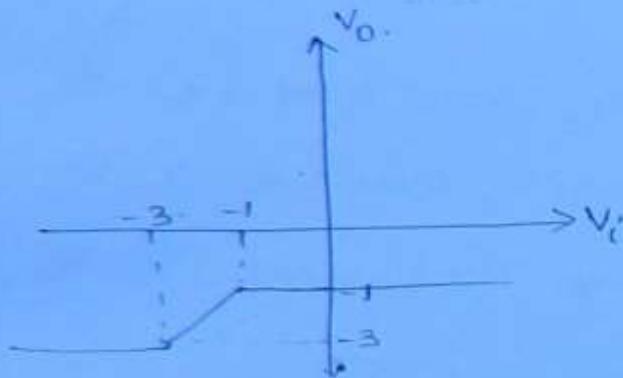


(8)

$V_i < -3$, D_1 OFF, D_2 ON, $V_0 = -3V$

$-3 < V_i < -1$, D_1 OFF, D_2 OFF, $V_0 = V_i$

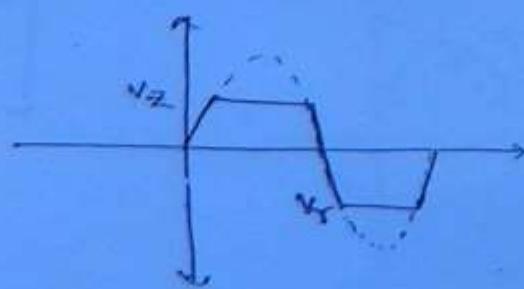
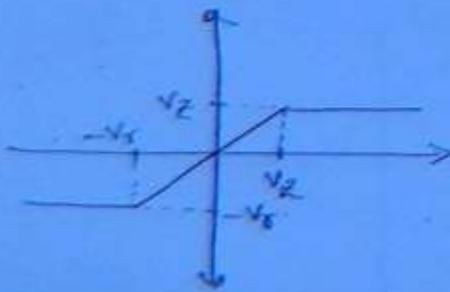
$V_i > -1$, D_1 ON, D_2 OFF, $V_0 = -1V$

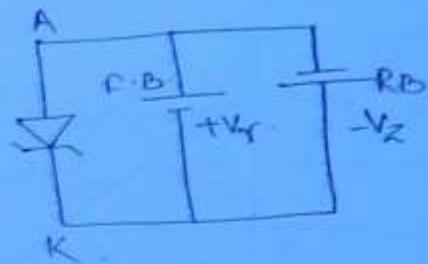
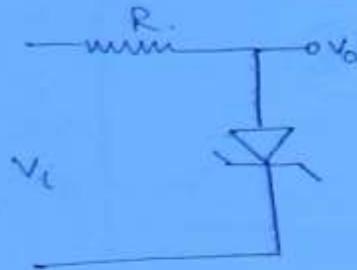


$V_i < -V_Y$, $V_0 = -V_Y$

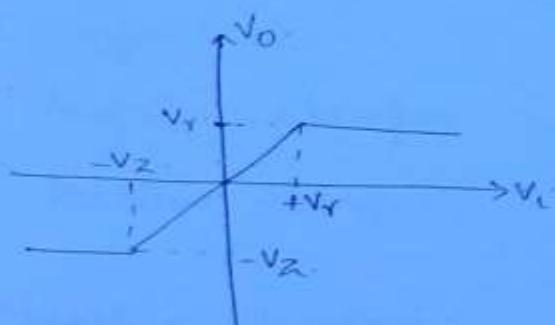
$-V_Y < V_i < V_Z$, $V_0 = V_i$

$V_i > V_Z$, $V_0 = V_Z$

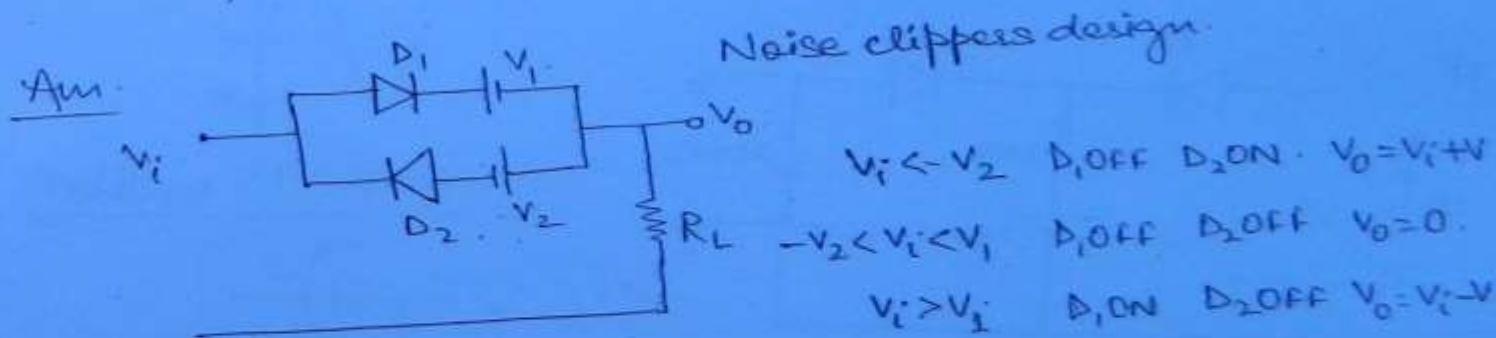
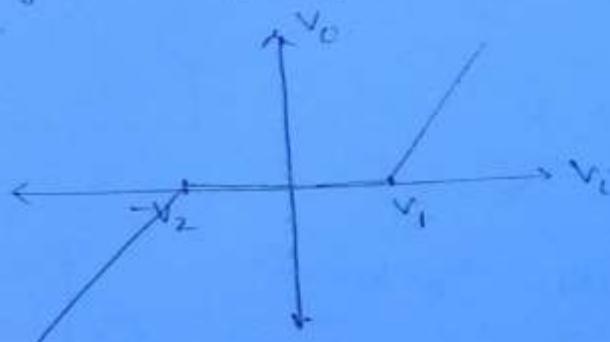




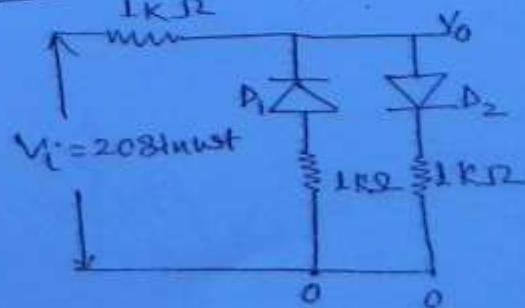
(81)



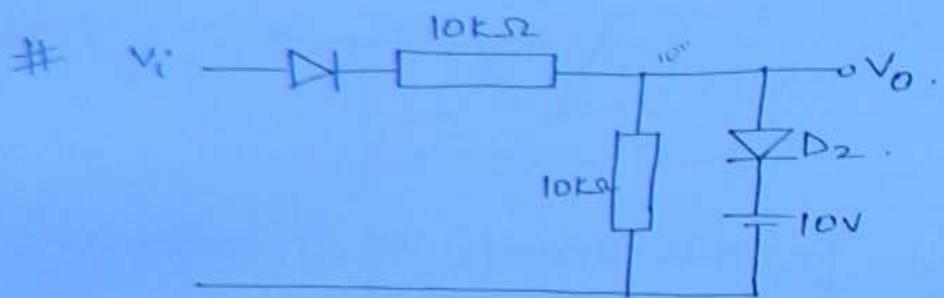
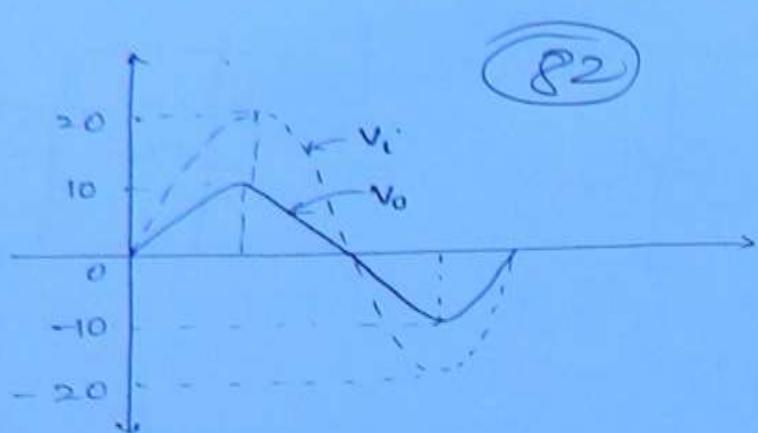
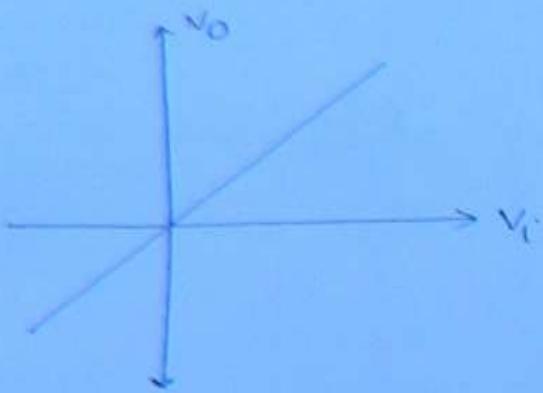
Design a clipping CKT for the transfer char. Shown below.



Attenuated CKT



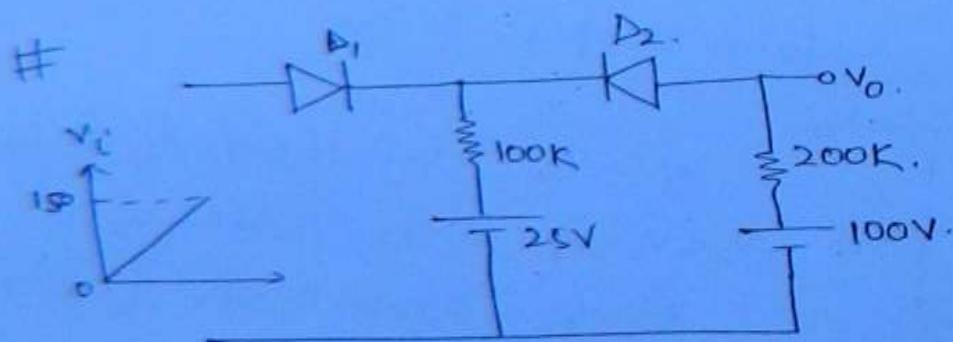
$$\begin{aligned}
 V_i < 0 & \quad D_1 \text{ ON} \quad D_2 \text{ OFF} \quad V_0 = \frac{V_i}{2} \\
 V_i > 0 & \quad D_1 \text{ OFF} \quad D_2 \text{ ON} \quad V_0 = \frac{V_i}{2}.
 \end{aligned}$$



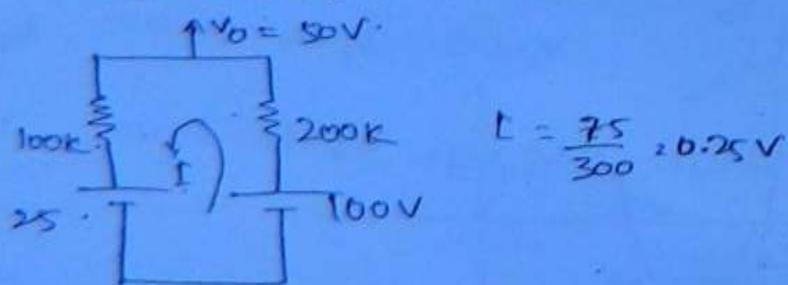
$$V_i < 0 \quad D_1 \text{ OFF} \quad V_o = 0$$

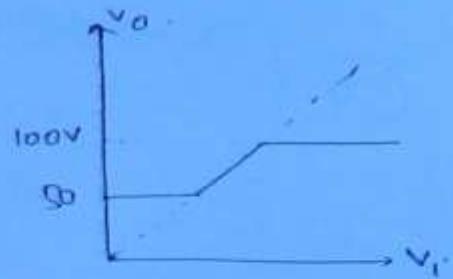
$$0 < V_i < 20V \quad D_1 \text{ ON} \quad D_2 \text{ OFF} \quad V_o = \frac{V_i}{2}$$

$$V_i > 20V \quad D_1 \text{ ON} \quad D_2 \text{ ON} \quad V_o = 10V$$



$$\text{At } V_i = 0V \rightarrow D_1 \text{ OFF} \quad D_2 \text{ ON}.$$





$V_i = 0 \quad D_1 \text{ OFF} \quad D_2 \text{ ON} \quad V_o = 50V$
 $50V < V_i < 100V \quad V_o = V_i$
 $V_i > 100V \quad V_o = 100V$

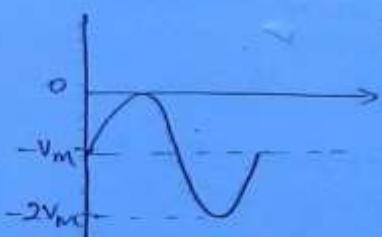
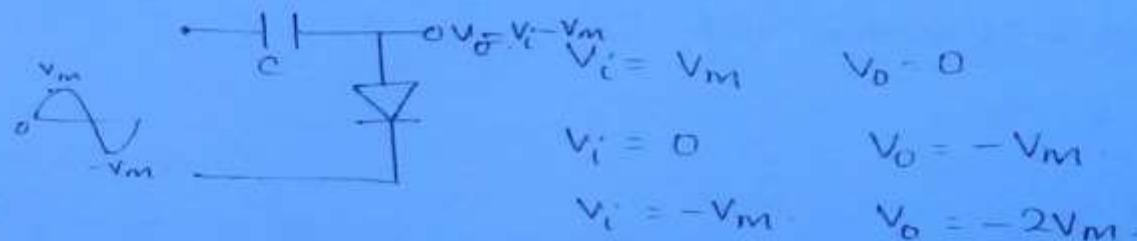
(83)

Clampers →

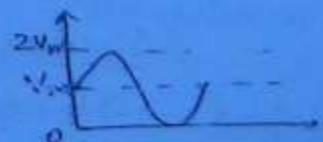
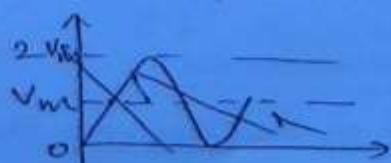
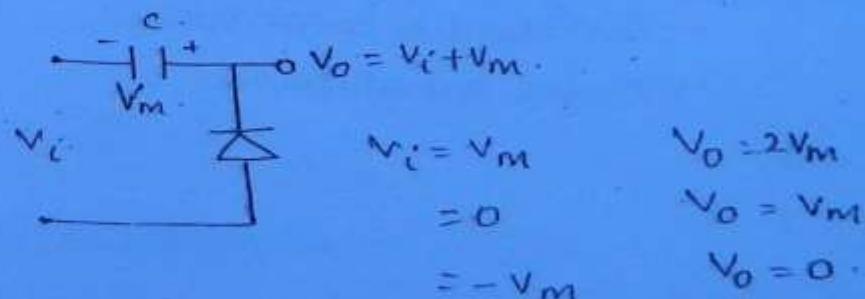
Negative clapper

Positive clapper.

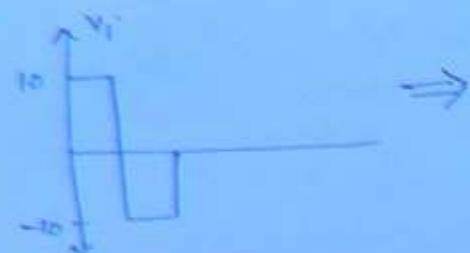
Negative clampers :-



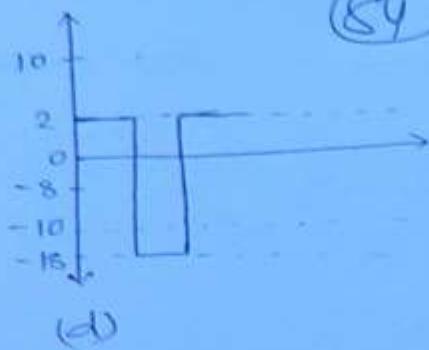
Positive clampers -



Q3



(84)



(d)

Conclusions →

- 1) When the diode is in downward dirⁿ, the total signal will be clamped below the ref. voltage.
- 2) When the diode is in Upward dirⁿ, the total signal will be clamped above the ref. Voltage.

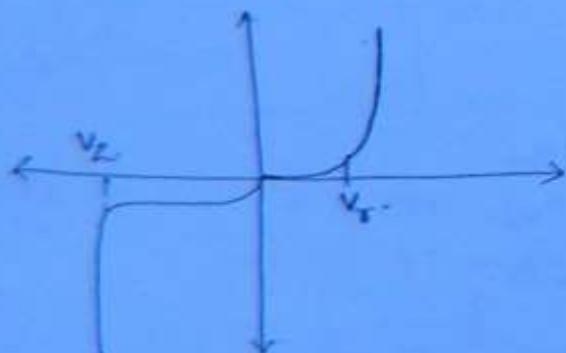
Special diodes →

Zener diode →

- 10^3 s.c. atoms → 1 impurity → ordinary diode.
- 10^6 s.c. atoms → 1 impurity → Zener diode
- 10^3 s.c. atoms → 1 impurity → Tunnel diode.

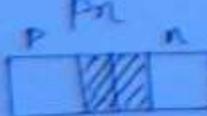
Breakdown mechanism →

- two types of breakdown.
- Avalanche breakdown
- zener breakdown.



Avalanche breakdown.

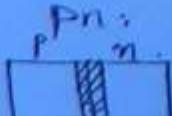
It occurs in a lightly doped



$$V_Z > 6V$$

Zener breakdown.

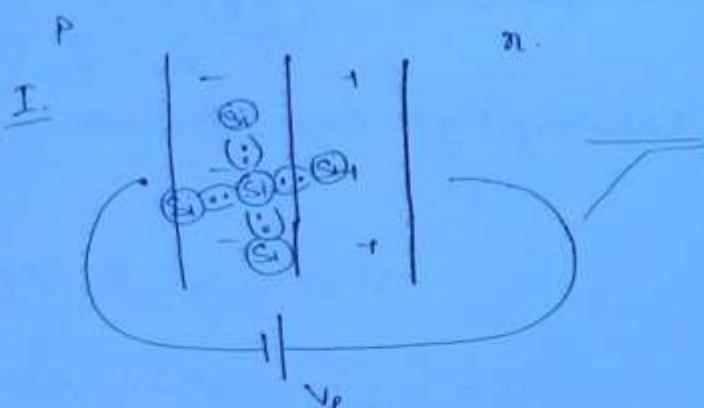
It occurs in a heavily doped



$$V_Z < 6V$$

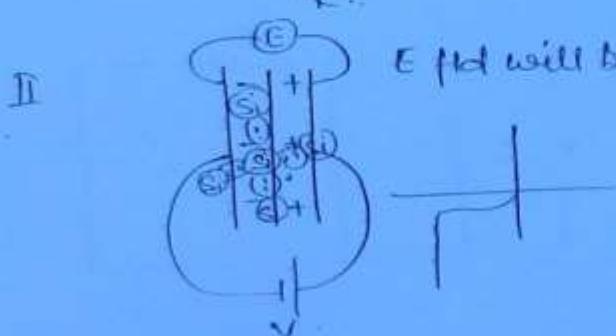
Mechanism →

(85)



Linear breakdown

Avalanche breakdown



Instant breakdown

Zener breakdown

I This type of breakdown occurs because of the velocity of minority charge carriers colliding with the stable atom in the depletion region.

II Due to heavily doped p-n junction, depletion region becomes narrower. When small reverse bias voltage is applied, strong int. E-fld will be generated bcoz of immobile ions.

Temp coeff. of V_{BR}

Zener breakdown →

$T \uparrow, V_{BR} \downarrow \quad \therefore$ negative temp coeff.

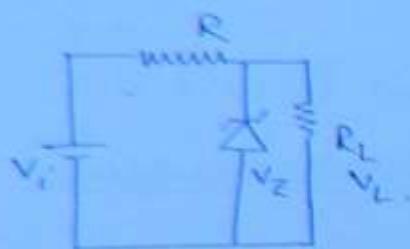
Avalanche breakdown →

$T \uparrow, V_{BR} \uparrow \quad \therefore$ fine Temp coeff.

As T has a vibrational effect i.e., so we require more en.

Zener diode as a voltage regulator.

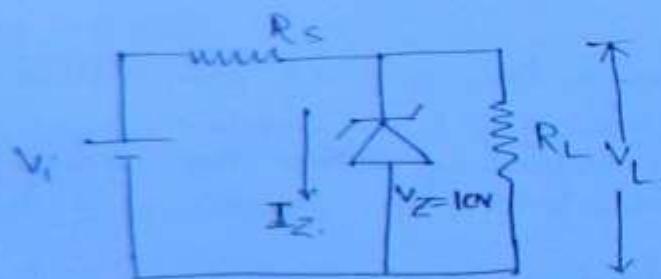
(86)



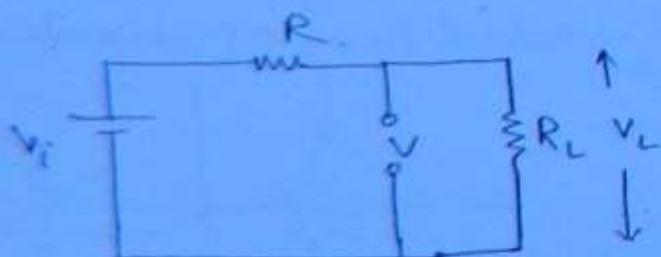
$V_Z = V_L$ (always) at any condition

- 1) V_i & R_L fixed.
- 2) V_i fixed and R_L variable.
- 3) V_i variable and R_L fixed.
- 4) V_i & R_L variable.

V_i & R_L fixed problem.

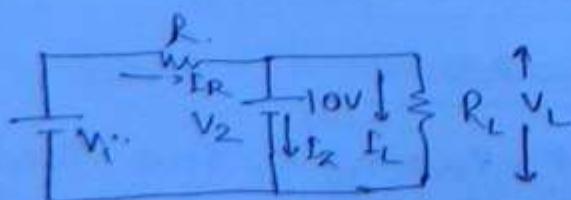


calc. V_L , I_Z , P_Z .



$$V = V_L = \frac{V_i \times R_L}{R + R_L}$$

if $V > V_Z$,



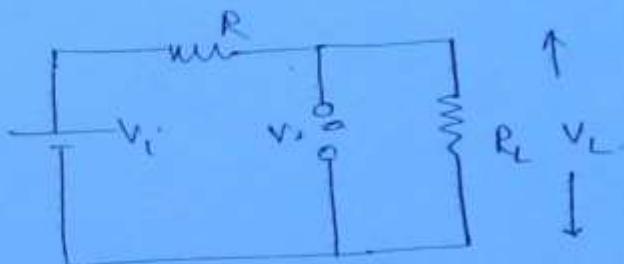
$$1) V_Z = V_L = 10V$$

$$(2) I_Z = I_R - I_L$$

$$= \frac{V_i - V_Z}{R} - \frac{V_Z}{R_L}$$

$$(3) R P_Z = V_Z I_Z$$

When $V < V_Z$:

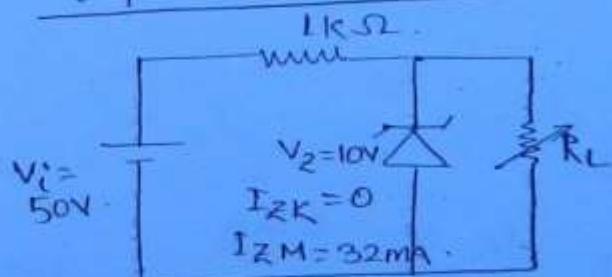


$$1) V_i = V$$

$$2) I_Z = 0$$

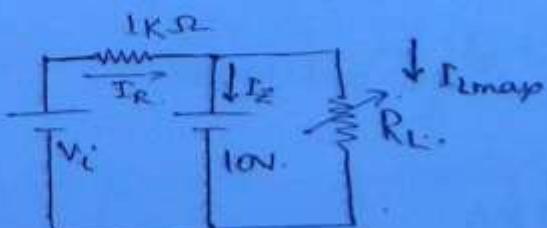
$$3) P_Z = 0$$

II V_i fixed and R_L variable \rightarrow



B/w $R_{L\min}$ and $R_{L\max}$,
Zener diode is ON.

Cal. $R_{L\min}$, $R_{L\max}$, $I_{L\min}$, $I_{L\max}$.



$$\begin{aligned} P_{L\max} &= P_R - P_{ZK} \\ &= \frac{50 - 10}{1K} - 0 \\ &= 40mA \end{aligned}$$

$$R_{L\min} = \frac{V_Z}{I_{L\max}} = \frac{10}{40mA} = 250\Omega$$

$$I_{Z\min} = I_R - I_{ZM}$$

$$= 40 \text{ mA} - 32 \text{ mA}$$

$$= 8 \text{ mA}$$

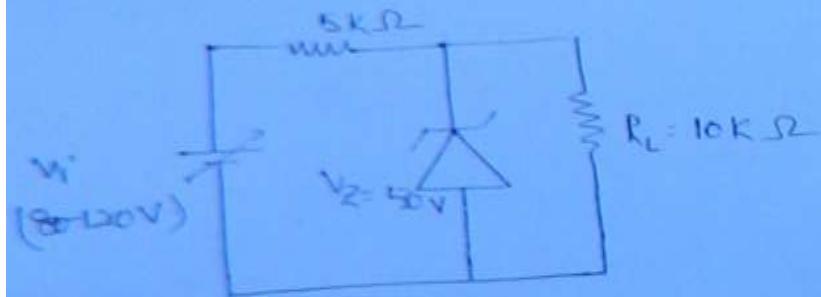
(88)

$$R_{\text{max}} = \frac{V_Z}{I_{Z\min}}$$

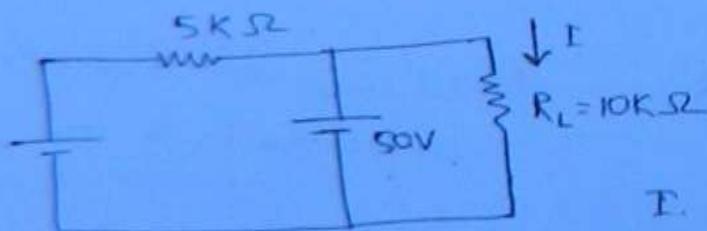
$$= \frac{10}{8 \text{ mA}}$$

$$= 1.25 \text{ k}\Omega$$

iii) V_i variable and R_L fixed :-



Cat. $I_{Z\min}$ and $I_{Z\max}$.



$$I_z = \frac{50 \text{ V}}{10 \text{ k}\Omega} = 5 \text{ mA}$$

$I_{Z\max}$,

$$I_{R\max} = \frac{120 - 50}{5 \text{ k}\Omega} = \frac{70}{5} = 14 \text{ mA}$$

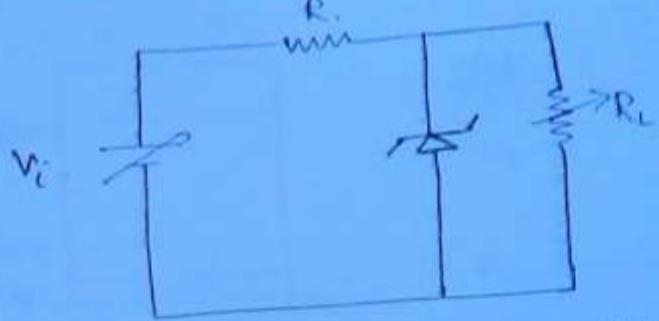
$$\text{or } I_{Z\max} = (14 - 5) \text{ mA}$$

$$= 9 \text{ mA}$$

$$\underline{I_{Z\min}}, \quad I_{R\min} = \frac{80 - 50}{5 \text{ k}\Omega} = \frac{30}{5} = 6 \text{ mA} \quad I_{Z\min} = (6 - 5) \text{ mA}$$

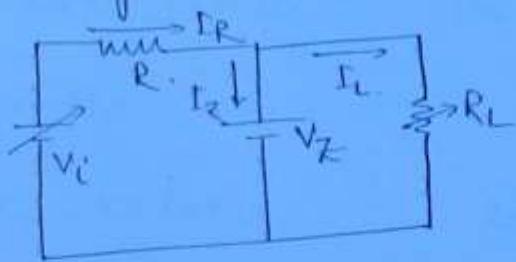
$$= 1 \text{ mA}$$

IV V_i and R_L variable \rightarrow



(39)

Cat. the dynamic range of series resistance R .



$$R_{\min} = \frac{V_i \max - V_z}{(I_R)_{\max}}$$

$$R_{\max} = \frac{V_i \min - V_z}{(I_R)_{\min}}.$$

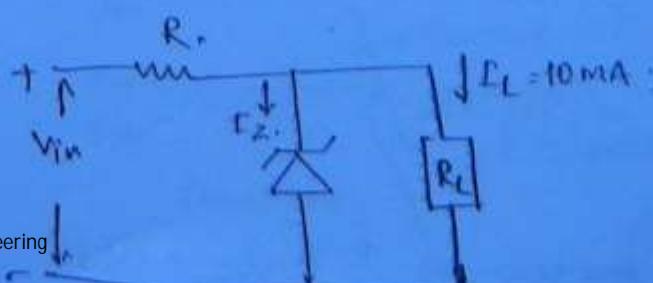
$$I_R = I_z + I_L.$$

$$\frac{V_i - V_z}{R} = I_z + I_L.$$

NOTE \rightarrow

For variable problems in zener diode, we can have an eq.

$$\frac{V_i - V_z}{R} \geq I_z + I_L.$$



Given

$$V_{in} = 30V \text{ to } 50V$$

(9)

$$I_L = 10mA$$

$$V_o = V_Z = 10V$$

$$I_{ZK} = 1mA$$

$$I_R \geq I_Z + I_L$$

$$\frac{V_i - V_Z}{R} \geq I_Z + I_L$$

$$V_{in} = 30V$$

$$\frac{30 - 10}{R} \geq 1mA + 10mA$$

$$\boxed{R \leq \frac{20}{11mA} = 1818.52} \rightarrow A_m$$

$$V_{in} = 50V$$

$$\frac{50 - 10}{R} \geq 11mA$$

$$R \leq \frac{40}{11mA} = 3636\Omega$$

16)

$$\frac{V_i - V_Z}{R} \geq I_Z + I_L \quad I_L = 10mA$$

$$I_L = 100mA$$

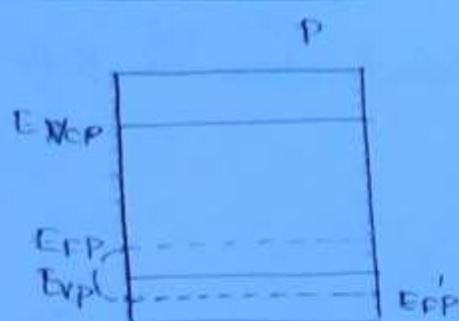
$$\frac{12 - 5}{R} \geq 0 + 100$$

$$R \leq \frac{7}{100mA} = 70\Omega$$

$$I_L = 500mA$$

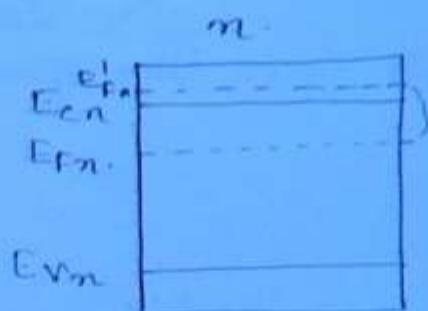
$$\frac{12 - 5}{R} \geq 0 + 500 \Rightarrow R \leq \frac{7}{500} = 14\Omega$$

Tunnel diode →



$$E_{FP} = E_V + kT \ln \frac{N_V}{N_A}$$

$$N_A \gg N_V$$

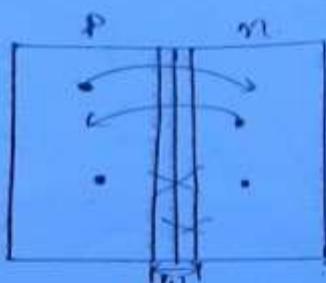


$$E_{Fn} = E_C e^{-kT \ln \frac{N_C}{N_D}}$$

$$N_D \gg N_C$$

$$E_{PP} = E_V - kT \ln N_A$$

$$E_{pn} = E_C + kT \ln N_D$$



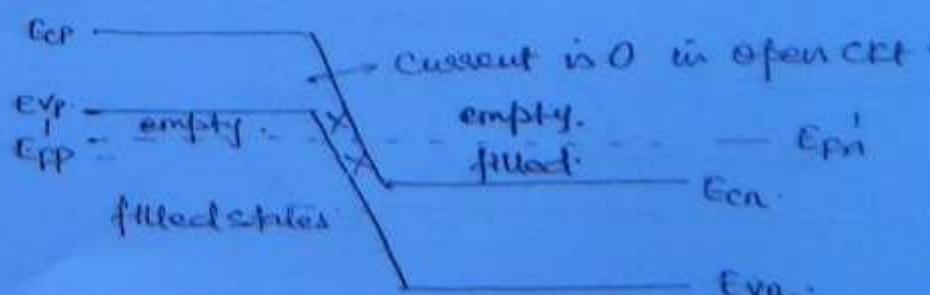
$$\omega = 100 \text{ rad/s}$$

$$1 \text{ Å} = 10^{-8} \text{ cm}$$

15th wavelength of light

Case 1. →

① open ckt P-n junction



Q9) Reverse bias

(Q9)

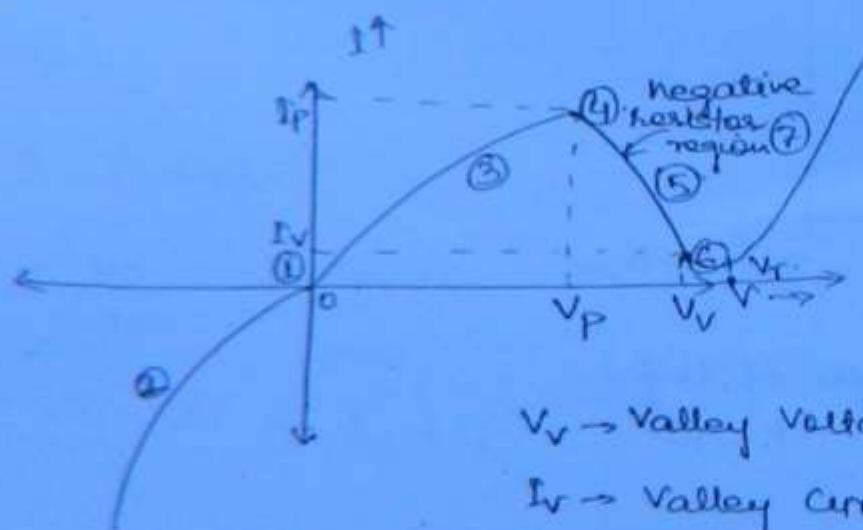
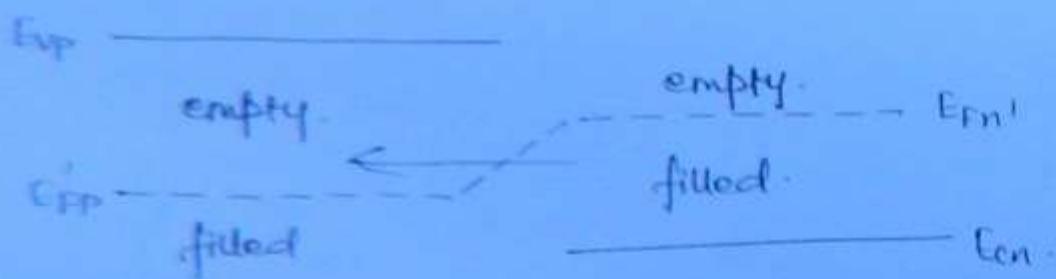
It acts like good conductor in R.B.



Case 3:

Small FB (mv)

Zener \rightarrow Si
Tunnel \rightarrow Ge

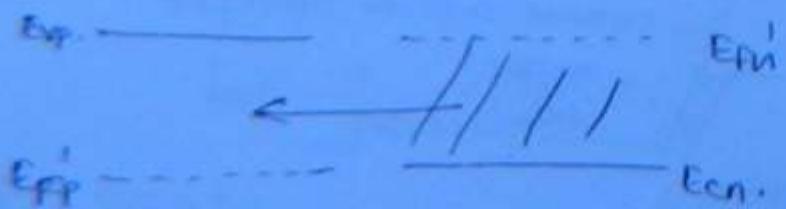


$V_V \rightarrow$ Valley Voltage

$I_V \rightarrow$ Valley Current

$V_r \rightarrow$ Cut off Voltage
 $\approx 0.3V$

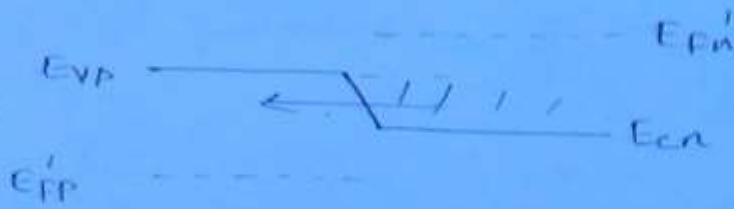
Case 4:



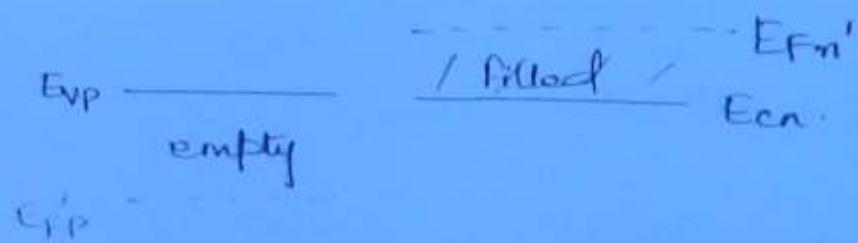
Case 5 →

$$V_f > V_P$$

(Q3)

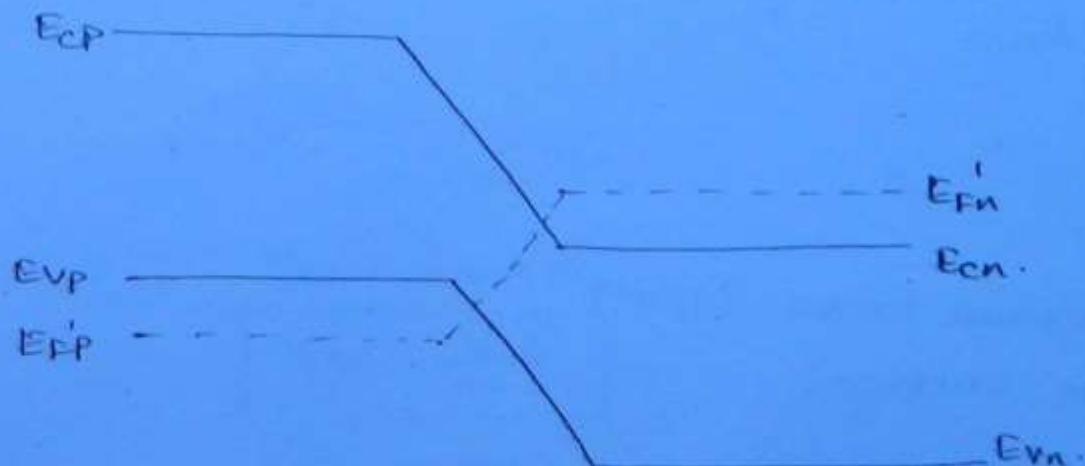


Case 6 →



Case 7 →

$$V_f > V_V$$



$$\frac{E_p}{J_V} \text{ ratio} = 15 \quad (\text{kaAs})$$

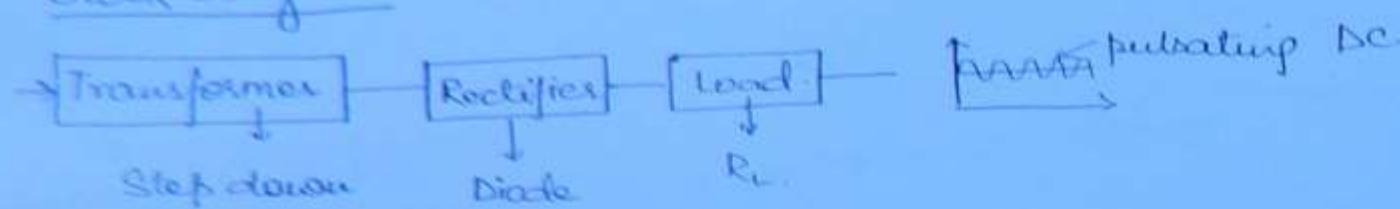
$$= 8 \quad (\text{Ko})$$

$$= 3 \quad (\text{Si})$$

Q112 Rectifiers →
A/C

(94)

Block diagram



It is a circuit which converts AC to rectifying DC.

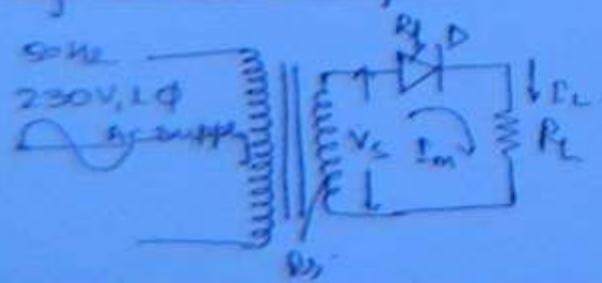
Practical rectifiers designs :-

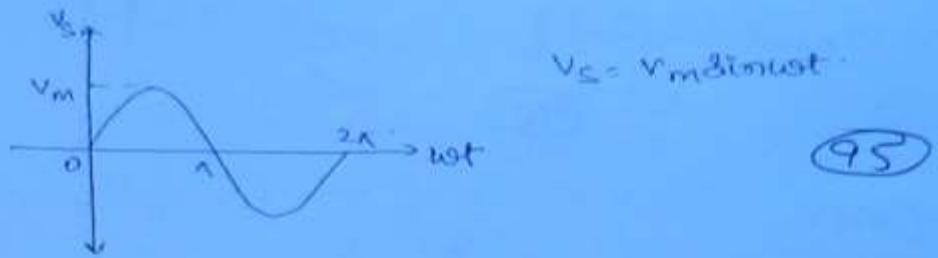
- 1) half wave rectifier →
- 2) full wave rectifier →
- 3) Bridge rectifiers →

Rectifier parameters →

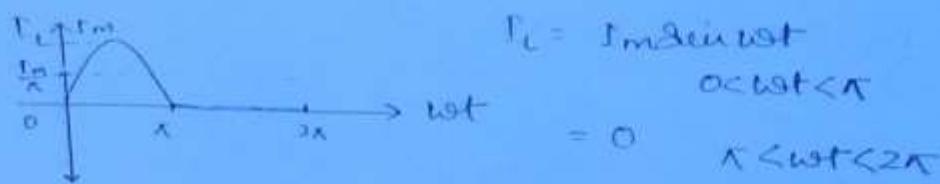
- i) AC current I_{AC}
- ii) DC output voltage V_{DC}
- iii) Rms load current I_{rms}
- iv) Ripple factor
- v) Voltage regulation
- vi) Rectification η
- vii) transformer utilisation factor (TUF)
- viii) PIV (Peak inverse Voltage)
- ix) I.F.
- x) Peak factor

Half wave Rectifier →





(95)



Rectifier parameters :-

1) Avg. current I_{dc} :-

$I_{dc} = \frac{\text{area under the curve}}{2\pi}$

$$= \frac{1}{2\pi} \int_0^{2\pi} I_S d(\omega t)$$

$$= \frac{I_m}{2\pi} \int_0^{2\pi} \sin \omega t d(\omega t)$$

$$\boxed{I_{dc} = \frac{I_m}{\pi}}$$

2) Dc O/P Voltage V_{dc} :-

$$V_{dc} = I_{dc} \times R_L$$

$$\boxed{V_{dc} = \frac{I_m}{\pi} R_L}$$

$$= \frac{V_m}{\pi (R_p + R_s + R_L)} \cdot R_L$$

$$= \frac{V_m}{\pi} \cdot \frac{1}{\frac{R_p + R_s}{R_L} + 1}$$

When $R_L \rightarrow \infty$,

$$\boxed{(V_{dc}) = \frac{V_m}{\pi}}$$

Notation.

⇒ KMS wind current (Kms) :-

RMS ←

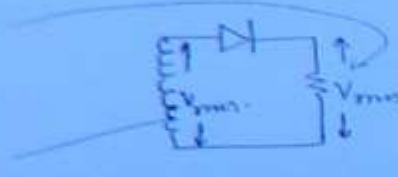
96

$$I_{rms} = \sqrt{\frac{1}{2\pi} \int I^2 d(\omega t)}$$

$$= \frac{D_m}{\sqrt{2}} \quad \frac{F_m}{2}$$

$$V_{ms} = \frac{V_m}{\sqrt{2}}$$

$$= \frac{V_{\text{ref}}}{\sqrt{2}}$$



4) Ripple factor →

RMS of alternating component	I'rms
Av. Value	Idc

Assume \rightarrow

I' = Ac current

I_{dc} = dc current

I → total current
 I_{rms} = rms value of ac current

$$I_{rms} = \left[\frac{1}{2\pi} \int_0^{2\pi} I^2 d\alpha \right]^{1/2}$$

$$F' = F - F_{\text{dec}}$$

$$E_{max} = \left[\frac{1}{2\pi} \int_0^{2\pi} (t - t_{dc})^2 dt \right]^{1/2}$$

$$I_{rms}^2 = \frac{1}{2\pi} \int_0^{2\pi} I^2 d\alpha - 2 I_{dc} \frac{1}{2\pi} \int_0^{2\pi} I d\alpha + I_{dc}^2 \frac{1}{2\pi} \int_0^{2\pi} d\alpha.$$

$$= I_{ms}^2 - 2I_{dc}^2 + I_{dc}^2$$

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$$h.f. = \frac{I_{rms}}{I_{dc}} = \sqrt{\frac{I_{rms}^2 - I_{dc}^2}{I_{dc}^2}}$$

$$R.f. = \sqrt{\frac{\frac{I_{rms}^2}{I_{dc}^2} - 1}{\frac{I_{rms}^2}{I_{dc}^2}}} \quad (97)$$

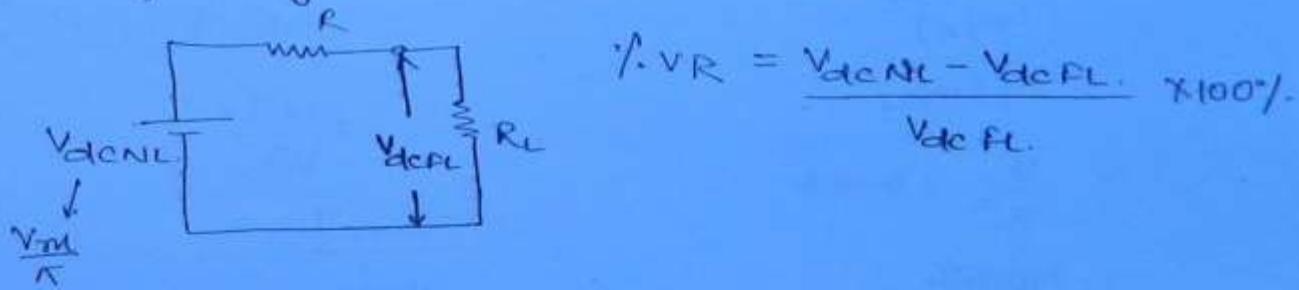
HWR

$$\begin{aligned} R.f. &= \sqrt{\left(\frac{I_m/2}{I_m/\pi}\right)^2 - 1} \\ &= \sqrt{\left(\frac{\pi}{2}\right)^2 - 1} \\ &= 1.21 \\ &= 121\% \end{aligned}$$

Conclusion →

Ripple v factor value is 1.21 for half wave rectifier i.e. 121%.
of ac comp. is present in dc value.

5) Voltage Regulation →



HWR

$$I_{dc} = \frac{I_m}{\pi}$$

$$I_{dc} = \frac{V_m}{\pi (R_f + R_s + R_L)}$$

$$I_{dc}(R_d + R_s) + I_{dc}R_L = \frac{V_m}{\pi}$$

$$\downarrow \qquad \uparrow$$

$$V_{dcFL} \qquad V_{dcNL}$$

$$\%VR = \frac{I_{dc}(R_d + R_s)}{\frac{V_m}{\pi} - I_{dc}(R_d + R_s)} \times 100\%$$

Ideally the v.v. should be 0, necessarily it should be zero in value.

6) Rectification η :-

(98)

$$\eta = \frac{\text{DC power delivered to the load}}{\text{AC F.P. power}}$$

$$= \frac{I_{dc}^2 R_L}{I_{rms}^2 (R_f + R_s + R_L)}$$

$$= \frac{I_{dc}^2}{I_{rms}^2} \frac{1}{\frac{R_f + R_s}{R_L} + 1}$$

$$\frac{R_f + R_s}{R_L} \ll 1.$$

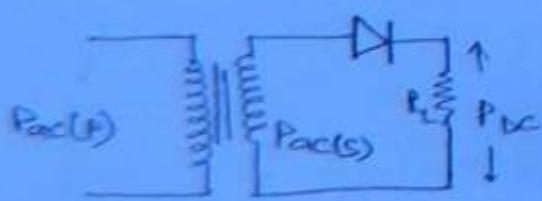
$$\eta = \frac{I_{dc}^2}{I_{rms}^2}$$

$$= \frac{(I_m/\pi)^2}{(I_m/2)^2}$$

$$= \frac{4}{\pi^2} = 0.406.$$

$$= 40.6\%.$$

7) Transformer utilization factor :-



$$TUF = \frac{(TUF)_P + (TUF)_S}{2}$$

for Full wave.

$$(TUF)_P = \frac{P_{DC}}{(P_{AC})_P}$$

for utilization of 360°

$$(TUF)_S = \frac{P_{DC}}{(P_{AC})_S}$$

$$TUF = (IUF)_S$$

= $\frac{\text{DC power delivered to load}}{\text{Pac rated sec.}}$

$$= \frac{E_{dc}^2 R_L}{V_{rms} \times I_{rms}}$$

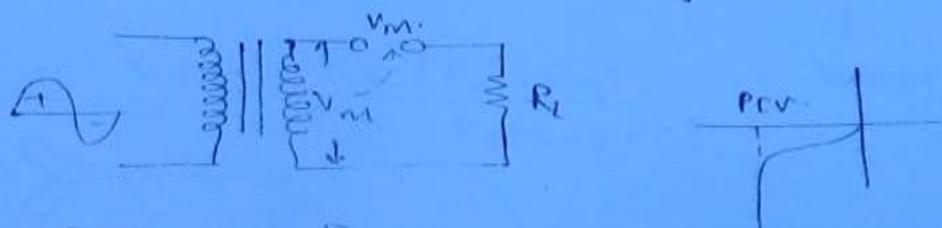
$$\downarrow \quad \downarrow$$

$$\frac{V_m}{\sqrt{2}} \quad \frac{I_m}{2}$$

$TUF = 28\%$

(99)

8) PIV (Peak Inverse Voltage) →



$$PIV = V_m [\text{negative half cycle}]$$

9) Form factor →

$$\frac{\text{RMS}}{\text{AV}}$$

$$= \frac{I_{rms}}{I_{dc}}$$

$$= \frac{I_m/2}{I_m/\pi} =$$

$$= \frac{\pi}{2}$$

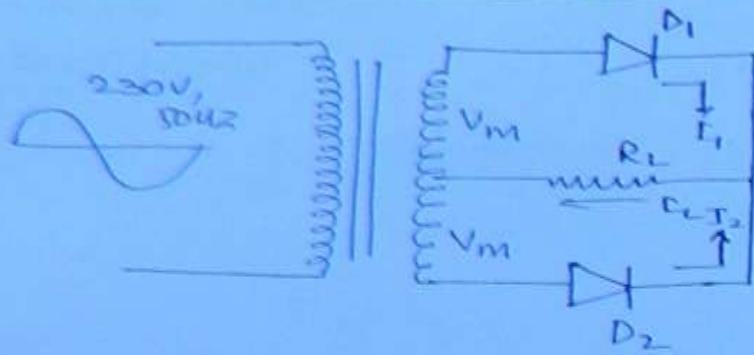
10) Peak factor →

$$\frac{\text{Peak}}{\text{RMS}}$$

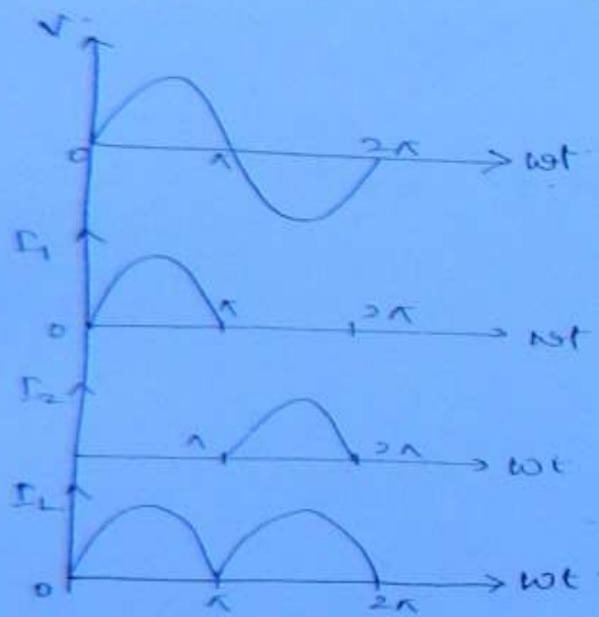
$$= \frac{I_m}{I_m/2}$$

$= 2$

Full wave Rectifier →



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Rectifier parameters →

1) Avg. current I_{DC} →

$$I_{DC} = \frac{2I_m}{\pi}$$

2) Dc Output Voltage V_{DC} →

$$V_{DC} = \frac{2V_m}{\pi}$$

3) line forms →

$$I_{rms} = \frac{I_m}{\sqrt{2}}$$

$$V_{rms} = \frac{V_m}{\sqrt{2}}$$

$$4) R.f. = \int \frac{I_{ms}}{I_{dc}^2} - 1$$

$$= \int \left(\frac{I_m/f_2}{\frac{\alpha I_m}{\pi}} \right)^2 - 1$$

$$= \int \frac{\pi^2}{4f_2^2} - 1$$

$$= 48\%$$

(101)

5) Voltage Regulation :

$$I_{dc}(R_d + R_s) + I_{dc}R_L = V_{dc} N_L$$

$$\downarrow \quad \downarrow$$

$$\% R. = \frac{I_{dc}(R_d + R_s)}{\frac{2V_m}{\pi} - I_{dc}(R_d + R_s)}$$

$$\begin{aligned} 6) \eta &= \frac{P_{dc}}{P_{ac}} \\ &= \frac{I_{dc}^2}{I_{ms}^2} \\ &= \frac{(2I_m/\pi)^2}{(I_m/f_2)^2} \\ &= \frac{8}{\pi^2} \\ &= 81.2\% \end{aligned}$$

7) TUF →

$$= \frac{(TUF)_P + (TUF)_S}{2}$$

$$(TUF)_S = \frac{P_{dc}}{P_{ac}}$$

$$\begin{aligned} P_{ac} \text{ rated sec one half} &\rightarrow V_{rms} L_{rms} \cdot \frac{I_m}{f_2} \cdot \frac{f_2}{2} \\ + P_{ac} \text{ rated sec other half} &\rightarrow V_{rms} L_{rms} \cdot \frac{I_m}{f_2} \cdot \frac{f_2}{2} \\ = & 57.3\% \end{aligned}$$

$$(TUF)_P = \eta = 81.2\%$$

(102)

$$\begin{aligned} TUF &= \frac{81.2 + 57.3}{2} \\ &= 69.3\% \end{aligned}$$

8) PIV →

$$2V_m$$

$$9) P.F. = \frac{R_{rms}}{AV}$$

$$= \frac{I_{rms}}{E_{dc}}$$

$$= \frac{I_m/\sqrt{2}}{2I_m/N}$$

$$= \frac{1}{2\sqrt{2}}$$

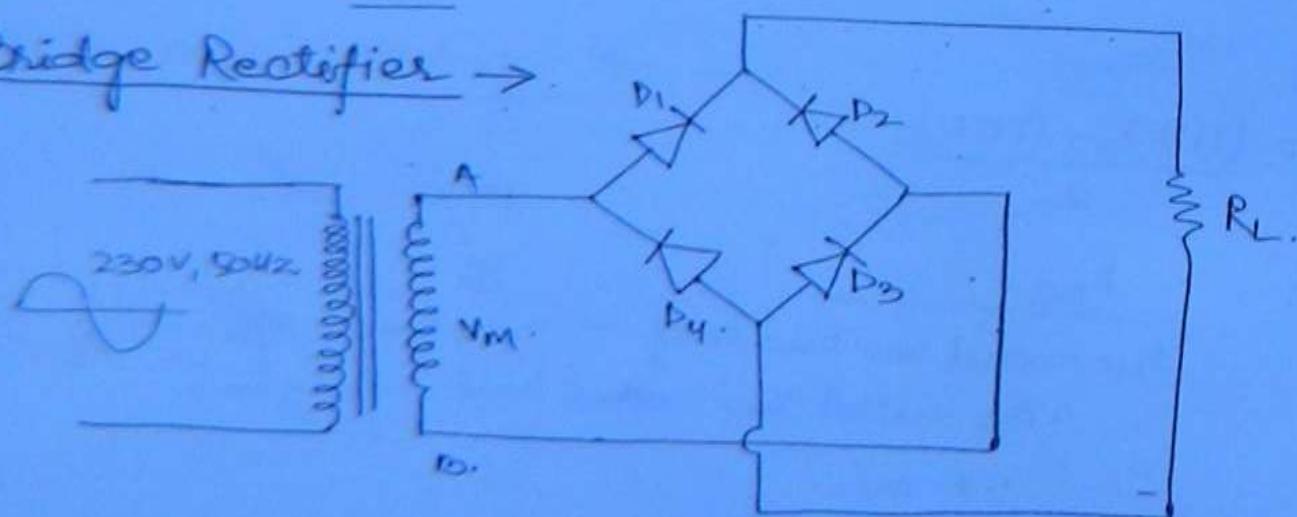
10) Peak factor =

$$\frac{\text{Peak}}{\text{RMS}}$$

$$\Rightarrow \frac{I_m}{I_m/\sqrt{2}}$$

$$= \sqrt{2}$$

Bridge Rectifier →



One half cycle →

A D₁ R_L D₃ B

D₁, D₃ → FB.

D₂, D₄ → R.B.

One half cycle

B D₂ R_L D₄ A

D₂, D₄ → FB.

D₁, D₃ → R.B.

(103)

Common parameters as full wave Rectifier:

$$I_{DC} = \frac{2V_m}{\pi}$$

$$V_{DC} = \frac{2V_m}{\pi}$$

$$I_{rms} = \frac{I_m}{\sqrt{2}}$$

$$V_{rms} = \frac{V_m}{\sqrt{2}}$$

$$R.F. = 48\%$$

V.R.

$$\eta = 81.2\%$$



Other parameters →

Voltage Regulation =

$$I_{DC}(2R_d + R_s) + I_{DC}R_L = \frac{2V_m}{\pi}$$

\downarrow
 R_L

\downarrow
 N.L.

$$TUF = \frac{(TUF)_P + (TUF)_S}{2}$$

$$= 81.2\%$$

$$PIV = V_m$$

Filters →

R.f. (HWR) → 1.21.

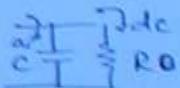
(FWR) → 0.48.

(BR) → 0.48.

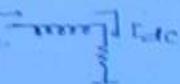
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Filters →

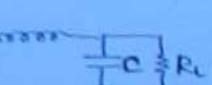
→ Capacitive filter



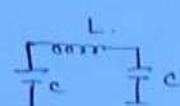
→ Inductor filter



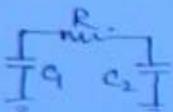
→ L section filter



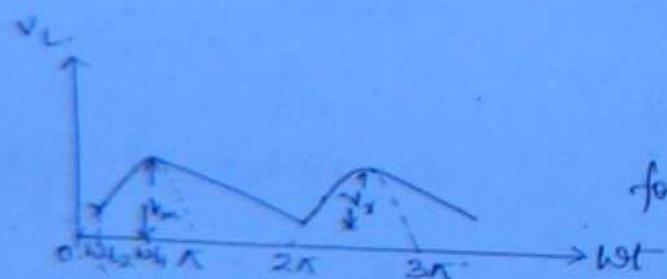
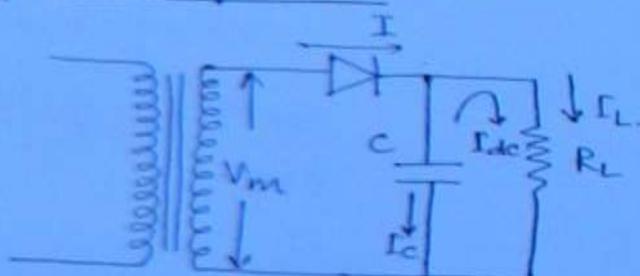
→ T section filter [not for heavier loads]



→ RC filter

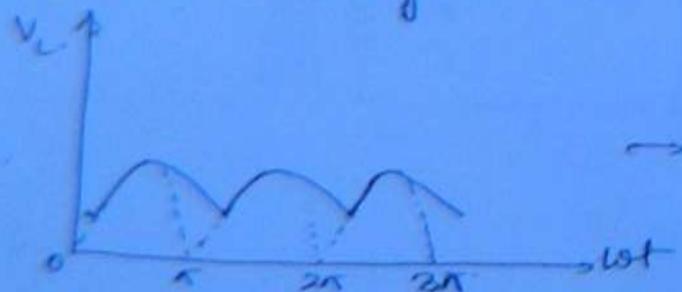


Capacitive filters →

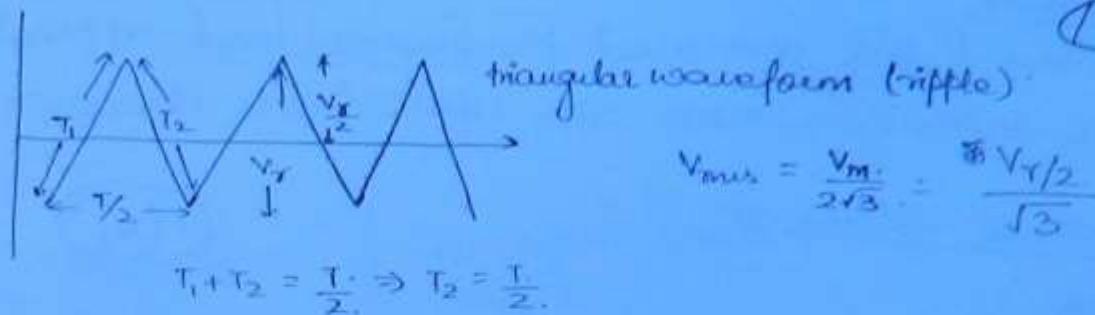


ωt_2 → cut in angle.

ωt_1 → cut out angle.



- expression for ripple voltage per half wave →



charge lost at time T_2 = charge lost by the capacitor.

$$I_{\text{DC}} \times T_2 = C \times V_T$$

$$V_t = \frac{I_{\text{DC}} \times T}{2C}$$

$$\frac{I_{\text{DC}}}{2fC}$$

$$\frac{V_{\text{DC}}}{2fCR_L}$$

$$\begin{aligned} R_{\text{f}} &= \frac{V_{\text{max}}}{V_{\text{DC}}} \\ &= \frac{V_S}{2\sqrt{3}} / V_{\text{DC}} \\ &= \frac{V_{\text{DC}}}{4\sqrt{3}fCR_L} / V_{\text{DC}} \end{aligned}$$

$$R_{\text{f}} = \frac{1}{4\sqrt{3}fCR_L}$$

→ for high load.
and Capacitive value must be high
for low R.f.

ωt_2 → Cut in angle →

It is the angle at which the diode starts conducting or capacitor gets charged.

ωt_1 → Cut Out angle →

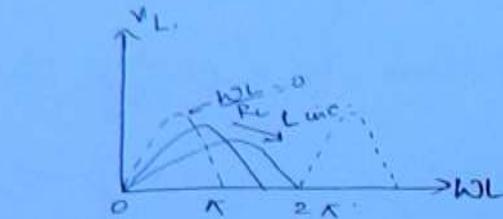
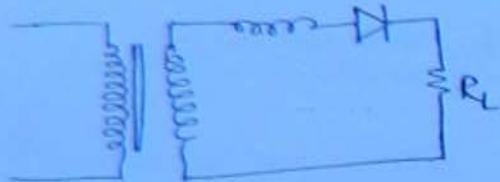
It is the angle at which the diode stops conducting or capacitor gets discharged.

- comm.....
- Capacitive filters are used for heavier load application.
 - As the capacitive value increases, ripple factor decreases.

Inductive filters:

(106)

HWR.



L.m.c.

- can not block 2nd harmonics.
- block all the harmonic components except 2nd.

because in 2nd, $\chi_L = 2\pi f' L$

$$f' = 2 \times 50 \\ = 100 \text{ Hz}$$

not very high, unable to block.

$$I(t) = \frac{I_m}{\pi} - \frac{2I_m}{3\pi} \cos 2\omega t \\ \downarrow \\ \text{dc} \quad \downarrow \\ \text{2nd harmonic}$$

FWR.

$$I(t) = \frac{2I_m}{\pi} - \left(\frac{4I_m}{3\pi} \right) \cos 2\omega t$$

$$I_{dc} = \frac{\partial I_m}{\pi} = \frac{2V_m}{\pi R_L}$$

$$(I_{rms})_{2\text{nd}} = \frac{I_m'}{\sqrt{2}} = \frac{4I_m}{3\pi\sqrt{2}} \\ = \frac{4V_m}{3\pi\sqrt{2}(R_L + j2\omega L)}$$

$$= \frac{4V_m}{3\pi\sqrt{2} \sqrt{R_L^2 + 4\omega^2 L^2}}$$

(107)

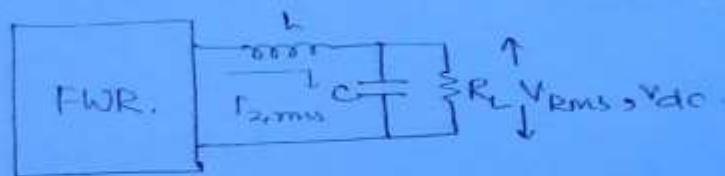
$$R.f. = \frac{I_{rms}}{I_{dc}}$$

$$= \frac{\sqrt{2}}{3} \frac{R_L}{2\omega L} \quad] \rightarrow \text{for lighter loads } (R_L \downarrow) \\ \text{high } L.$$

Conclusion →

- 1) Inductor filter designs are used for lighter load application [R_L]
- 2) If the inductor value is more, ripple factor will be less.

L-section filter → [for varying load application]



$$(I_{rms})_{2nd} = \frac{4V_m}{3\pi\sqrt{2}} \frac{1}{X_L} \quad (X_L = 2\omega L)$$

$$= \frac{2}{3\sqrt{2}} \left(\frac{2V_m}{\pi} \right) \frac{1}{X_L} \xrightarrow{V_{dc}}$$

$$= \frac{\sqrt{2}}{3} \frac{V_{dc}}{X_L}$$

$$V_{rms} = \frac{\sqrt{2}}{3} \frac{V_{dc}}{X_L} X_C \quad X_C = \frac{1}{j2\omega C}$$

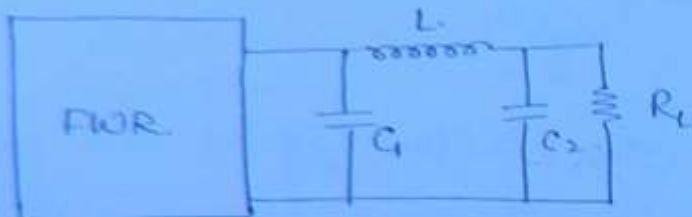
$$\eta = \frac{V_{rms}}{V_{dc}} = \frac{\frac{\sqrt{2}}{3} \frac{V_{dc}}{X_L} X_C}{V_{dc}}$$

$$R.f. = \frac{\sqrt{2}}{3} \frac{X_C}{X_L} \quad \text{free from load.}$$

$$X_L > X_C$$

L-section filters are used for varying load applications

K section filter →



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$$\text{R.L.} = \frac{\sqrt{2} X_0 X_{02}}{X_L \cdot R_L} = \frac{J_2}{3} \frac{X_0}{X_L}$$

Parameters

L section

K section

V_{dc}

better

r.f.

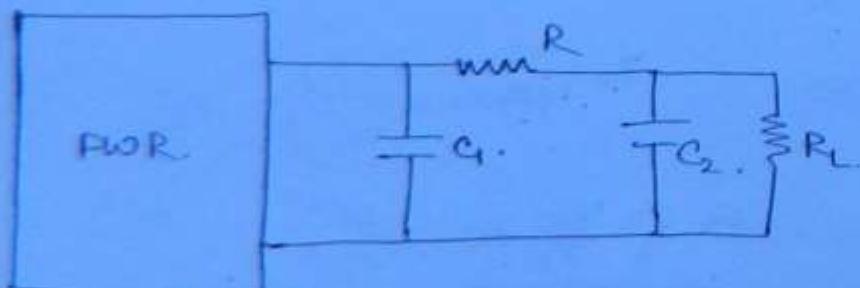
better

f.vr.

better

P.D.V.

RC filter :-



R ≤ 10X_{C2}

$$\text{R.L.} = \frac{\sqrt{2} X_0 X_{02}}{R \cdot R_L}$$

The main drawback of 1 section filter is it can or not be used for heavier load application because of inductor property.

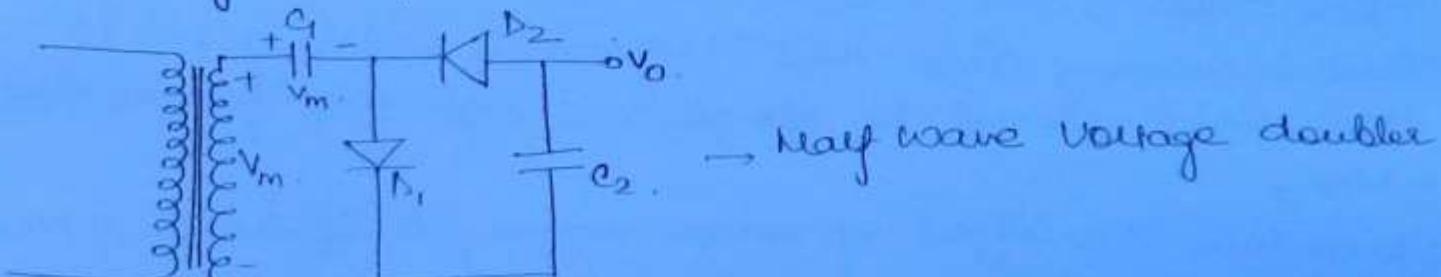
(109)

In practical applications, inductor is becoming more costlier. To reduce that costeffectiveness, we replace inductor by resistor.

Voltage

5H1R

Voltage multiplier :-



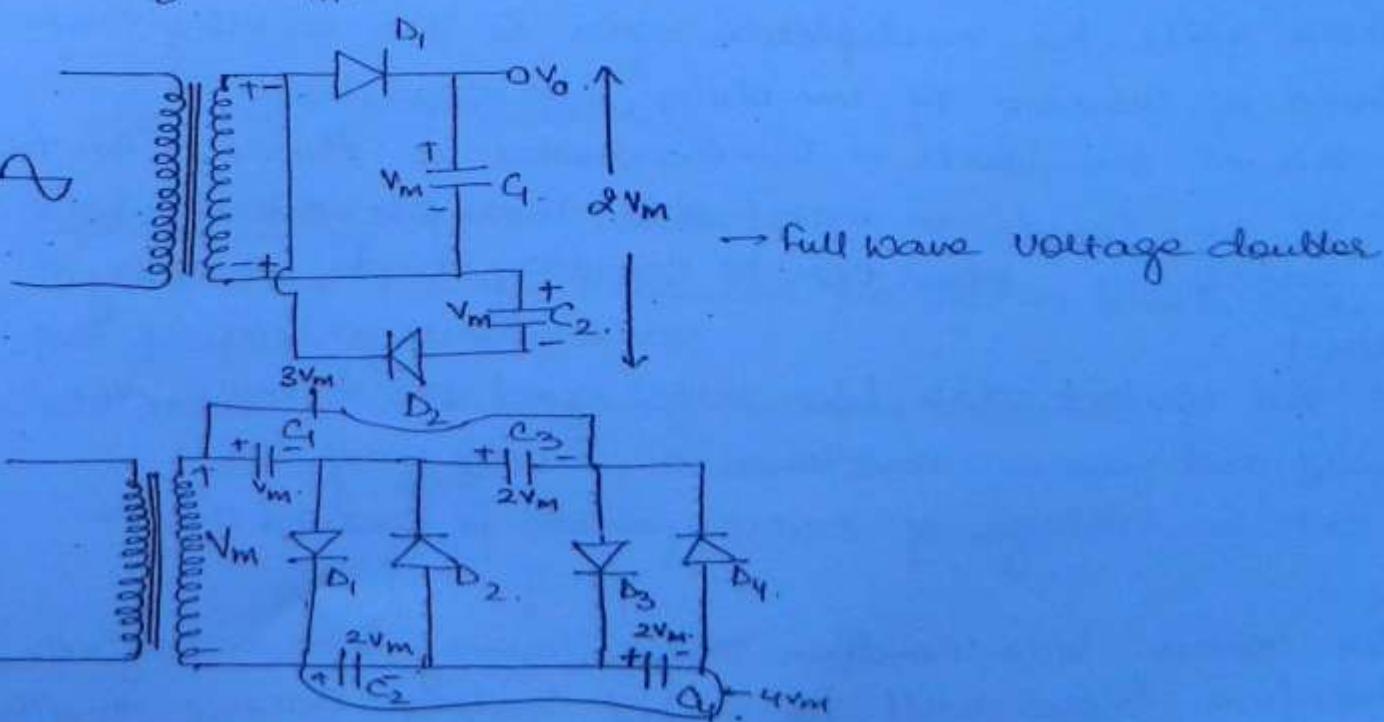
First half cycle,

D₁ ON D₂ OFF

Second half cycle,

D₁ OFF D₂ ON.

$$V_0 = -2V_m$$

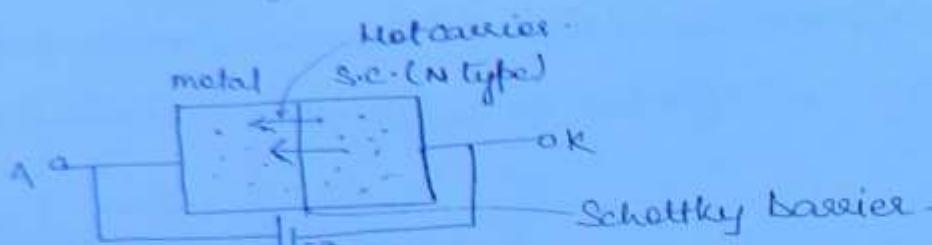


special diode -

Schottky diode →

$$f > 10 \text{ MHz}$$

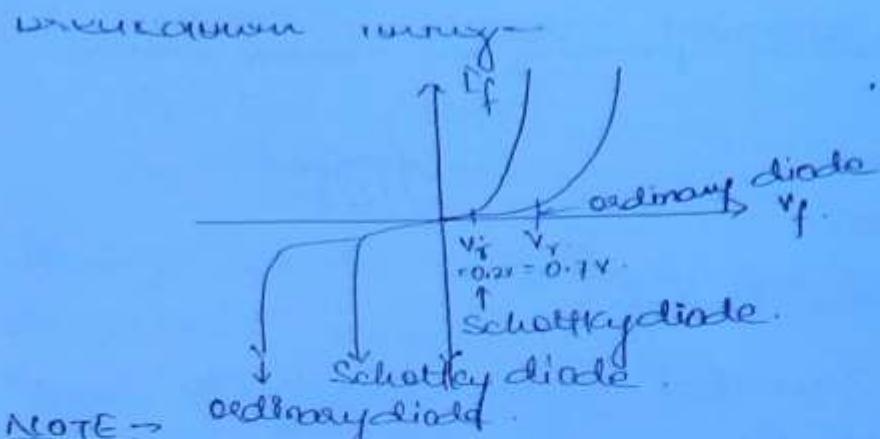
(1/10)



Holes are not present. depletion region is not present.

Conclusion →

- Reverse recovery time is a problem in ordinary P-n-j diode which cannot be operated for high freq greater than 10 MHz.
- To reduce the effect of reverse recovery time above 10 MHz range special diode called as Schottky diode was implemented.
- Schottky diode construction details are diff. from ordinary diode.
- Schottky diode is a unipolar device whereas ordinary diode is a bipolar device.
- There will be no depletion region in the Schottky diode because of missing of immobile ions and holes.
- As the e^- en. levels in semiconductor is always less than e^- en. levels in metal side. Therefore current is not possible in open circuit for Schottky diode [Schottky barrier]
- If the contact area b/w metal and S.C. is more, the forward and reverse resistance ω is very very less.
- A cut in voltage of Schottky diode is around 0.2 to 0.25 V.
- On reverse bias condition, reverse recovery time is neglected therefore there will be rapid leakage current and less



(11)

NOTE → ordinary diode.

When Schottky diode is operated in anti bias, the e-fom N type will penetrate towards the metal side such case are called as hot carrier. That is the reason we called it as hot carrier diode.

Simple representation →



Application →

- 1) mainly used to rectify the signals above 300 MHz.
- 2) In digital comp., we already use this diode.
- 3) Digital ORPs (special TTL diodes)
- 4) TTL high speed logic family

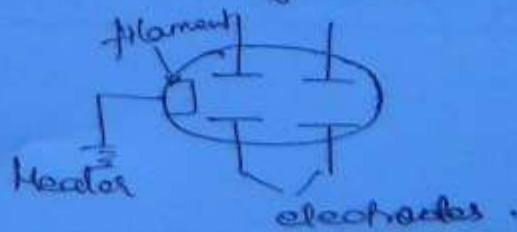
BJT →

(Bipolar j² transistor)

Introduction →

Before 1957, Vacuum tubes are the devices which solve the purpose of amplification.

The main disadvantage of vacuum tubes are



It is having more power or heater which requires more power.

b) It takes more space.

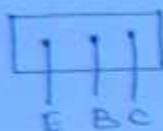
c) Its life span is less.

d) Its power dissipation is high.

(12)

After 1957 BJT was invented which can also serve the purpose of amplification.

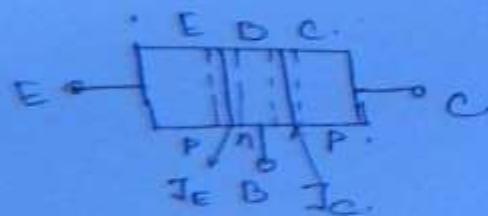
The main advantage of BJT compare to vacuum tubes are



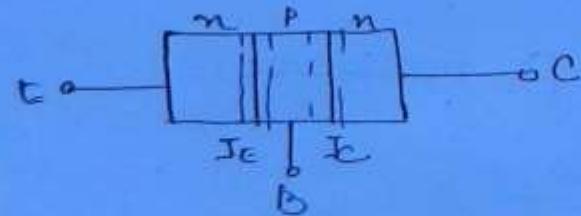
- 1) It is not having any internal filament or heater which requires more power.
- 2) It takes very less space.
- 3) Its life span is more.
- 4) Its power dissipation is very less in the order of mw (milli watt).

Types of BJT: →

→ PNP



nPN



For proper working of BJT: →

conditions →

1) Doping level

$$E > C > B.$$

2) $W_B < L_p \text{ or } L_n$.

i) width of the base should be narrower.

→ Diode + Resistor = Transistor.

$Z_i \rightarrow$ low (high)
 $Z_o \rightarrow$ high (low)

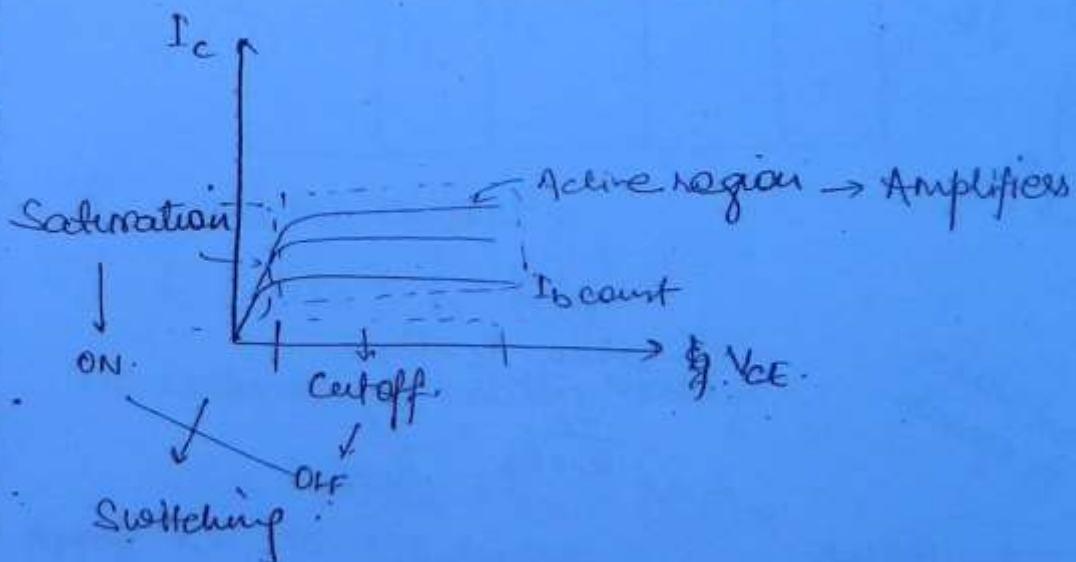
(113)

→ Transfer of I from one place to another impd. is called transistor.

Types of operating region →

Region	I_E	I_C
Active Region	FB	RB
Saturation Region	FB	FB
Cutoff region	R.B.	R.B.
Reverse Active region	R.B.	FB

→ BJT is current controlled device.

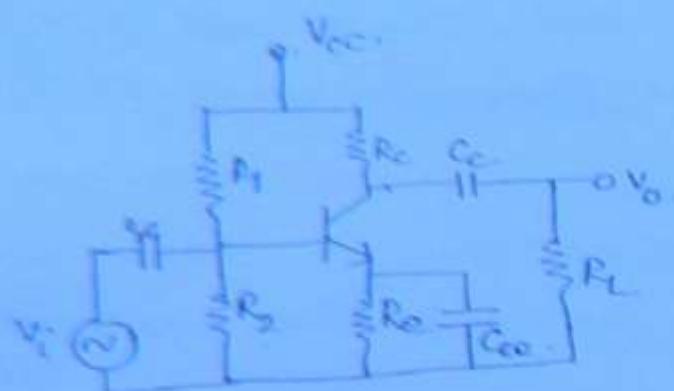


DC load line and operating pt.

DC biasing and operating pt:-

CE amplifier →

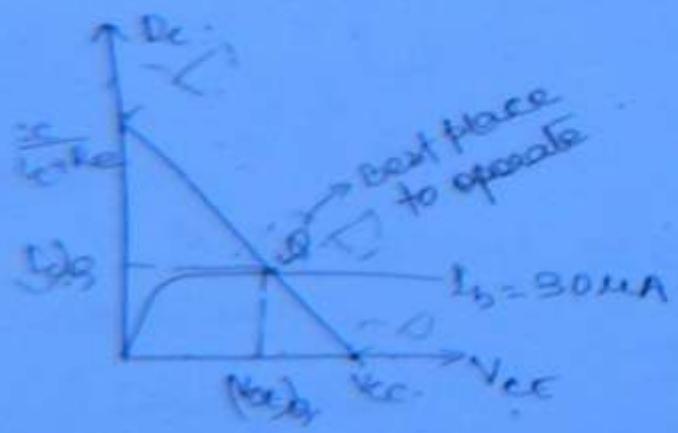
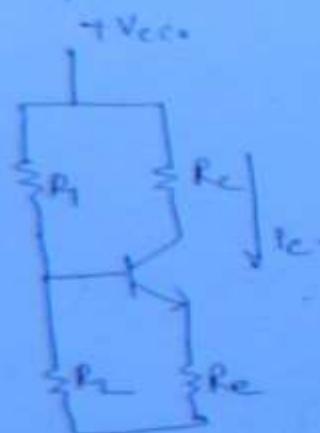
(1/4)



DC analysis →

▷ ac should be grounded.

$$\Rightarrow x_{ce} f_{\rightarrow 0} = 0$$



when $I_c = 0$,

$$\frac{V_{cc}}{R_{ct} + R_e} = \frac{V_{cc}}{R_{ct} + R_e}$$

$$\Rightarrow V_{ce} = V_{cc}$$

O/P loop → $V_{cc} = I_c (R_{ct} + R_e) + V_{ce}$.

$$I_c = \frac{V_{cc}}{R_{ct} + R_e} - \frac{V_{ce}}{R_{ct} + R_e}$$

Conclusion :—

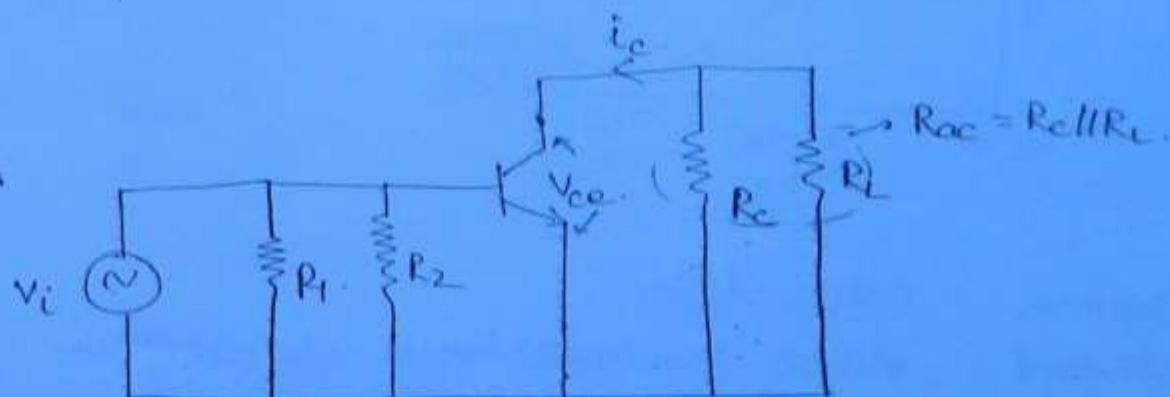
- For any analysis of BJT, we always prefer O/P char of BJT [it is a current controlled device] (15)
- DC load line \rightarrow The locus of all quiescent points are conc. on a line is called as DC load line.
- Operating pt :—
 (Quiescent pt)
 \downarrow
 Inactive

It is the intersection pt b/w sample graph of I_C w.r.t dc load line

AC Analysis \rightarrow

DC should be grounded.

$$X_C \propto f_{-3dB} = 0$$



AC collector current =

$$\dot{i}_C = \Delta I_C = \dot{I}_C - (I_C)_Q$$

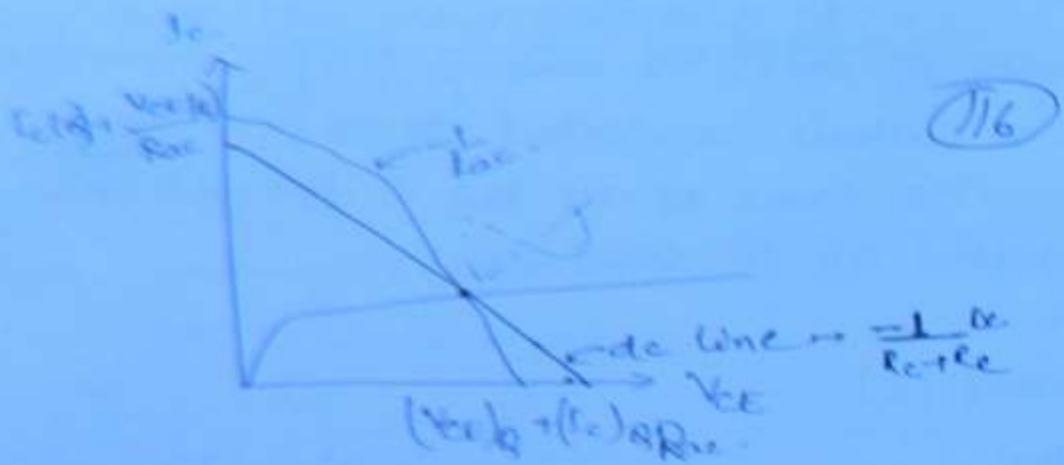
AC collector to emitter Voltage

$$\dot{V}_{CE} = \Delta V_{CE} = V_{CE} - (V_{CE})_Q$$

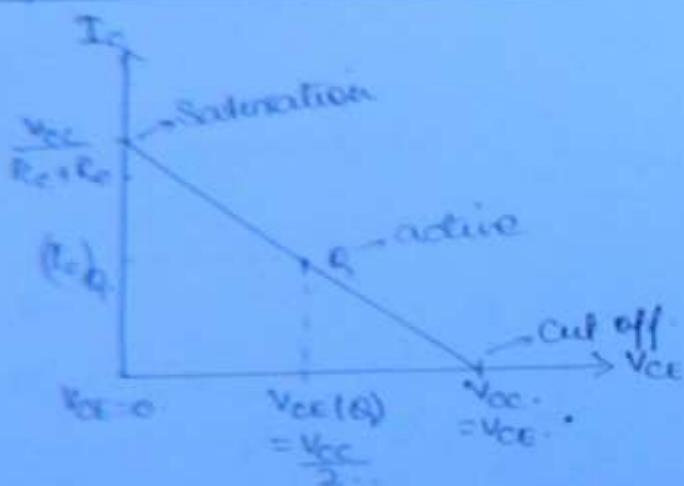
Apply KVL to O/P loop

$$V_{CE} + i_C(R_{AC}) = 0$$

$$V_{CE} - (V_{CE})_Q + (i_C t - (I_C)_Q) R_{AC} = 0$$



Condition for V_{CE} in saturation, active and cut off :—

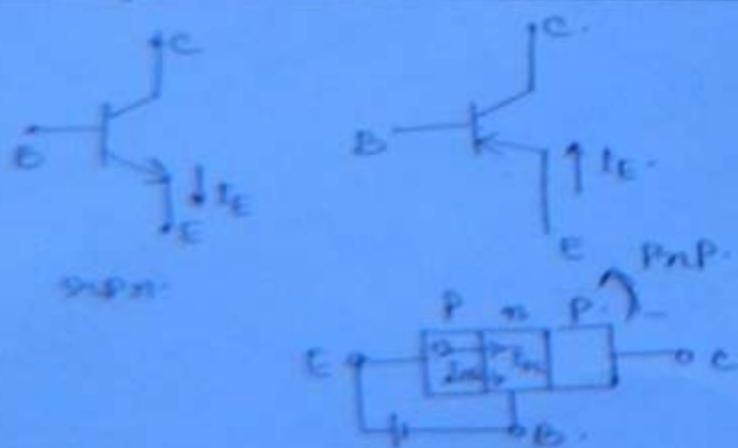


Active Source
Power delivered
e.g. — Volt-Source
or

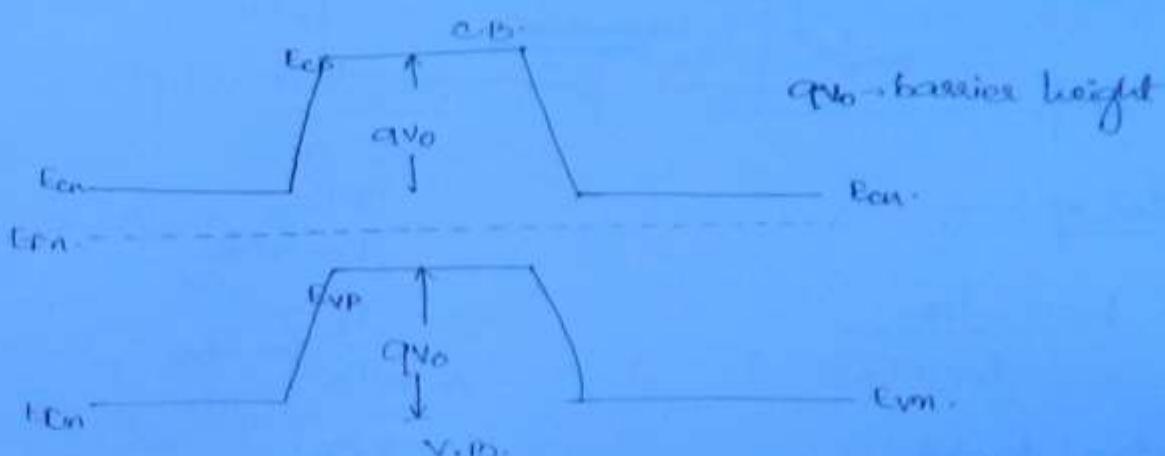
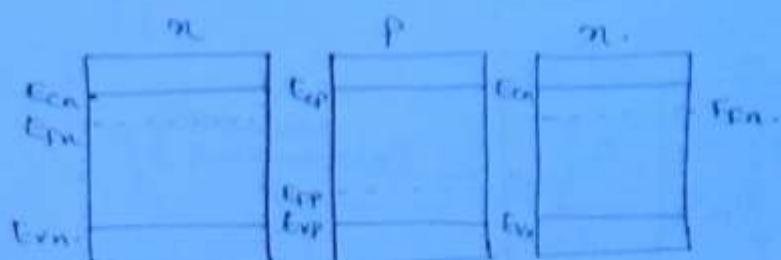
Current Source

Active device
which produces some internal gain.
e.g. — BJT, FET, MOSFET, OPAMP.

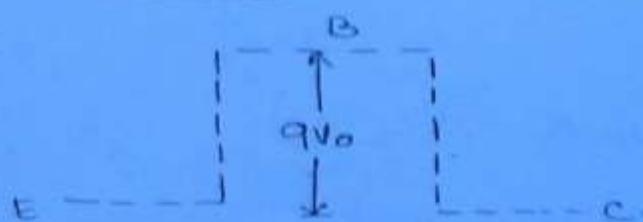
Simple representation of BJT :—



(117)

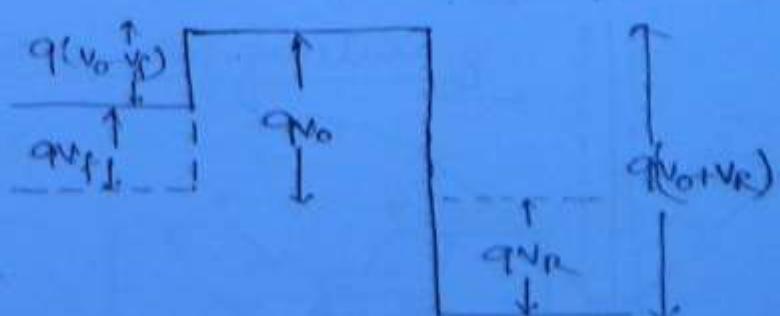


Conclusion →



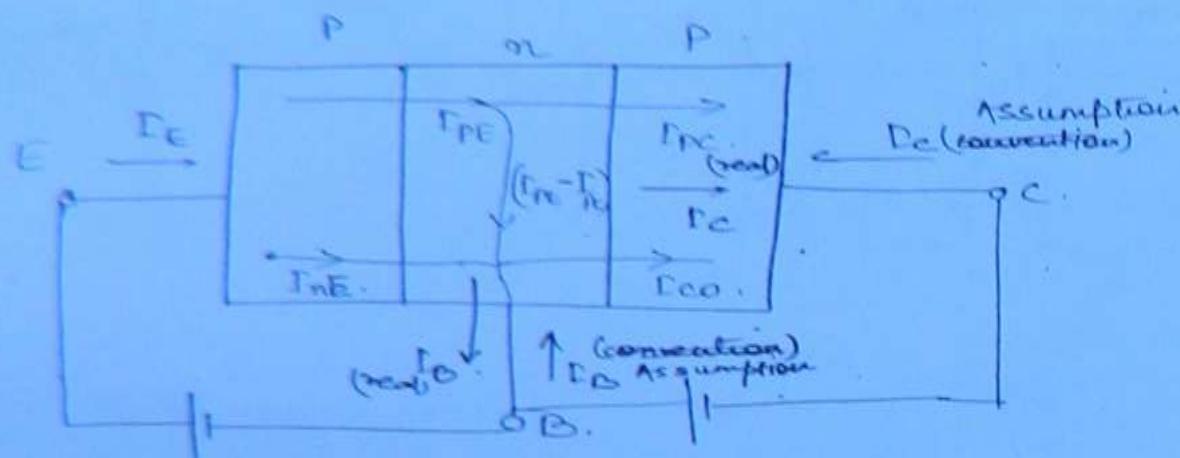
Note → Any no. of materials are joined, fermi levels will be in aligned position.

Biased condition →



Transistor current components →

718



1) emitter η :—

$$\eta = \frac{I_{PE}}{I_{PE} + I_{nE}}$$

PnP.

I_E -ive

I_B } -ive
 I_C }

2) Transport factor :—

$$\beta^* = \frac{I_{PC}}{I_{PE}}$$

nPN.

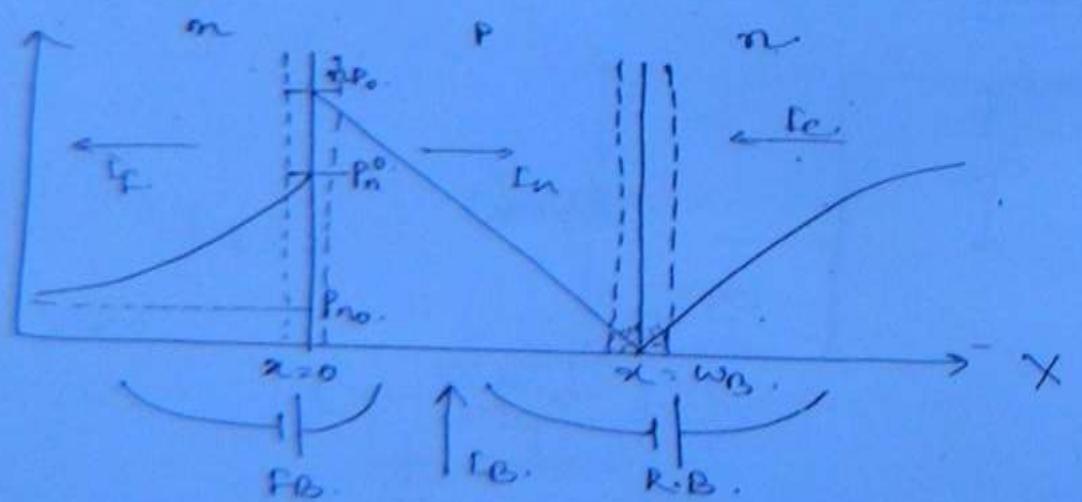
I_E -ive

I_B } -ive
 I_C }

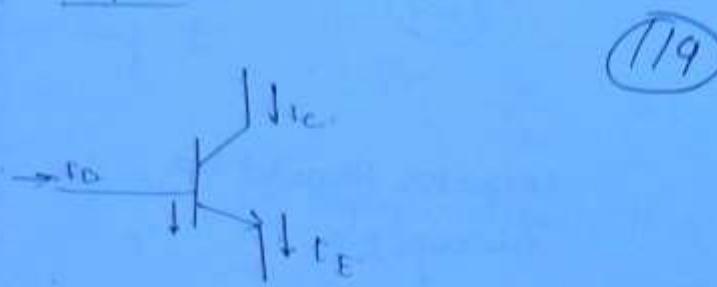
3) Large ~~or~~ signal current gain $\alpha = -\frac{(I_C - I_{CO})}{I_E - 0}$

$$\alpha = \beta^* \eta$$

Carrier Concentration V/S distance in BJT :—



n-p-n →



(119)

$$I_n = Aq D_B \frac{dn(x)}{dx}$$

$$= Aq D_B \frac{n_{p(0)} - 0}{w_B}$$

$$= -\frac{Aq D_B n_{p_0}}{w_B}$$

$$I_c = -I_n = \left\{ \frac{Aq D_B n_{p_0}}{w_B} \right\} e^{\frac{V_{BE}}{V_T}}$$

$$n_{p(0)} = n_{p_0} e^{\frac{V_{BE}}{V_T}}$$

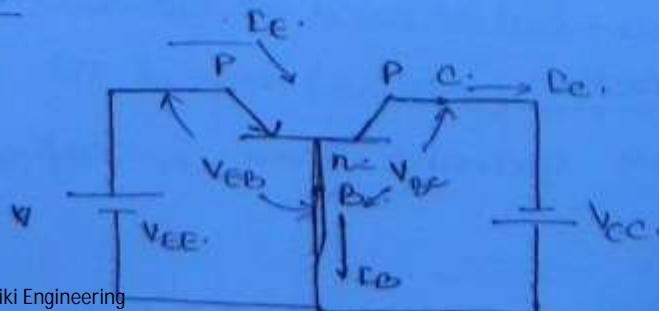
Law of I_n .

$$I_c = I_s e^{\frac{V_{BE}}{V_T}}$$

Where $I_s = \frac{Aq D_B n_{p_0}}{w_B}$

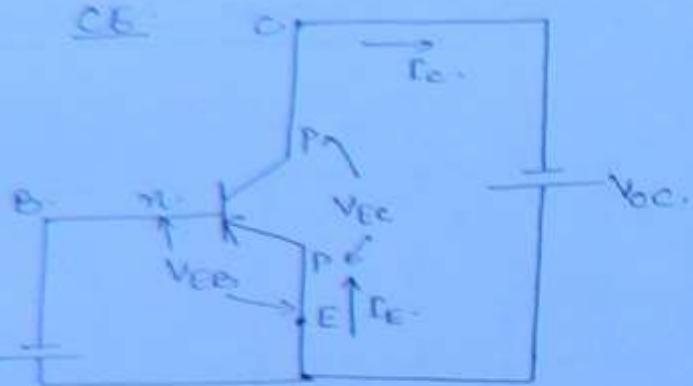
Transistor Configuration →

CB .



$$\text{Current gain} = \frac{I_c}{I_e} = \alpha$$

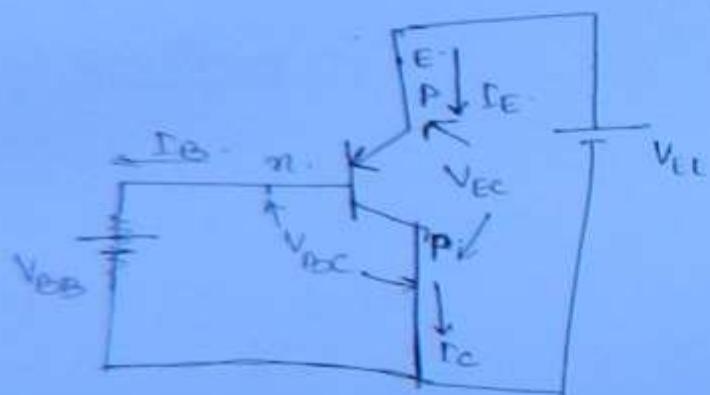
(120)



Collector should be always R.B.

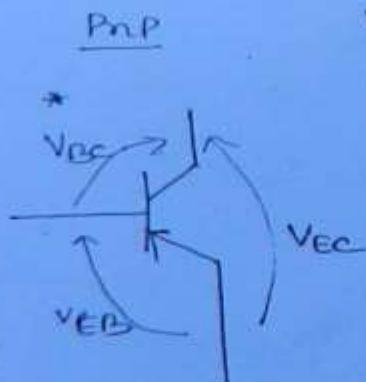
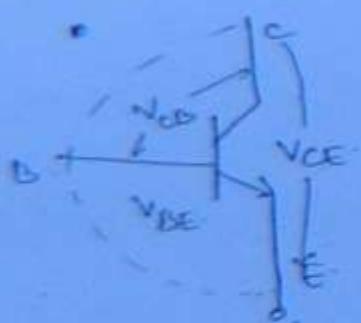
$$\text{current gain} = \frac{I_c}{I_b} = \beta.$$

CC:



$$\frac{I_E}{I_B} = \gamma$$

n Pn



α, β, γ Relations →

current amplification factor:

- 1) In CE configuration the current gain is represented by α .

$$\alpha = \frac{I_c}{I_E}$$

Practically it lies b/w 0.9 to 0.99

2) In CE configuration, the current gain is represented by β

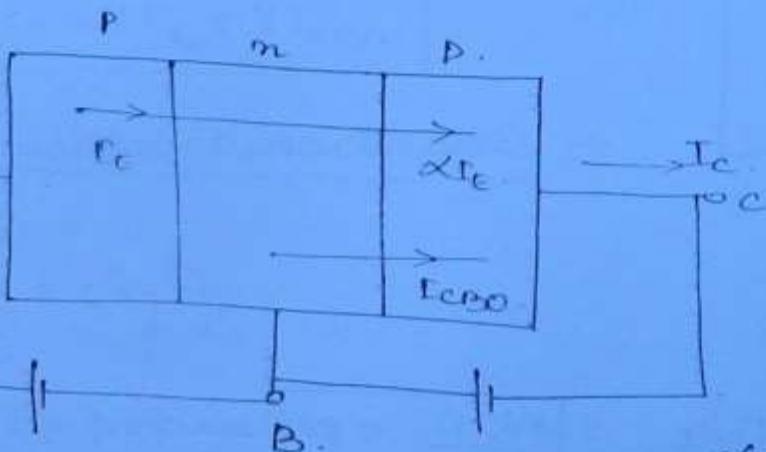
$$\beta = \frac{I_C}{I_B} \Rightarrow 20 \text{ to } 500. \quad (12)$$

3) In CC configuration, the current gain is represented by γ .

$$\gamma = \frac{I_E}{I_B} \Rightarrow 20 \text{ to } 500.$$

Total O/P current in CB: —

* magnitude



$$\alpha = \frac{I_C}{I_E}$$

$$I_C = \alpha I_E + I_{CBO}$$

$$I_E = I_B + I_C$$

$$I_C = \alpha (I_B + I_C) + I_{CBO}$$

$$\Rightarrow I_C (1 - \alpha) = \alpha I_B + I_{CBO}$$

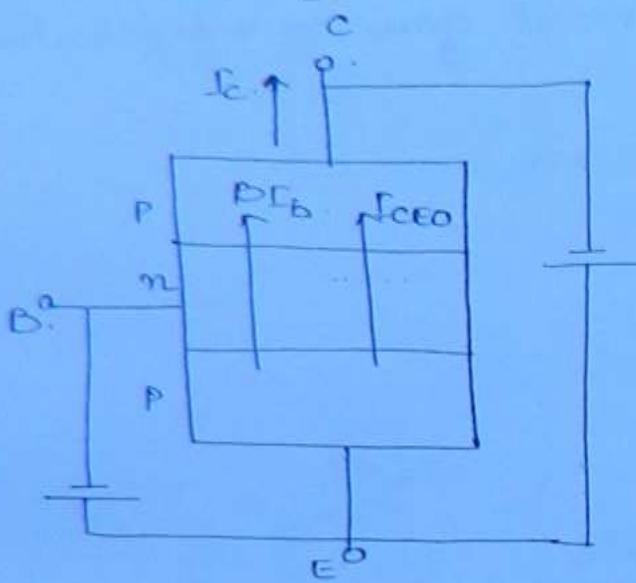
$$I_C = \frac{\alpha}{1 - \alpha} I_B + \frac{I_{CBO}}{1 - \alpha}$$

$I_{CBO} \rightarrow$ collector to base value never Saturation current when EIP is open (emitter)

Total O/P current in CE \rightarrow

(122)

$$\beta = \frac{I_C}{I_B}$$



$$I_C = \beta I_B + I_{CEO}$$

$$I_{CEO} > I_{CB0}$$

$$\beta = \frac{I_C}{I_B} = \frac{I_C}{I_E - I_C} = \frac{I_C/I_E}{1 - I_C/I_E} = \boxed{\frac{\alpha}{1-\alpha}} = \beta$$

$$\boxed{\frac{1}{1-\alpha} = 1+\beta}$$

$$I_C = \frac{\alpha}{1-\alpha} I_B + \frac{1}{1-\alpha} I_{CB0}$$

$$I_{CEO} = \frac{1}{1-\alpha} I_{CB0}$$

$$\Rightarrow I_C = \beta I_B + (1+\beta) I_{CB0}$$

$$\boxed{I_{CEO} = (1+\beta) I_{CB0}}$$

Total O/P current in CC \rightarrow

$$I_E = I_B + I_C$$

$$I_C = \alpha I_E + I_{CEO}$$

$$I_E(1-\alpha) = I_B + I_{CEO}$$

$$I_E = \frac{I_B}{1-\alpha} + \frac{I_{CEO}}{1-\alpha}$$

(123)

$$I_E = (1+\beta) I_B + (1+\beta) I_{CEO}$$

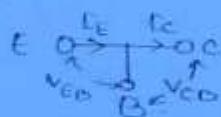
$$\gamma = \frac{I_E}{I_B} = \frac{I_E}{I_E - I_C} = \frac{1}{1 - I_C/I_E} = \frac{1}{1-\alpha} = 1+\beta.$$

$$\gamma = \frac{1}{1-\alpha} = 1+\beta.$$

$$I_C = \gamma I_B + \gamma I_{CEO}$$

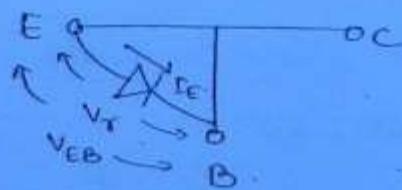
Transistor characteristics \rightarrow

CB \rightarrow



I/P parameters = I_E, V_{BEB}

O/P parameters = V_{CB}, I_C .



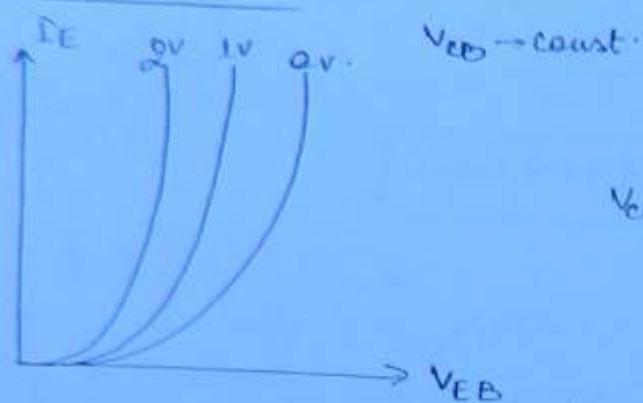
$V_{EB} \rightarrow 0.5$ to 0.7 V.

$I_E \rightarrow 0$ mA to 140 mA.

Conclusion \rightarrow

- 1) This is to get the I/P char., O/P voltage should be constant [O/P current I_C never change the I/P current I_E]
- 2) To get the O/P char., I/P current should be constant. [I/P voltage will have less dynamic range]
- 3) BJT is current controlled device. That means the O/P char are controlled by I/P current but not voltage.

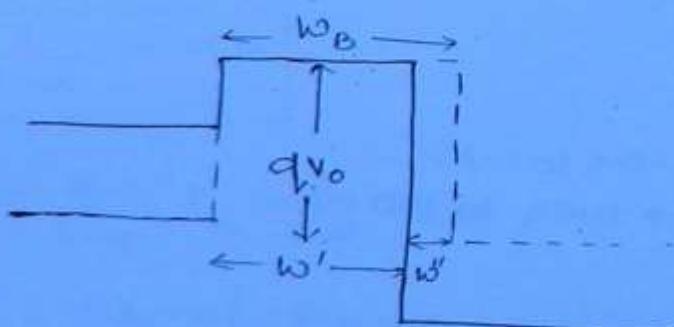
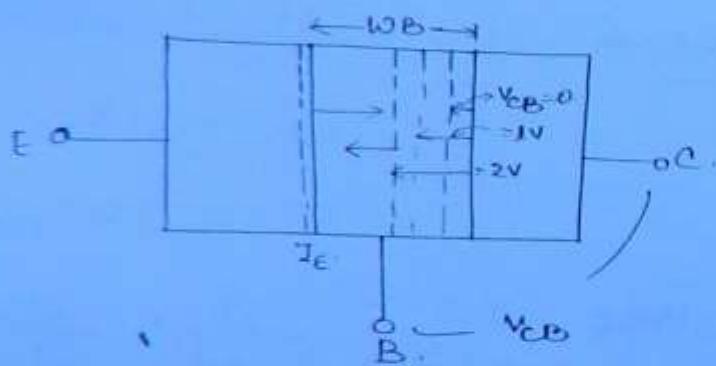
LTP char in CB:-



$V_{CB} \uparrow, W_B \downarrow, I_B \downarrow, I_{PPB} \uparrow,$
 $I_E \uparrow$

early

Early effect or Base width modulation:



$$W_B = W_f + W'' \uparrow$$

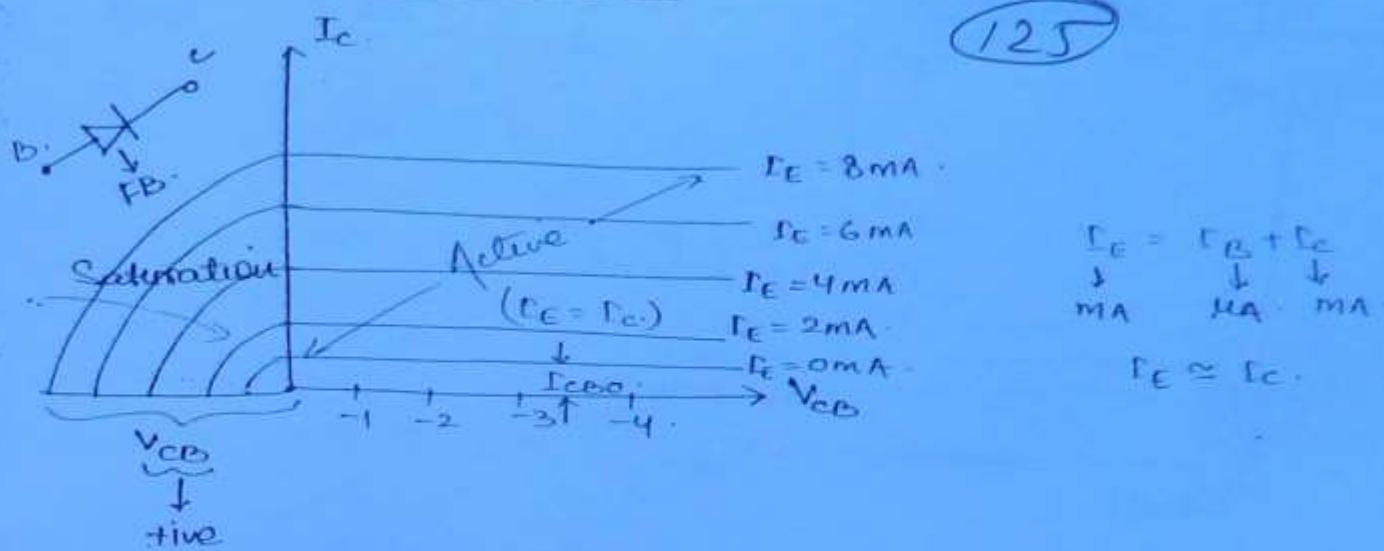
Physical width
of:
base

effective base width

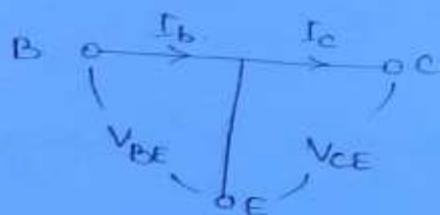
← penetration width.

$W_B = W''$
 $W' = 0.$ } \rightarrow punch through or reach through.

C.B. O/P characteristics :-



C.E. I/P characteristics :-

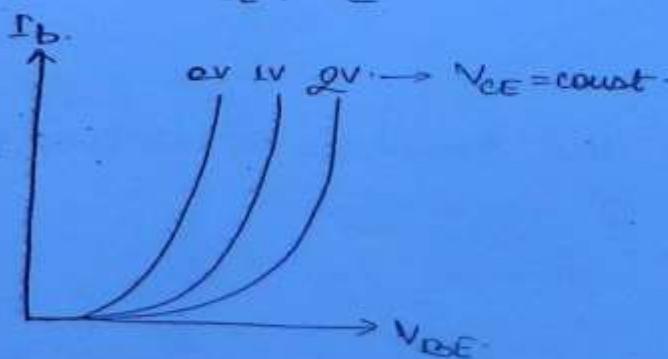


I/P parameters →

V_{BE} , I_b .

O/P parameters →

V_{CE} , I_c

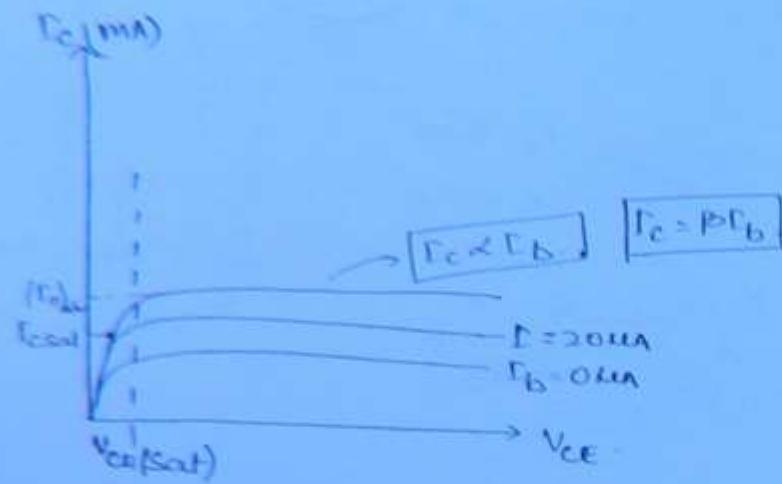


$V_{CE} \uparrow, R_B \downarrow, I_b \downarrow$

early effect is possible in CE because collector terminal is R.B.

CE - O/P Characteristics

(126)



Q. In an n-p-n transistor if $V_{CE} = 0.3V$ then the transistor is acting in Active region.

Q. If $I_c = \beta I_b$ then the transistor is acting in Active region.

Q. If $I_b > \frac{I_c}{\beta}$, then the transistor is acting in Saturation region.

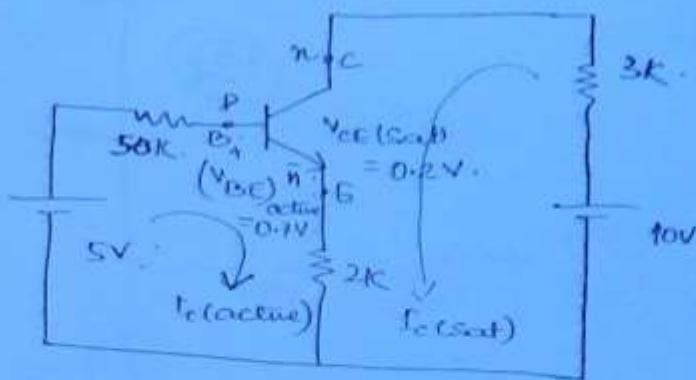
Q. If $(I_c)_{active} > I_c(sat)$, Then the transistor is acting in Saturation region.

Q. If $(I_c)_{active} < I_c(sat)$, then the transistor is acting in Active region.

	$V_{CE(sat)}$	$V_{BE(sat)}$	$V_{BE(active)}$	$V_{BE(cutoff)}$	$V_{BE(cutin)}$
Si	0.2 V	0.8 V	0.7 V	0.5 V	0.0 V
Ge	0.1 V	0.3 V	0.2 V	0.1 V	-0.1 V

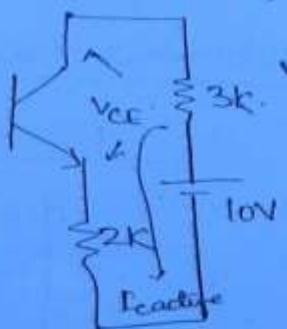
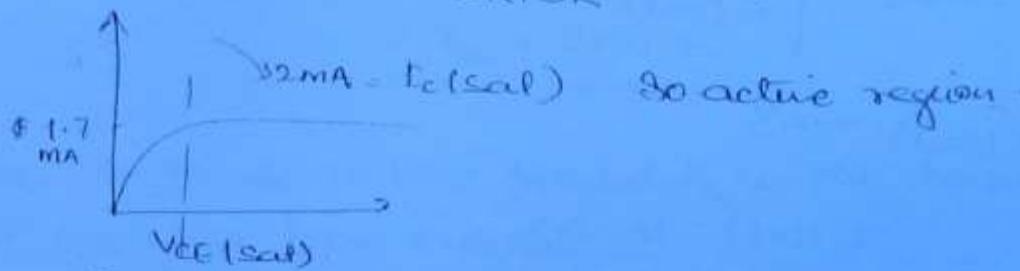
Pg - 22
Ans.

(127)



$$I_c(\text{active}) = \frac{5 - 0.7}{2k} = 1.7 \text{ mA}$$

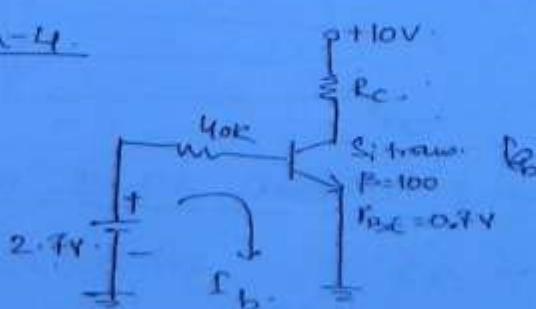
$$I_c(\text{sat}) = \frac{10 - 0.2}{2k + 3k} = \frac{10}{5k} = 2 \text{ mA}$$



$$V_{CE} = 10 - 5k \times I_c(\text{active}) \\ \approx 1.5V$$

Active	D/P	O/P
Sat	D.B.	R.B.
	L.B.	D.B.

Pg - 21
Ch - 4
Q1.



Inactive region only,

$$I_b = \frac{2.7 - 0.7}{40k} \\ = \frac{2}{40k} = \frac{1}{20} \text{ mA}$$

$$I_c = \beta I_b$$

$$> \frac{100 \times 1}{20} \text{ mA} = 5 \text{ mA}$$

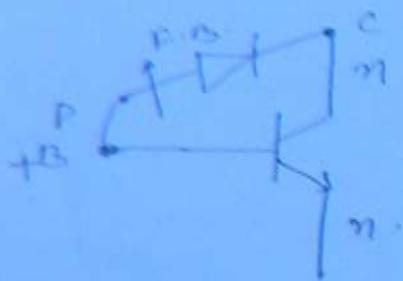
$$\text{Q2. } V_{CE} = 10 - 2.5 \times 5 \text{ mA} \\ = -2.5 \text{ V}$$

$$V_B + V_{BE} \approx V_{CE}$$

$$V_{BE} = -2.5 - 0.7$$

$$\approx -3.2 \text{ V}$$

(128)



$$I_C = 2.5 \text{ mA}$$

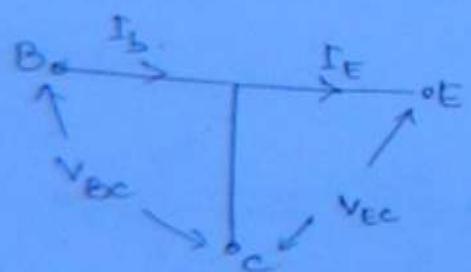
$\downarrow I_C(\text{sat})$

$$V_{CE(\text{sat})} = 0.2 \text{ V}$$

$$I_C(\text{sat}) = \frac{10 - 0.2}{2.5 \text{ k}}$$

$$= 3.9 \text{ mA}$$

Common Collector characteristics →

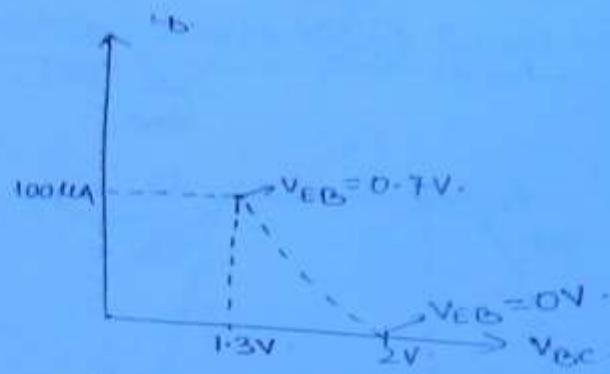


I/P parameters —

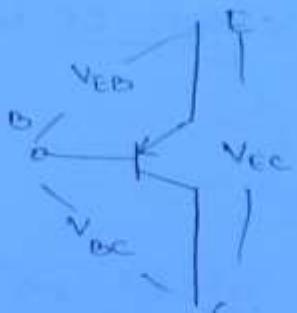
V_{BE}, I_B

O/P parameters —

V_{CE}, I_E



(129)



$$V_{EC} = V_{EB} + V_{EC}$$

$$V_{EC} = V_{EC} - V_{EB}$$

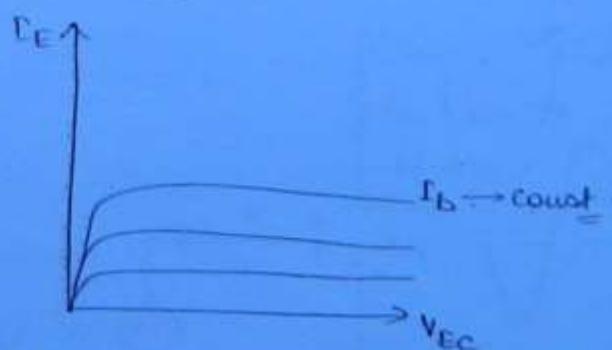
Assume $V_{EC} = 2V$.

$$V_{EC} = 2 - 0.7 \\ = 1.3V$$

~~EB~~ V_{EB} can create a base current I_B in the transistor. V_E can also create a base current.

Common collector O/P characteristics :-

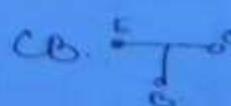
C.C. O/P



Diff. b/w CB, CE, and C.C. :-

Characteristics.

1) Z_i



$$\frac{V_{EB}}{I_E} = \frac{0.7}{100\text{mA}} = 7\Omega$$

Moderate

$$\frac{V_{EC}}{I_B} = \frac{10V}{1mA} = 10k\Omega$$

2) Z_o

$$\frac{V_{EB}}{I_C} = \frac{10V}{10mA} = 1k\Omega$$

Moderate

$$\frac{V_{EC}}{I_C} = \frac{10V}{1k\Omega} = 10\text{V}$$

3) A_V

$$\frac{V_{OB} - V_B}{V_{CB}}$$

$A_V > 1$

(130)

$$\frac{V_{EC}}{V_{BC}} \approx 1.$$

4) A_I

$$\frac{I_C}{I_E} = 1$$

$A_I > 1$.

$$\frac{I_E}{I_B} > 1.$$

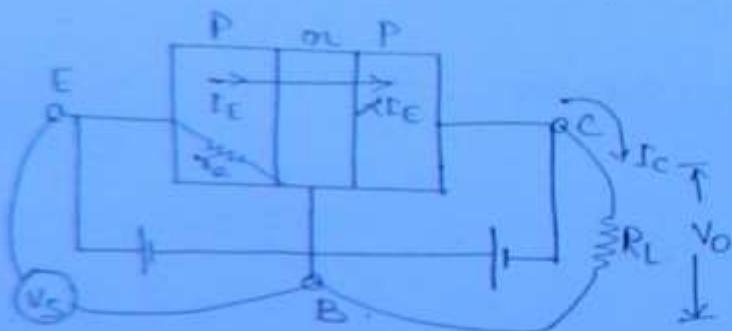
Conclusions →

- 1) On most of the practical application, we choose CE because power gain will be high. $A_V > 1$, $A_I > 1$
- 2) On CC, voltage gain = unity
- 3) On CB, current gain will be unity.

3/1/12

BJT Applications →

▷ Transistor as an amplifier →



$$A_V = \frac{V_O}{V_I} = \frac{I_C R_L}{I_E r_e}$$

$$= \frac{\alpha I_E R_L}{I_E r_e}$$

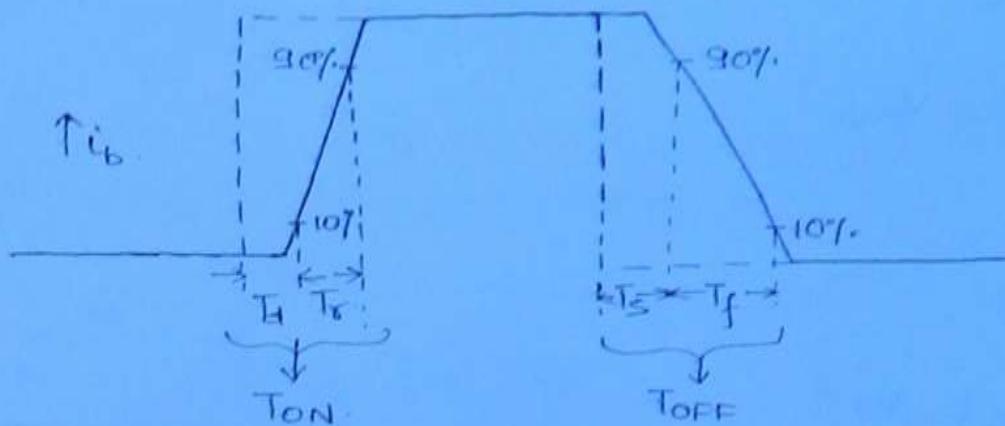
$$= \frac{\alpha R_L}{r_e}$$

Assume $\alpha = 1$, $R_L = 3k\Omega$, $r_e = 30\Omega$

$$A_V = \frac{\alpha R_L}{r_e} = \frac{1 \times 3000}{30} = 100$$

2) Transistor switching times →

(131)



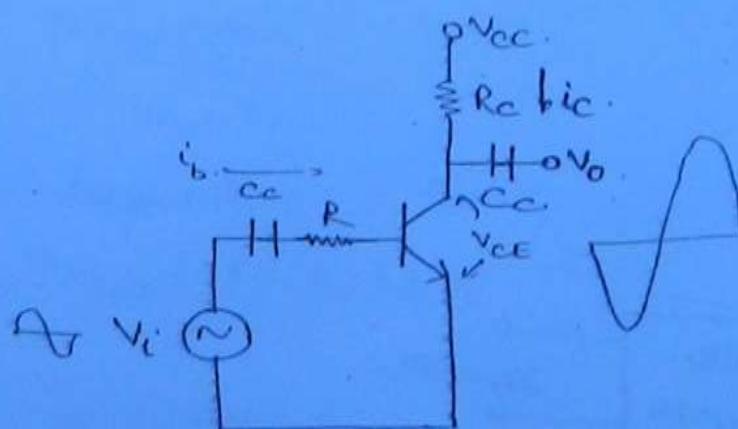
$$T_{ON} = T_d + T_r$$

↑ ↑
delay time rise time

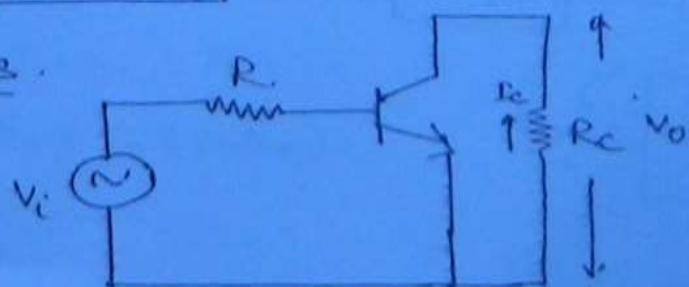
$$T_{OFF} = T_s + T_f$$

↓ ↓
Storage time fall time.

CE as 180° phase shift :→



Ac Analysis



$$V_o = -i_c R_C$$

(132)

positive half cycle →

$i_b \uparrow, i_c \uparrow, i_c R_C \uparrow, V_o \downarrow$

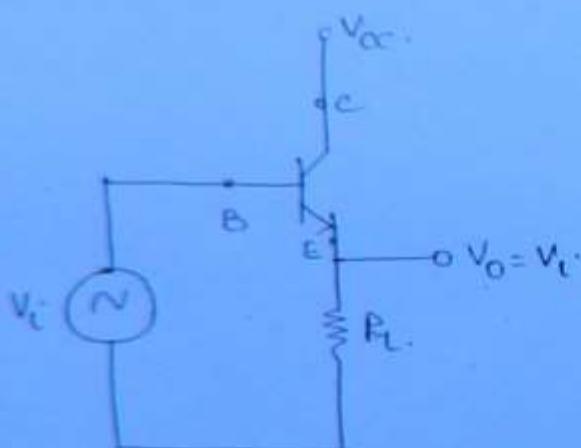
$$i_c = \beta i_b$$

negative half cycle →

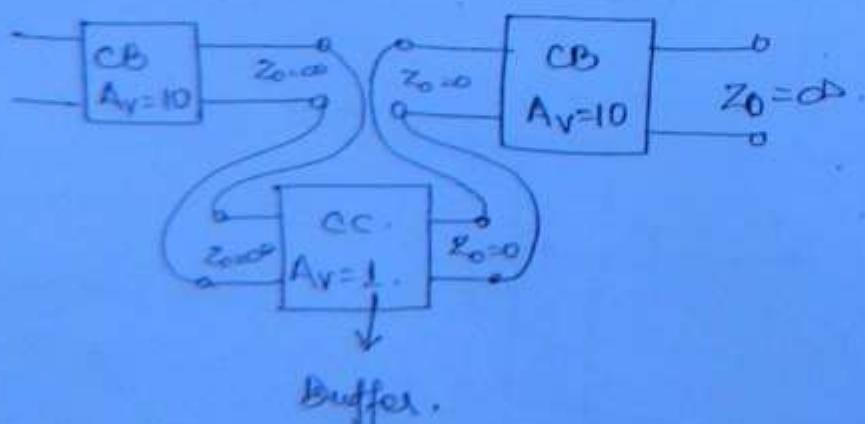
$i_b \uparrow, i_c \downarrow, i_c R_C \downarrow, V_o \uparrow$

CC in impedance matching →

* $A_v = 1$ CC as emitter follower.



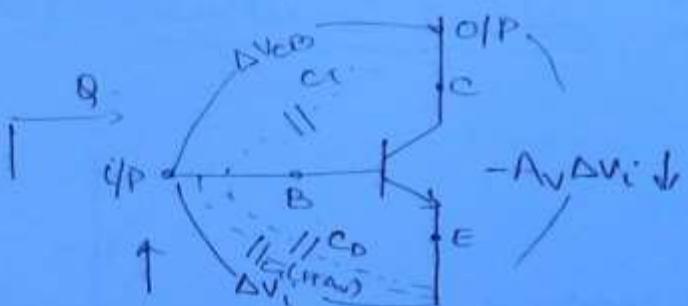
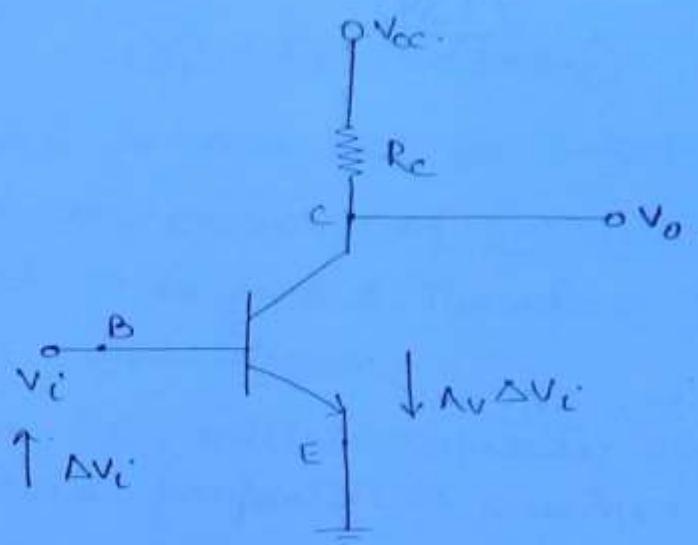
Impedance matching:



CB in high freq. application \rightarrow

CE.

(133)



$$\Delta v_{CB} + \Delta v_i = -A_v \Delta v_i$$

$$V_B > V_C$$

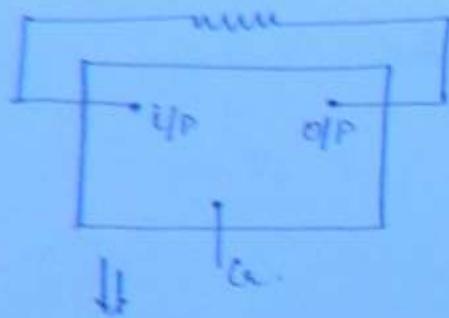
$$-\Delta v_{CB} + \Delta v_i = -A_v \Delta v_i$$

$$\Delta v_{CB} = (1 + A_v) \Delta v_i$$

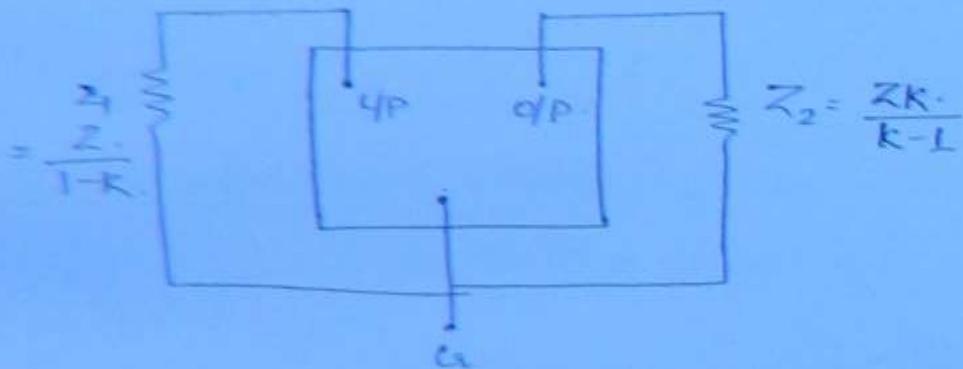
$$\begin{aligned} Q_p &= C_T \Delta v_{CB} \\ &= C_T (1 + A_v) \Delta v_i \end{aligned}$$

$$C_{in}' = C_D + C_T (1 + A_v)$$

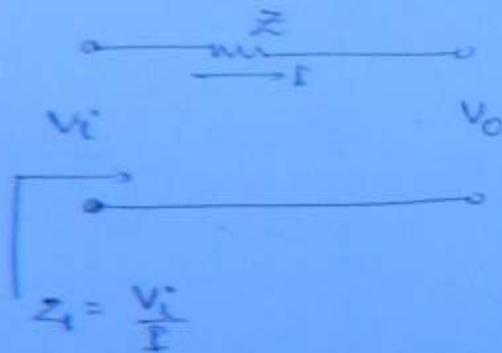
QUESTION



134



Proof →



$$Z_1 = \frac{V_i}{I}$$

$$I = \frac{V_i - V_o}{Z}$$

$$= \frac{V_i \left[1 - \frac{V_o}{V_i} \right]}{Z}$$

$$Z_1 = \frac{V_i}{I} = \frac{Z}{1 - V_o/V_i}$$

$\frac{V_o}{V_i} = K$

Conclusion →

- 1) In CE, because of 180° phase shift property, Miller's capacity effect is existing at the EFP as

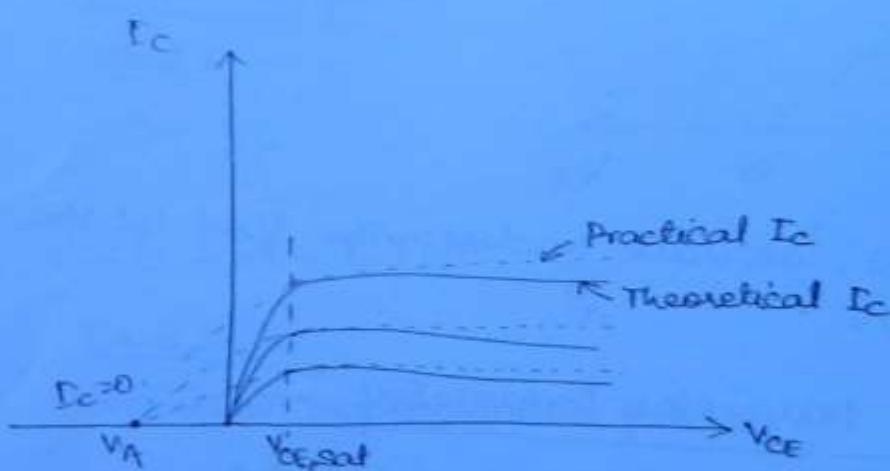
$$C_{in'} = C_D + C_T(1+A_V) \quad (135)$$

Hence it can not be used for high freq. applications.

- 2) In CB, Because of inphase property, Miller's capacity effect is neglected. Therefore it can be used for high freq. applications.

- 3) In CC, Miller's capacity effect is neglected because of inphase property. It can not be used for high freq. because voltage gain is unity.

I_C dependence on V_{CE} →



$$\uparrow I_c = I_s e^{\frac{V_{BE}}{V_T}}$$

$$\text{Where } A_Q \uparrow I_s = \frac{A_Q D_B R_{L0}}{W_B}$$

early effect →

$V_{CE} \uparrow, W_B \downarrow$

$$I_c' = I_s e^{\frac{V_{BE}}{V_T}} \left[1 + \frac{V_{CE}}{V_A} \right]$$

If $V_A = \infty$

$$I_c' = I_c$$

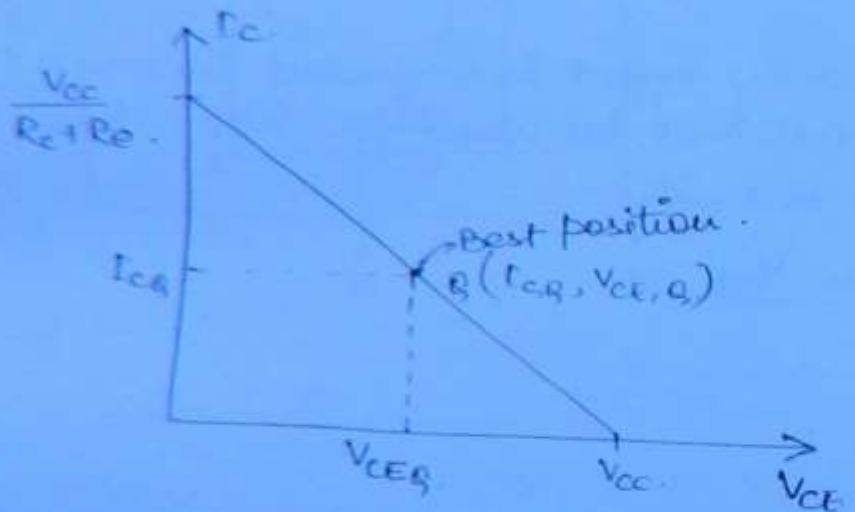
If $V_A = 0$,

$$I_c' = \infty$$

136

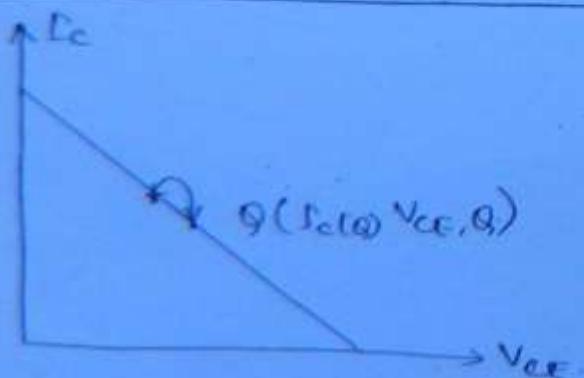
BJT biasing \rightarrow

Location of Q point on DC load line.



For amplifier analysis, we have to design the Q pt at the centre of dc load line.

Temp dependence on transistor parameters :-



$I_{CQ} \rightarrow I_{CO}, V_{BE}, \beta$

Temp. dependence,

$$\text{if } V_A = \infty$$

$$I_{C'} = I_C$$

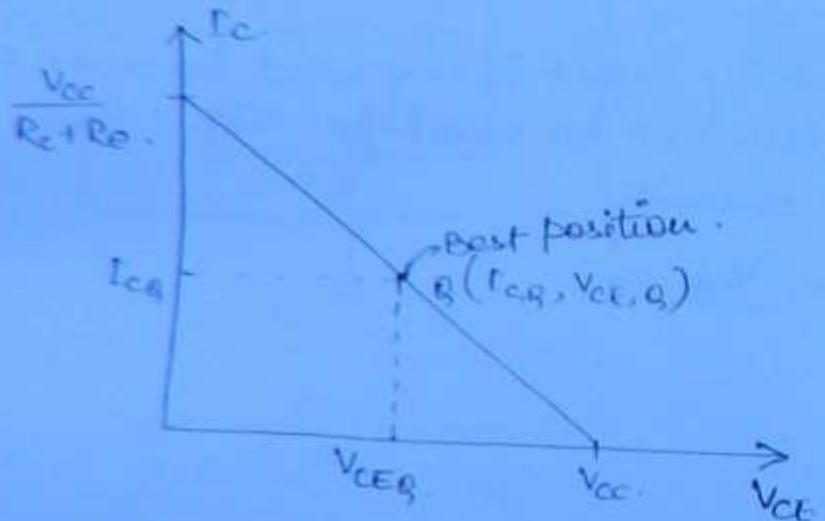
if $V_A = 0$,

$$I_{C'} = \infty$$

(136)

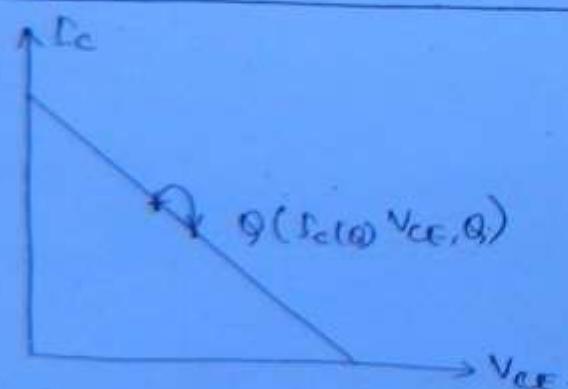
BJT biasing \rightarrow

Location of Q point on DC load line.



For amplifier analysis, we have to design the Q pt at the centre of dc load line.

Temp dependence on transistor parameters :-



$I_{CQ} \rightarrow I_{C0}, V_{BE}, \beta$

Temp. dependence,

I_{CO} v/s temp -

I_{CO} increases by 7% for every $^{\circ}\text{C}$ rise in temp or doubles for every 10°C rise in temp.

$T \uparrow, I_{CO} \uparrow$

(137)

As temp inc, I_{CO} will increase.

V_{BE} v/s temp -

$$\frac{dV_{BE}}{dT} = -2.5 \text{ mV}/^{\circ}\text{C}$$

$T \uparrow, V_{BE} \downarrow$

β v/s temp \rightarrow

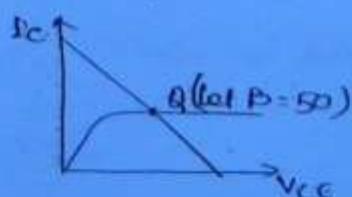
Case 1 \rightarrow

$$\beta = \frac{I_C}{I_B}$$

$T \uparrow, I_{CO} \uparrow, I_C \uparrow, \uparrow\beta = \frac{I_C}{I_B}$

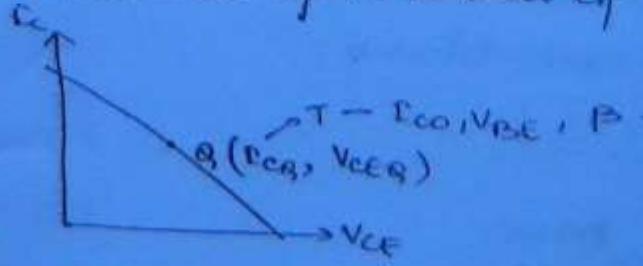
Case 2 \rightarrow

Transistor replacement problem.



Stability factor \rightarrow "S"

It is a measure of variation of operating pt w.r.t. temp



$$S_1 = \frac{\partial I_C}{\partial T_{CO}} \quad \text{keeping } B, V_{BE} \rightarrow \text{const}$$

$$S_2' = \frac{\partial I_C}{\partial V_{BE}} \quad T_{CO} \rightarrow \text{const} \quad (138)$$

$$S_2'' = \frac{\partial I_C}{\partial B} \quad T_{CO}, V_{BE} \rightarrow \text{const}$$

Stability factor must be less.

NOTE:

The most dominant parameter w.r.t temp is I_{CO} .

Ideally the Stability factor should be 0.

Practically the Stability factor should be min in Value
Expression for stability factor :—

$$I_C = \beta I_B + (1+\beta) I_{CO}$$

diff w.r.t I_C ,

$$1 \pm \beta \frac{\partial I_B}{\partial I_C} + (1+\beta) \left(\frac{\partial I_{CO}}{\partial I_C} \right)$$

$$S = \frac{1+\beta}{1 - \beta \frac{\partial I_B}{\partial I_C}}$$

Biasing techniques →

Biasing →

1) Stabilization techniques

→ Fixed bias

→ Collector to base bias

→ Voltage divider bias
or

Self bias

or

Emitter base

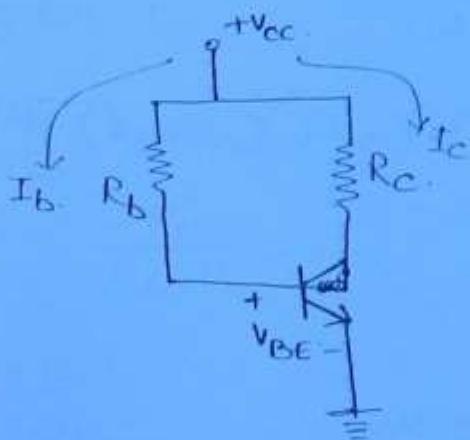
or
Universal bias

2) Compensation Techniques →

- Through diode
- Through Thermistor
- Through Transistor.

(139)

Fixed Bias :-



I/P loop →

$$V_{CC} = I_b R_b + V_{BE}$$

$$I_b = \frac{V_{CC} - V_{BE}}{R_b}$$

$$V_{CC} \gg V_{BE}$$

$$I_b = \frac{V_{CC}}{R_b}$$

$$I_c = \beta I_b \xrightarrow{\text{fixed}} \text{depend on } T \text{ & } \beta \text{ replacement}$$

$$S = \frac{1 + \beta}{1 - \beta \frac{\partial I_b}{\partial I_c}}$$

$$\boxed{S = 1 + \beta}$$

$$I_b \approx \frac{V_{CC}}{R_b}$$

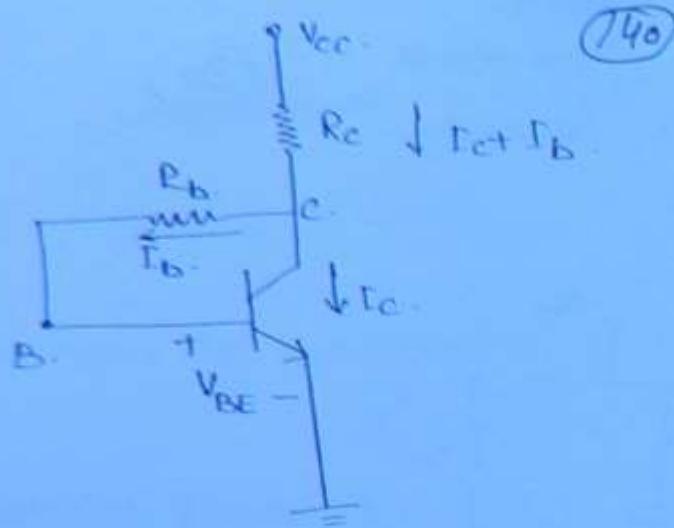
Assume $\beta = 100$

diff. w.r.t I_c

$$\frac{dI_b}{dI_c} = 0$$

$\boxed{S = 101} \rightarrow$ so high so not preferred fixed biasing

Collector to base open :-



(740)

IIP loop →

$$V_{CC} = (I_C + I_B) R_C + I_B R_B + V_{BE}$$

$$V_{CC} = I_B (R_B + R_C) + I_C R_C + V_{BE}$$

$$I_B = \frac{V_{CC} - I_C R_C - V_{BE}}{R_B + R_C}$$

O/P loop →

$$V_{CC} = (I_C + I_B) R_C + V_{CE}$$

$$V_{CC} - I_C R_C = I_B R_C + V_{CE}$$

$$\therefore I_B = \frac{V_{CE} + I_B R_C - V_{BE}}{R_B + R_C}$$

Analysis →

• T↑, I_{C0}↑, I_C↑

• (I_c+I_b)R_c↑, V_{ce}↓, I_b↓, I_c↓

$\downarrow I_C = \beta I_B$

stability factor is common in case necessary.

$$S = \frac{1+\beta}{1-\beta \frac{\partial I_b}{\partial I_c}}$$

(141)

$$V_{OC} = I_b(R_b + R_c) + I_c R_c + V_{BE}$$

diff. w.r.t. I_c .

$$0 = \frac{\partial I_b}{\partial I_c} (R_b + R_c) + R_c + 0$$

$$\frac{\partial I_b}{\partial I_c} = \frac{-R_c}{R_b + R_c}$$

$$S = \frac{1+\beta}{1+\beta \frac{R_c}{R_b + R_c}}$$

$$\Rightarrow S = \frac{1+\beta}{1+\beta \frac{R_b}{R_c + 1}}$$

when $\frac{R_b}{R_c} \ll 1$. $R_c \gg R_b$

$$S = \frac{1+\beta}{1+\beta}$$

S = 1

Conclusion -

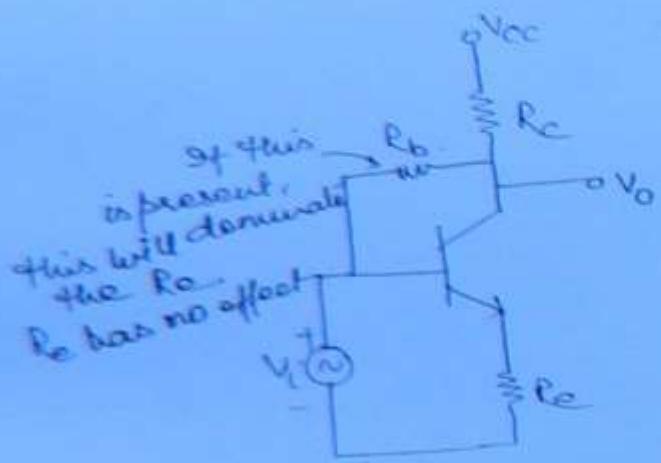
- 1) If $\frac{R_b}{R_c} \ll 1$, the stability factor approaches to unity.
- 2) If R_b is less, base current drawn from the battery will be more that too means it reduces the battery life time.
- 3) If R_c is more, power dissipation losses increases and it may disturb the Q pt also.

Voltage divider bias :-

(142)

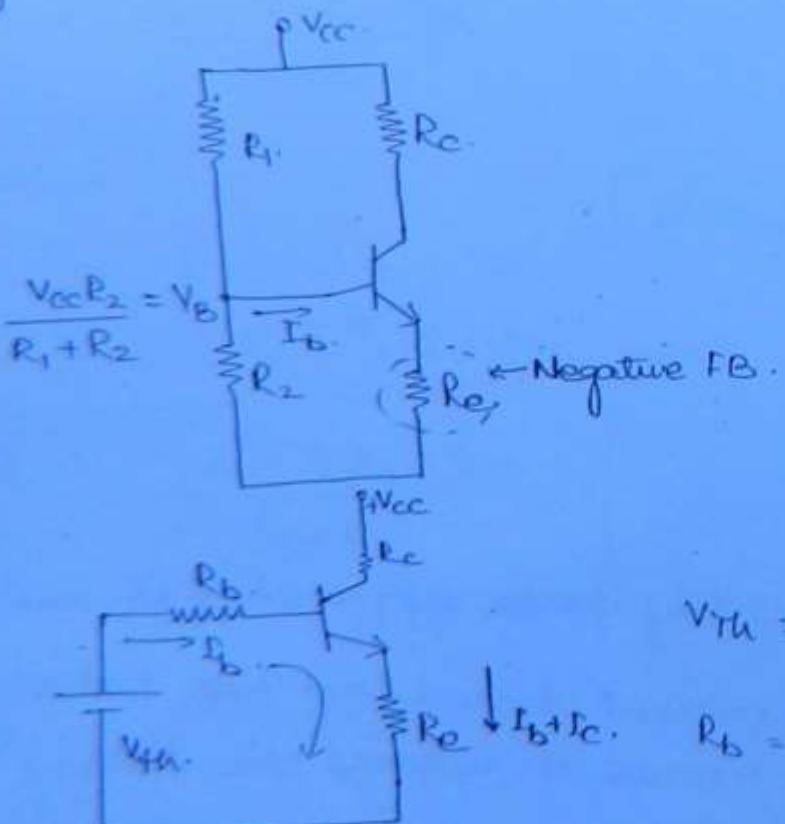
Feedback

- +ve feedback $A_v \uparrow, S \downarrow \rightarrow$ oscillator
- -ve feedback $A_v \downarrow, S \uparrow \rightarrow$ Amplifier



* If we have two feedbacks in the OCL, we take the feedback which is nearest to the V_{cc} .

Voltage divided bias ckt :-



$$V_{fb} = \frac{V_{cc} \times R_2}{R_1 + R_2}$$

$$R_b = R_1 \parallel R_2$$

I/P toop :-

$$V_{TH} = I_b R_b + V_{BE} + I_b I_c (R_b + R_e) \quad (143)$$

$$V_{TH} = I_b (R_b + R_e) + V_{BE} + I_c R_e.$$

diff w.r.t. I_c .

$$0 = \frac{\partial I_b}{\partial I_c} (R_b + R_e) + R_e.$$

$$\Rightarrow \frac{\partial I_b}{\partial I_c} = -\frac{R_e}{R_b + R_e}$$

$$S = \frac{1 + \beta}{1 + \beta \frac{R_e}{R_b + R_e}}$$

$$= \frac{1 + \beta}{1 + \beta \frac{1}{R_b/R_e + 1}}$$

$$\text{if } \frac{R_b}{R_e} \ll 1$$

$$S = \frac{1 + \beta}{1 + \beta}$$

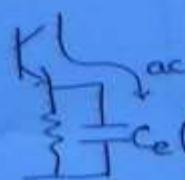
$$S = 1$$

Conclusions -

1) If $\frac{R_b}{R_e} \ll 1$, stability factor reaches to unity

2) R_b value should be less that means R_1 and R_2 resistors should be less. If R_1 is less, it reduces the battery life time. So, take $R_1 > R_2$ in the design.

3)

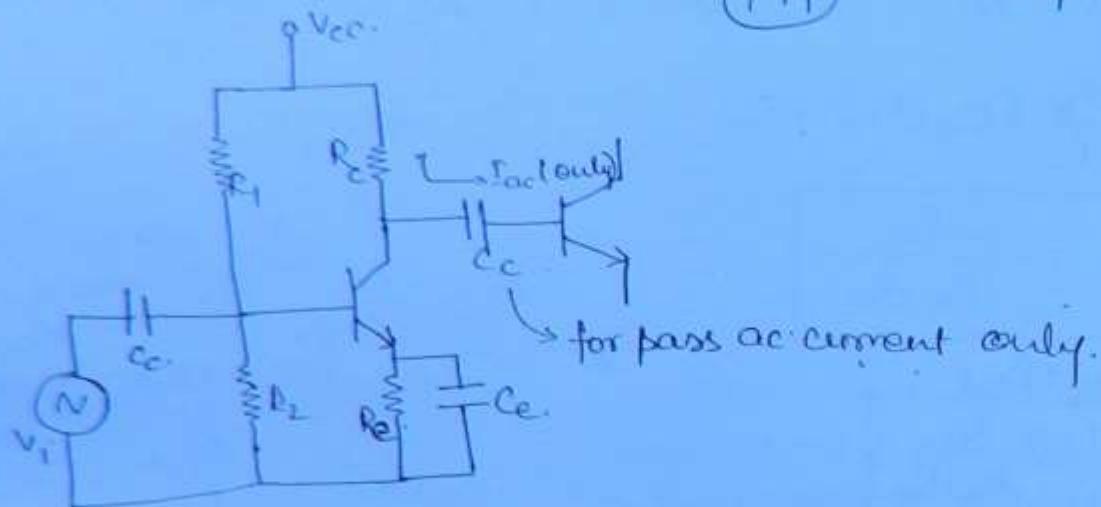


C_L (by pass capacitor)
to make the gain stable

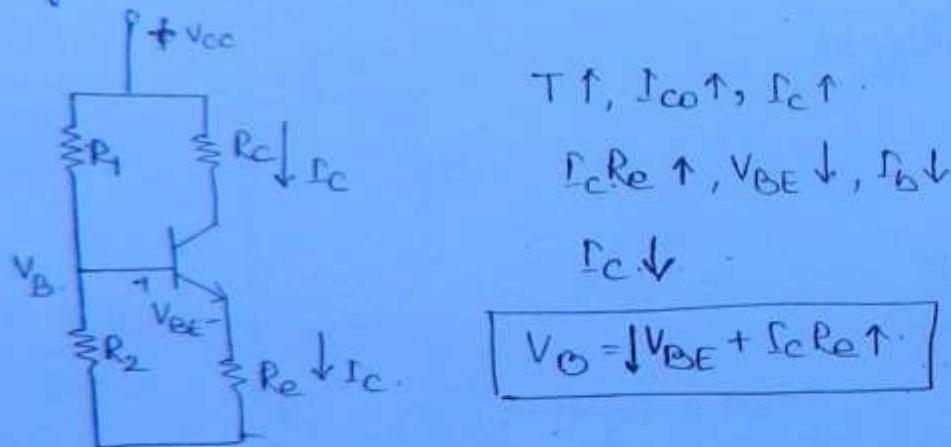
If R_E is more, it is increasing the junction reverse of the CTR that means the gain be affected. This problem can be solved by keeping a shunt capacitor C_E to resistor R_E . Hops

(by pass capacitor)

144

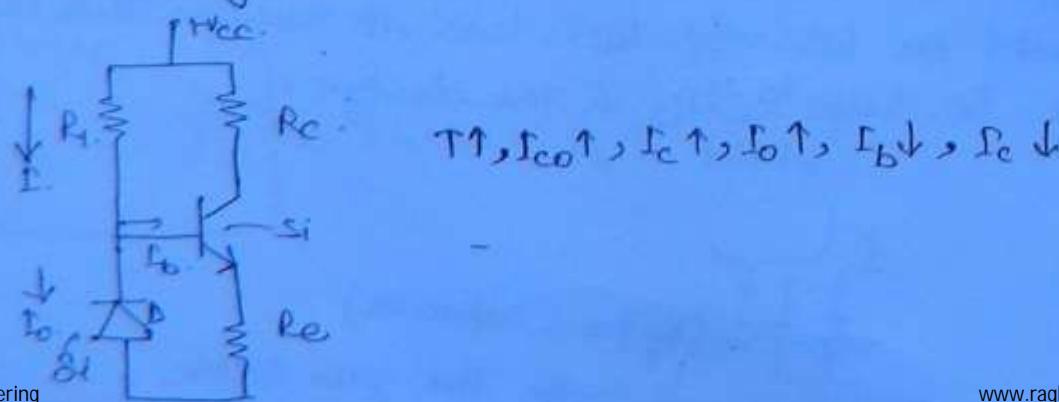


Analysis →



compensation techniques →

compensation through diode →



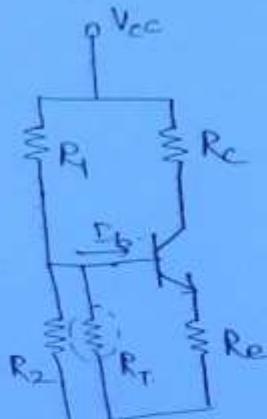
Compensation through Transistor

Thermistor →

(T45)

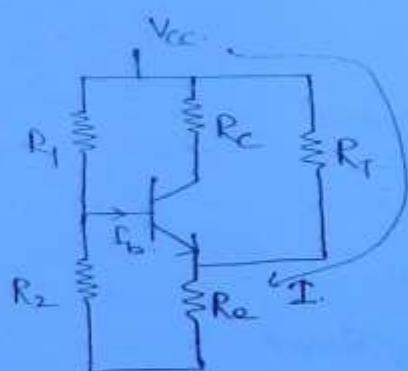


R_T $T \uparrow, R_T \downarrow$, -ve temp coeff.



$T \uparrow, I_{CO} \uparrow, I_c \uparrow, R_T \downarrow, R_2 \parallel R_T \downarrow$

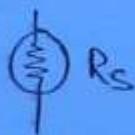
$V_{BE} \downarrow, I_b \downarrow, (I_c \downarrow)$



$T \uparrow, I_{CO} \uparrow, I_c \uparrow, R_T \downarrow, I_c \uparrow, I_c R_e \uparrow,$

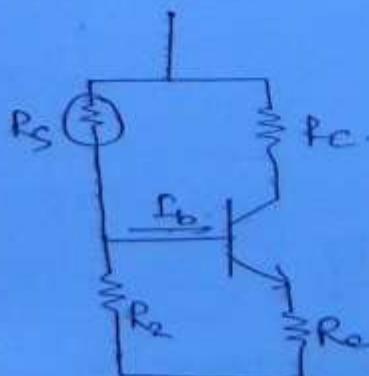
$V_{CE} \downarrow, I_b \downarrow, I_c \downarrow$

Compensation through Transistor →



R_s

$T \uparrow, R_s \uparrow$



$\nabla T \uparrow, I_{CO} \uparrow, I_c \uparrow,$

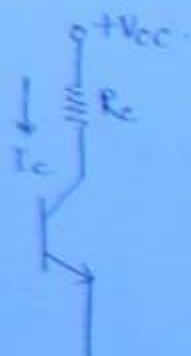
$R_s \uparrow, I_b \downarrow, I_b \downarrow, (I_c \downarrow)$

10/12

Thermal runaway :-

$$T_J \uparrow, I_{CO} \uparrow, I_C \uparrow, P_D = I_C^2 R_C,$$

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Thermal resistance (θ)

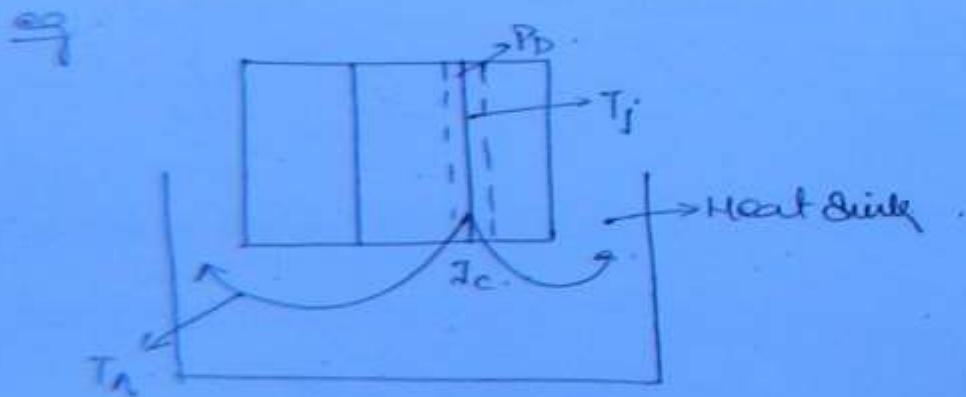
$$T_J - T_A \propto P_D$$

$= \theta P_D$ $\theta \rightarrow$ Thermal resistance

$T_J \rightarrow j^2$ temp

$T_A \rightarrow$ Ambient Temp

$P_D \rightarrow$ power dissipation



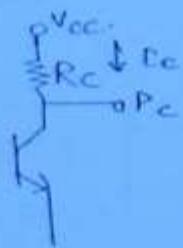
$$\theta = \frac{T_J - T_A}{P_D} \quad ^{\circ}\text{C/MW}$$

Condition for Thermal stability

$$\frac{\partial P_C}{\partial T_J} < \frac{\partial P_D}{\partial T_J} \rightarrow \text{Safe Operation}$$

The rate of heat generated at the collector junction should not exceed the heat dissipated at the collector junction.

(147)



$\partial P_c = \text{Power dissipated generated at } C-j^{\circ}$

$$T_j - T_A = \theta P_D$$

diff w.r.t T_j

$$I = \frac{\partial P_D}{\partial T_j}$$

$$\frac{\partial P_D}{\partial T_j} = \frac{1}{\theta}$$

$$\left(\frac{\partial P_c}{\partial T_j} < \frac{1}{\theta} \right)$$

$$P_c =$$

$$\frac{\partial P_c}{\partial T_j} = \frac{\partial P_c}{\partial I_c} \frac{\partial I_c}{\partial T_j}$$

$$P_c = V_{cc} I_c - I_c^2 R_c$$

diff. w.r.t I_c ,

$$\frac{\partial P_c}{\partial I_c} = V_{cc} - 2 I_c R_c$$

$$\frac{\partial I_c}{\partial T_j} = \frac{\partial I_c}{\partial I_{co}} \frac{\partial I_{co}}{\partial T_j}$$

$$= 5 \times 0.07 I_{co}$$

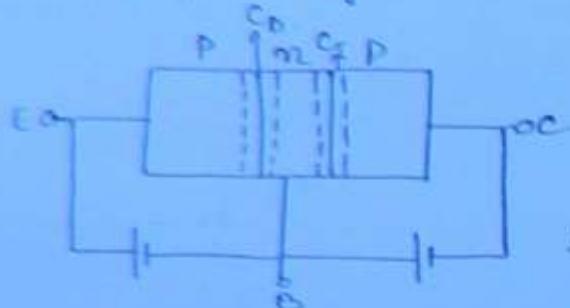
$$\left[(V_{cc} - 2 I_c R_c) 5 \times 0.07 I_{co} < \frac{1}{\theta} \right]$$

Small Signal Analysis :-

BJT :-

- low freq. Analysis.

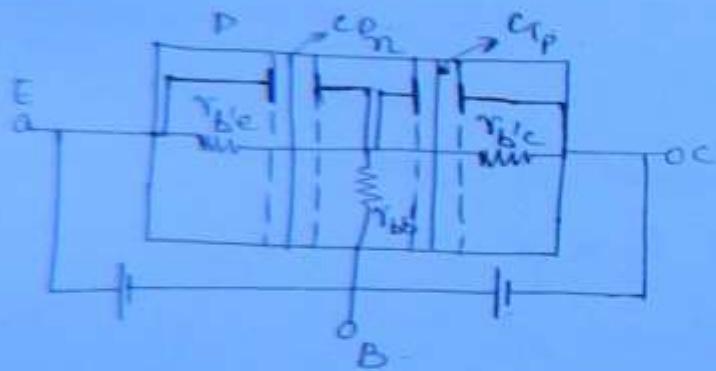
(148)



$$X_C \ll 1 \quad f \rightarrow 0$$

Internal Capacitance should be open in low freq.

- High freq. Analysis.



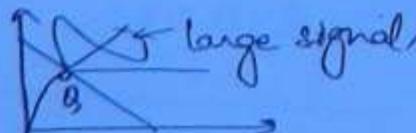
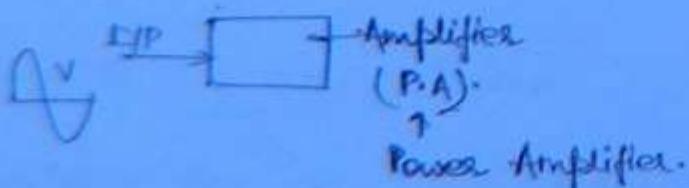
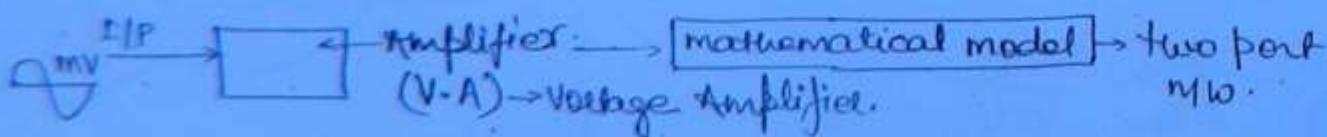
$$X_C \ll 1 \quad f \rightarrow \infty$$

∴ Internal capacitance are taken into account

We can not short ckt the capacitance as if it happens all resistance will be gone and no action as BJT.

Q. what is the diff. b/w small signal and large signal in amplifiers?

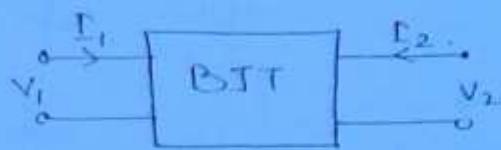
Ans:-



Low freq. Analysis →

Two port n/w →

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$$V_1 = h_{11}I_1 + h_{12}V_2$$

$$I_2 = h_{21}I_1 + h_{22}V_2$$

Case 1. →

$$V_2 = 0$$

$$h_{11} = \frac{V_1}{I_1} \rightarrow \text{I/P impedance}$$

$$h_{21} = \frac{I_2}{I_1} \rightarrow \text{forward current gain}$$

Case 2. →

$$I_1 = 0$$

$$h_{12} = \frac{V_1}{V_2} \rightarrow \text{Reverse Voltage gain}$$

$$h_{22} = \frac{I_2}{V_2} \rightarrow \text{O/P admittance}$$

$$V_1 = h_i I_1 + h_r V_2$$

$$I_2 = h_f I_1 + h_o V_2$$

For amplifier analysis, we require general char. like

1) Input Impedance Z_i

2) O/P Impedance Z_o

3) Voltage gain A_v

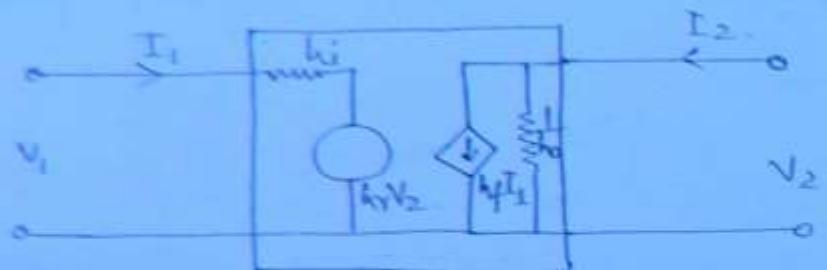
4) Current gain A_I

All these char. are efficiently explained by h-parameter model.

h-parameter model →

low freq. analysis

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CE	CB	CC
h_{ie}	h_{ib}	h_{ic}
h_{fe}	h_{fb}	h_{fc}
h_{re}	h_{rb}	h_{rc}
h_{oe}	h_{ob}	h_{oc}

Typical Values of h-parameters :→

Parameter	CE	CC	CB
h_{ie}	1100Ω	1100Ω	22Ω
h_{fe}	50	$-51 \frac{I_E}{I_B}$	$-0.98 \frac{I_E}{I_E}$
h_{re}	2.4×10^{-4}	≈ 1	2.9×10^{-4}
h_{oe}	$24 \times 10^{-6} A/V$	$25 \times 10^{-6} A/V$	$0.48 \times 10^{-6} A/V$

Conversion Techniques →

CE to CB

$$h_{ib} = \frac{h_{ie}}{1 + h_{fe}}$$

$$h_{fb} = \frac{-h_{fe}}{1 + h_{fe}}$$

$$h_{ob} = \frac{h_{oe}}{1 + h_{fe}}$$

$$h_{rb} = \frac{h_{ie}h_{oe}}{1 + h_{fe}} - h_{re}$$

CE to CE →

$$h_{ie} = \frac{h_{ib}}{1+h_{fb}}$$

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$$h_{fe} = \frac{-h_{fb}}{1+h_{fb}}$$

$$h_{re} = \frac{h_{ib}h_{fb}}{1+h_{fb}} - h_{rb}$$

$$h_{oe} = \frac{h_{rb}}{1+h_{fb}}$$

CE to CC →

$$h_{ic} = h_{re}$$

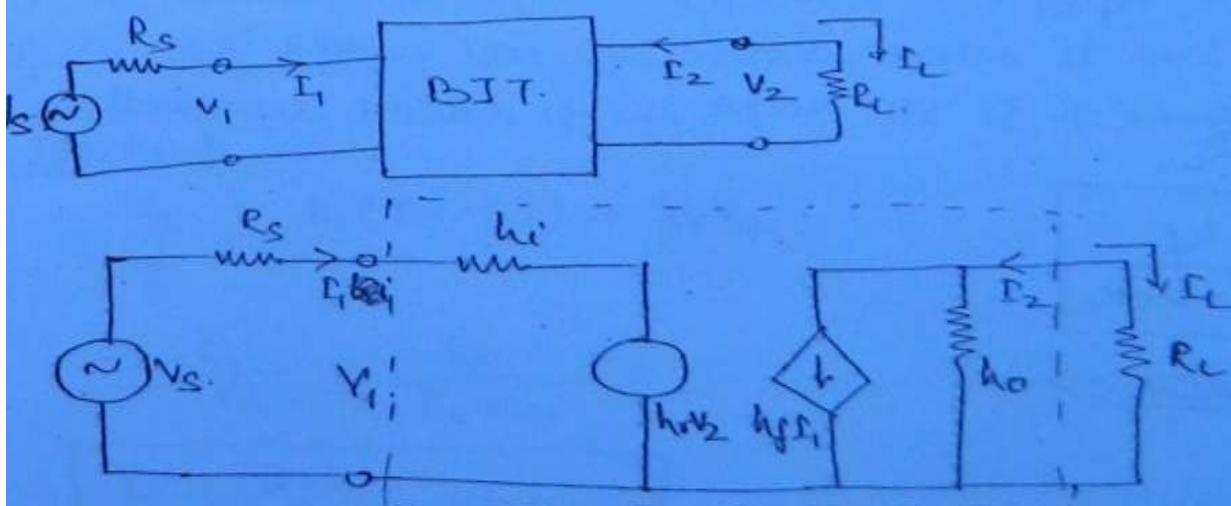
$$h_{fc} = -(1+h_{fe})$$

$$h_{rc} = 1$$

$$h_{oc} = h_{oe}$$

Transistor Amplifier Analysis :→

[using exact model]



Characteristics of amplifier →

- 1) current gain A_I
- 2) I/P Impedance $A Z_i$
- 3) Voltage gain A_v
- 4) O/P Impedance Z_o
- 5) Voltage amplification A_{vS}
- 6) Current Amplification A_{IS}
- 7) effective I/P Impedance Z'_i
- 8) effective O/P Impedance Z'_o

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Current gain →

$$V_1 = h_i I_1 + h_r V_2$$

$$I_2 = h_f I_1 + h_o V_2$$

$$A_I = \frac{I_2}{I_1} = -\frac{I_2}{I_1}$$

$$I_2 = h_f I_1 + h_o V_2 \quad V_2 = I_L R_L$$

$$I_2 = h_f I_1 + h_o (-I_2 R_L) \quad = -I_2 R_L$$

$$\Rightarrow I_2 (1 + h_o R_L) = h_f I_1$$

$$\Rightarrow \frac{I_2}{I_1} = \frac{h_f}{1 + h_o R_L}$$

$$A_I = -\frac{I_2}{I_1} = -\frac{h_f}{1 + h_o R_L}$$

Input Impedance →

$$Z_i = \frac{V_1}{I_1}$$

$$V_1 = h_i I_1 + h_r V_2$$

$$\frac{V_1}{I_1} = h_i + h_r \frac{V_2}{I_1} = h_i + h_r \left(\frac{-I_2 R_L}{I_1} \right) = h_i + A_I h_r R_L$$

$$Z_i = h_i + h_{rA} A_I R_L$$

Voltage gain :-

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$$\begin{aligned} A_V &= \frac{V_2}{V_1} \\ &= -\frac{I_2 R_L}{I_1} \\ &= V_1 / Z_i \end{aligned}$$

$$A_V = \frac{A_I R_L}{Z_i}$$

Output Impedance →

$$Z_o = \frac{V_2}{I_2}$$

$$Y_o = \frac{I_2}{V_2}$$

$$\begin{aligned} &= h_f \left(\frac{I_1}{V_2} \right) + h_o \left(\frac{V_2}{V_2} \right) \\ &= h_f \left(\frac{I_1}{V_2} \right) + h_o \end{aligned}$$

- To cal. the O/P impedance, two conditions should be follow
- 1) R_L should be open. (R_L = ∞)
 - 2) If the O/P is voltage source, make it as short ckt
Otherwise make it as open ckt if it is a current source

O/P loop →

$$\begin{matrix} V_o \\ \downarrow 0 \end{matrix} = I_1 (R_s + h_i) + h_r V_2$$

$$\Rightarrow \frac{I_1}{V_2} = \frac{-h_r}{R_s + h_i}$$

$$Y_o = \frac{-h_f h_r}{R_s + h_i} + h_o$$

$$Z_o = \frac{1}{Y_o}$$

Voltage Amplification →

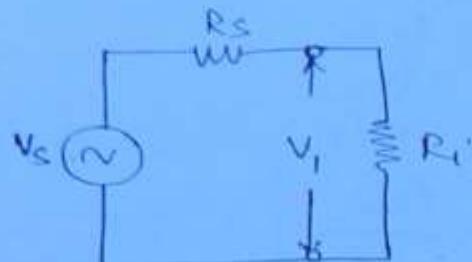
$$A_{VS} = \frac{V_2}{V_S}$$

(TS4)

$$= \frac{V_2}{V_1} \times \frac{V_1}{V_S}$$

$$= A_V \left(\frac{V_1}{V_S} \right)$$

$$\boxed{A_{VS} = A_V \cdot \frac{R_i}{R_i + R_S}}$$



When $R_S = 0$ [Ideality]

$$\boxed{A_{VS} = A_V}$$

$$V_I = \frac{R_i}{R_i + R_S} V_S$$

$$\frac{V_I}{V_S} = \frac{R_i}{R_i + R_S}$$

Current Amplification →

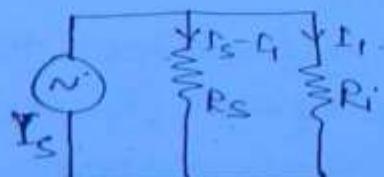
$$A_{IS} = \frac{I_L}{I_S} = \frac{I_L}{I_I} \times \frac{I_I}{I_S}$$

$$= A_I \frac{I_I}{I_S}$$

$$= A_I \frac{R_S}{R_i + R_S}$$

When $R_i = 0$,

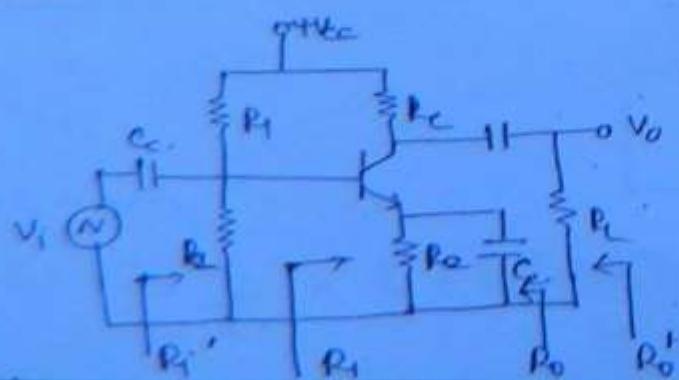
$$\boxed{A_{IS} = A_I}$$



$$(I_S - I_i)R_S = I_i R_i$$

$$\frac{I_I}{I_S} = \frac{R_S}{R_i + R_S}$$

Effective I/P and O/P Imp. →



$$R_i = h_{ie}$$

$$R'_i = R_1 \parallel R_2 \parallel h_{ie}$$

$$R_o = \frac{1}{h_{oe}}$$

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$$R'_o = \frac{1}{h_{oe}} \parallel R_C \parallel R_L$$

Conclusion →

Exact analysis is valid for all the 3 types of configurations like common emitter, CB, CC.

For eg →

$$(A_I)_{CB} = \frac{-h_{fe}}{1 + h_{oe} R_L}$$

$$(A_I)_{CC} = \frac{-h_{fe}}{1 + h_{oe} R_L}$$

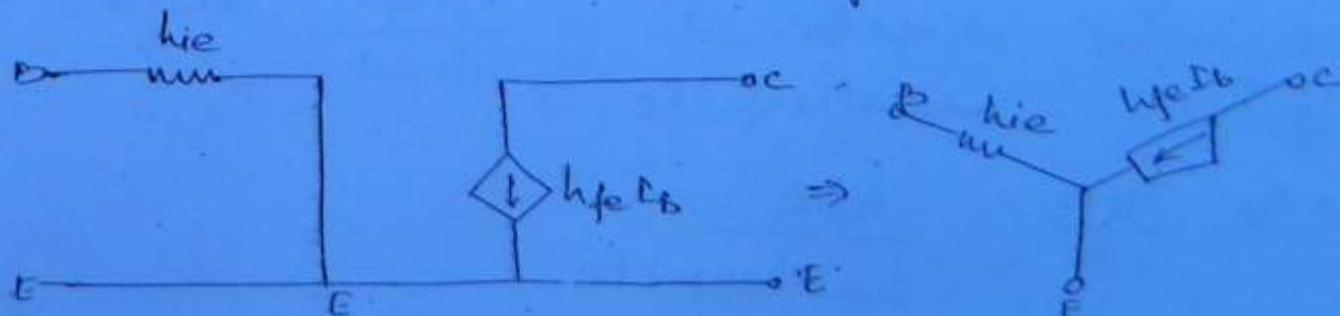
Approximate model Analysis :→

1) $h_{oe} R_L \leq 0.1$.

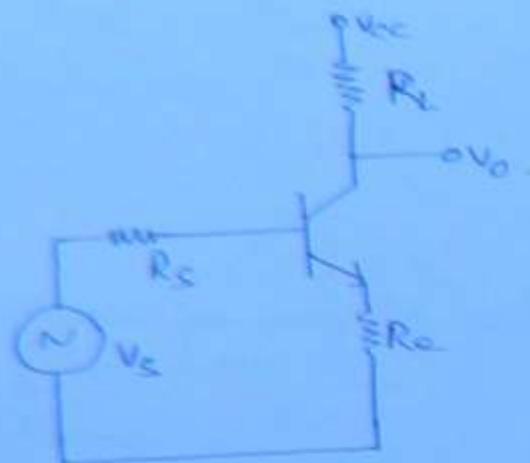
$$\text{eg. } A_I = \frac{-h_{fe}}{1 + h_{oe} R_L}$$
$$= \frac{-h_{fe}}{1 + 0.1}$$
$$= -0.91 h_{fe}$$

2) h_{re} and h_{oe} should be neglected

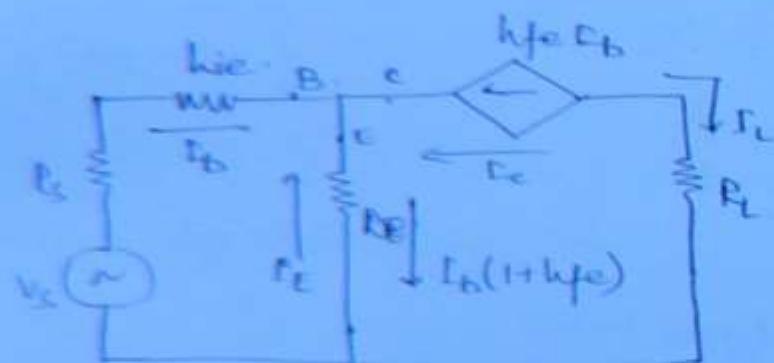
3) This is valid in CE mode only.



CE Unbypassed amplifier



(156)



$$\Rightarrow A_E = \frac{I_c}{I_b} = -\frac{h_{fe} I_b}{R_E}$$

$$= -h_{fe}$$

$$\text{or } \frac{-h_{fe}}{1+h_{fe}R_L} \text{ hce} \rightarrow \text{neglected}$$

$$= -h_{fe}$$

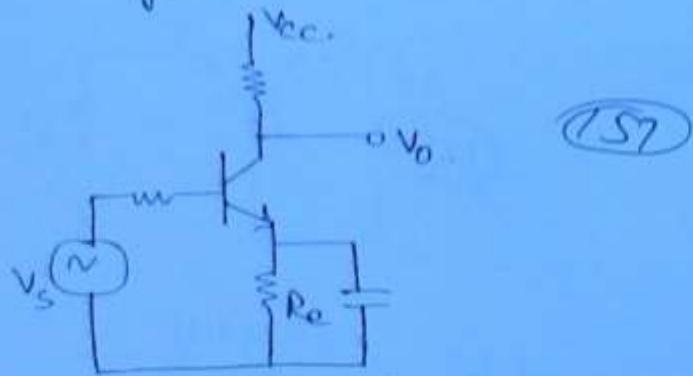
$$\Rightarrow R_E = \frac{V_s}{I_b} = \frac{h_{ie} I_b + (1+h_{fe}) I_b R_E}{I_b}$$

$$= h_{ie} R_E + (1+h_{fe}) R_E$$

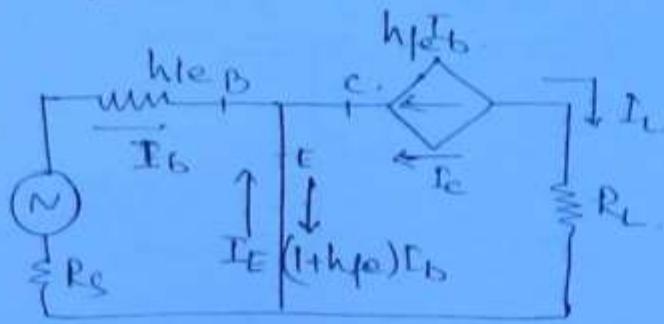
$$\Rightarrow A_V = \frac{A_E R_E}{R_E} = \frac{-h_{fe} R_E}{h_{ie} + (1+h_{fe}) R_E}$$

$$\Rightarrow R_O = \frac{V_2}{I_2} \rightarrow \infty$$

CE bypass \rightarrow



(157)



$$A_f = \frac{I_L}{I_B} = -h_{fe}$$

$$R_i = h_{ie}$$

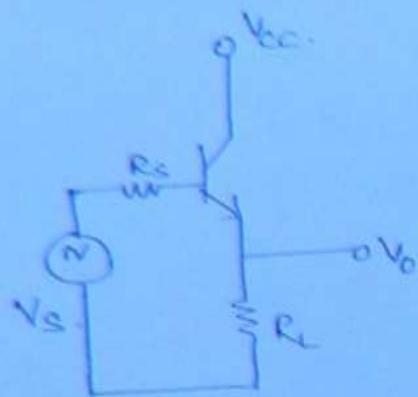
$$A_v = -\frac{h_{fe}R_L}{h_{ie}}$$

$$R_o = \frac{V_2}{I_C \rightarrow 0} \Rightarrow \infty$$

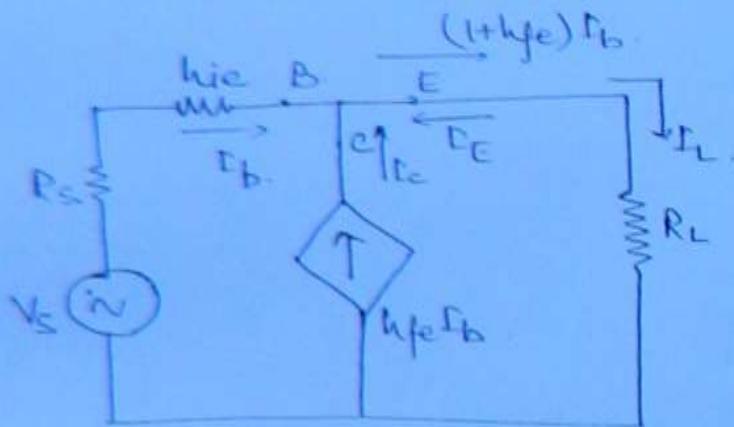
Table \rightarrow

	A_v	R_i	Feedback
CE bypass	$-h_{fe}R_L$	h_{ie}	No
CE unbypass	$\frac{-h_{fe}R_L}{h_{ie} + (1+h_{fe})R_L}$	$h_{ie} + (1+h_{fe})R_L$	Yes (negative)

CC →



(158)



$$A_I = \frac{I_L}{I_B} = \frac{(1+hfe) I_B}{I_B} = 1+hfe.$$

$$R_i = \frac{V_1}{I_B} = \frac{hie I_B + (1+hfe) I_B R_L}{I_B}$$

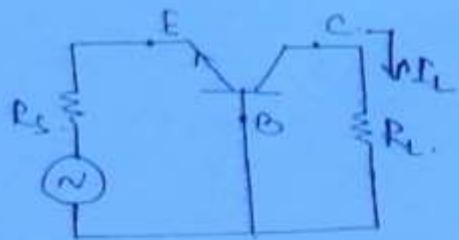
$$= hie + (1+hfe) R_L.$$

$$A_V = \frac{(1+hfe) I_c}{hie + (1+hfe) R_L}$$

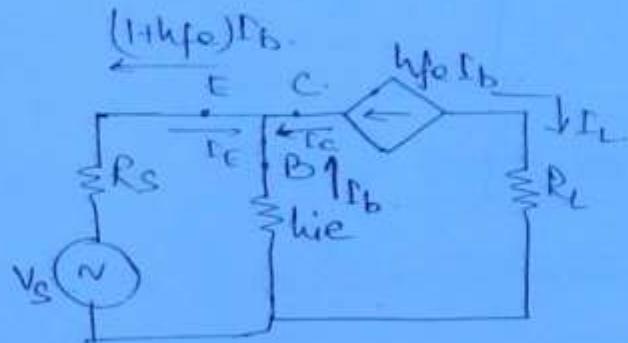
$$R_o = \frac{1}{h_{oc} - \frac{h_{re} hfe}{h_{ic} + R_S}} \Rightarrow ?$$

$$= \frac{hie + R_S}{1+hfe}$$

CB \rightarrow



(159)



$$A_f = \frac{I_L}{I_E} = \frac{-h_{fe} I_B}{(1+h_{fe}) I_B}$$

$$= \frac{h_{fe}}{1+h_{fe}}$$

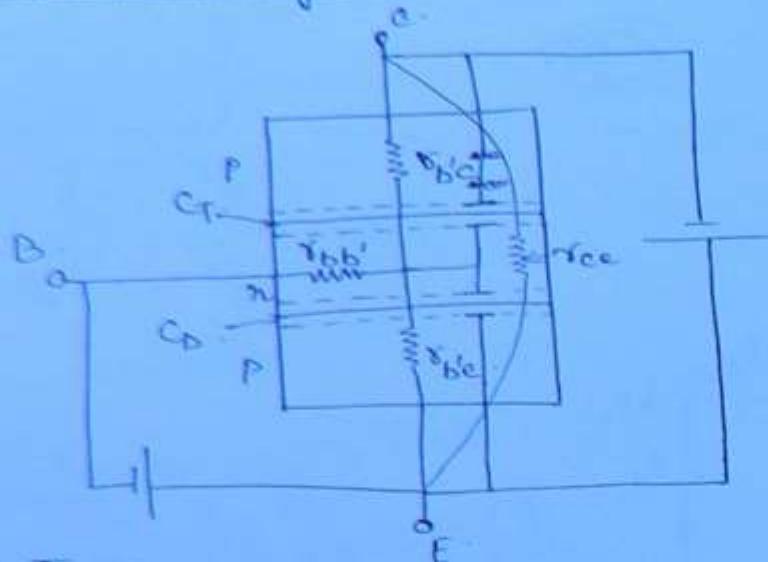
$$R_i = \frac{V_I}{I_E} = \frac{-h_{ie} I_B}{-(1+h_{fe}) I_B}$$

$$= \frac{h_{ie}}{1+h_{fe}}$$

$$A_v = \frac{h_{fe} R_L}{h_{ie}} \quad [\text{nominal sign because of same phase shift}]$$

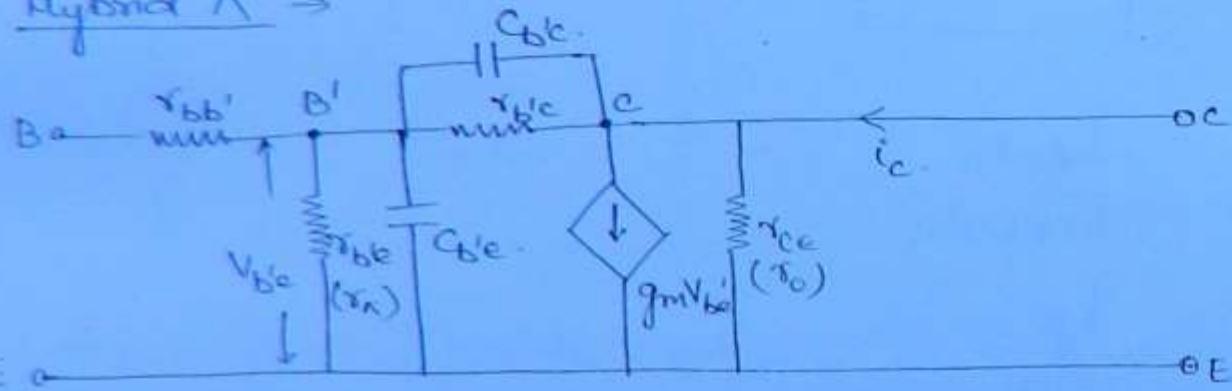
$$R_o = \frac{V_2}{I_C} \Rightarrow \infty$$

High freq. analysis of BJT :-



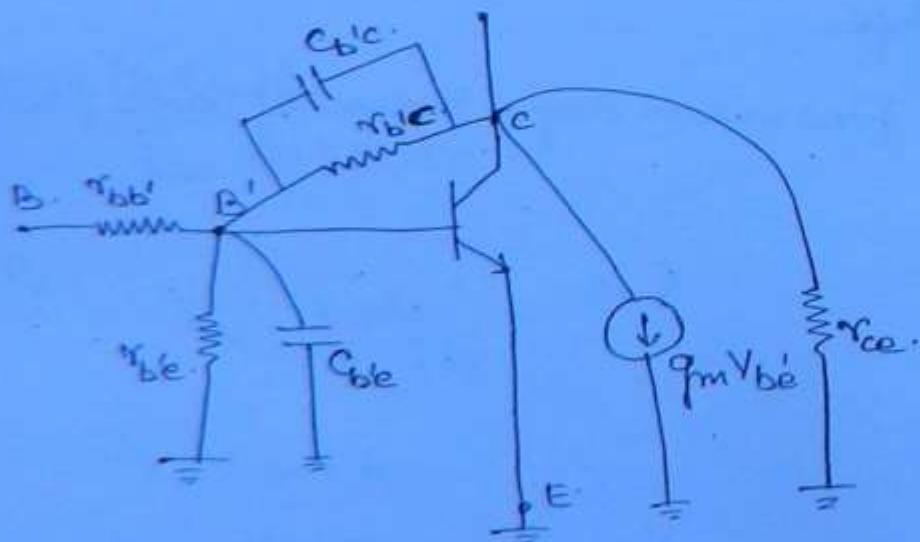
(160)

Hybrid π \rightarrow



$$gmV_{be} = \frac{i_c}{V_{be}} \times V_{be}$$

$$= i_c$$



$g_m \rightarrow$ transconductance = 50 mA/V

$r_{be} \rightarrow$ Input resistance = $1 \text{ k}\Omega$ (161)

$r_{bc} \rightarrow$ feedback resistance = $4 \text{ M}\Omega$

$r_{bb'} \rightarrow$ base spread resistance = $100 \text{ }\Omega$

$r_{ce} \rightarrow$ O/P resistance = $80 \text{ k}\Omega$

$C_{be} \rightarrow$ Diffusion Capacitance = 100 fF

$C_{bc} \rightarrow$ Transition Capacitance = 3 pF

Conclusion: →

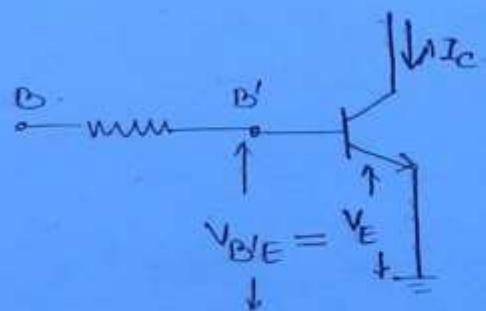
Hybrid π parameters are depending on 3 parameters

1) Collector current I_C

2) temp. T

3) Collector-to-Emitter Voltage V_{CE} .

Transconductance g_m : →



$$g_m = \frac{\partial I_C}{\partial V_{BE}}$$

$$\Gamma_C = \alpha \Gamma_E$$

$$\Delta \Gamma_C = \lambda \Delta \Gamma_E$$

$$g_m = \lambda \frac{\partial \Gamma_E}{\partial V_{BE}}$$

$$V_{BE} = V_E$$

$$= \frac{\lambda \Gamma_E}{\eta V_T}$$

$$= \left| \frac{\Gamma_C}{V_T} \right| \quad \eta = L \quad \Gamma_C \rightarrow \text{dc current}$$

$\Gamma_C \uparrow, g_m \uparrow$

$T \uparrow, g_m \uparrow$

$V_{BE}, g_m = \text{const}$

$$g = \frac{I + I_0}{\eta V_T}$$

A_B:

$$g = \frac{I}{\eta V_T}$$

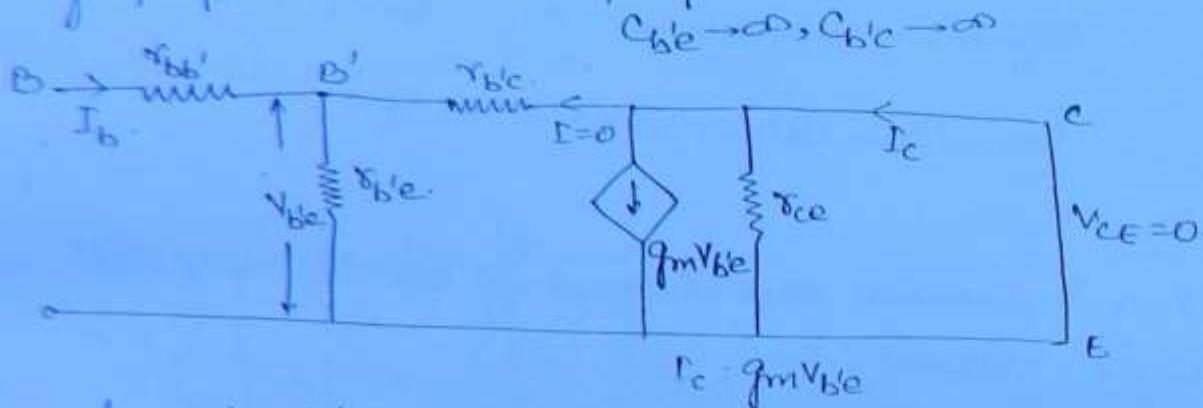
$$g = \frac{\partial \Gamma_E}{\partial V_E} = -\frac{\Gamma_E}{\eta V_T}$$

- Conclusion
- 1) As collector current I_c increases, transconductance g_m also increases.
 - 2) As T increases, transconductance $g_m \downarrow$. $\left[g_m = \frac{I_c}{T} \times 11600 \right]$

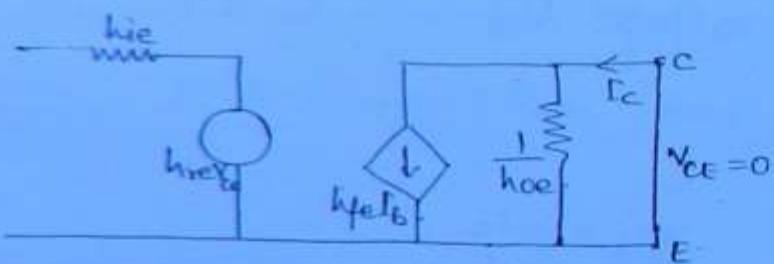
$r_{b'e}$ →

(162)

High freq. model to low freq.



low freq. model :-



$$I_c = h_f e I_b$$

$$\boxed{\frac{I_c}{I_b} = h_f e}$$

High to low →

$$I_c = g_m V_{be}$$

$$I_c = g_m I_b r_{be}$$

$$V_{be} = I_b r_{be}$$

$$\frac{I_c}{I_b} = g_m r_{be}$$

$$\Rightarrow h_f e = g_m r_{be}$$

$$\Rightarrow \boxed{r_{be} = \frac{h_f e}{g_m}}$$

Conclusion

- As I_C increases, $r_{b'e}$ value decreases
- As temp increases, $r_{b'e}$ value increases.

$r_{b'c} \rightarrow$

O/P parameter

$$I_B = 0$$

(163)

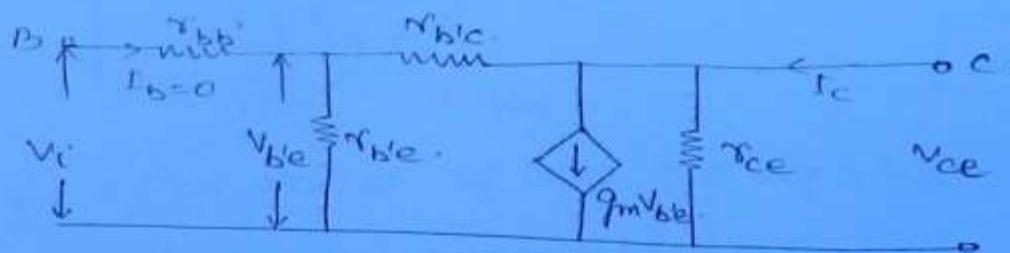
low freq model \rightarrow

$$V_i = h_{ie} I_B + h_{re} V_{ce}$$

$$I_B = 0,$$

$$V_i = h_{re} V_{ce}$$

high freq model



$$V_{b'e} = \frac{V_{ce} \times r_{b'e}}{r_{b'e} + r_{b'c}}$$

$$V_{b'e} = V_i = h_{re} V_{ce}$$

$$h_{re} V_{ce} = V_{ce} \frac{r_{b'e}}{r_{b'e} + r_{b'c}}$$

$$\Rightarrow h_{re} = \frac{r_{b'e}}{r_{b'c}}$$

$$\Rightarrow \boxed{r_{b'c} = \frac{r_{b'e}}{h_{re}}}$$

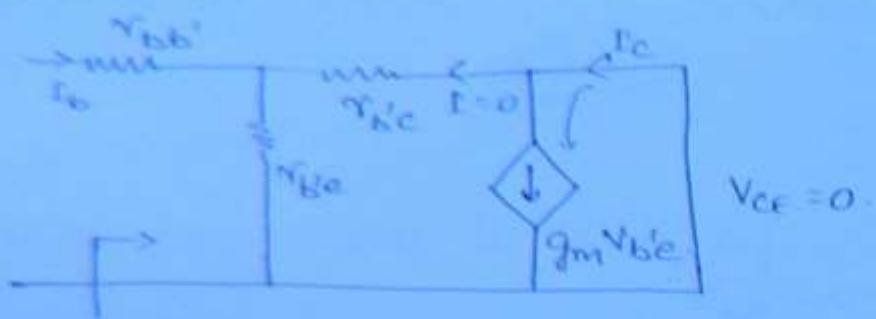
conclusions :

- 1) As I_C current \uparrow , $r_{b'c}$ decrease.
- 2) As temp increases, $r_{b'c}$ increases.

V_{bb'}

O/P parameter

$$V_{OE} = 0$$



$$Z_i = r_{bb'} + r_{bb}$$

low freq. model →

$$Z_i = h_{ie}$$

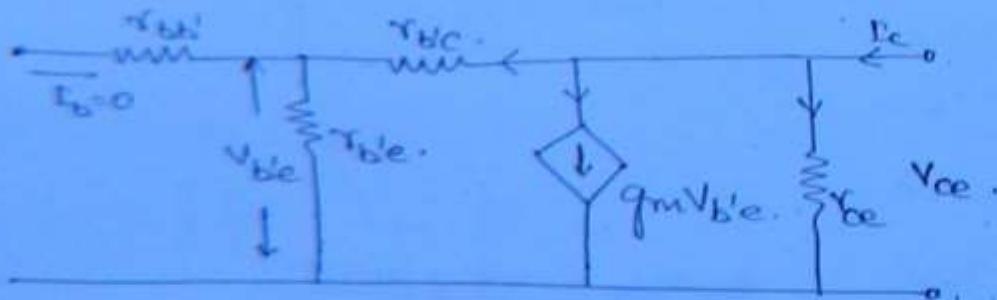
$$h_{ie} = r_{bb'} + r_{be}$$

$$\Rightarrow r_{bb'} = h_{ie} - r_{be}$$

V_{ce} : →

O/P parameter

$$I_b = 0$$



low freq. →

$$h_{oe} = \frac{r_c}{V_{ce}}$$

$$I_c = \frac{V_{ce}}{r_{ce}} + q_m V_{be} + \frac{V_{ce}}{r_{be} + r_{bc}}$$

$$= \frac{V_{ce}}{r_{ce}} + q_m \frac{V_{ce} r_{be}}{r_{be} + r_{bc}} + \frac{V_{ce}}{r_{be} + r_{bc}}$$

$$h_{oe} = \frac{V_C}{V_{ce}} + \frac{1}{r_{ce}} + \frac{h_{fe} + 1}{r_{be} + r_{be}}$$

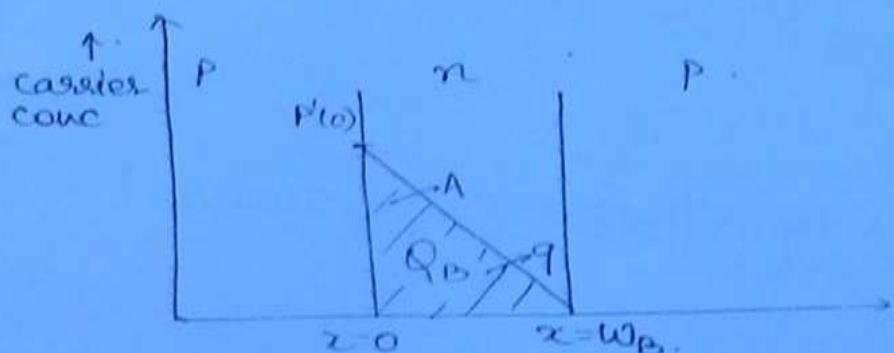
$$h_{oe} = g_{ce} + h_{fe} g_{bc}$$

(65)

$$\boxed{g_{ce} = h_{oe} - h_{fe} g_{bc}}$$

$$\boxed{V_{ce} = \frac{1}{g_{ce}}}$$

C_{be} →



$Q_B = \text{av. value of conc.} \times A \times q \times w_B$

$$= \frac{1}{2} P'(0) \times A \times q \times w_B$$

$$\Gamma = -Aq D_B \frac{dP(x)}{dx}$$

$$= -Aq D_B \frac{\{P'(0) - 0\}}{w_B}$$

$$\Gamma = Aq D_B \frac{P'(0)}{w_B}$$

$$Q_B = \frac{1}{2} D_B \Gamma w_B^2$$

$$C_{be} = \frac{dQ_B}{dV} = \frac{1}{2 D_B} w_B^2 \left(\frac{d\Gamma}{dV} \right) q_m$$

$$\boxed{C_{be} = \frac{1}{2 D_B} w_B^2 q_m}$$

$$\boxed{C_{be} = \frac{1}{2 D_B} w_B^2 \frac{1}{r_e}}$$

$$\boxed{r_e = \frac{1}{q_m} = \frac{V_T}{I_E}}$$

C_{BC} :-

transition capacitance.

$$C_T \propto \frac{1}{\sqrt{V_R}} \rightarrow \text{Alloy type}$$

$$C_T \propto \frac{1}{V_R} \rightarrow \text{grown j.}$$

$$V_R \rightarrow V_{CE}$$

$$C_{BC} \propto \frac{1}{(V_{CE})^n}$$

$n = \frac{1}{2} \rightarrow \text{Alloy}$

$= \frac{1}{3} \rightarrow \text{grown j.}$

(166)

Q1. As $V_{CE} \uparrow$, what happens to diffusion capacitance?

Ans. Early effect

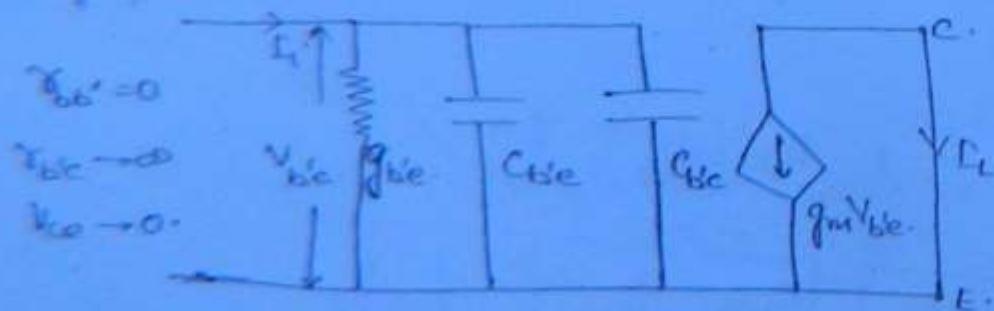
$V_{CE} \uparrow$; $W \downarrow$; $C_{DE} \downarrow$

$$C_{DE} = \frac{1}{2} W_0^2 q_m$$

Q2. In all the hybrid π parameter which parameter is independent of f_c and temp?

C_{BC} .

Short circuit current gain :-



$$- A_I = \frac{i_L}{I_i}$$

$$= \frac{-g_m V_{BE}}{V_{BE} (g_{BE} + j\omega(C_{BE} + C_{BC}))}$$

(T67)

$$= \frac{-g_m}{\frac{g_m}{h_{FE}} + j2\pi f}$$

$$= \frac{-g_m}{\frac{g_m}{h_{FE}} + j2\pi f \frac{g_m}{2\pi f T}}$$

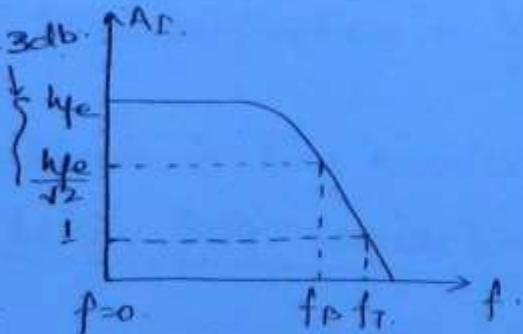
$$= \frac{-g_m}{\frac{g_m}{h_{FE}} \left[1 + j \left(\frac{f}{f_B} \right) \right]}$$

$$f_T = \frac{1}{2\pi RC} = \frac{1}{2\pi C_{BE}}$$

$$f_B = \frac{f_T}{h_{FE}}$$

$$A_I = \frac{-h_{FE}}{1 + j(f/f_B)}$$

freq. Response :-



$$A_I = \frac{-h_{FE}}{1 + j(f/f_B)}$$

$$|A_I| = \frac{h_{FE}}{\sqrt{1 + (f/f_B)^2}}$$

Beta cut off freq. :-

If f_B is the freq. at which C.E. short ckt current gain reduces by 3dB of its value.

Unity gain band width freq(f_T) :-

If f_T is the freq. at which CE short ckt current gain reduces to unity.

f_T

$$f_T = h_{FE} f_B$$

(T68)

X cut off freq: →

It is the freq. at which CB short ckt gain reduces by 3dB of its value.

$$f_C = (1 + \beta) f_B$$

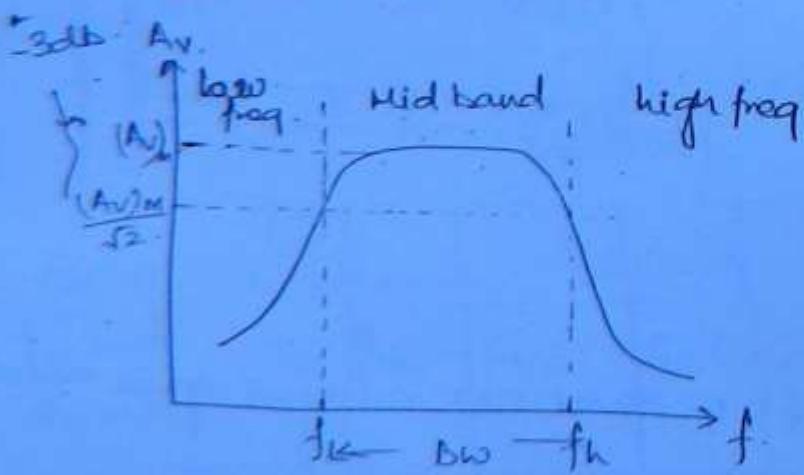
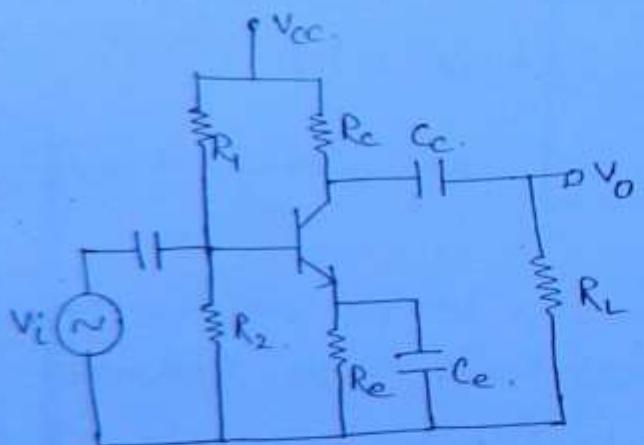
$$= \frac{1}{1 + \kappa} f_B$$

CB is used for high freq. than CE.
as bandwidth is higher.

Frequency response of an amplifier: —

BJT

CE amplifier —



Capacitance →

Internal Capacitance.

- C_D (Diffusion Capacitance)
- C_T (transition Capacitance)

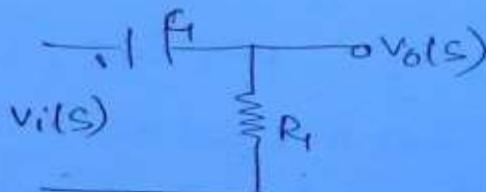
(169)

External capacitance

- C_e (coupling)
- C_o - (by pass)

Low freq. region →

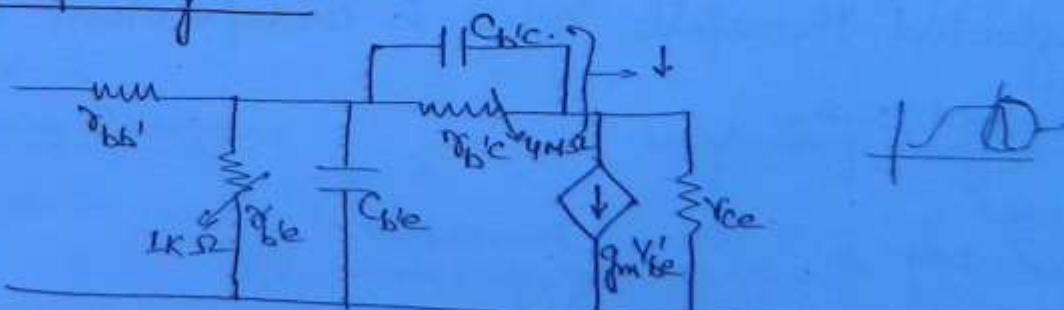
- At low freq. Analysis, internal capacitors are neglected which are parallel to the jy of transistors [open]
- If ext. capacitors are open, the signal will not pass into the transistors that means C_o and C_e are affecting sys. response.
- The system response is considered as high pass response.



$$\text{Transfer function} = \frac{V_0(s)}{V_i(s)} = \frac{s}{s + \frac{1}{R_1 C_1}}$$

There is one zero and one pole is considered.

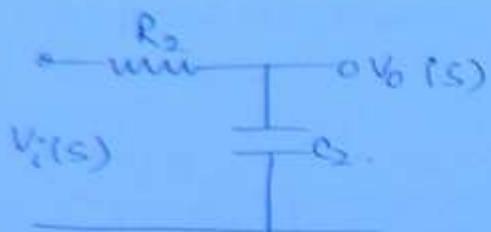
High freq. region: →



- At high freq. range, ext. capacitors are not affecting the system response because they are short ckt.
- When the int. capacitors are short ckt, it will affect

The 'b' & 'c' are 'bc' name.
 That means int. Capacitors # are affecting the sys. response.

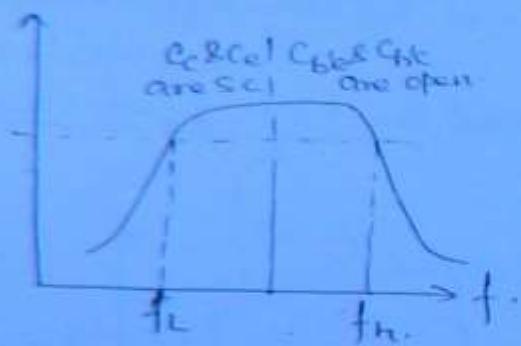
If The System response is considered as low pass response



(170)

$$T.F. = \frac{V_o(s)}{V_i(s)} = \frac{1}{s + \frac{1}{R_2 C_2}}$$

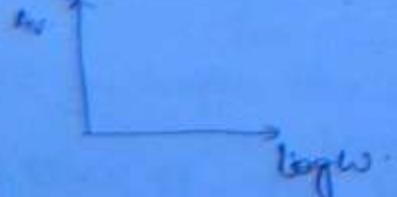
Mid band Range :-



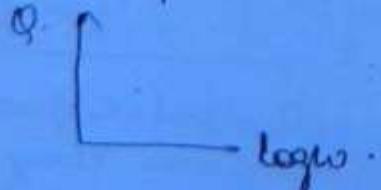
- At low frequencies, mid band Range freq. is considered as high freq, therefore ext. capacitors are neglected.
- At high freq. range mid band range freq. can be considered as low freq. Therefore int. capacitors are neglected.
- At the mid band range, all the internal and ext. capacitors are neglected. Therefore gain is independent of freq.

-3dB concept :-

Dode plot →
 magnitude plot.



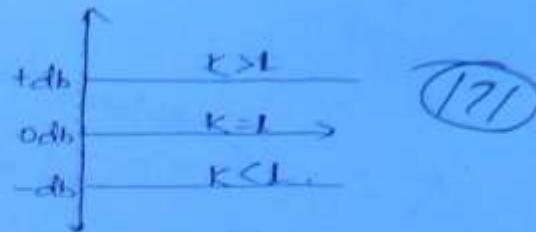
Phase Plot



$$T.F. = \frac{KS}{1+ST}$$

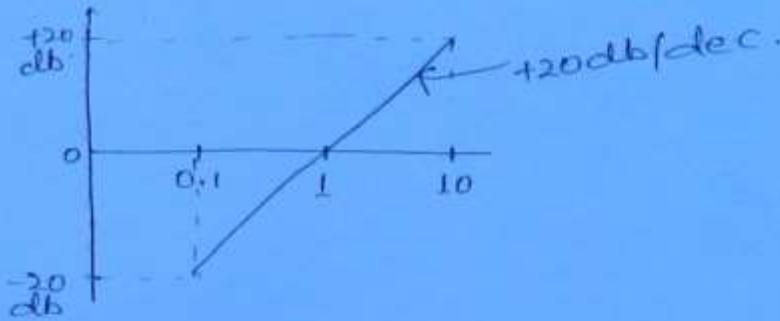
$$G(s) = K$$

$$|G(j\omega)|_{db} = 20 \log K$$



$$\Rightarrow G(s) = S$$

$$|G(j\omega)|_{db} = 20 \log \omega$$



$$\Rightarrow G(s) = \frac{1}{1+ST}$$

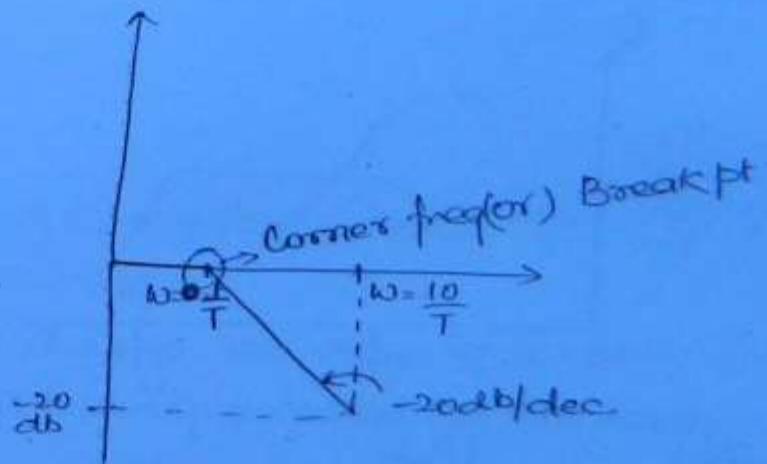
$$|G(j\omega)|_{db} = -20 \log \sqrt{1+\omega^2 T^2}$$

$\omega T \ll 1$, low freq.

$$|G(j\omega)| = -20 \log 1 = 0 \text{dB}$$

$\omega T \gg 1$, high freq.

$$|G(j\omega)| = -20 \log \omega T$$



Bode plot →

low freq Range →

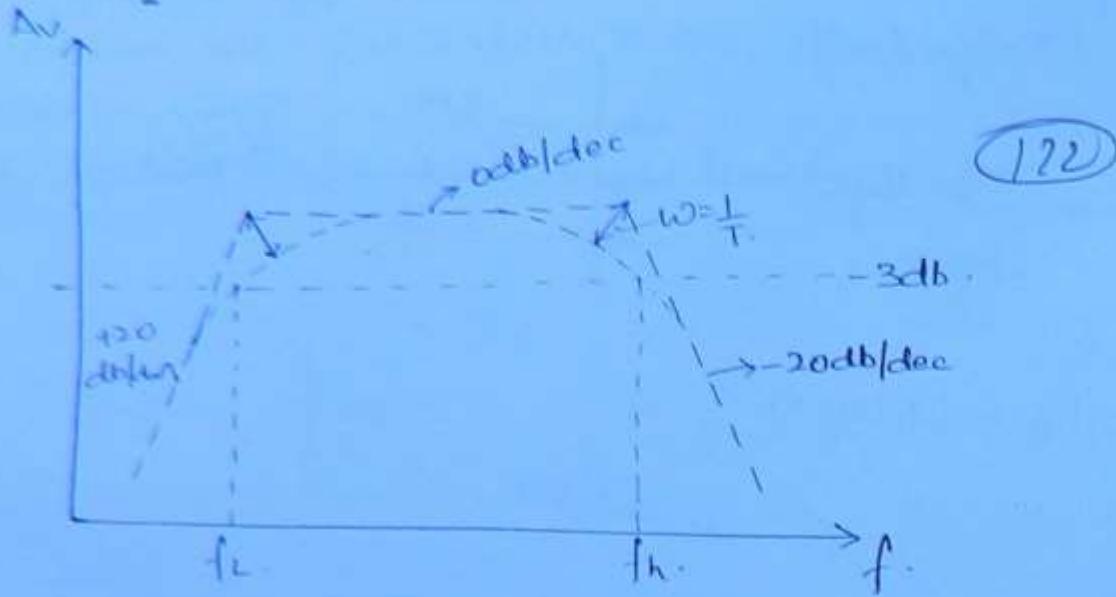
$$T.F. = \frac{s}{s + \frac{1}{R_1 C_1}} \rightarrow \text{one pole}$$

one pole → one pole

High freq. Range →

$$T.F. = \frac{1}{s + \frac{1}{R_2 C_2}} \rightarrow \text{one pole}$$

one pole → one pole



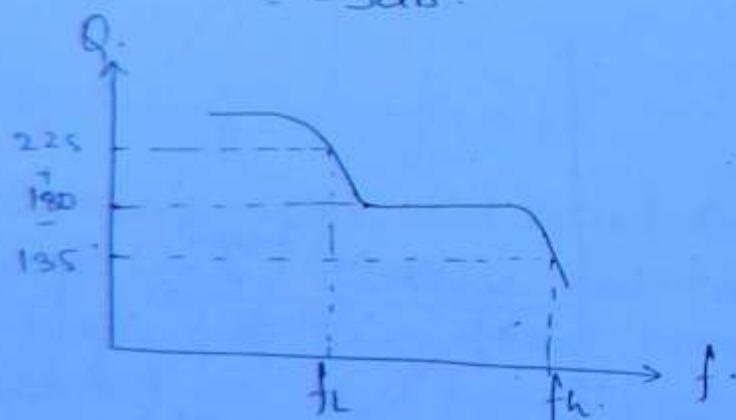
$$|A(j\omega)|_{db} = -20 \log \sqrt{1 + \omega^2 T^2}$$

$$\omega = \frac{1}{T}$$

$$= -20 \log \sqrt{1+1}$$

$$= -20 \log \sqrt{2}$$

$$= -3db$$



$$(Av)_L = \frac{(Av)_m}{1 - j \left(\frac{f_L}{f} \right)}$$

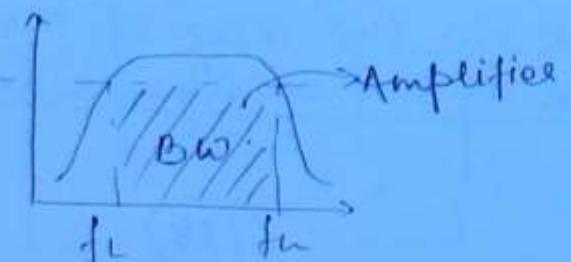
$$(Av)_H = \frac{(Av)_m}{1 + j \left(\frac{f}{f_H} \right)}$$

$$\theta_L = -\tan^{-1} \left(\frac{f_L}{f} \right)$$

$$\theta_H = \tan^{-1} \left(\frac{f}{f_H} \right)$$

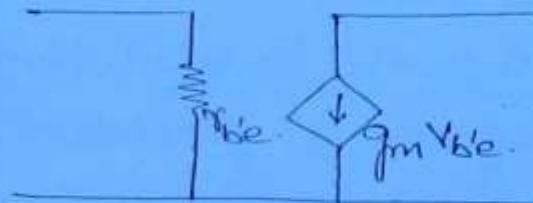
Conclusion →

Concept of amplifier parameters.



(123)

Amplifier →



$$C_{be} \rightarrow \infty$$

$$C_{b'c} \rightarrow \infty$$

$$r_{bb'} \rightarrow 0$$

$$r_{b'c} \rightarrow \infty$$

$$r_{ce} \rightarrow \infty$$

Ch-2

Ch-2

Ques. 9-4. 160 (a).

Ag-34

Q10. b.

2/1/12

Feedback Amplifier :-

- Amplifier The basic char. of an amplifier are input imp., O/P imp., voltage gain, BW. etc.
- Suppose if we want to change the char. of a basic amp. lifer, we have to use a technique called as feedback.

Feedback →

"When a part or a fraction of the O/P feedback to I/P, feedback is said to be exist."

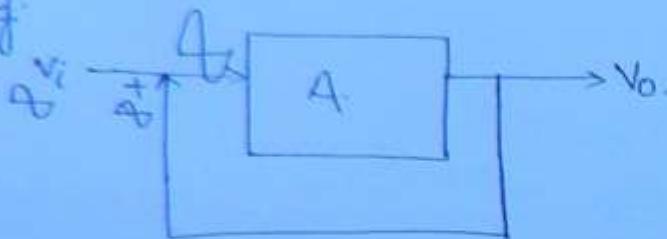
It classified into two ways. —

- 1) \downarrow ive feedback
- 2) \uparrow ive feedback.

Positive feedback :—

If the net effect of the feedback inc. the mag. of the EIP signal, it is called as live or direct or regenerative feedback.

e.g.

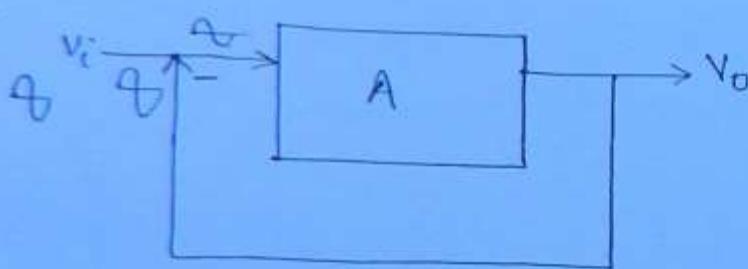


(194)

Negative feedback :—

If the net effect of the feedback decreases the mag. of the EIP signal, it is called as live or inverse or degenerative feedback.

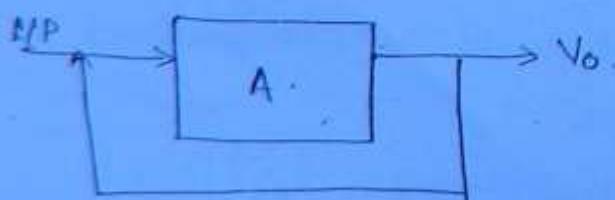
e.g.



Feedback can also be classified as

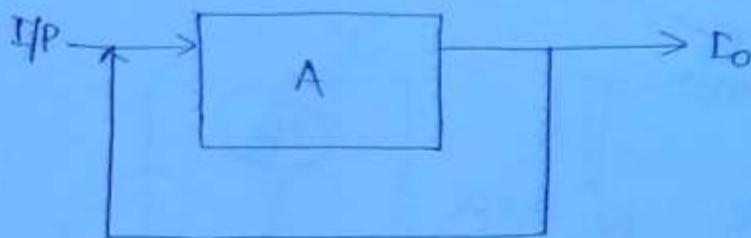
- 1) Voltage feedback.
- 2) Current feedback.

Voltage feedback :—



feedback signal $\propto v_o$.

Current feedback →



(125)

feedback signal $\propto I_o$.

Limitations of basic amplifiers : →

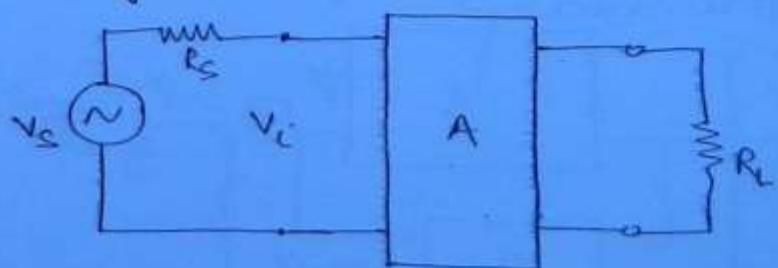
- 1) Instability of ac gain.
 - Due to power supply variation
 - Due to change in h parameter
 - age of the device
- 2) SIP impedance is low.
- 3) Output impedance is high.
- 4) Noise level is high.
- 5) Distortion is more.
- 6) BW is not sufficiently large.

Types of basic amplifiers →

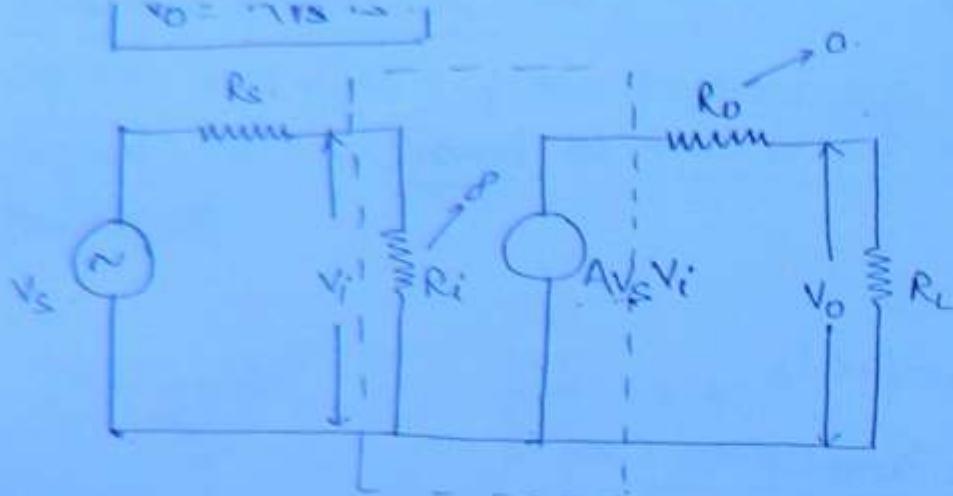
based on Z_i and Z_o →

- 1) Voltage amplifiers
- 2) Current amplifier.
- 3) Transconductance amplifiers.
- 4) Transresistance amplifiers.

Voltage amplifiers : →

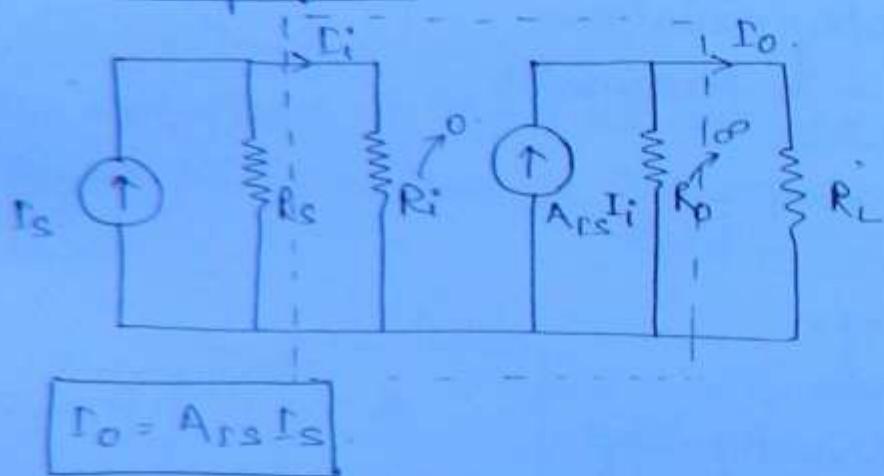


Voltage gain $A_v = \frac{V_o}{V_i}$. Voltage Amplification $A_{vs} = \frac{V_o}{V_s}$



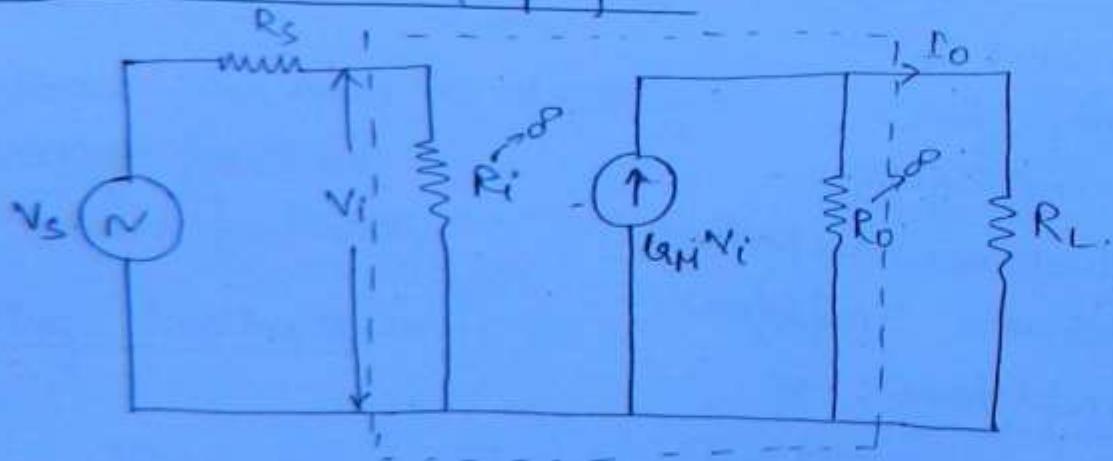
(126)

Current Amplifier \rightarrow



$$I_o = A_{Is} I_s$$

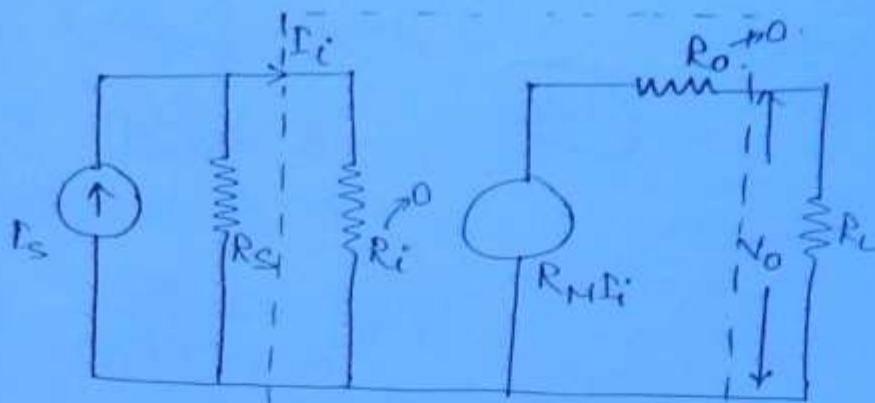
Transconductance Amplifier \rightarrow



$$g_m = \frac{I_o}{V_s}$$

$$I_o = g_m V_s$$

Transresistance amplifier:



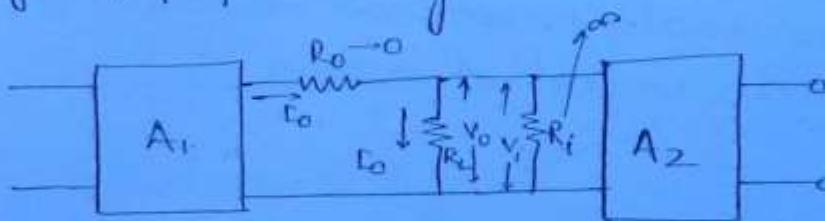
(177)

$$R_M = \frac{V_o}{I_s}$$

$$\boxed{V_o = R_M I_s}$$

#Q) In most of the practical applications why we choose Voltage Amplifiers Only?

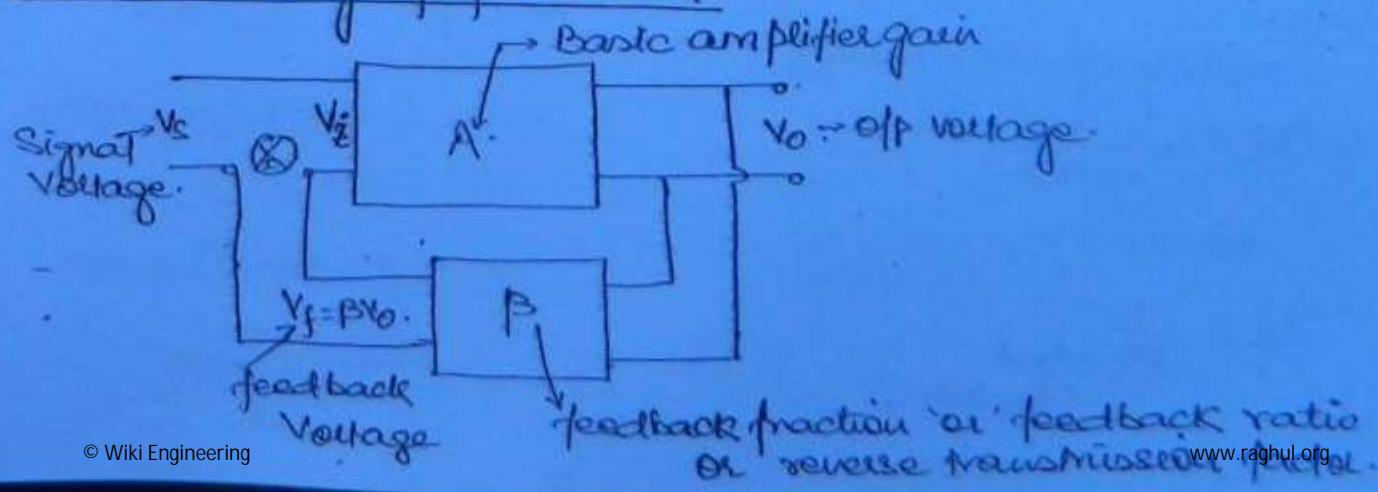
Aus.



For any ideal amplifier, I/P impedance should be ∞ and O/P impedance should be 0.

Therefore voltage amplifier specification are matching with ideal amplifier specification. That is the reason, most of the practical applications, voltage amplifiers are used.

General theory of feedback: →



Positive FB

$$V_o = AV_i$$

$$V_i = V_s + V_f$$

$$V_f = A(V_s + \beta V_o)$$

$$\Rightarrow \frac{V_o}{V_s} = \frac{A}{1 - A\beta}$$

Conclusions →

$$> A_{pf} > A > A_{nf}$$

$$> A_{nf} = \frac{V_o}{V_s} = \frac{A}{1 + A\beta}$$

$A_{nf} \downarrow, S \uparrow$

Always for amplifier analysis we use negative feedback because stability is an important criteria

$$\Rightarrow A_{pf} = \frac{V_o}{V_s} = \frac{A}{1 - A\beta}$$

$$|A\beta| = 1.$$

$$A_{pf} \rightarrow \infty, S \rightarrow 0.$$

Negative feedback is always be applied for unstable sys like oscillators.

Negative FB amplifiers →

Adv →

1) Stability of ac gain.

$$A_f = \frac{A}{1 + A\beta}$$

$$A\beta \gg 1.$$

$$A_f = \frac{1}{\beta} \rightarrow \text{fixed}$$

(Resistor)

Negative FB →

$$V_o = AV_i$$

$$V_i = V_s - V_f$$

$$V_f = A(V_s - \beta V_o)$$

$$\frac{V_o}{V_s} = \frac{A}{1 + A\beta}$$

(178)

resistance of an amplifier then the fractional change of gain with feedback is .

$$A_f = \frac{A}{1+AB}$$

(79)

diff. w.r.t. A.

$$\frac{\partial A_f}{\partial A} = \frac{(1+AB) - A(p)}{(1+AB)^2}$$

$$= \frac{1}{(1+AB)^2}$$

$$\Rightarrow \frac{\partial A_f}{A_f} = \frac{1}{(1+AB)^2} \frac{\partial A}{A}$$

$$\boxed{\frac{\partial A_f}{A_f} < \frac{\partial A}{A}}$$

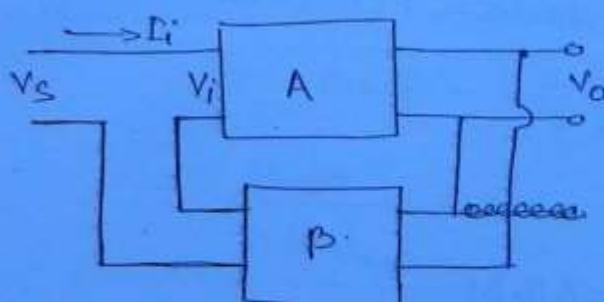
$\frac{\partial A}{A} \rightarrow$ w/o feedback fractional change of gain.
 $\frac{\partial A_f}{A_f} \rightarrow$ with feedback fractional change of gain

$$\Rightarrow \frac{1}{1+AB} \rightarrow \text{sensitivity}$$

$$\Rightarrow 1+AB \rightarrow \text{Desensitivity}$$

Increase in I/P impedance \rightarrow

(Z_i)



$$Z_{if} = \frac{V_s}{E_i}$$

$$Z_i = \frac{V_i}{E_i}$$

$$V_i = V_s - BV_o$$

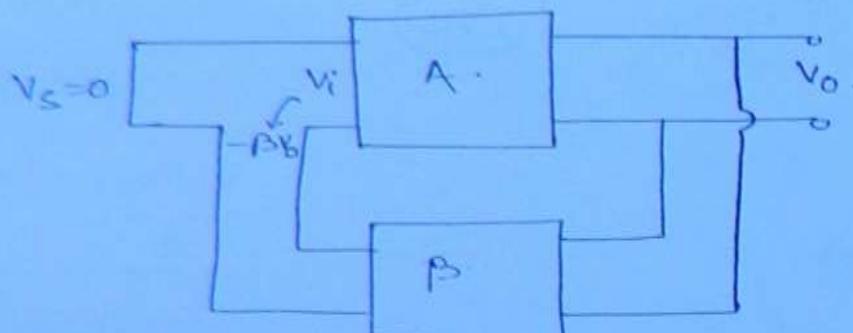
$$= V_s - BAV_i$$

$$\cancel{V_e = (1+AB) \frac{V_o}{R_f}} = \frac{V_s}{R_f}$$

$$\boxed{\cancel{AV_e = (1+AB) Z_i = Z_{if}}}$$

Decrease in output impedance ~ v.

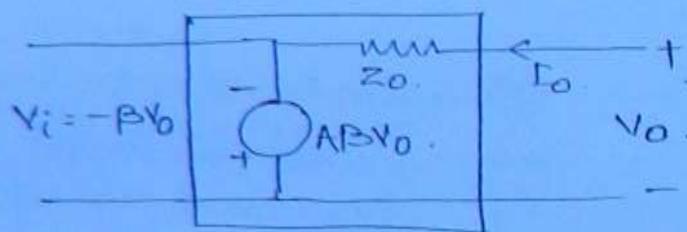
(180)



$$V_S =$$

$$V_i'' = V_S - \beta V_O, V_S = 0$$

$$\boxed{V_i'' = -\beta V_O}$$



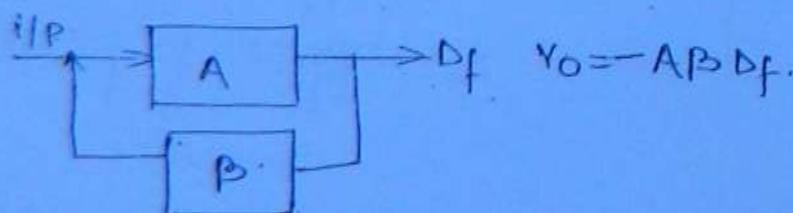
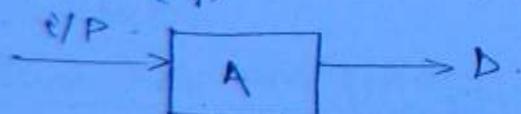
$$V_O + ABV_O = I_O Z_0$$

$$V_O(1+AB) = I_O Z_0$$

$$\boxed{\frac{V_O}{I_O} = Z_{of} = \frac{Z_0}{1+AB}}$$

Reduction in distortion and noise :-

$$\text{Net distortion} = \text{Original distortion} + \text{distorted O/P} \cdot (D_f) \quad (D)$$



$$D_f = D - ABD_f$$

$$D_f(1+AB) = D$$

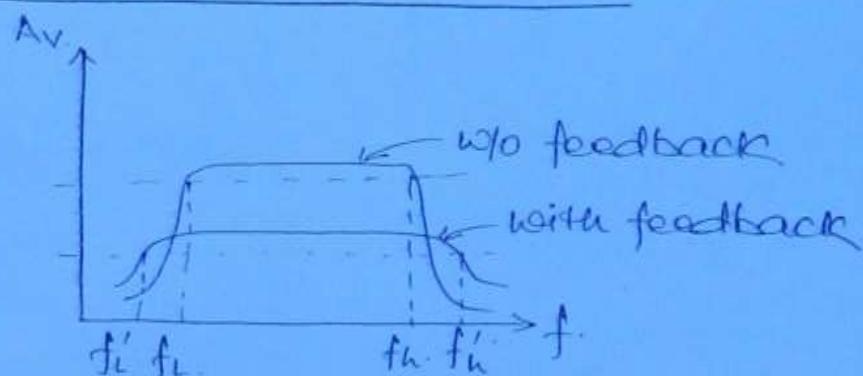
$$\boxed{D_f = \frac{D}{1+AB}}$$

dominance,

$$N_f = \frac{N}{1 + A\beta}.$$

(18)

Increase in Bandwidth : \rightarrow



cutoff.

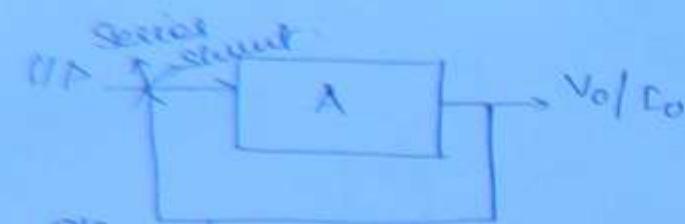
lower freq \rightarrow

$$\begin{aligned}(Av)_L &= \frac{(Av)_m}{1 - j(\frac{f_L}{f})} \\&= \frac{(Av)_m}{1 + (Av)_m \beta} \\&= \frac{(Av)_m}{1 - j(\frac{f_L}{f})} \Bigg/ \frac{1 + (Av)_m \beta}{1 - j(\frac{f_L}{f})}\end{aligned}$$

$$\begin{aligned}(Av)_{hf} &= \frac{Av_m}{1 + Av_m \beta - j(\frac{f_L}{f})} \\&= \frac{(Av)_m}{1 + (Av)_m \beta} \\&\quad \frac{1 - j \frac{f_L}{f}}{f(1 + (Av)_m \beta)} \\&= \frac{(Av)_{nf}}{1 - j(\frac{f_L}{f})}\end{aligned}$$

$$f_L' = \frac{f_L}{1 + (Av)_m \beta}, \quad \Rightarrow f_H' = f_H(1 + (Av)_m \beta)$$

Topology : →



(182)

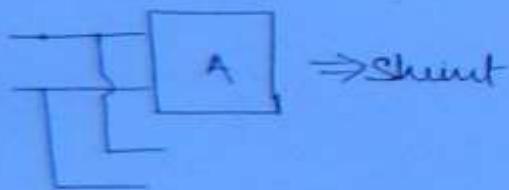
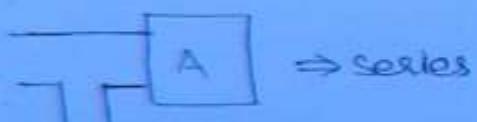
I/P	O/P
Voltage	Series
Voltage	Shunt
Current	Series
Current	Shunt

Topology →

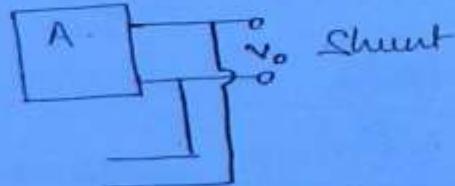
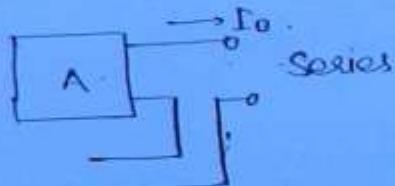
- Block diagram Analysis.
- Practical CRT Analysis.

Block diagram Analysis : →

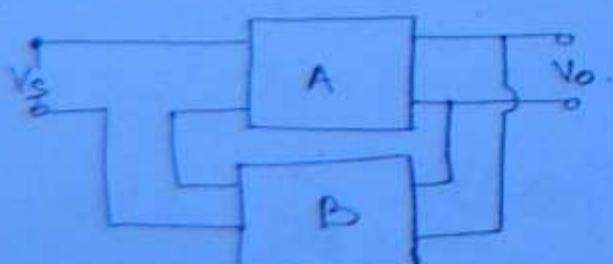
I/P.



O/P side.



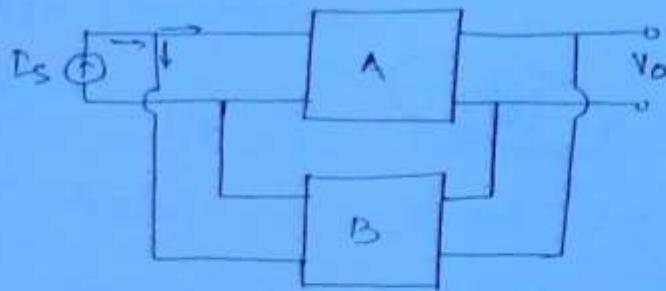
Voltage Series →



→ Voltage amplifier.

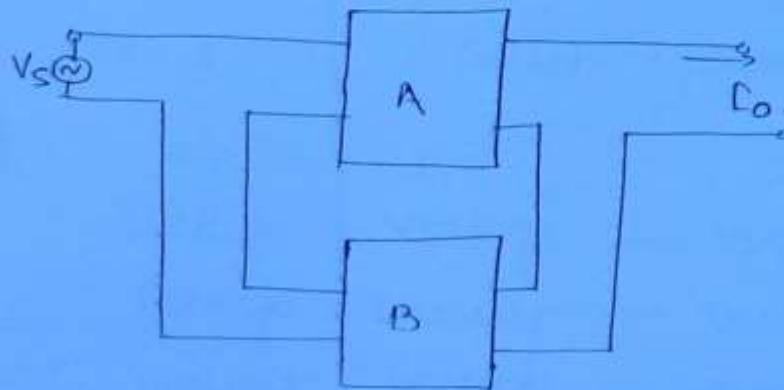
Voltage series

(183)



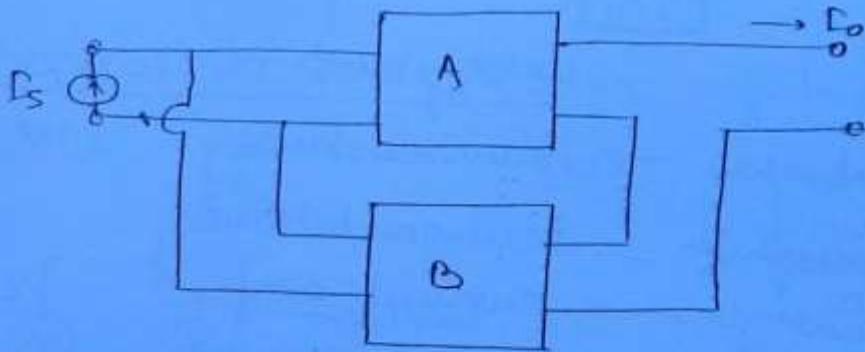
→ transresistance amplifier

Current Series



→ transconductance amplifier.

Current Shunt



→ current amplifier

I
1) In Voltage Series _____ amplifier is used.

2) In Voltage Shunt _____ amplifier is used.

3) In Current Series _____ amplifier is used.

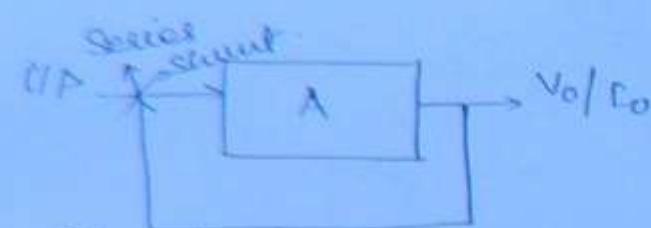
4) In Current Shunt _____ amplifier is used.

II
1) In O/P is series connection _____ source is taken.

2) In O/P is shunt connection _____ source is taken.

III
1) $\frac{V_o}{V_s}$ VC VS
 $\frac{I_o}{I_s}$ NC LS

Topology : →



(182)

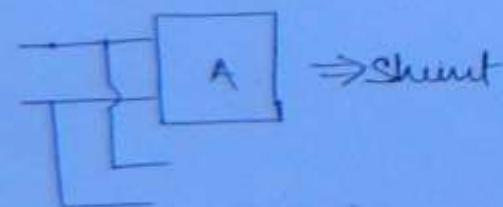
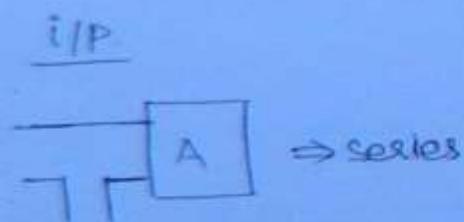
<u>I/P</u>	<u>O/P</u>
Voltage	Series
Voltage	Shunt
Current	Series
Current	Shunt

Topology →

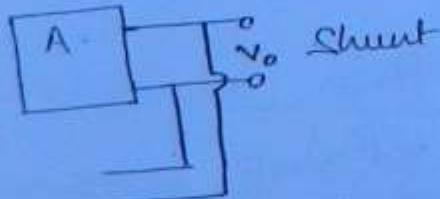
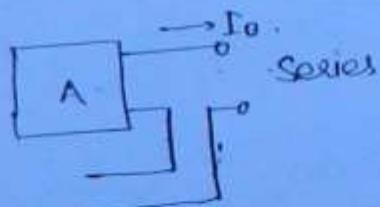
→ Block diagram Analysis.

→ Practical CRT Analysis.

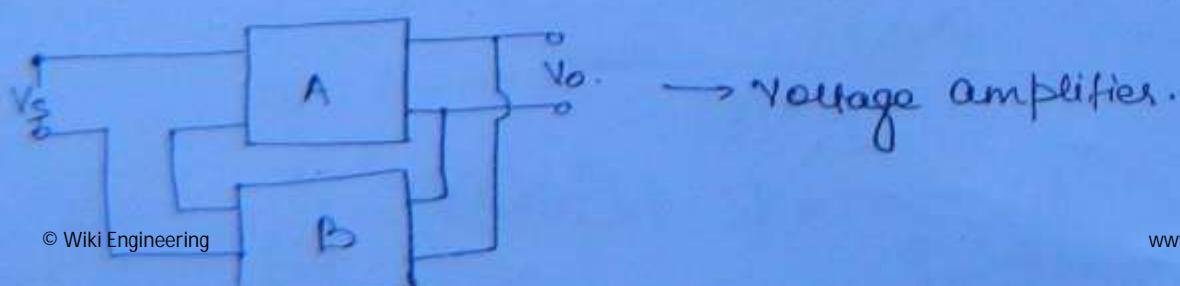
Block diagram Analysis : →



O/P Side :

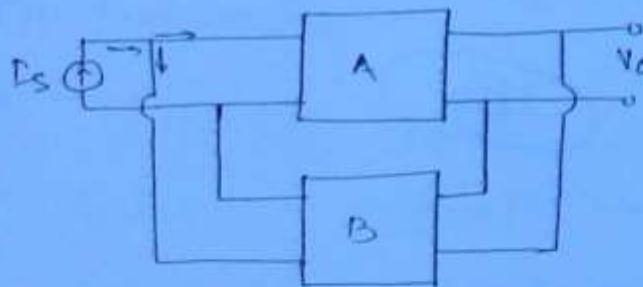


Voltage Series →



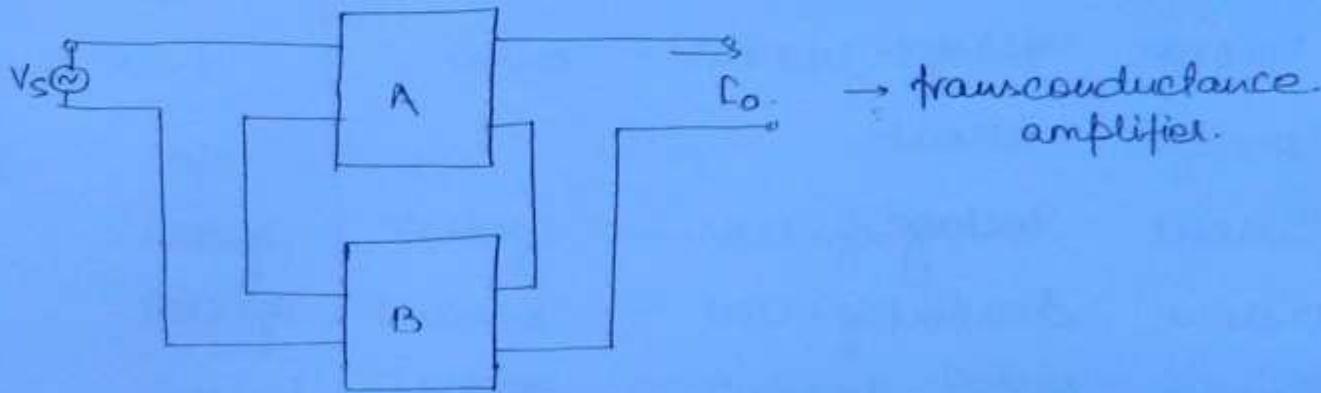
Voltage -

783

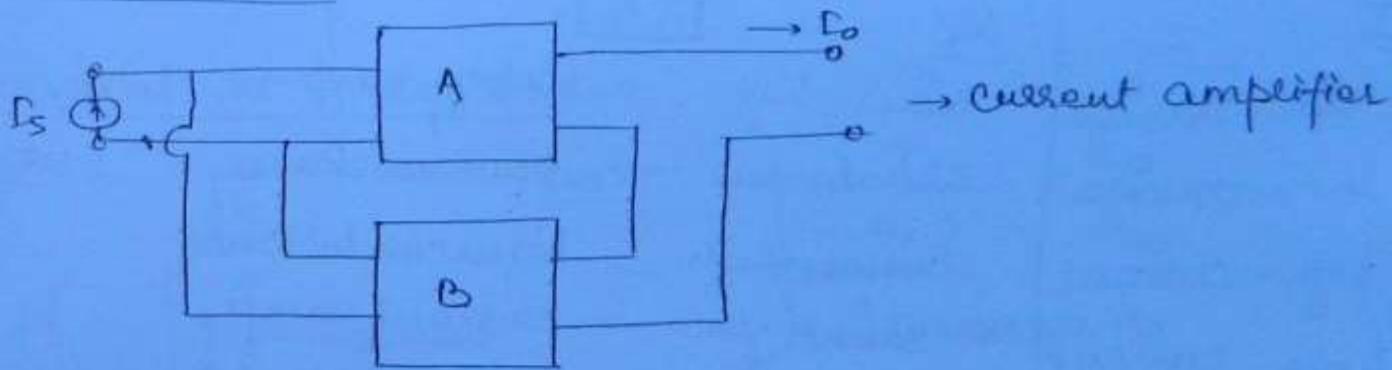


→ transresistance amplifier.

Current Series:



Current Shunt:



I
1) In Voltage Series _____ amplifier is used.

2) In Voltage Shunt _____ amplifiers is used.

3) In Current Series _____ amplifier is used.

4) In Current Shunt _____ amplifier is used.

II
1) If S/P is series connection Voltage source is taken.

2) If S/P is shunt connection Current source is taken.

III
1) V_C V_S

N_C I_S

V_C V_S

IV

Series	Shunt
Shunt	Shunt
Series	Series
Shunt	Series

184

V Voltage Voltage
 Voltage current
 Current Voltage
 Current current.

Answers →

I $\frac{Z_o}{Z_i}$
 low voltage
 low voltage
 high current
 high current

Z_i $\frac{Z_i Z_o}{Z_o + Z_i} \rightarrow$
 Series → high → voltage amp.
 Shunt → low → transresistance
 Series → high → transconductance
 Shunt → low → current amp.

Opamp is a voltage control device $\rightarrow V_{od} \propto V_{in}$

FET is a voltage control device $\rightarrow I_d \propto V_{ds}$

BJT is a current control device $\rightarrow I_c \propto I_b$

III D/P S/P
 series VC VS → sen voltage series
 series VC IS → current series.
 Shunt DC. VS → voltage shunt
 Shunt DC. IS → current shunt.

Any device having more than one number of I/P
E/I/P parameter.

(188)

IV

I/P

Series

O/P

shunt \rightarrow voltage series

Shunt

shunt \rightarrow voltage shunt

series

series \rightarrow current series

Shunt

series \rightarrow current shunt

V

O/P

Voltage

I/P

Voltage \rightarrow voltage series

Voltage

current \rightarrow voltage shunt

Current

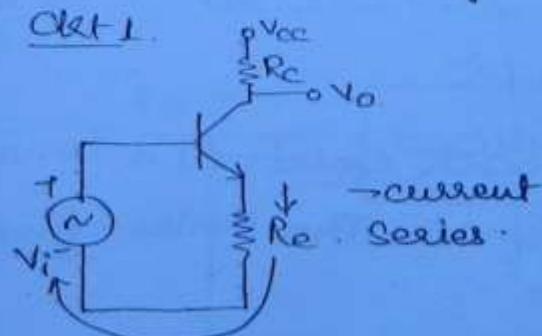
Voltage \rightarrow current series

Current

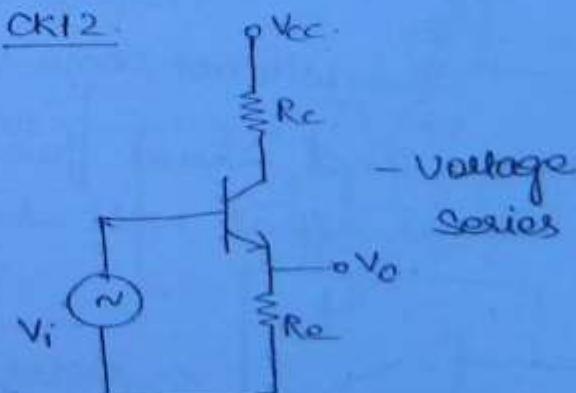
current \rightarrow current shunt

Practical CKT Analysis :-

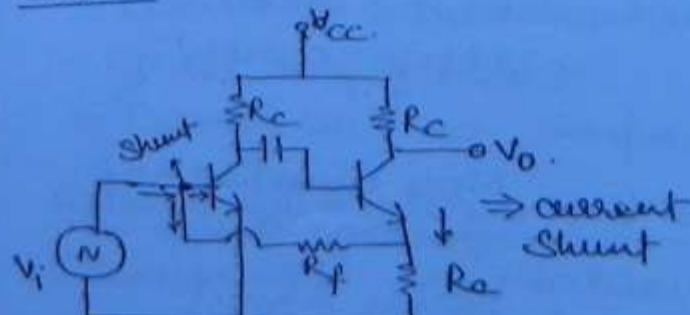
CKT 1.



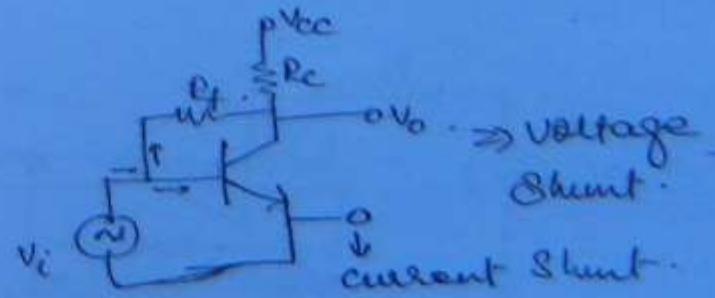
CKT 2.



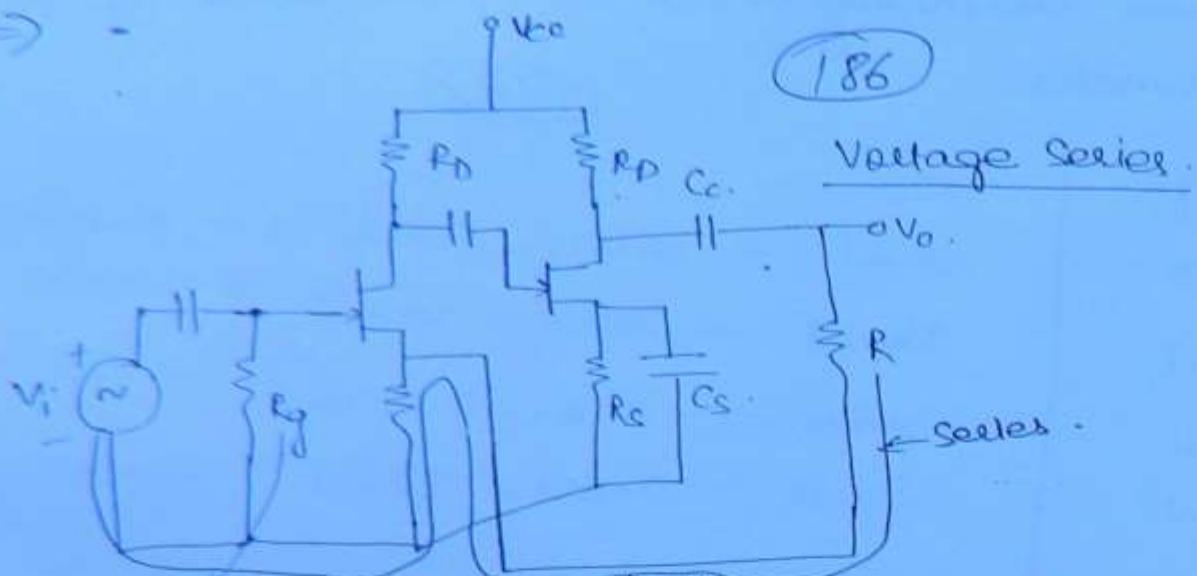
CKT 3.



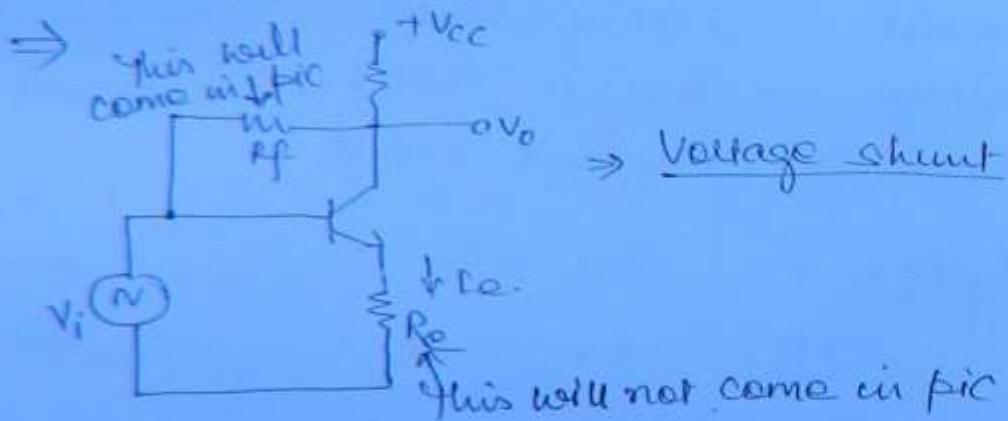
CKT 4.



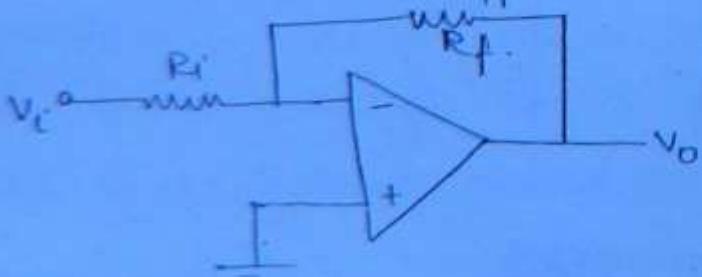
\Rightarrow



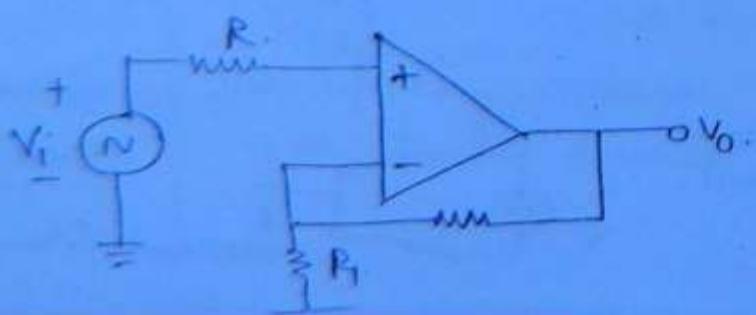
$R_g \rightarrow$ This is not feed back resistance. so, it is series connection.



Whenever series and shunt feedback exist at a time in the ckt, shunt effect will dominate the series effect.



Inverting amplifier.
Voltage shunt
Shunt shunt
Voltage current



Non inverting amp.
Voltage series
Series shunt
Voltage Voltage

Calculation of ω_0 & ω_m in terms of Z_i & Z_o impedance of diff. topology :-

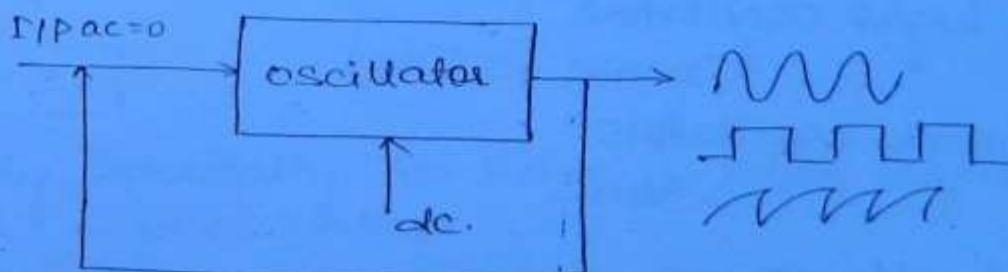
(187)

	$Z_i = 0 \quad Z_o = \infty$ Voltage Series	$Z_i = 0 \quad Z_o = \infty$ Voltage Shunt	$Z_i = \infty \quad Z_o = 0$ Current Series	$Z_i = \infty \quad Z_o = 0$ Current Shunt
Z_{if}	$Z_i(1+AB)$	$Z_i/1+AB$	$Z_i(1+AB)$	$Z_i/1+AC$
Z_{of}	$Z_o/1+AB$	$Z_o/1+AB$	$Z_o(1+AB)$	$Z_o(1+AC)$

OSCILLATORS →

Definitions →

- It is a CKT which converts dc en. into ac en. at any required freq.
- It is an electronic CKT of alternating current and voltage having Sine, square, sawtooth waveform etc.
- It is a CKT which generates ac o/p signal w/o requiring any ac I/P signal.
- It is an unstable amplifier.



Classification of oscillators →

- Based on nature of wave generated
- Based on fundamental mechanism involved.
- Based on feedback
- Based on freq. response.

Based on nature of wave generated →

- Sinusoidal oscillations
eg tunnel diode, RC, LC oscillation.

- non linear circuit
 - eg - UJT, Astable multivibrator using opamp.

Based on fundamental mechanism involved:-

- Negative resistance region
 - * Tunnel diode , UJT.
- Feedback
 - Rc oscillator
 - Lc oscillator

Based on freq. response :-

- Audio freq oscillators
(60Hz - 20kHz)
- Radio freq oscillators.
(20kHz to 30MHz)
- Very high freq. oscillators.
(30MHz - 300MHz),
- Ultra high oscillators
(300MHz - 3 GHz)
- Microwave oscillators
 $> 3\text{GHz}$

Based on feedback →

- Rc oscillators
 - [Rc phase shift oscillators
 - [Wien bridge oscillators.

- Lc oscillators .

- [Hartley
- [Colpitts
- [Clapp

- Crystal oscillators

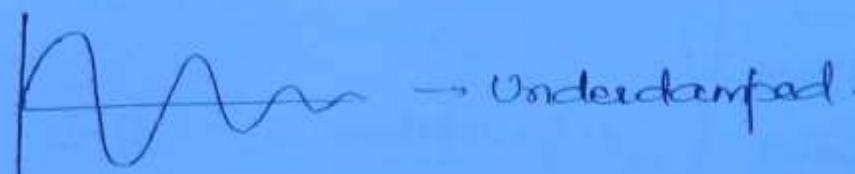
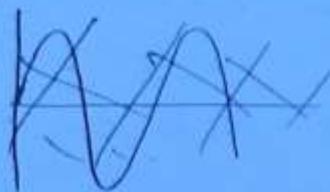
Effect of $|AB|$ on oscillations :-

$$|AB|=1.$$

(189)



$$|AB| < 1.$$



$$|AB| > 1$$

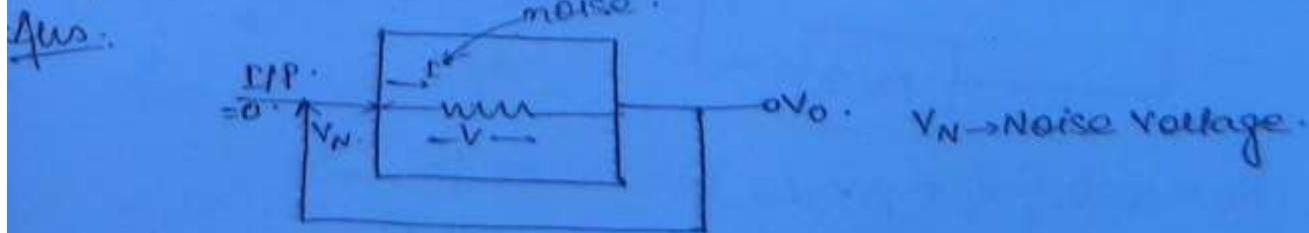


$$|AB| \geq 1$$

Q. Why practically AB value is taken slightly greater than 1. in oscillators.

Aus. Because of the non linearities in the O.C.F, we take AB slightly greater than 1.

Q. W/o giving any input how an oscillator can produce an O/P?

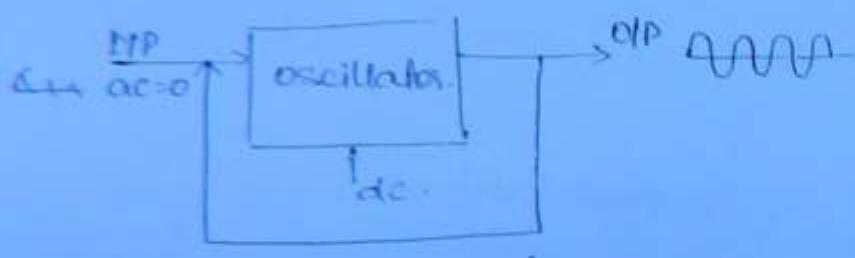
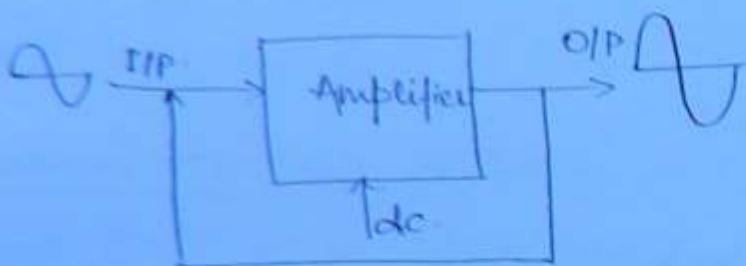


Any variation in the mean random current of the random moment of e^- in an electronic device a noise voltage will be produced. Such noise voltage will be feedback to the I/P which will be a regenerative action, that means there is no requirement of giving an ext. I/P.

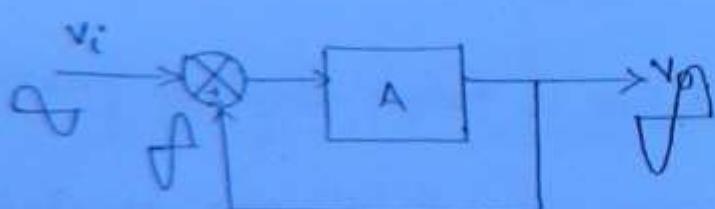
3/1/12

Basic diff. b/w Amplifier and oscillator :-

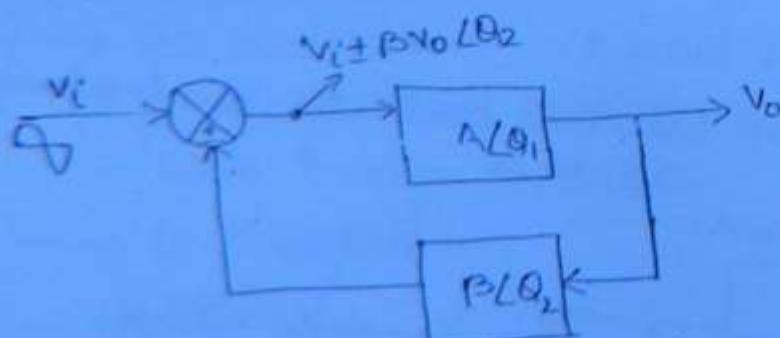
(P90)



Feedback oscillators —



→ CE give 180° phase shift
at ext O/P \int for I/P-A
So phase shift is taken
at A and B.



$$V_0 = A/Q_1 \{ V_i \pm \beta V_0 Q_2 \}$$

for positive feedback.

$$V_o = A \angle \theta_1 \{ V_i + \beta V_o \angle \theta_2 \}$$
$$= A \angle \theta_1 V_i + A \beta V_o / (\theta_1 + \theta_2)$$

(191)

$$\therefore V_o (1 - A\beta / (\theta_1 + \theta_2)) = A \angle \theta_1 V_i$$

$$\therefore \frac{V_o}{V_i} = \frac{A \angle \theta_1}{1 - A\beta / (\theta_1 + \theta_2)}$$

For Oscillators,

for $V_i = 0$,

$$\frac{1 - A\beta / (\theta_1 + \theta_2)}{A\beta} = 0.$$

Magnitude

$$|A\beta| = 1$$

Phase,

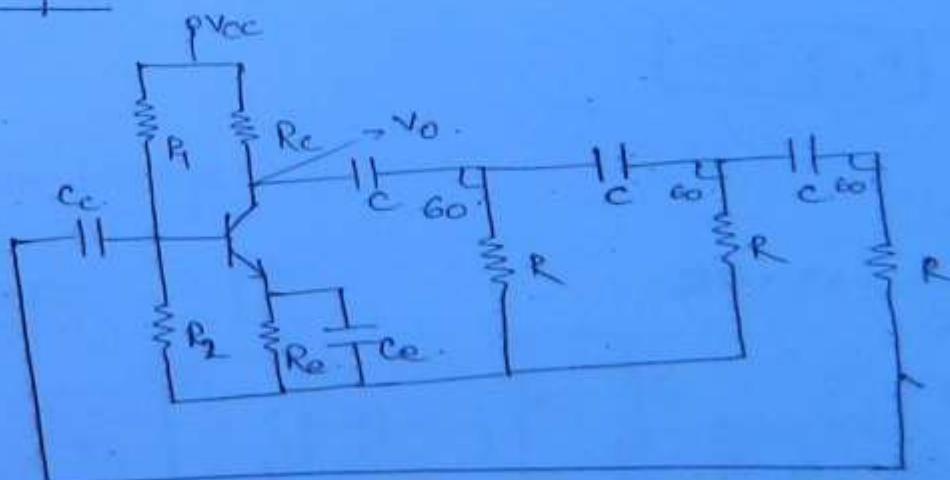
$$\theta_1 + \theta_2 = 0 \text{ or multiple of } 2\pi$$

θ_1

} Barkhausen criteria

RC oscillators →

Phase shift :



Conclusion :

$$1) Q + 360^\circ \rightarrow 360^\circ \rightarrow \text{ideal.}$$

$$3 \text{ sets of } 120^\circ = 360^\circ$$

$$2) \quad f = \frac{1}{2\pi RC \sqrt{4K+G}}$$

$$\text{where } K = \frac{R_C}{R}$$

for $K=1$,

(192)

$$f = \frac{1}{2\pi RC \sqrt{10}}$$

for $K \ll 1$,

$$f = \frac{1}{2\pi RC \sqrt{G}}$$

$$3) \quad -h_{fe} \frac{R_C}{R} = -29 - 23K - 4K^2$$

$$\boxed{A_V = -29} \quad K \ll 1.$$

$$\begin{aligned} B &= \pm \frac{1}{A_V} \quad \text{as } |AB| = 1. \\ &= \pm \frac{1}{-29} \end{aligned}$$

$$A_V \neq -29 \quad \boxed{A_V \geq -29}$$

$$4) \quad (h_{fe})_{min}$$

$$h_{fe} = \frac{29}{K} + 23 + 4K$$

diff. w.r.t. K .

$$\frac{\partial h_{fe}}{\partial K} = \frac{-29}{K^2} + 4 = 0$$

$$K = 2.7$$

$$\boxed{h_{fe\ min} = 44.5}$$

Drawbacks of π form circuit

for 3 kHz - 20 kHz

$$f = \frac{1}{2\pi RC \sqrt{G+4K}}$$

(193)

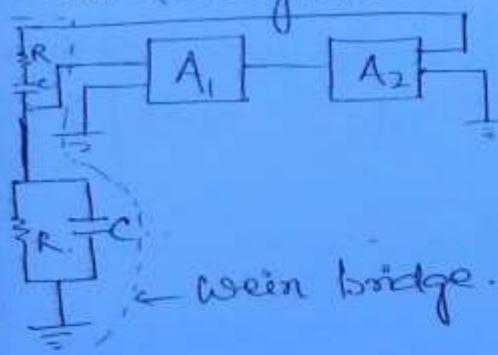
We cannot make it for dynamic frequency.
as R and C can't be change as phase is affected.

- 1) RC phase shift oscillator is used for single freq. operation
- 2) Due to thermal variation Resistance tolerance value may change which will disturb the phase relations
- 3) This type of CKT can be used for low freq oscillation

[audio range] [20 Hz - 20 kHz] because Q-factor of RC η/ω is poor

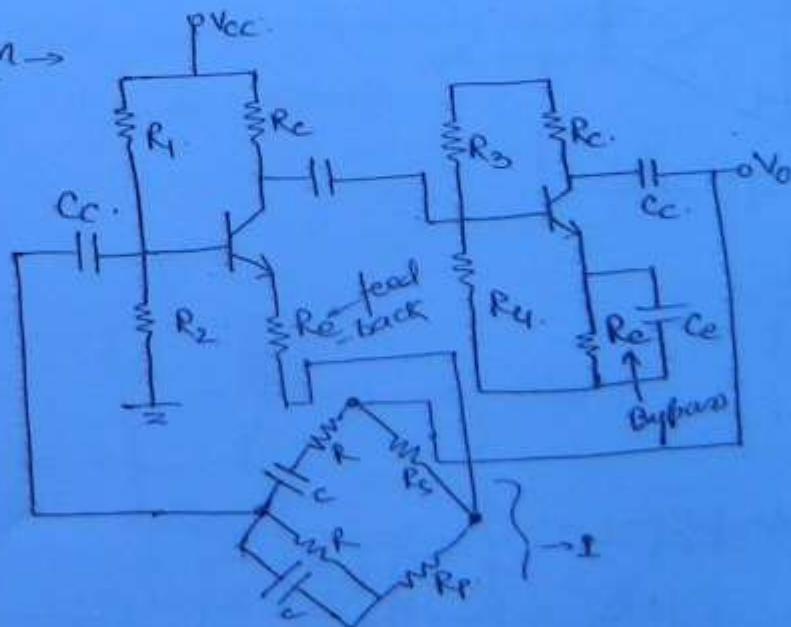
Wien bridge oscillator:

Block diagram: →



Wien bridge.

CKT diagram →



Wien bridge -

$$1) Q_1 + Q_2 + \text{Wien bridge} \\ \downarrow \quad \downarrow \quad \downarrow \\ 180^\circ \quad 180^\circ \quad 0^\circ \rightarrow 360^\circ$$

(194)

$$2) f = \frac{1}{2\pi\sqrt{C_1 C_2 R_1 R_2}} \rightarrow \text{In I.}$$

$$R_1 = R_2 = R, C_1 = C_2 = C$$

$$f = \frac{1}{2\pi RC}$$

$$3) A_V = -3$$

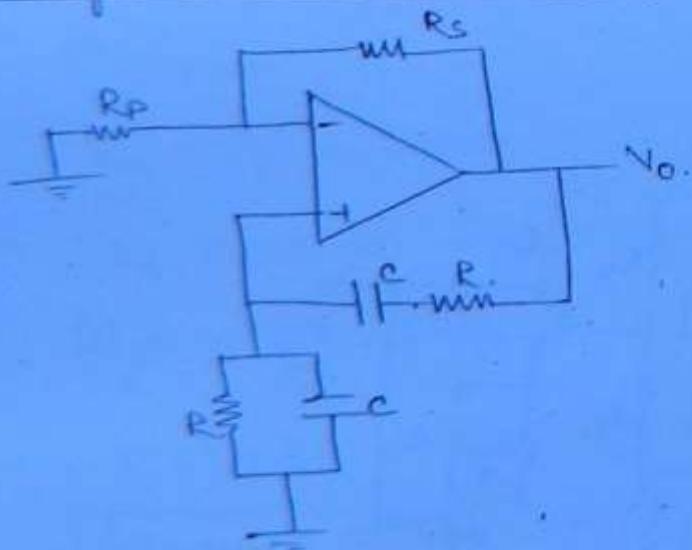
$$\beta = -\frac{1}{3}$$

Gain stabilization -

In Wien bridge oscillator, the gain requirement is 3 but because of cascading of two transistors the gain is becoming very high.

To reduce the gain, a -ve feedback is implemented across the transistor Q_1 by R_F resistor.

Bridge balance condition :-



Non-inverting Amplifier -

$$A_V = 1 + \frac{R_F}{R_A} = 1 + \frac{R_S}{R_P} = 3 \Rightarrow \frac{R_S}{R_P} = 2$$

$$K_S = 2RP$$

Importance of Wien bridge :-

(195)

- It has good freq. stability.
- It can be used for dynamic range of freq. because Wien bridge do not depend on phase.

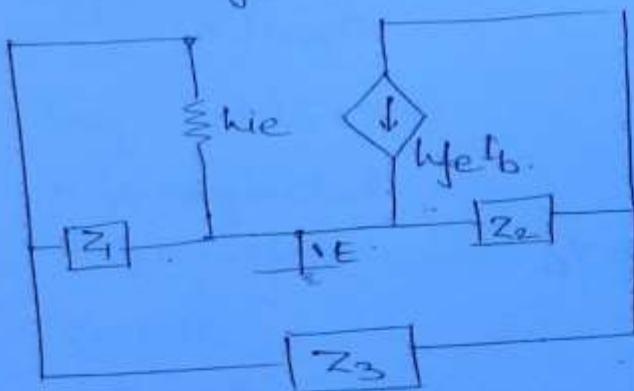
$$f = \frac{1}{2\pi RC}$$

Drawbacks :-

- Ckt complexity is more.
- It can not be used for high freq. because Q-factor of RC n/w is poor.

LC Oscillators :-

Block diagram :-

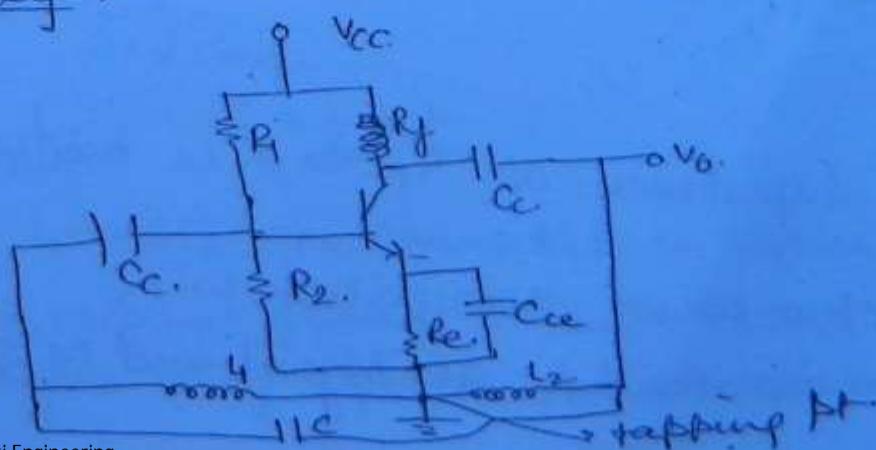


Condition :-

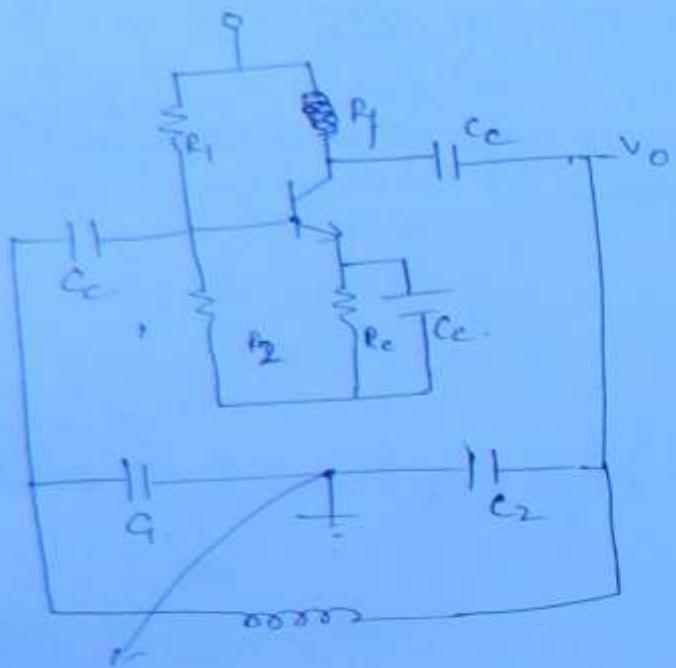
Z_1 and Z_2 are same reactive comp.

Z_3 is opp. reactive comp.

Harley →



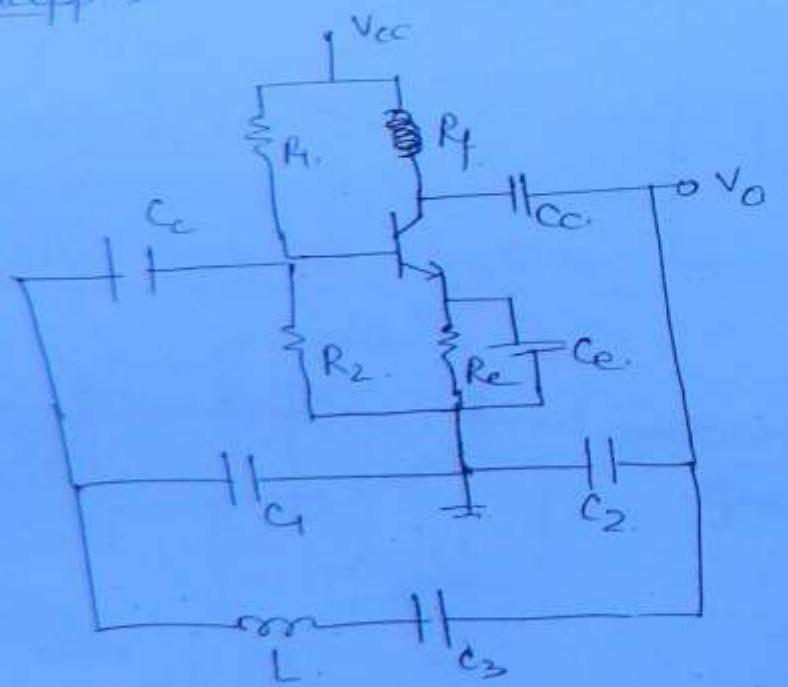
Output



(196)

tapping pt

Clapp →



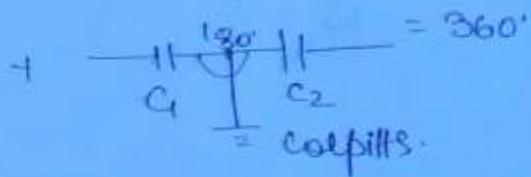
Analysis →

Q1 What is the importance of R_f or in LC oscillatory circuit?

- Ans1) To reduce the power dissipation loss,
 2) ~~gives~~ an isolation b/w ac signal and DC Supply.

$$Y + \frac{-4m + -L_2}{-V_f - V_o} \rightarrow \text{Hartley}$$

(or)



197

Tapping pt is an adjustable moving pt which can control the fine feedback nature in the ckt.

→ Explain the freq. of oscillation in the LC oscillators?

Ans. $f = \frac{1}{2\pi\sqrt{LC}}$

Hartley →

$$f = \frac{1}{2\pi\sqrt{L_{eq}C}}$$

$$L_{eq} = L_1 + L_2 + 2M$$

M is neglected

$$L_{eq} = L_1 + L_2$$

Colpitts

$$f = \frac{1}{2\pi\sqrt{L_{eq}C_{eqv}}}$$

$$= \frac{1}{2\pi\sqrt{L \frac{C_1 C_2}{C_1 + C_2}}}$$

Clapp

$$f = \frac{1}{2\pi\sqrt{L_{eq}}}$$

$$\frac{1}{C_{eq}} = \frac{1}{C_1} + \frac{1}{C_2} + \frac{1}{C_3}$$

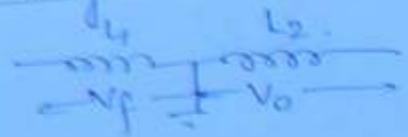
Q. Why L₁ and L₂ are connected in series in LC oscillators

Ans. The current flowing through L₁ and L₂ are same.

Therefore they are connected in series.

enough in common for you in all oscillators.

Hartley -



(9)

$$B = \frac{V_f}{V_o} = \frac{N_1}{N_2} = \frac{L_1}{L_2}$$

$$A = \frac{L_2}{L_1}$$

Colpits



$$B = \frac{V_f}{V_o} = \frac{1}{\omega C_1} = \frac{L_1}{C_2}$$

$$A = \frac{C_1}{C_2}$$

→ Why LC oscillators can not be designed for low freq. of operation.

$$f = \frac{1}{2\pi\sqrt{LC}}$$

Size of equipment become large.

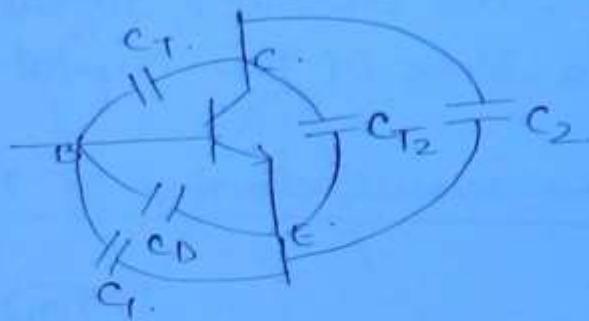
As the freq. of design reduces, the comps L and C values will increase. Practically it is impossible to design for very low freq.

→ LC oscillators are used for high freq. design because the Q-factor is more.

→ What is the imp. of Clapp oscillators?

Colpitts → :

(149)



$$f = \frac{1}{2\pi\sqrt{LC_{eq}}}$$

$$C_{eq} = \frac{C_1 C_2}{C_1 + C_2}$$

$$f = \frac{1}{2\pi\sqrt{LC_{eq}}}$$

$$\frac{1}{C_{eq}} = \frac{1}{C_1} + \frac{1}{C_2} + \frac{1}{C_3}$$

$$C_1 >> C_3$$

$$C_2 >> C_3$$

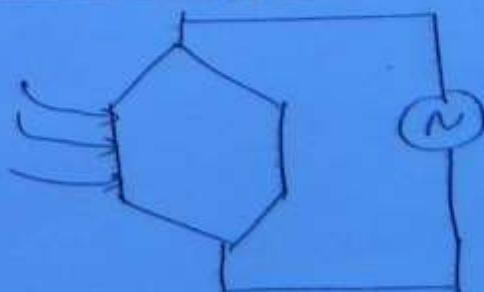
$$\left| \frac{1}{C_{eq}} = \frac{1}{C_3} \right|$$

$$f = \frac{1}{2\pi\sqrt{LC_3}} \rightarrow \text{independent of internal capacitors.}$$

Crystal oscillators →

when ever high freq. stability is required.

Piezo electric effect :-



When a mechanical force ~~force~~ acts on one side of the crystal, an Electrical signal will be generated on the other side of the crystal and vice versa.

Substances used for the manufacturing of the crystal:-

- 1) Rochelle Salts
- 2) Quartz
- 3) tourmaline.

(200)

Which substance will have more piezoelectric effect?

Ans: Rochelle salts > Quartz > tourmaline.

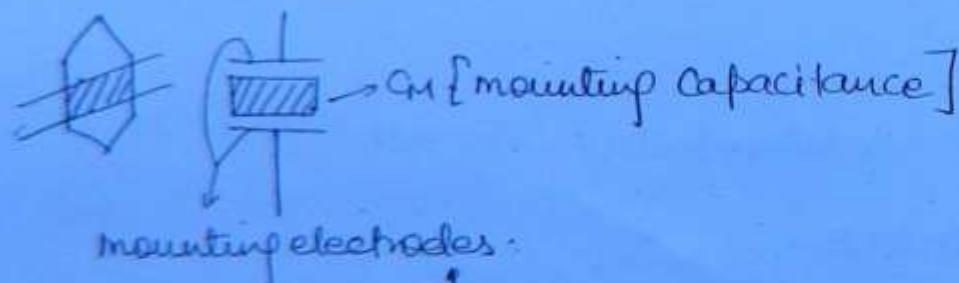
Q. Which substance is mechanically strongest?

Ans: tourmaline > Quartz > Rochelle salt

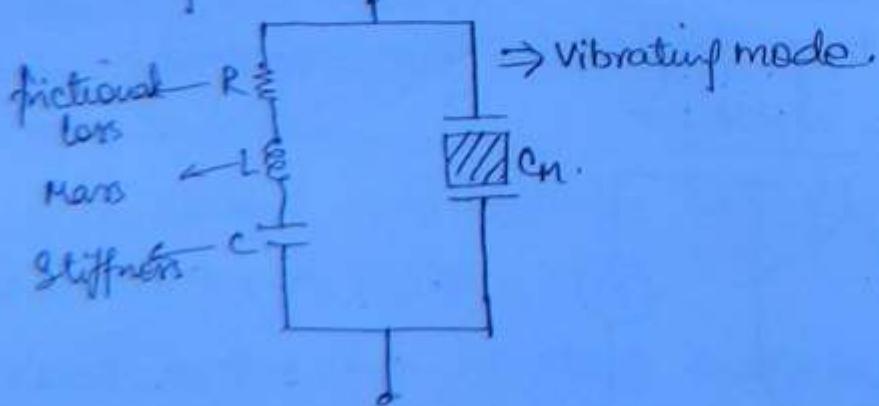
Quartz is a compromise b/w Rochelle Salts and tourmaline as easily available in nature.

Crystal equivalent model:-

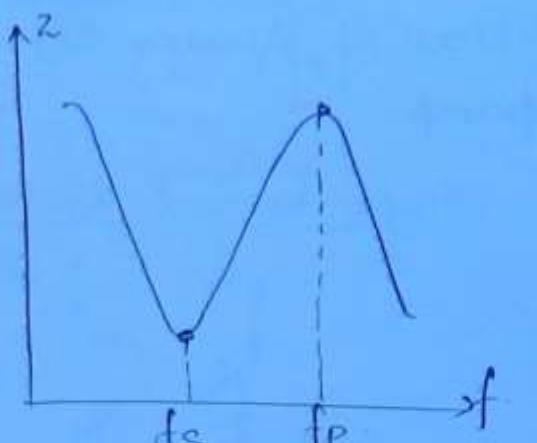
Non vibrating mode :-



mounting electrodes



Crystal operating mode



(201)

(zero
imp.
freq.) (infinite
impedance
freq)

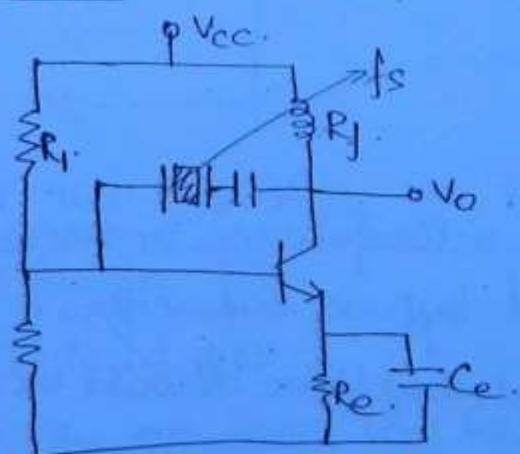
$$f_s = \frac{1}{2\pi\sqrt{LC}}$$

$$f_p = \frac{1}{2\pi\sqrt{LC}} \sqrt{1 + \frac{C}{C_M}}$$

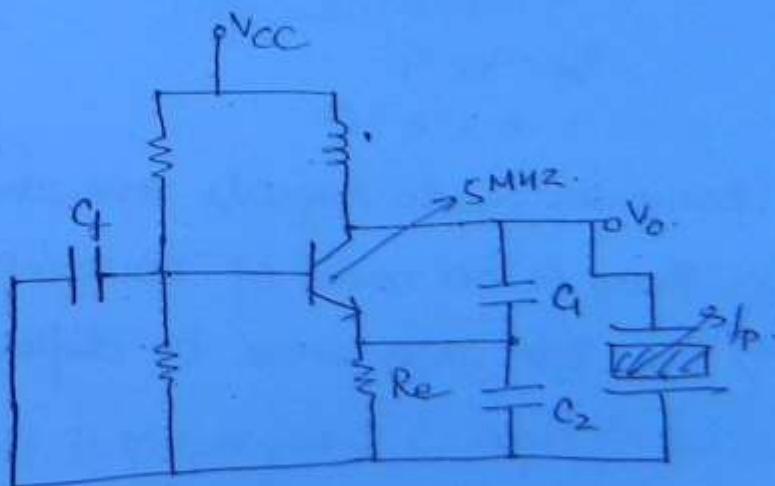
* $C_M \gg C$.

$$f_p \approx f_s$$

Ckt 1.



Ckt 2.

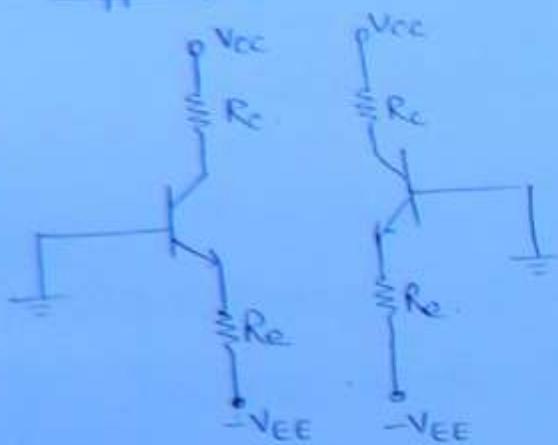


Differential amplifiers →

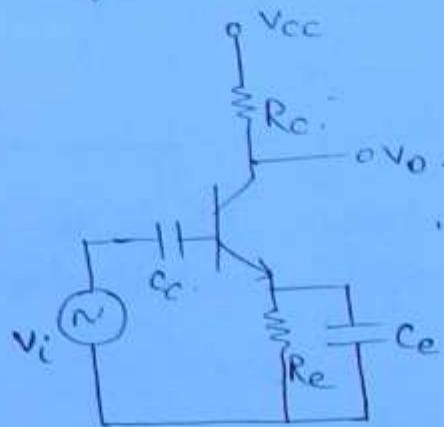
(202)

- It is the basic building block of Analog Circuits.
- It is the I/P stage of opamp.

Diff. Amp →



Single ended Amplifier



The imp. of differential amplifiers compare to single ended amplifiers are

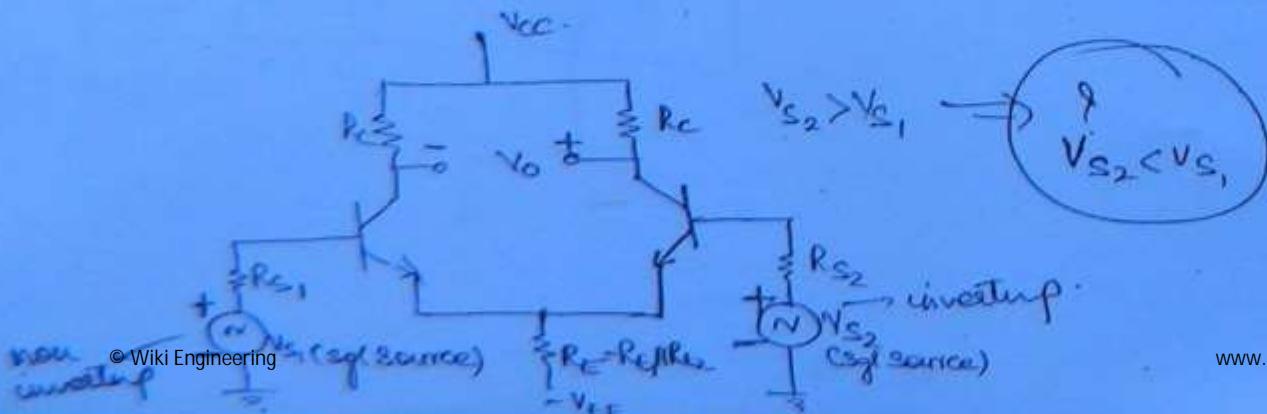
- 1) It is having best noise rejection capability.

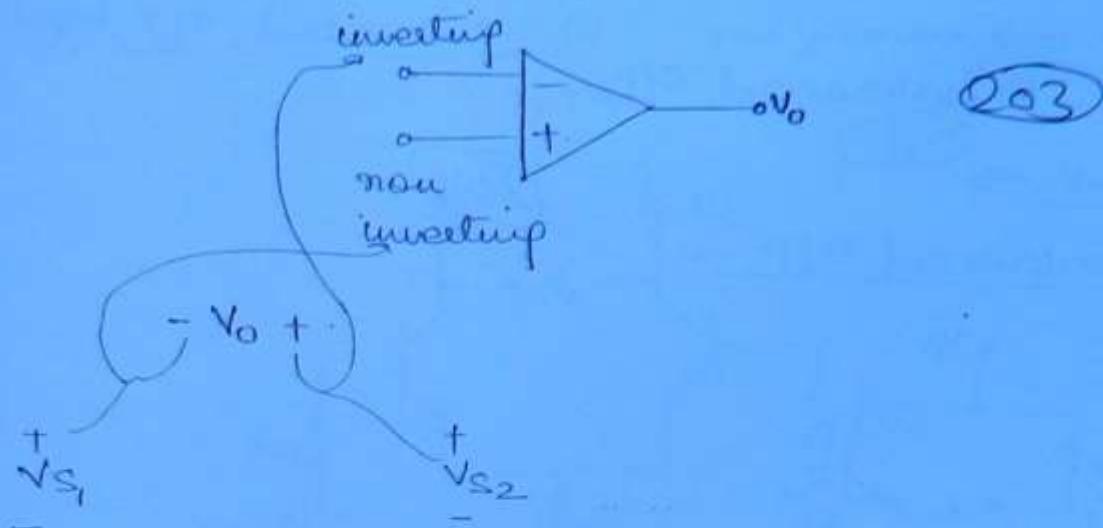
e.g -



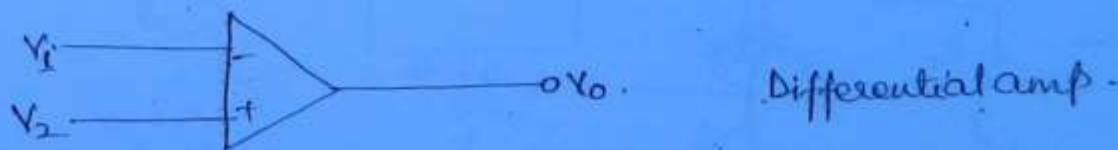
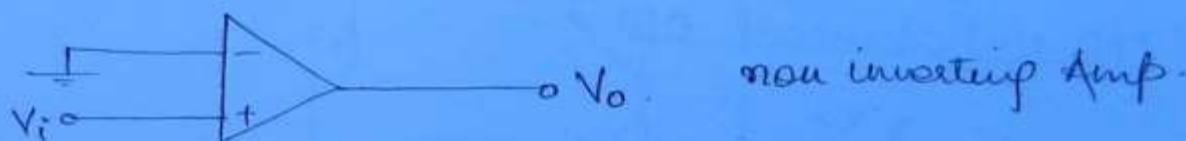
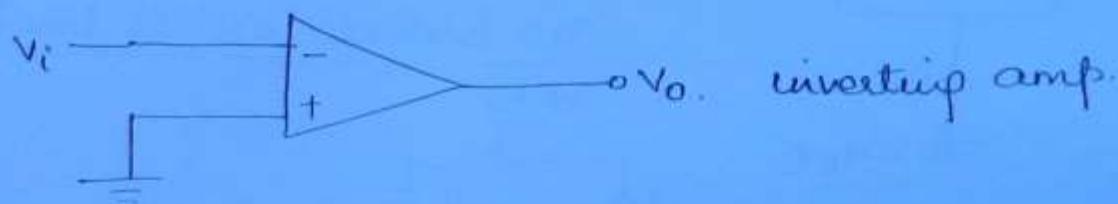
$$\begin{aligned} V_d &= V_2 - V_1 \\ &= 2 - 2 = 0 \end{aligned}$$

- Common mode signals are always interference or noise signals.
- 2) There is no need of coupling and bypass capacitors.
- 3) The I/P impedance of differential amplifier should be high.





Ckt Configuration : →



At the I/P side, we have,

- 1) Single I/P.
- 2) dual I/P.

At the O/P Side, we have,

- 1) balanced output [output is taken across C₁ and C₂]
- 2) Unbalanced output [output is taken across C₁ to ground or C₂ to ground].

Acc. to this we have four types of configuration.

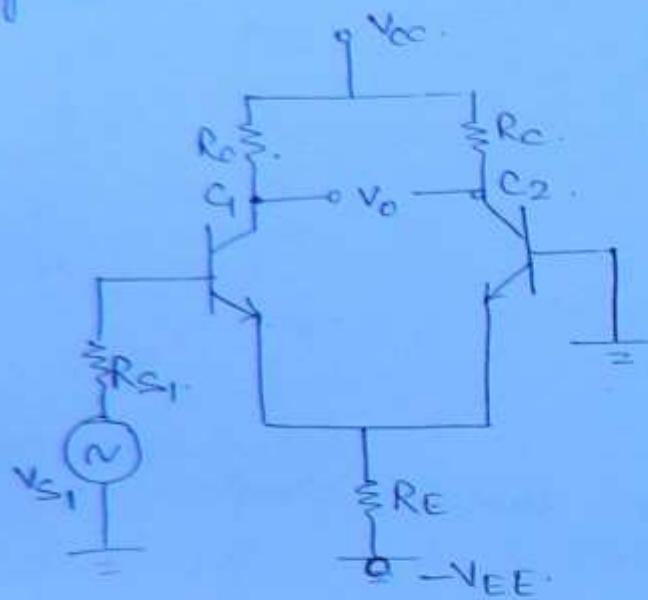
- 1) Single I/P balanced O/P.
- 2) Single I/P Unbalanced O/P.

- 3) Single EIP unbalanced O/P
 4) Dual EIP UnBalanced O/P.

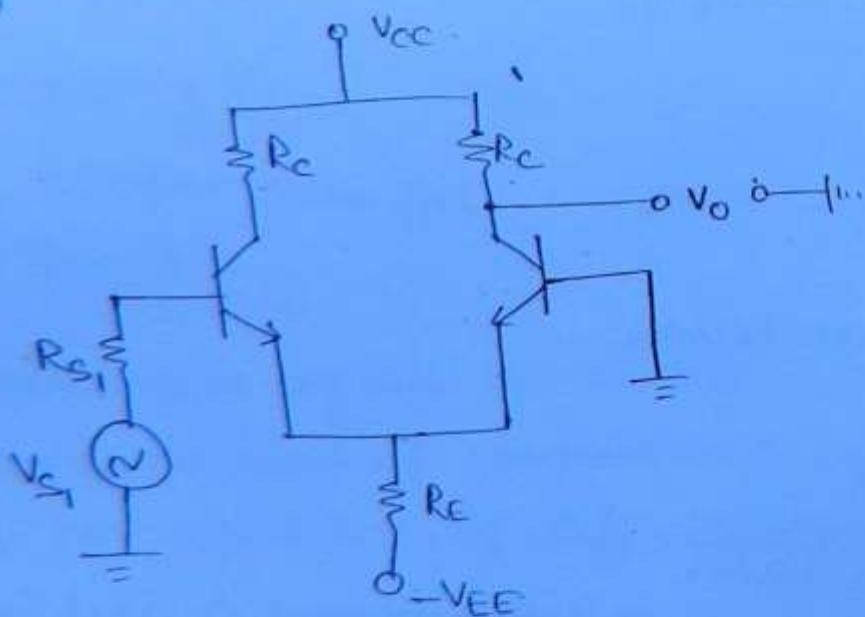
Circuit diagrams →

(264)

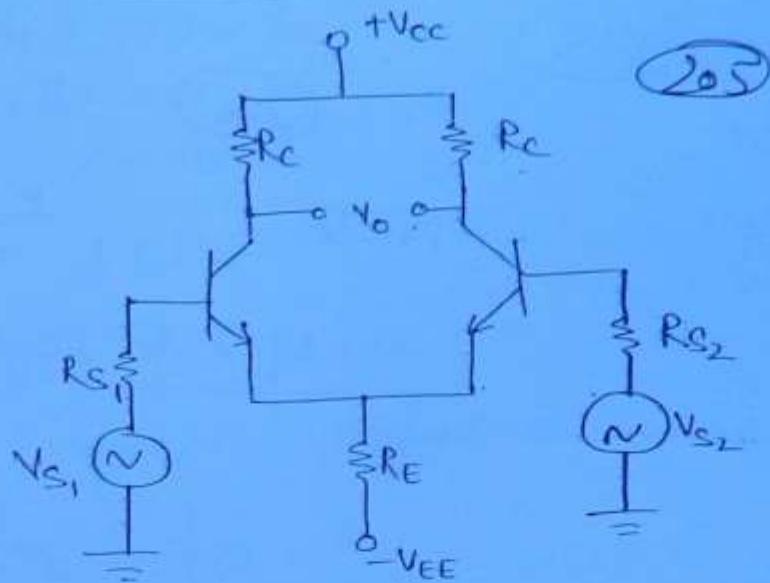
Single EIP balanced O/P →



Single EIP Unbalanced O/P →

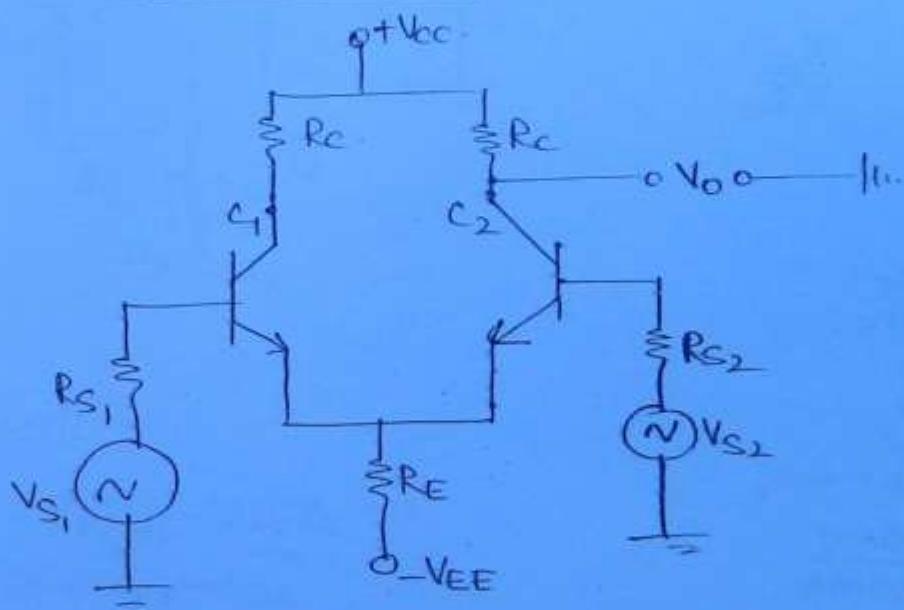


Dual D/P Balanced O/P



(205)

Dual D/P unbalanced O/P



Problems →

- 1) Cal. Voltage gain of a single D/P balanced O/P or dual D/P balanced O/P differential amplifier CKT with $R_C = 1K\Omega$ and $I_E = 26mA$.
- 2) Cal. Voltage gain for a single D/P or unbalanced O/P or dual D/P unbalanced O/P differential amplifier CKT with $R_C = 1K\Omega$ and $I_E = 26mA$.
- 3) Cal. D/P impedance of a differential amplifier CKT with $R_{DC} = 50$, $I_E = 26mA$.

What is the impedance of a common collector with $R_C = 1\text{ k}\Omega$

Single DIP
balanced O/P

A_V

$$\frac{R_C}{r_e}$$

R_i

(206)

R_o

$$2\beta_{ac} r_e$$

$$R_C$$

Single DIP
Unbalanced O/P

$$\frac{1}{2} \frac{R_C}{r_e}$$

" "

$$R_C$$

Dual DIP
balanced O/P

$$\frac{R_C}{r_e}$$

"

"

Dual DIP
Unbalanced O/P

$$\frac{R_C}{2r_e}$$

"

"

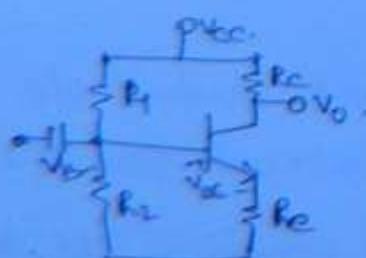
Answers →

$$1) A_V = \frac{R_C}{r_e}$$

$$\begin{aligned} r_e &= \frac{V_T}{I_E \rightarrow dc} \\ &= \frac{26\text{mV}}{26\text{mA}} \\ &= 1\text{ }\Omega \end{aligned}$$

$$R_C = 1\text{ k}\Omega$$

$$A_V = \frac{1\text{ k}\Omega}{1\text{ }\Omega} = 1000 \quad \rightarrow \text{for both O/P}$$



$$\rightarrow A_V = \frac{R_C}{R_E} = \frac{R_C \cdot R_E}{V_T}$$

$$V_{BE} = \frac{R_2}{R_1 + R_2} V_{CC} \quad I_E = \frac{V_{CC} - V_{BE}}{R_2 + R_E}$$

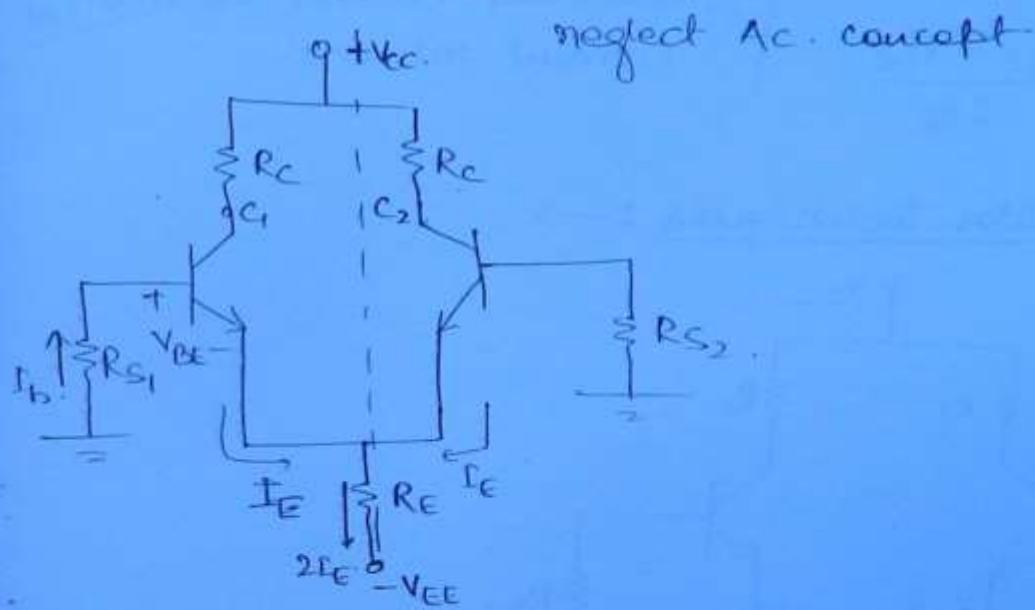
$$2) V_V = 500\text{V}$$

$$3) R_i = 2 \beta_{ac} \cdot r_e \\ = 2 \times 100 \times 1 \\ = 100 \Omega$$

(267)

$$4) R_o = 1 \text{ k}\Omega$$

Calculation of Q-pt: →



Q₁

IIP loop →

$$V_{EE} - I_b R_{S1} - 2 I_E R_E = 0$$

$$I_E = \frac{V_{EE} - V_{BE}}{2 R_E + \frac{R_{S1}}{1 + \beta}}$$

$1 + \beta \gg R_{S1}$

$$I_E = \frac{V_{EE} - V_{BE}}{2 R_E}$$

$$(V_{CE})_Q = V_{CC} - (I_c)_Q R_C + V_{BE}$$

$$(I_c)_Q = I_E = \frac{V_{EE} - V_{BE}}{2 R_E}$$

$$(V_{CE})_Q = V_C - V_E$$

$$V_C = V_{CC} - (I_c)_Q R_C \Rightarrow V_E = -V_{BE}$$

Swamping phenomena in common emitter configuration

⇒ $\text{Av} = \frac{R_C}{r_{\text{ce}}} \rightarrow \text{gain is not stable.}$

⇒ $R_C = 2\text{PA}_m^2 \times 10^{-3} = 2 \times 80 \times 10^{-3} \rightarrow 160 \Omega$

Rectify techniques
swamping
resistor techniques

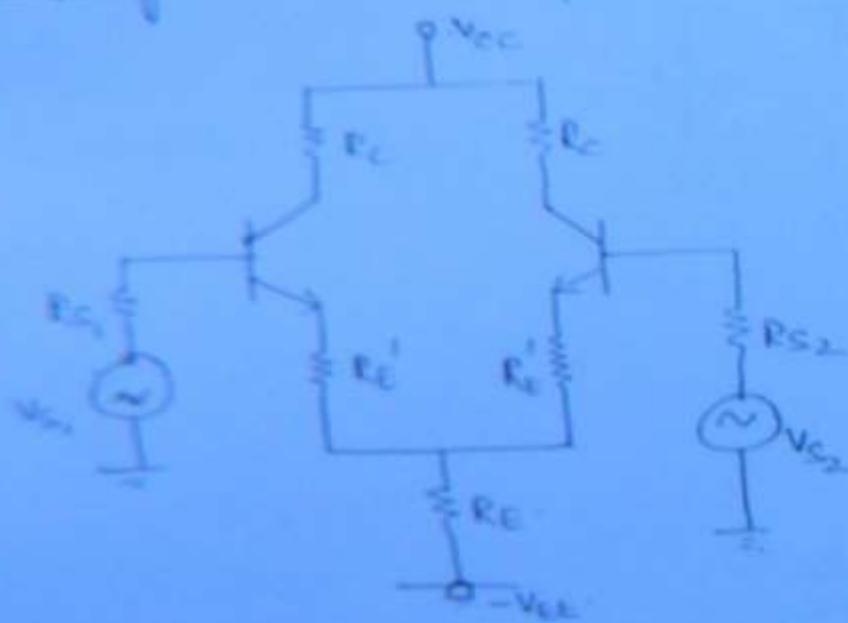
(208)

⇒ $\eta(V_{CE}, V_{BE})$

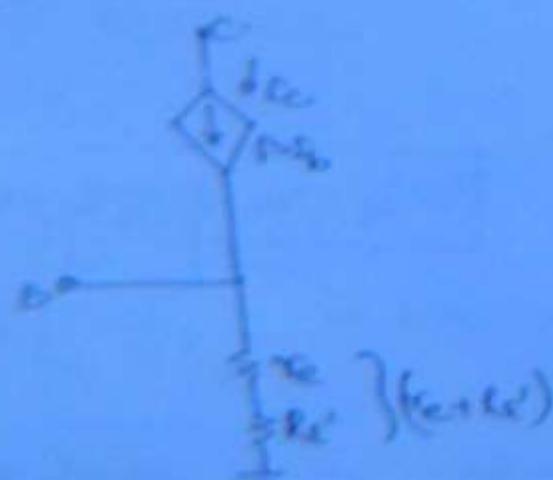
$$r_E = \frac{V_{CE} - V_{BE}}{2\text{A}_m}$$

Rectify techniques
constant current source
current mirror.

Swamping resistor techniques : →



z_o model



$$\text{Av} = \frac{R_C}{r_{\text{ce}}}$$

↓ swamping

$$\text{Av} = \frac{R_C}{r_{\text{ce}} + R_E'}$$

$$= \frac{R_C}{R_E'} \quad R_E' \gg r_{\text{ce}}$$

→ gain is stable.

$R_t = 4R_{ac}^2 R_o$

↳ jumping

$$R_t = 2R_{ac}(R_o + R_C')$$

(209)

Assume $R_C' = 100K$.

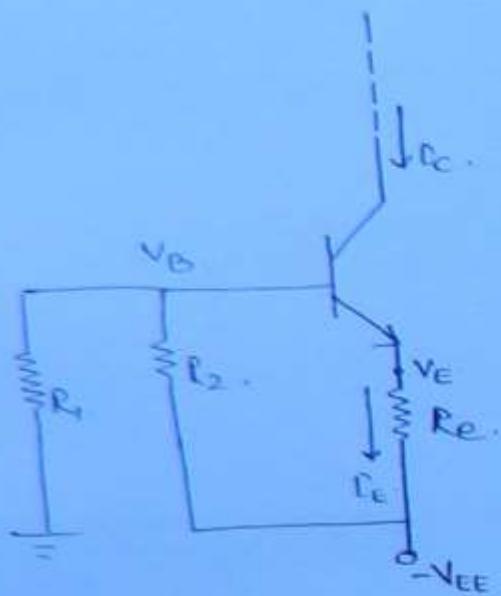
$$R_t = 2 \times 50 \times 100K$$

$\approx 10 M\Omega$.

6/11/12

Current source source \rightarrow

Ckt 2



(210)

$$I_E = \frac{V_E - (-V_{EE})}{R_E}$$

$$V_E = V_B - V_{BE}$$

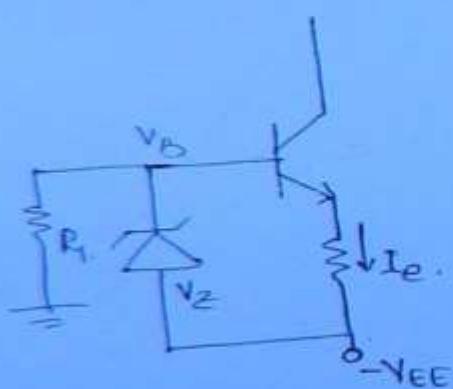
$$V_B = \frac{-V_{EE} \times R_1}{R_1 + R_2}$$

$$I_E = \frac{V_B - V_{BE} + V_{EE}}{R_E}$$

↓

The main drawback is I_E is depending on V_{EE} supply

Ckt 3



$$I_E = \frac{V_Z - V_{EE} - V_{BE} + V_{EE}}{R_E}$$

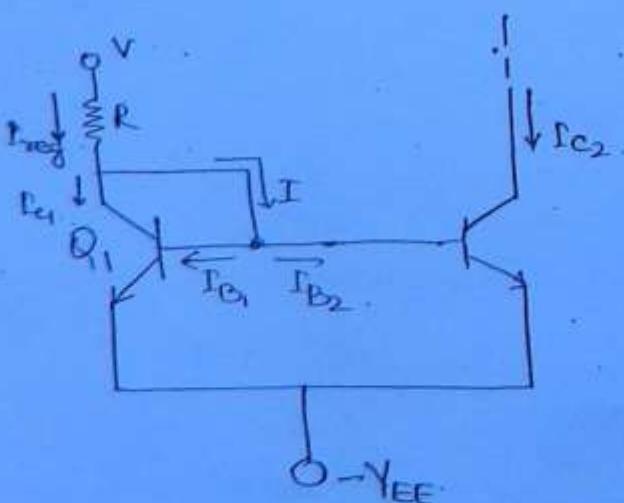
$$V_B = V_Z - V_{EE}$$

Current mirror \rightarrow

Ckt 1

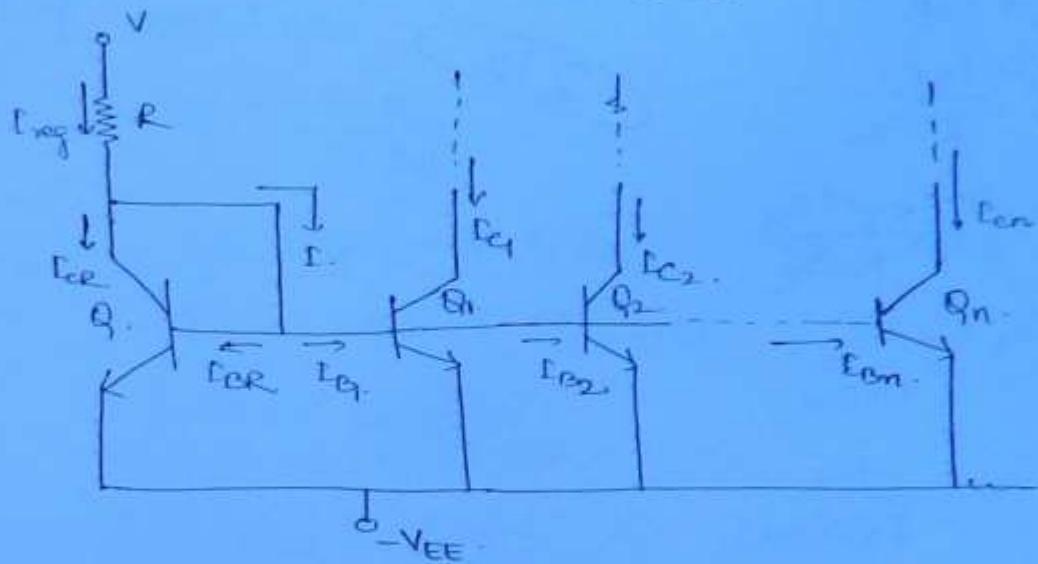
$$\begin{aligned} I_{\text{req}} &= I_{C_1} + I \\ &= I_{Q_1} + I_{B_1} + I_{B_2} \\ &= I_{C_2} + 2I_{B_2} \\ &= I_{C_2} + 2 \frac{I_{C_2}}{\beta} \\ &= I_{C_2} \left[1 + \frac{2}{\beta} \right] \end{aligned}$$

$$I_{C_2} = \frac{I_{\text{req}}}{1 + \frac{2}{\beta}}$$



n Stage \rightarrow CKT2.

(21)



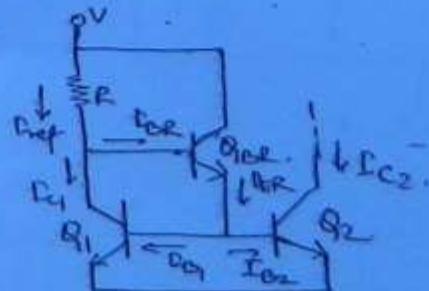
$$I_{C1} = I_{C2} = \dots = I_{Cn} = I_{CR} \\ = I_{Ci} \quad (i = 1, 2, 3, \dots, n).$$

$$I_{BR} = I_{B1} = I_{B2} = \dots = I_{Bn} = I_{Bi}$$

$$\begin{aligned} I_{in} &= I_{CR} + I_B \\ &= I_{CR} (I_{BR} + I_{B1} + I_{B2} + \dots + I_{Bn}) \\ &= I_{CR} + I_{BR} (1+N) \\ &\approx I_{CR} + \frac{I_{CR}}{\beta} (1+N) \\ &= I_{CR} \left[1 + \frac{1+N}{\beta} \right] \end{aligned}$$

$$I_{CR} = \frac{I_{in}}{1 + \frac{1+N}{\beta}} \quad N \text{ should be less for less bias.}$$

CKT3 \rightarrow



$$\begin{aligned}
 I_{\text{ref}} &= I_{C1} + I_{C2} \\
 &= I_{C1} + \frac{I_{C1}}{1+\beta_R} \\
 &= I_{C2} + \frac{I_{C1} + I_{B2}}{1+\beta_R} \\
 &= I_{C2} + \frac{2I_{B2}}{1+\beta_R} \\
 &= I_{C2} + \frac{2I_{C2}}{\beta(1+\beta_R)}
 \end{aligned}$$

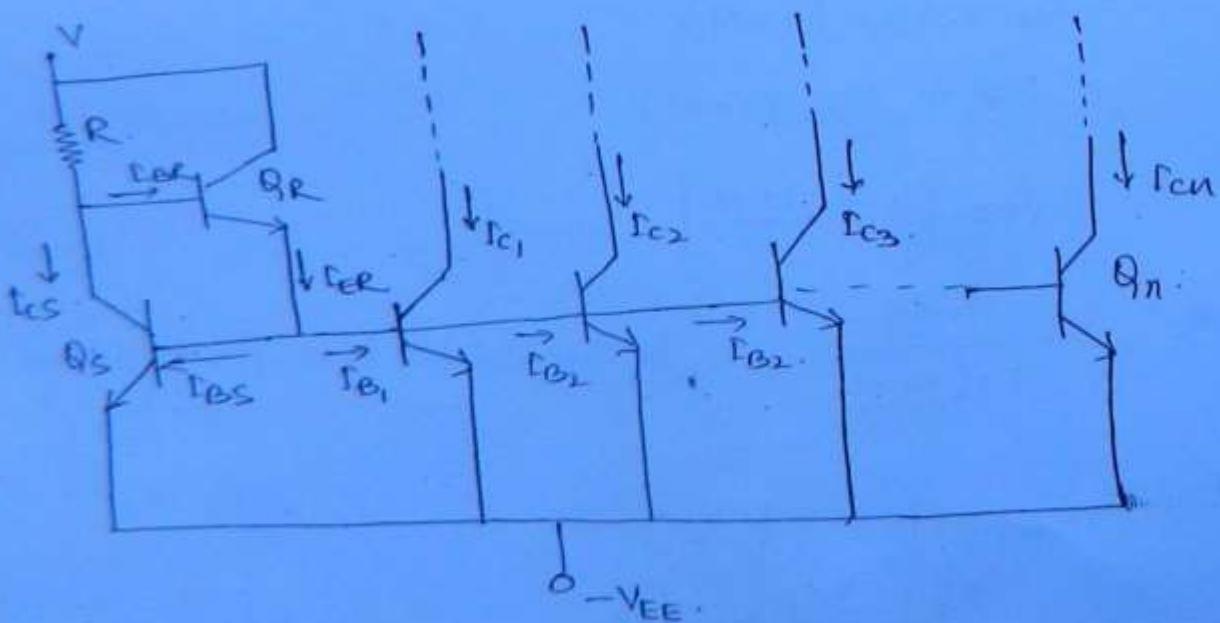
2/2

$$I_{C2} = \frac{I_{\text{ref}}}{1 + \frac{2}{\beta(1+\beta_R)}}$$

$$I_{C2} \approx I_{\text{ref}}$$

as $\beta(1+\beta_R) \gg 2$

n Stage \rightarrow (CKT-4)



$$\begin{aligned}
 I_{C1} = I_{C2} = \dots &= I_{Cn} = I_{CS} \\
 &= \frac{I_{C1}}{\beta} \\
 I_{BS} = I_{B1} = I_{B2} = \dots &= I_{Bn}
 \end{aligned}$$

$$I_{ref} = I_{C3} + I_{BR}$$

(213)

$$= I_{C3} + \frac{I_{ER}}{1 + \beta_R}$$

$$= I_{C3} + (I_{BS} + I_{B1} + I_{B2} + \dots + I_{Bn}) / 1 + \beta_R$$

$$= I_{C3} + I_{BS} (1 + N) / 1 + \beta_R$$

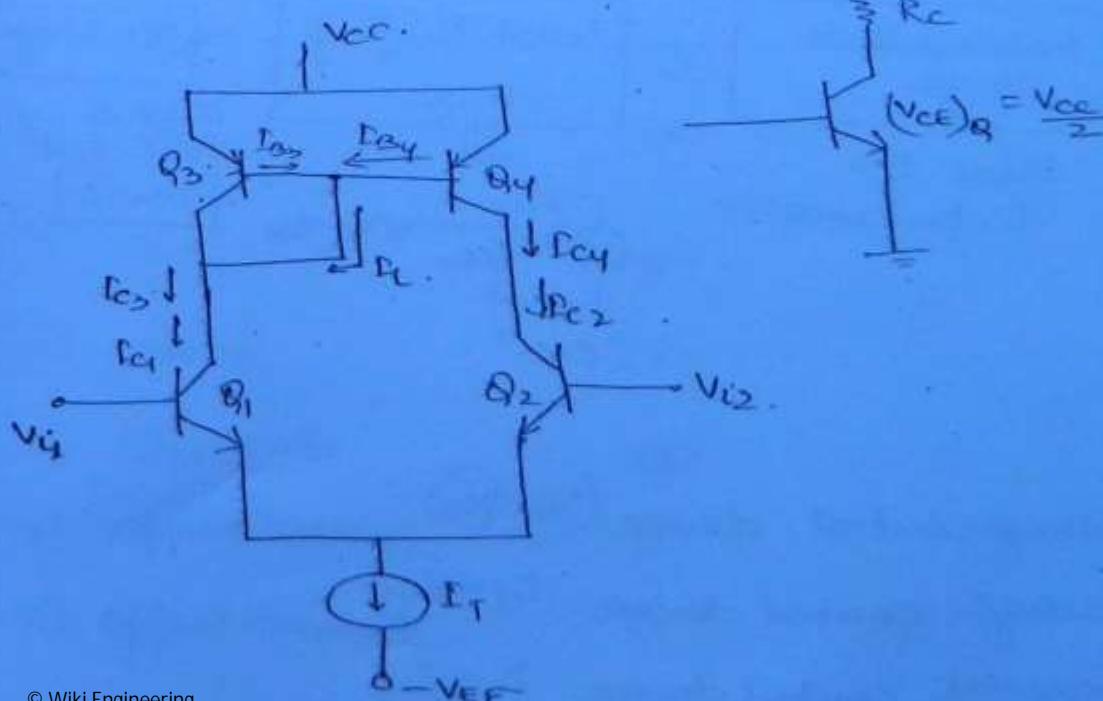
$$= I_{C3} + \frac{I_{CS}(1+N)}{\beta(1+\beta_R)}$$

$$= I_{C2} \left[1 + \frac{1+N}{\beta(1+\beta_R)} \right]$$

$$I_{C2} = \frac{I_{ref}}{1 + (1+N) \beta(1+\beta_R)}$$

Active load in differential amplifiers →

$$\uparrow A_d = \frac{R_C \uparrow}{r_e}$$



Assume N_1, N_2, N_3, N_4 are identical.

$$\begin{aligned}I_c &= I_{B3} + I_{B4} \\&= \frac{1}{\beta} (I_{C3} + I_{C4}) \\&= \frac{1}{\beta} (I_{C1} + I_{C2}) \\&= \frac{1}{\beta} I_T \approx 0.\end{aligned}$$

(214)

Active load = ∞

$$CMRR \uparrow = \frac{A_d \uparrow}{A_c}$$

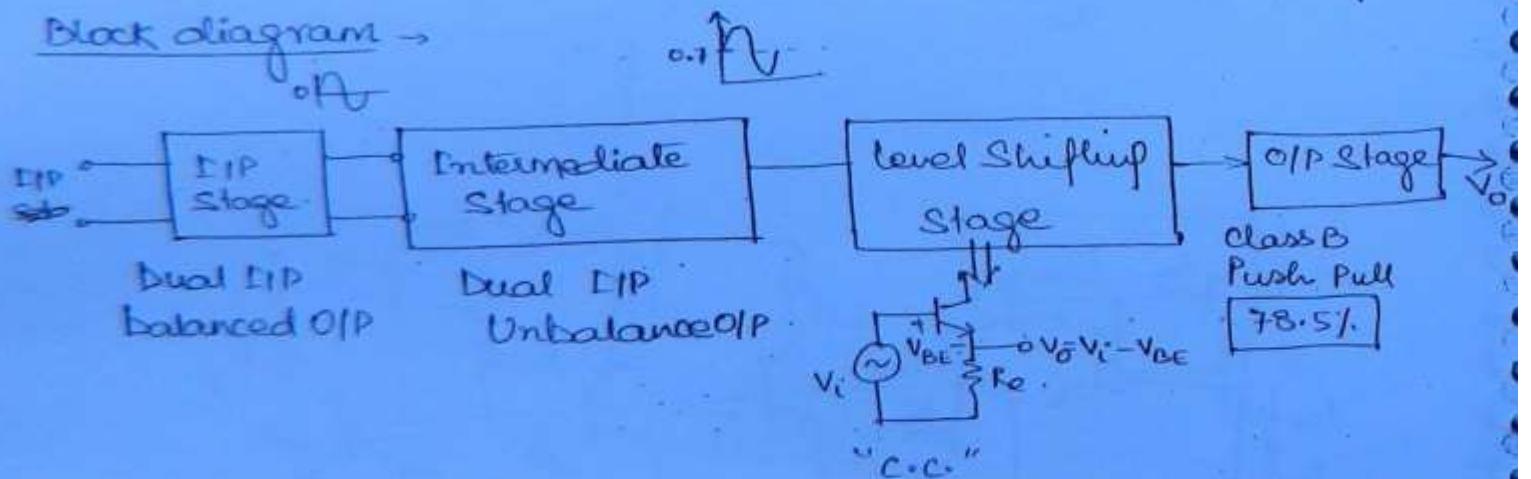
Active loads are used in differential amplifiers to improve

1) Differential gain A_d .

2) CMRR (common mode rejection ratio)

$$= \frac{A_d}{A_c}$$

OPAMP \rightarrow



Imp pts \rightarrow

- 1) Opamp is a voltage control device ($V_o \propto V_d$)
- 2) FET is a voltage control device ($I_d \propto V_{ds}$)
- 3) BJT is a current control device ($I_c \propto I_b$)

$I_{D, P}$

II Match 1

2) V_{CS} VS ...

3) V_{CS} ...

I_{CS} VS ...

1) I_{CS}

(215)

Match 2.

1) BIT

2) Opamp

3) FET.

III Increasing order of $Z_i \rightarrow$

BIT, opamp, FET, MOSFET.

Typical Values →

BIT → 1 K Ω

OPAMP → 10 6 Ω

FET → 10 7 to 10 10

MOSFET → 10 11 to 10 14 Ω

Characteristics of OP-AMP: →

Characteristics	Ideal	Practical
1) Z_i	∞	10 6
2) Z_o	0.	100 Ω
3) A_v	∞	10 6
4) B_w	∞	10 6 Hz
5) CMRR	∞	10 6 or 120 dB
6) Slew rate	∞	80 V/ μ s
7) Offset voltage	0	min
8) Offset current	0	min

UNIQUENESS →

$$CMRR = \frac{A_d}{A_c}$$

(216)

$$(CMRR)_{dB} = 20 \log \left(\frac{A_d}{A_c} \right)$$



If it is a linear rc. so, superposition theorem is applied.

$$V_0 \propto V_d$$

$$V_0 = A_1 V_1 + A_2 V_2 \quad \text{--- (1)}$$

$$V_d = V_2 - V_1$$

$$V_c = \frac{V_1 + V_2}{2}$$

$$2V_c = V_1 + V_2$$

$$V_1 = V_c + V_d/2$$

$$V_2 = V_c - V_d/2$$

Substitute in eq: (1)

$$V_0 = A_1 (V_c + V_d/2) + A_2 (V_c - V_d/2)$$

$$= (A_1 + A_2)V_c + \left(\frac{A_1 - A_2}{2} \right) V_d$$

$$\downarrow \\ A_c$$

$$\downarrow \\ A_d$$

$$V_0 = A_c V_c + A_d V_d$$

$$V_0 = A_d V_d \left[1 + \frac{A_c}{A_d} \frac{V_c}{V_d} \right]$$

$$\frac{A_c}{A_d} \rightarrow \frac{1}{CMRR}$$

Q. A differential Amplifier has E/P $V_1 = 1050 \text{ mV}$, $V_2 = 950 \text{ mV}$.

$$\text{CMRR} = 1000$$

$$\text{diff. error O/P} = ?$$

(217)

$$A_m = \frac{1}{1000} \times \frac{V_c}{V_d}$$

$$V_1 = V_c + V_d/2$$

$$1050 = V_c + V_d/2$$

$$950 = V_c - V_d/2$$

$$2V_c = 2000$$

$$V_c = 1000$$

$$V_d = 50 \times 2 \\ = 100$$

~~1000 \times 100~~

$$\text{diff. error O/P} = \frac{1}{1000} \times \frac{1000}{100} \times 100 = 1\%$$

SLEW RATE \rightarrow

$$SR = \left. \frac{dV_o}{dt} \right|_{\mu s}$$

$$= \frac{\Delta V_o}{\Delta V_i} \frac{\Delta V_i}{\Delta t}$$

$$S.R. = A_{cl} \frac{\Delta V_i}{\Delta t}$$



$$\omega_{map} = \frac{S.R.}{K} = \frac{S.R.}{A_{cl} \Delta V_i}$$

$$f_{map} = \frac{S.R.}{2\pi A_{cl} \Delta V_i}$$

$$f_{map} = \frac{S.R.}{K}$$

$\omega_{input} < \omega_{map} \rightarrow \text{O/P will be replica of I/P}$

$\omega_{input} > \omega_{map} \rightarrow \text{O/P will be distorted}$

It is a measure of maximum voltage error in op-amp.

OFF SET:

218



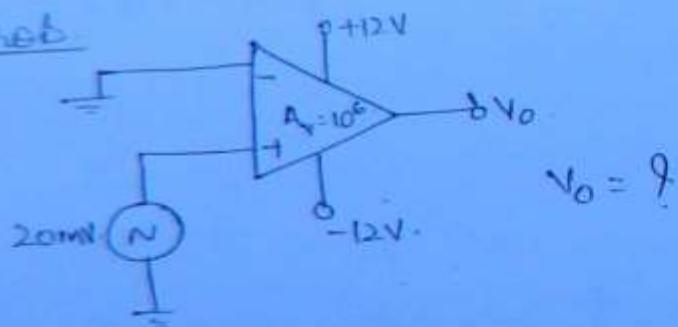
$$V_{IO} = V_D - V_A$$

↓
O/P offset Voltage.

used to make $V_O = 0$

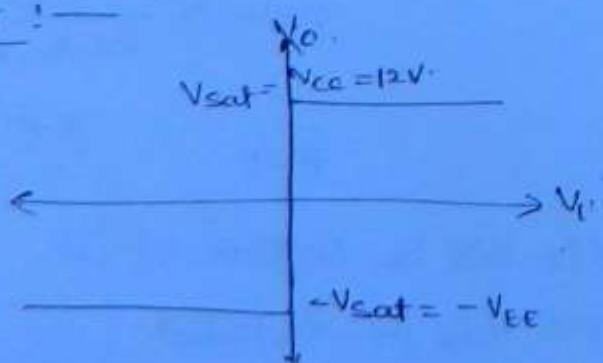
w/o giving any I/P to the terminals of the opamp, output is not 0 [small magnitude] the reason is I/P stage is differential amplifier where the two transistors should be identical. Practically it is not possible. To make the O/P V_O to 0 we use offset condition at the I/P of the OPAMP.

Prob.



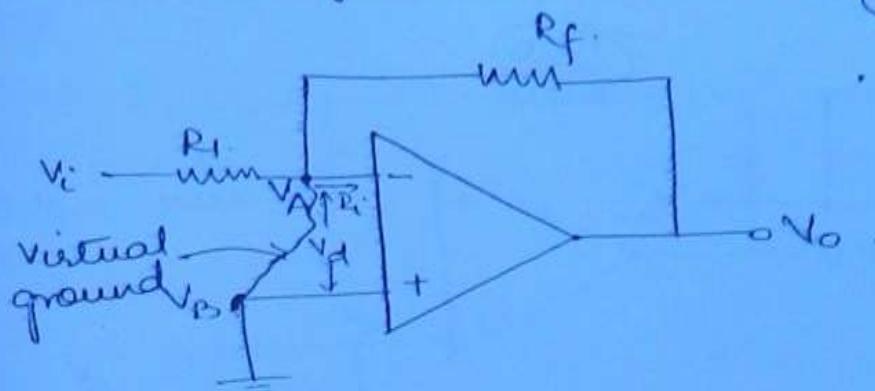
$V_O = 12V$ irrespective of supply because $+12V$ and $-12V$ is the sat value of this opamp.

transfer char:



Voltage source :-

(219)



$$V_d = V_B - V_A$$

Ideal →

$$R_i \rightarrow \infty$$

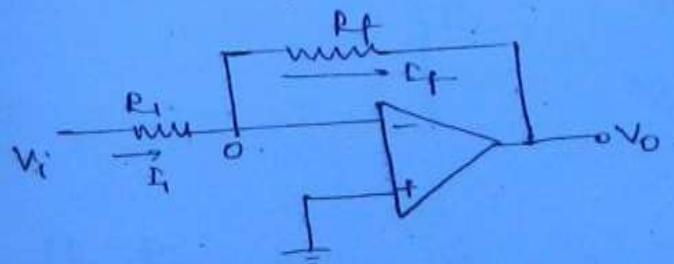
$$I_i \rightarrow 0$$

$$V_d \rightarrow 0$$

$$0 = V_B - V_A$$

$$\Rightarrow V_B = V_A$$

Inverting Amplifier →



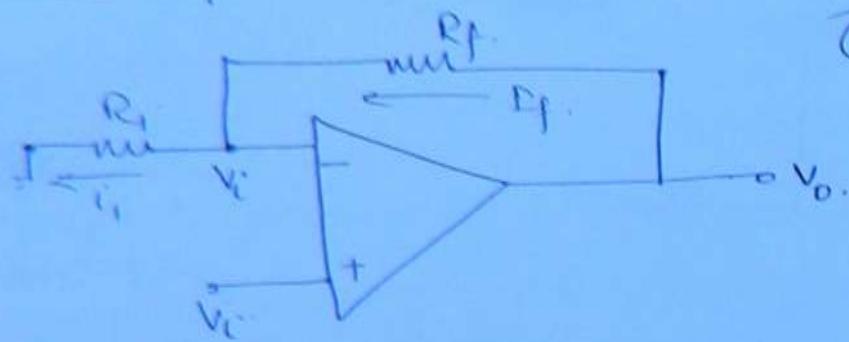
$$D_1 = D_f$$

$$\frac{V_i - 0}{R_i} = \frac{0 - V_o}{R_f}$$

$$\frac{V_o}{V_i} = -\frac{R_f}{R_i}$$

Non inverting amplifier

(220)

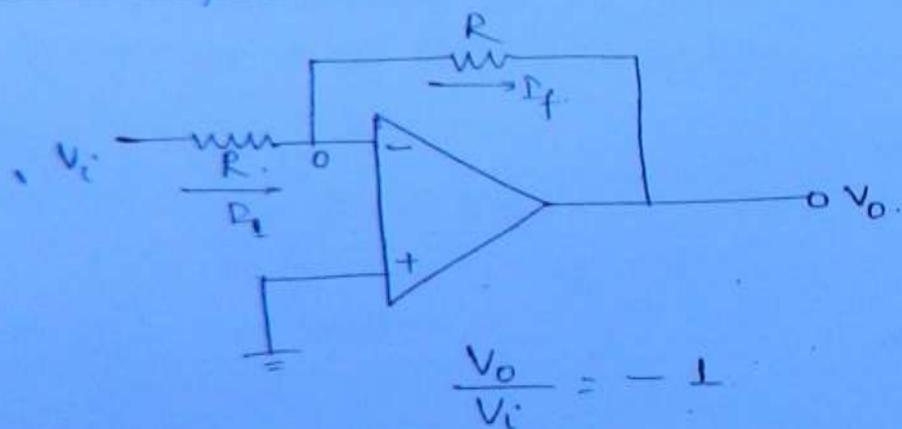


$$R_f = R_i$$

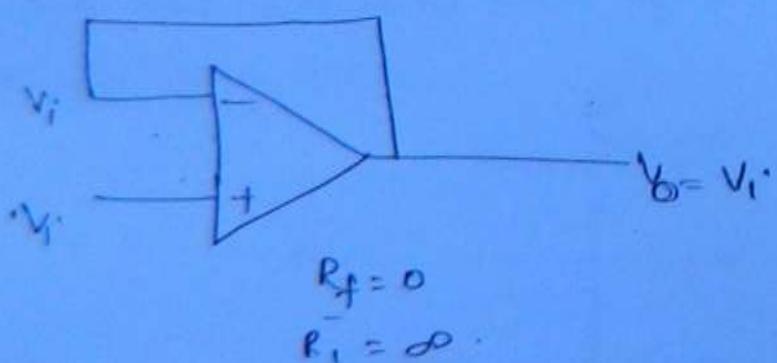
$$\frac{V_o - V_{o,i}}{R_f} = \frac{V_o - 0}{R_i}$$

$$\Rightarrow \boxed{\frac{V_o}{V_i} = 1 + \frac{R_f}{R_i}}$$

Phase shifter →

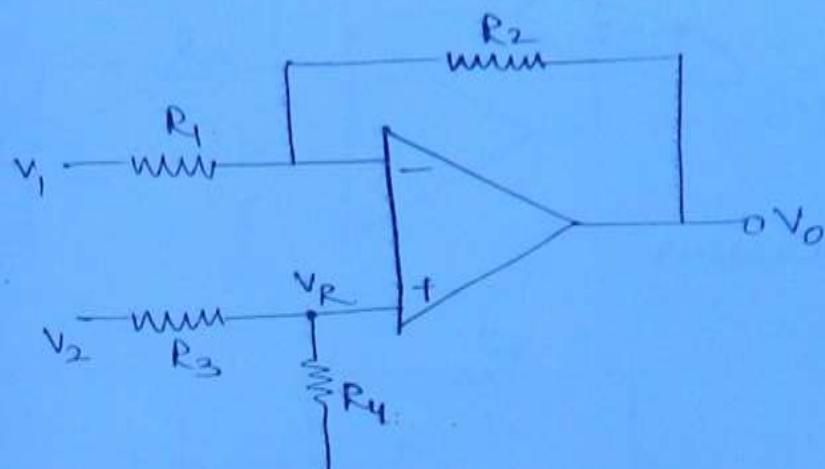


Voltage follower →



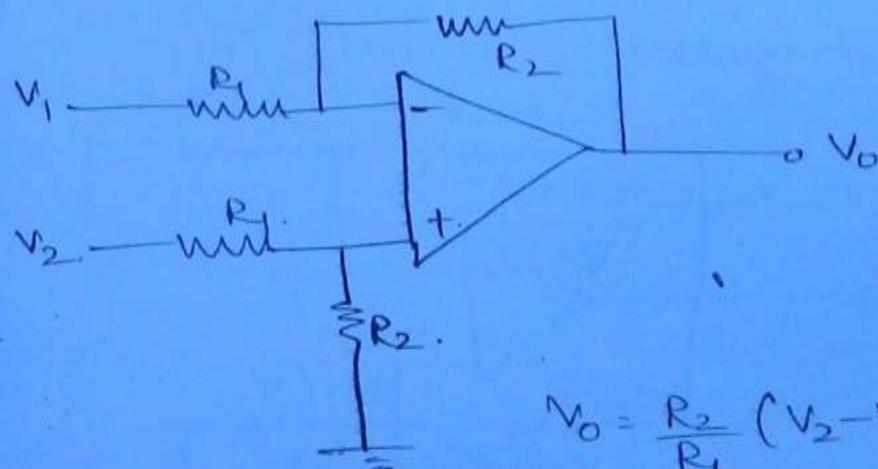
Differential Amplifier →

(Q21)



$$V_0 = -\frac{R_2}{R_1} V_1 + \left(1 + \frac{R_2}{R_1}\right) V_R$$

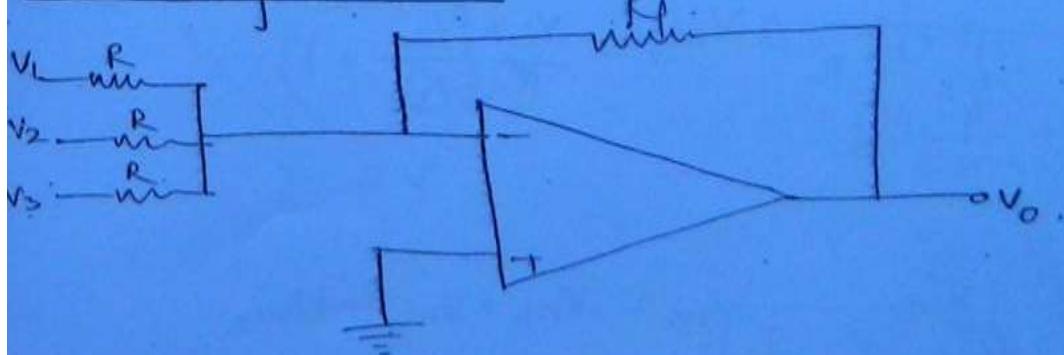
$$V_R = \frac{V_2 \times R_4}{R_3 + R_4}$$



$$V_0 = \frac{R_2}{R_1} (V_2 - V_1)$$

if $R_2 = R_1$, $V_0 = V_2 - V_1 \rightarrow \text{Subtractor.}$

Inverting adder →



$$\Gamma = \Gamma_f$$

$$\Gamma_1 + \Gamma_2 + \Gamma_3 = \Gamma_f$$

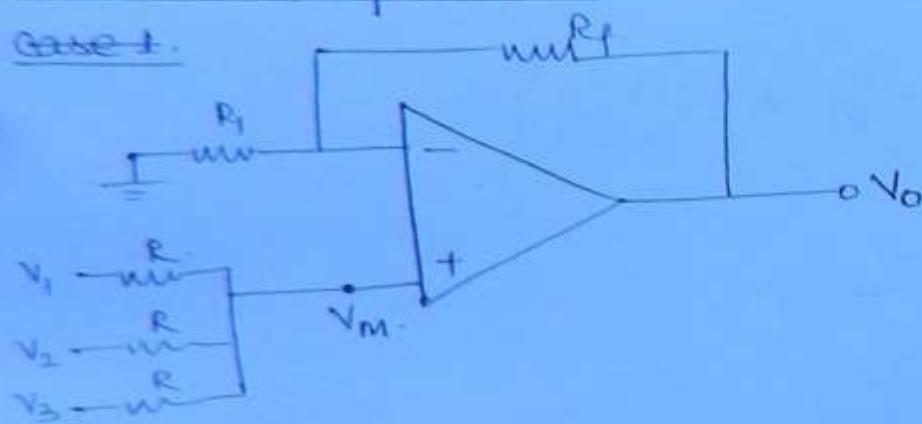
$$\Rightarrow \frac{(V_1 + V_2 + V_3)}{R} = -\frac{V_o}{R_f}$$

$$\Rightarrow V_o = -(V_1 + V_2 + V_3)$$

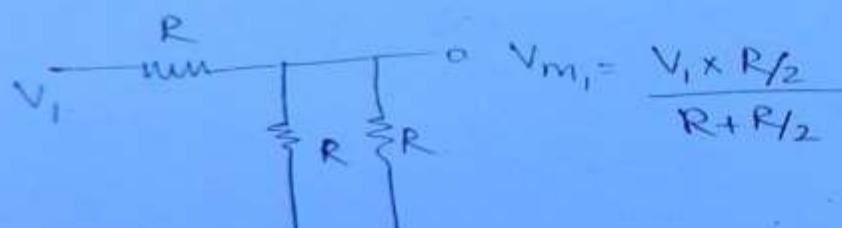
(222)

New inverting adder:

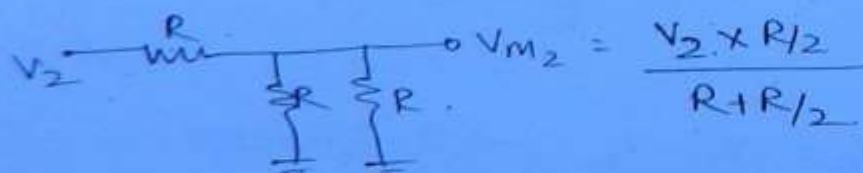
Case 1.



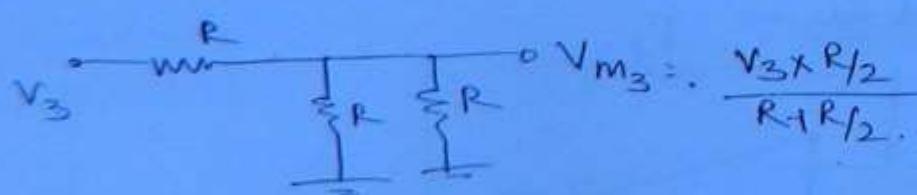
Case 1



Case 2

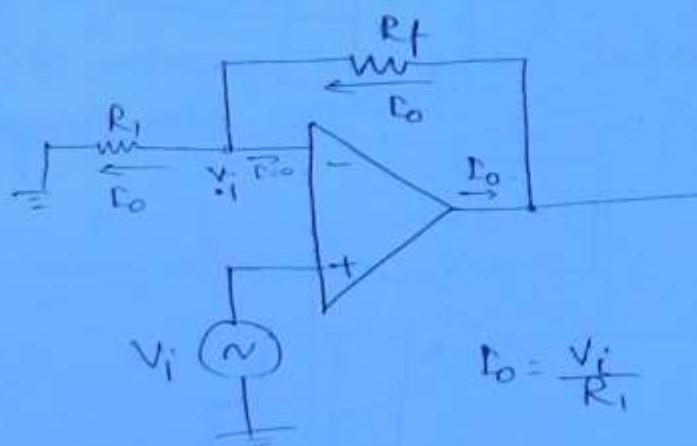
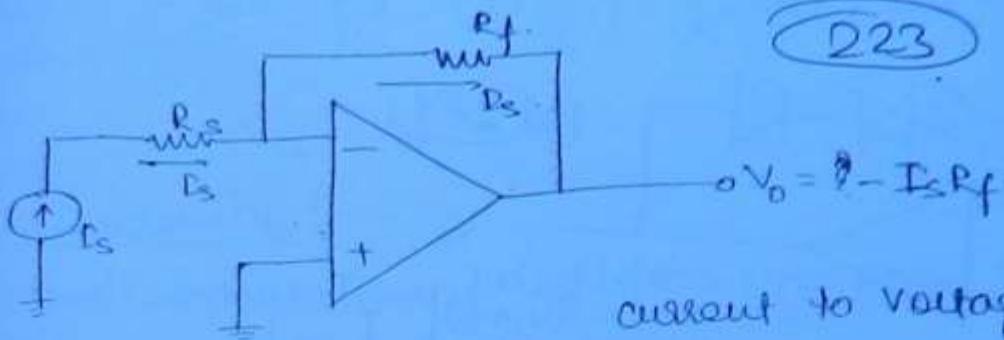


Case 3

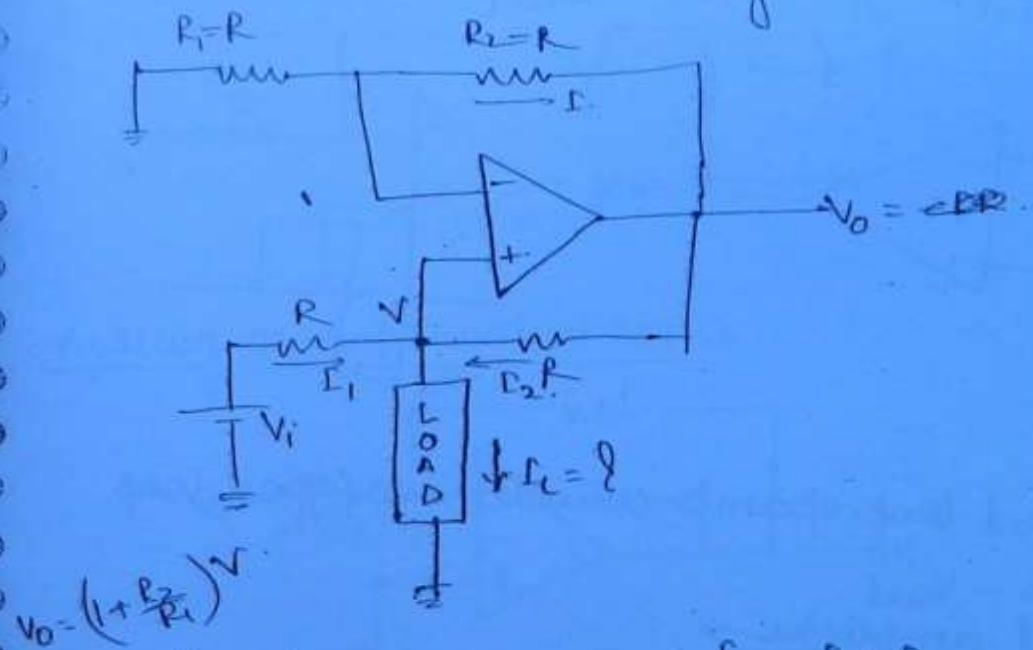


$$V_o = \left(1 + \frac{R_f}{R_1}\right) V_m$$

$$V_m = V_{m1} + V_{m2} + V_{m3}$$



Voltage to current converter



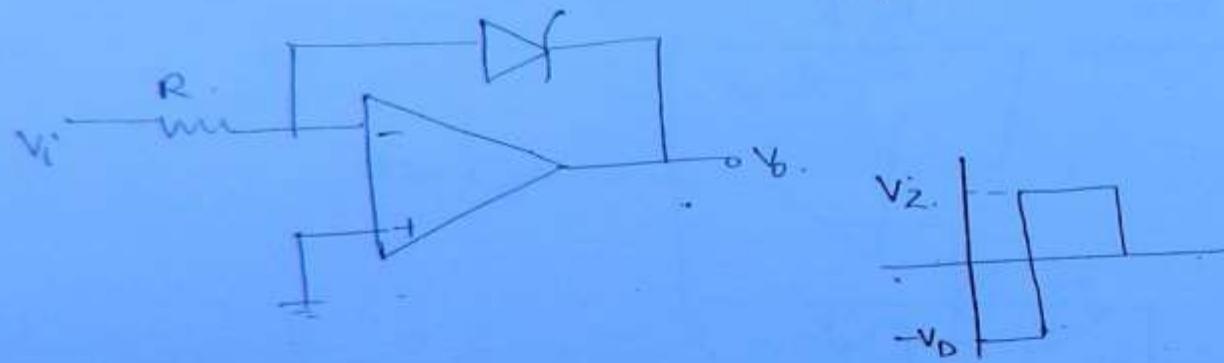
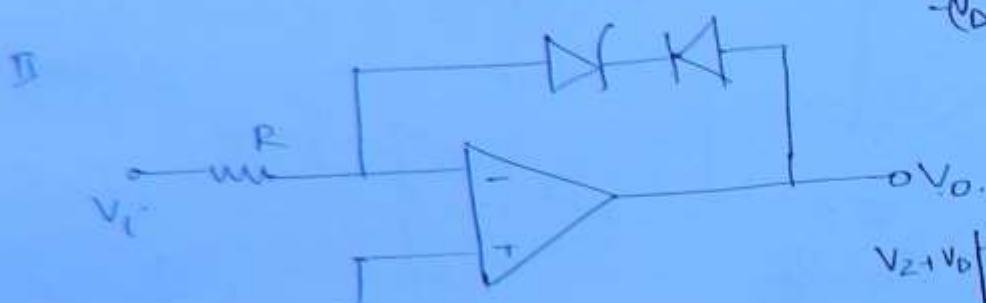
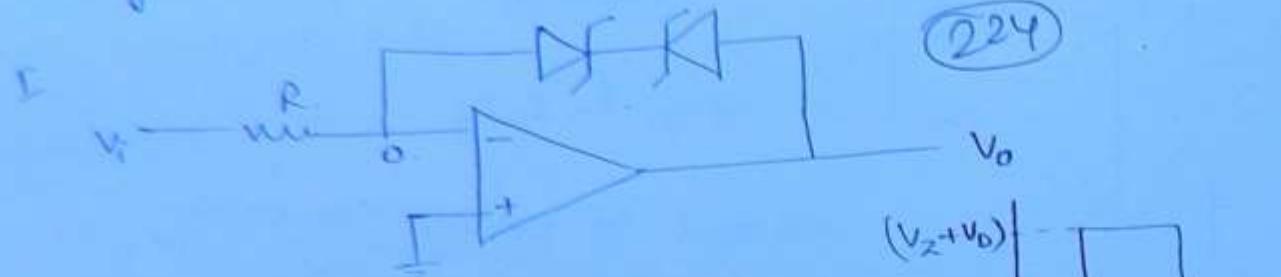
$$V_o = \left(1 + \frac{R_2}{R_1}\right) V$$

$$= 2V$$

$$\begin{aligned} I_L &= I_1 + I_2 \\ &= \frac{V_i - V}{R} + \frac{V_o - V}{R} \\ &= \frac{V_i - V}{R} + \frac{2V - V}{R} \end{aligned}$$

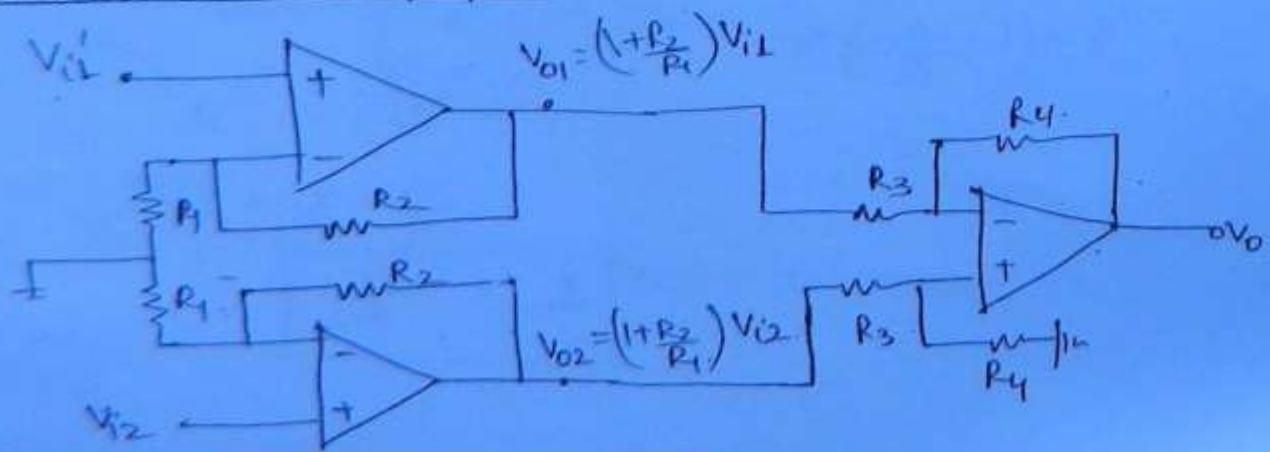
$I_L = \frac{V_L}{R}$

voltage limiters



whenever a closed loop opamp converts into open loop
Op will be $+V_{sat}$ or $-V_{sat}$

Instrumentational amplifier →



$$-V_o = \frac{R_4}{R_3} \left(1 + \frac{R_2}{R_1}\right) (V_{i2} - V_{i1})$$

$$V_{i2} - V_{i1} = V_d$$

(225)

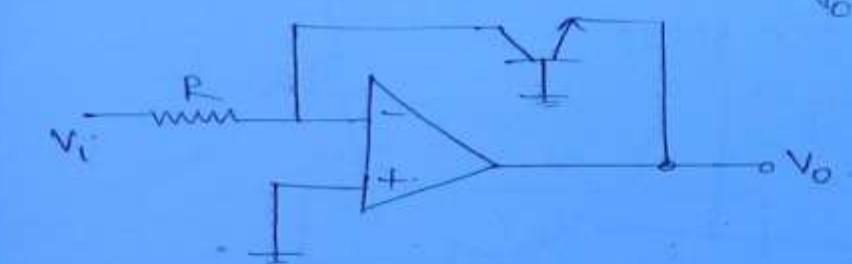
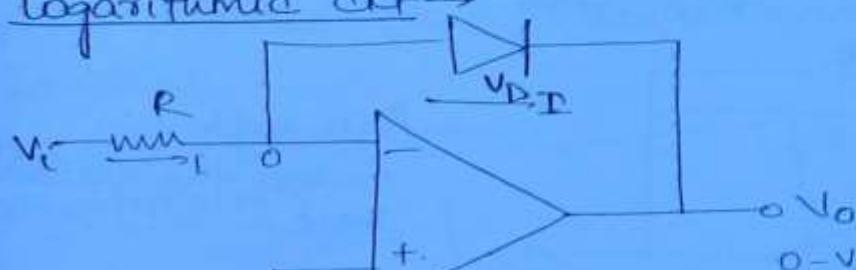
Conclusion:

Instrumentational amplifiers are used to improve

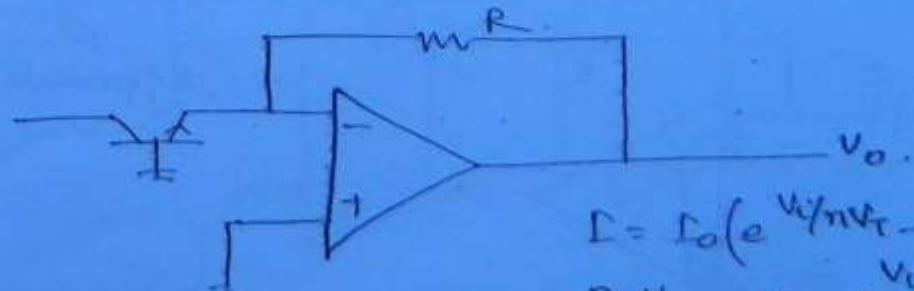
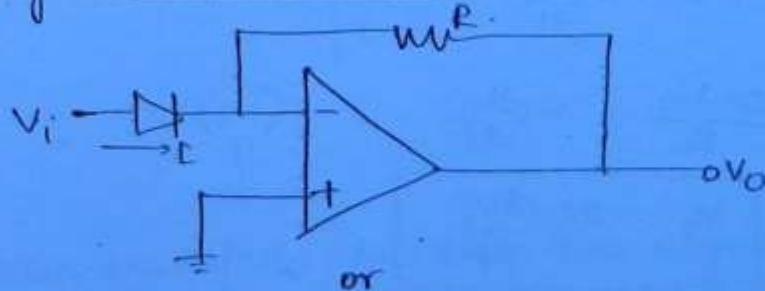
1) Differential voltage gain.

2) to improve the input impedance of differential amplifier

Logarithmic circuit →



Antilog or exponential circuit →



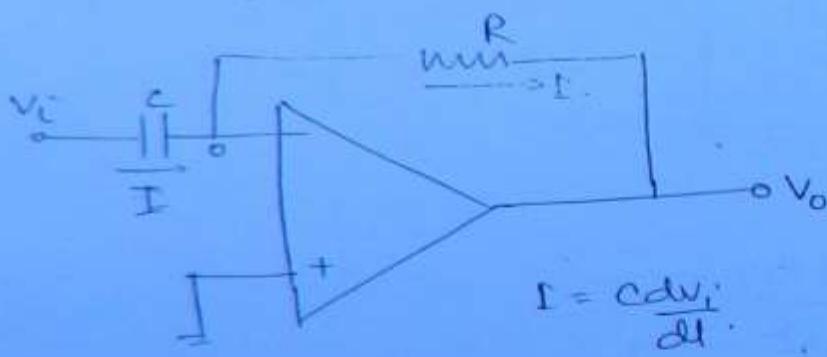
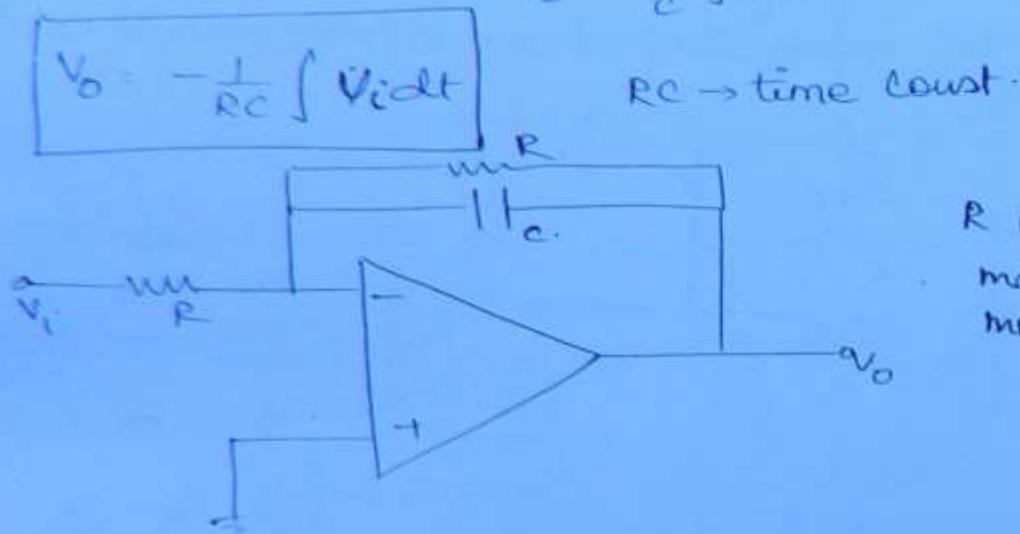
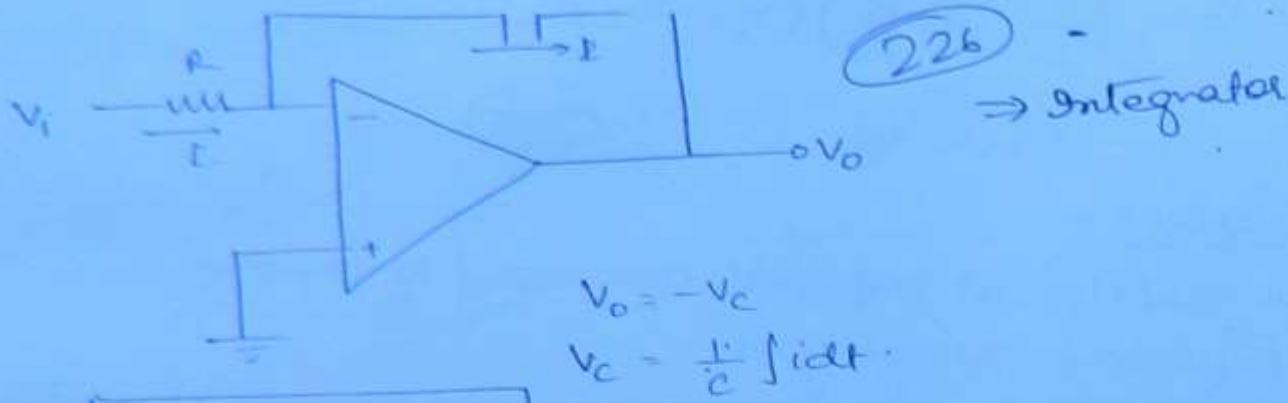
$$E = E_0 (e^{V_D/nV_T - 1})$$

But FB,

$$V_D = nV_T \ln\left(\frac{E}{E_0}\right)$$

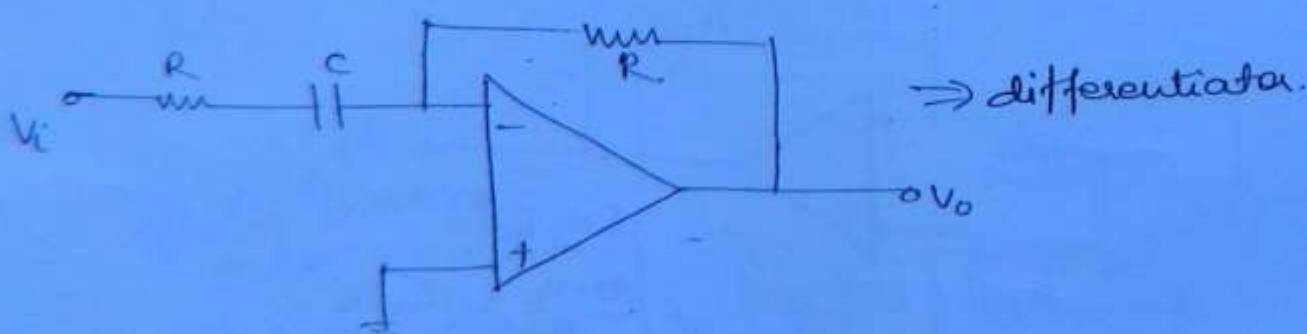
$$V_D = nV_T \ln\left(\frac{E_0 R}{V_i}\right) \quad E_0 = \frac{V_i}{R}$$

$$\begin{aligned} E &= E_0 (e^{V_D/nV_T - 1}) \\ \frac{E - E_0}{E_0} &= E_0 e^{-V_D/nV_T} \\ E_0 &= -E_0 R e^{-V_D/nV_T} \end{aligned}$$



$$\frac{dV_o}{dt} = C dV_i / dt$$

$$\Rightarrow V_o = -R C \frac{dV_i}{dt}$$



Integrator →

(227)

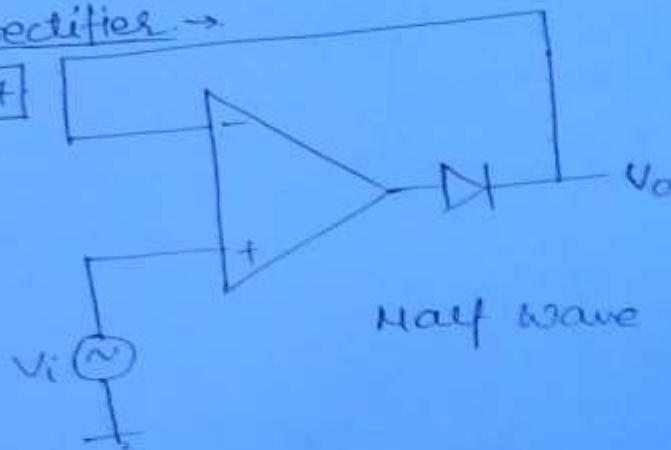
For practical Integrator, we take resistor shunt to the capacitor because at low freq, capacitor becomes O.C. which make the opamp to work in open loop system.

Differentiator:-

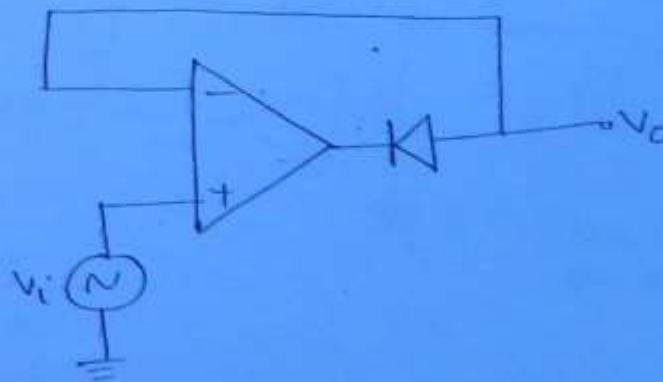
At the I/P resistor is in the series with the capacitor because at high freq capacitor acts as a S.C. High current flow through the device which creates a problem.

Precision rectifier →

when $V_i < 0.7$

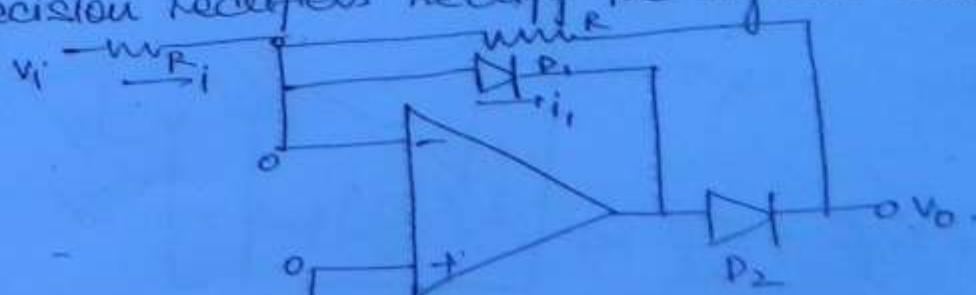


for the half cycle,
D is FB.



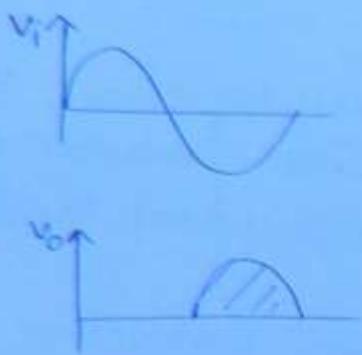
for -ive half cycle,
D is R.B.

Precision rectifiers rectify the signals below 0.7 Volts.

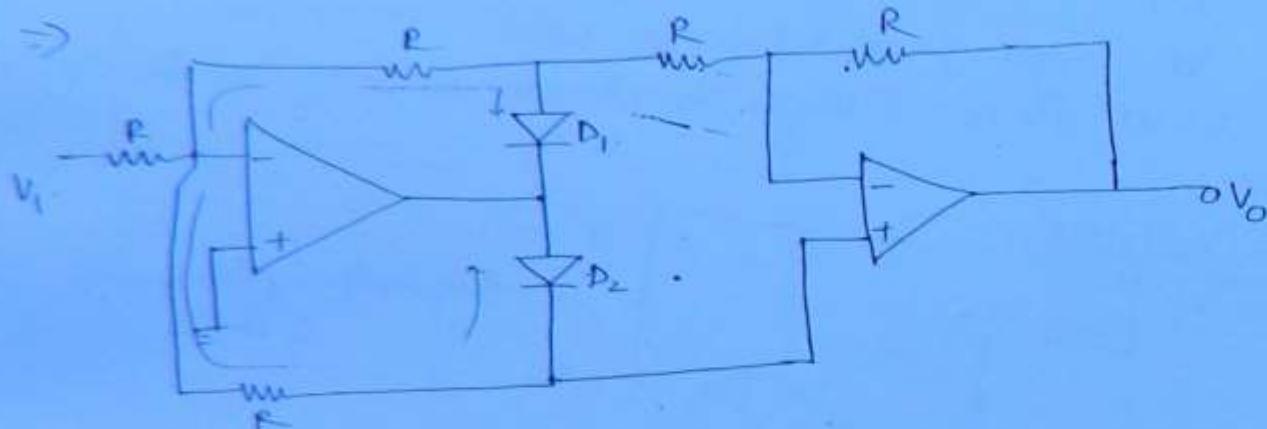


for the half,
for the half,

~~if $V_o = 0$~~ D_1 PB, D_2 RB, $V_o = 0$
 D_1 RB, D_2 PB $\rightarrow V_o = -V_i$



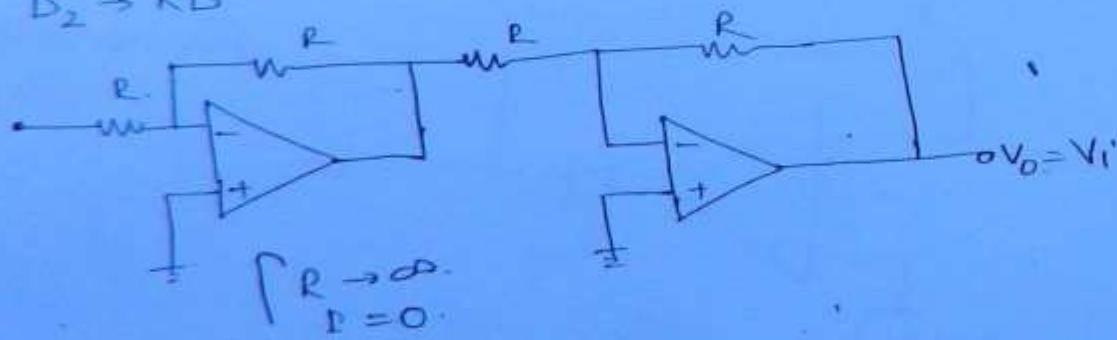
(228)



positive half cycle →

$D_1 \rightarrow F.B.$

$D_2 \rightarrow R.B.$



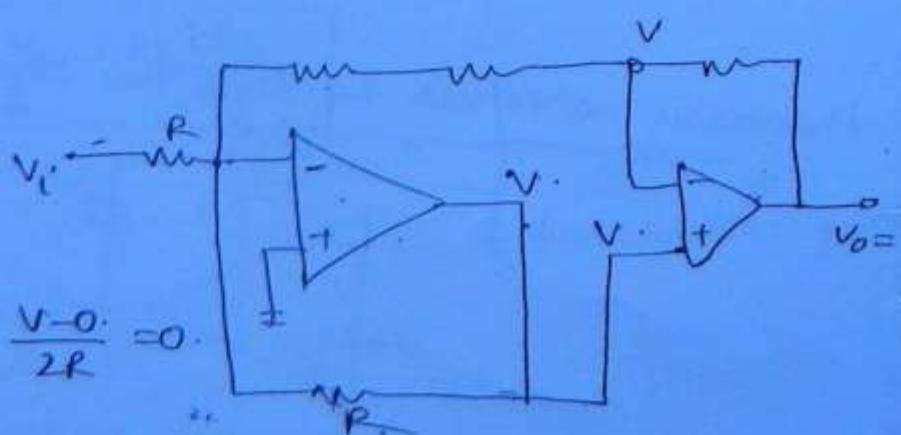
negative half cycle →

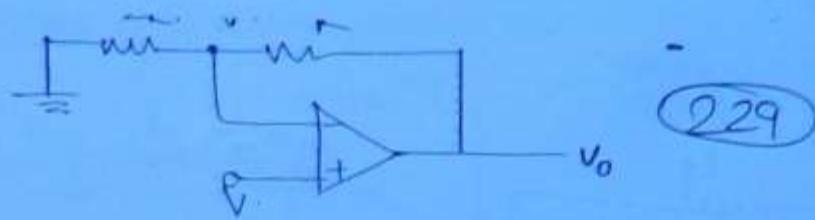
$D_1 \rightarrow R.B.$

$D_2 \rightarrow F.B.$

$$\frac{V_P - 0}{R} + \frac{V - 0}{R} + \frac{V - 0}{2R} = 0.$$

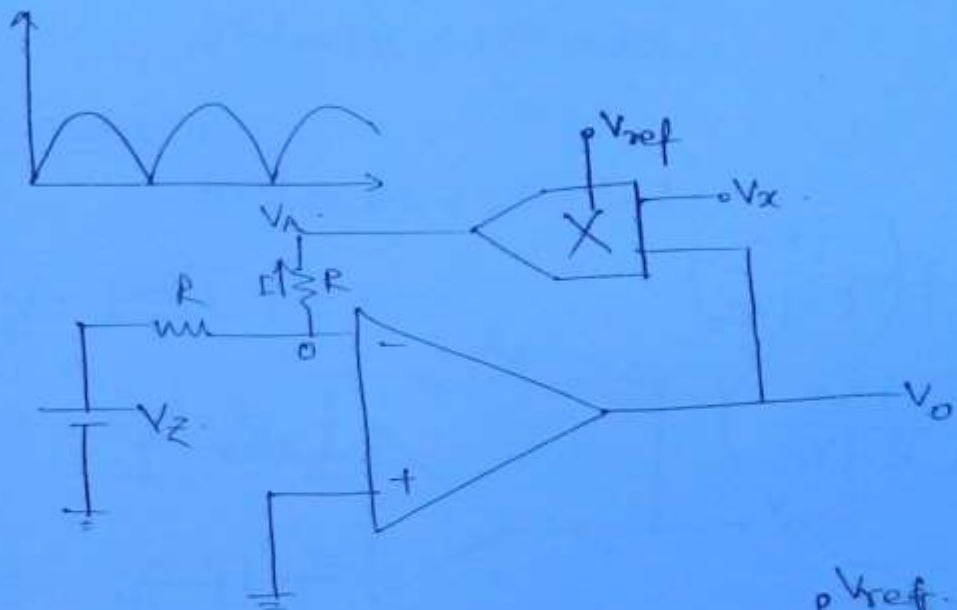
$$V = -\frac{2}{3} V_i$$





(229)

$$\begin{aligned}
 V_o &= \left(1 + \frac{R}{2R}\right) v \\
 &= \frac{3}{2} v \\
 &= \frac{3}{2} \times \left(-\frac{2}{3}\right) v_i \\
 &= -v_i
 \end{aligned}$$

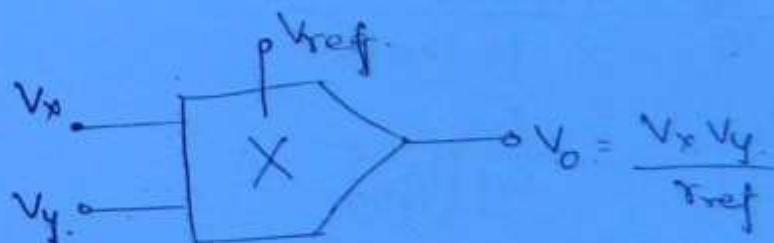


$$V_A = \frac{V_x V_o}{V_{ref}}$$

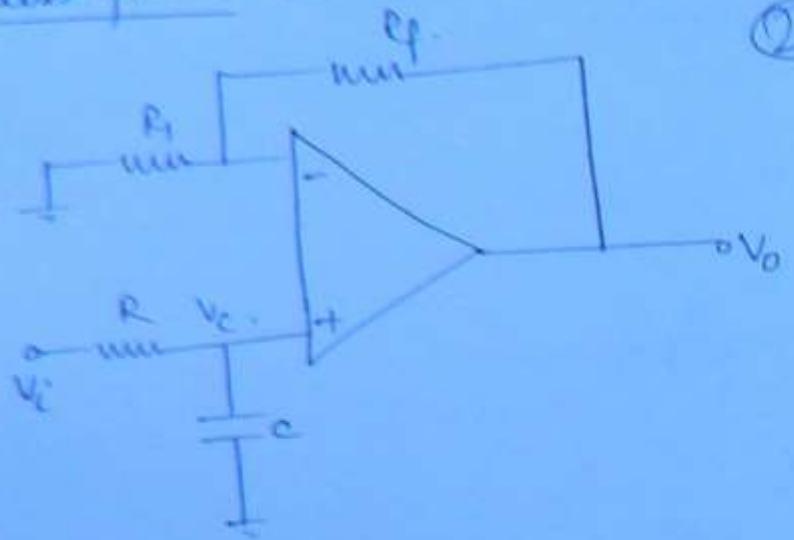
$$1 + \frac{R}{R} = \frac{V_x V_o}{V_{ref}}$$

$$1 - \frac{V_Z}{V_o} = \frac{V_p V_o}{V_{ref}}$$

$$V_o = -V_{ref} \left(\frac{V_Z}{V_p} \right)$$



Increase gain \rightarrow
low pass filters \rightarrow



Q30

$$V_0 = \left(1 + \frac{R_f}{R_i}\right) V_C$$

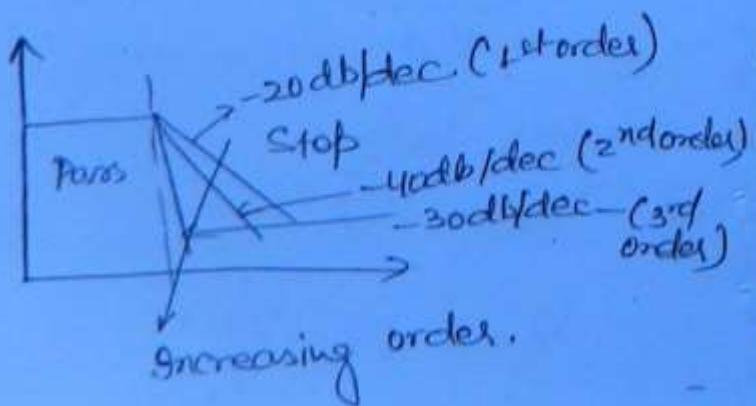
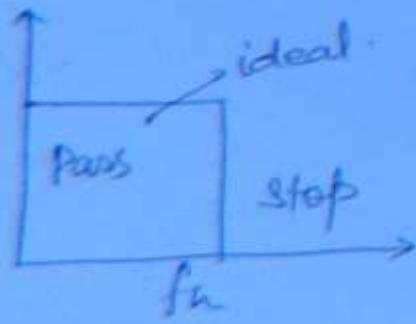
$$= \left(1 + \frac{R_f}{R_i}\right) V_i \times \left(\frac{-jX_C}{R - jX_C}\right)$$

$$\frac{V_0}{V_i} = \left(1 + \frac{R_f}{R_i}\right) \left(\frac{-jX_C}{R - jX_C}\right)$$

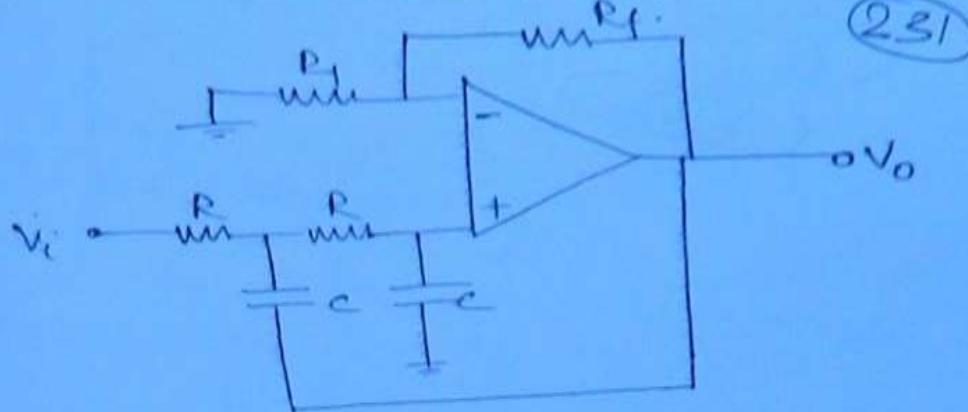
$$\frac{V_0}{V_i} = \frac{A_{cl}}{1 + j\frac{2\pi f R C}{}}$$

$$= \frac{A_{cl}}{1 + j\left(\frac{f}{f_H}\right)}$$

$$f_H = \frac{1}{2\pi R C}$$



2nd order low pass filter \rightarrow



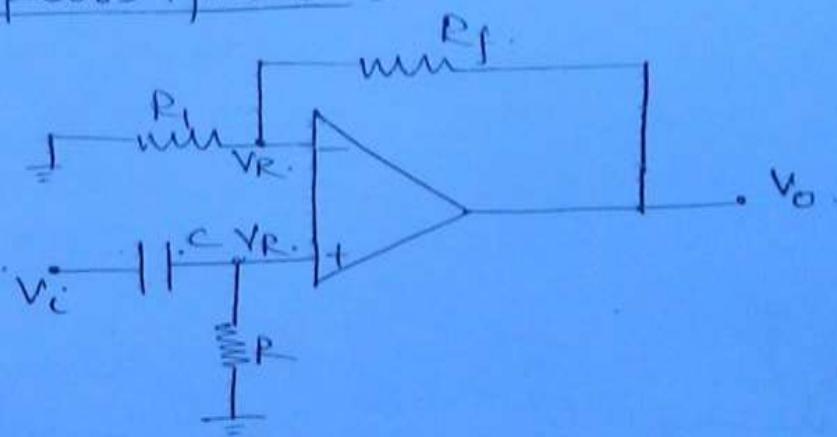
3rd order \rightarrow

2nd order + 1st order

4th order \rightarrow

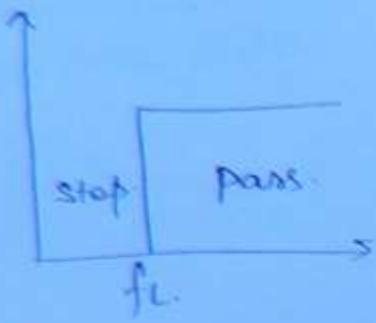
2nd order + 2nd order.

High pass filter \rightarrow



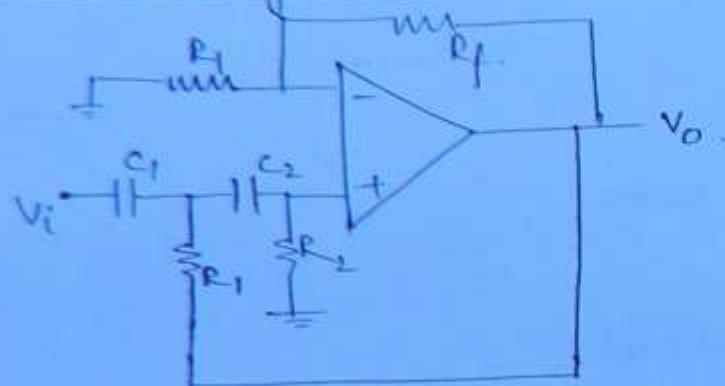
$$\begin{aligned}
 V_o &= \left(1 + \frac{R_f}{R_1}\right) V_R \\
 &= \left(1 + \frac{R_f}{R_1}\right) V_i \left(\frac{R}{R - j\omega C}\right) \\
 &= \frac{A_{cl.}}{1 - j(\frac{1}{R}C\omega_f)}
 \end{aligned}$$

$$f_L = \frac{1}{2\pi RC}$$

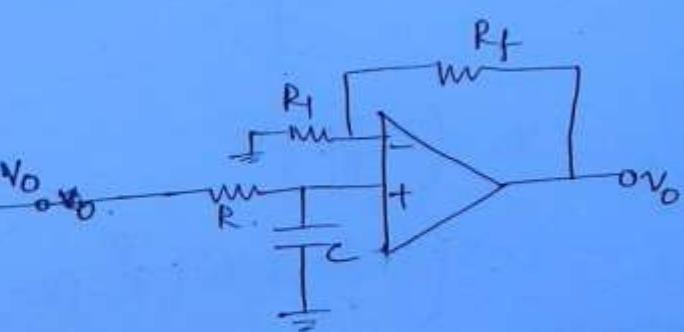
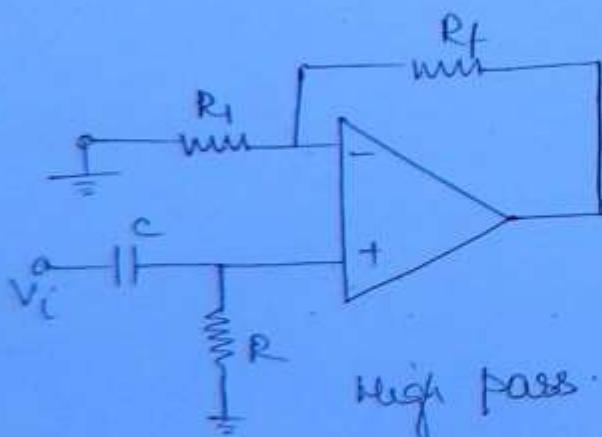
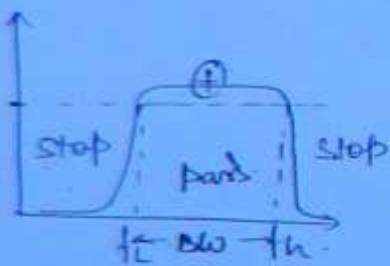


(232)

2nd order high pass \rightarrow

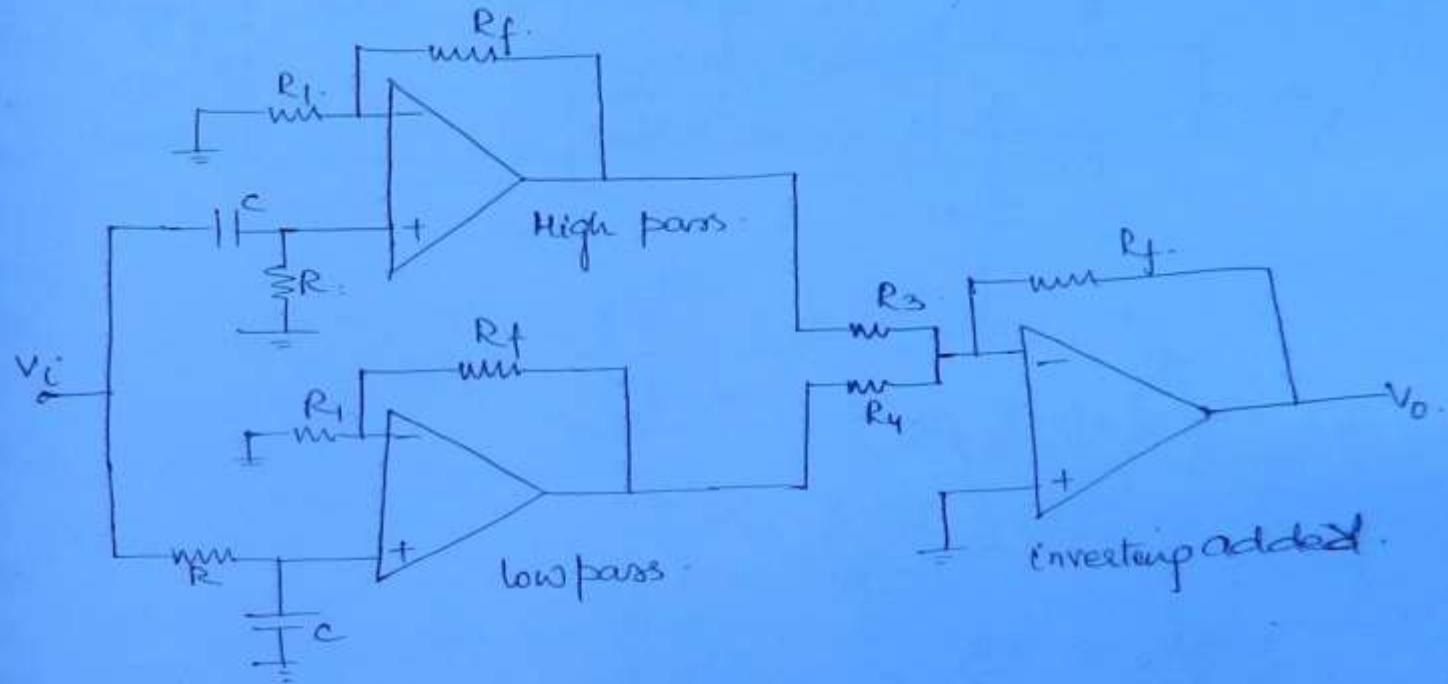
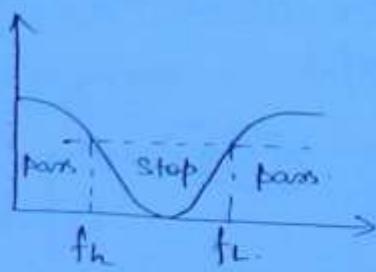


Band pass \rightarrow

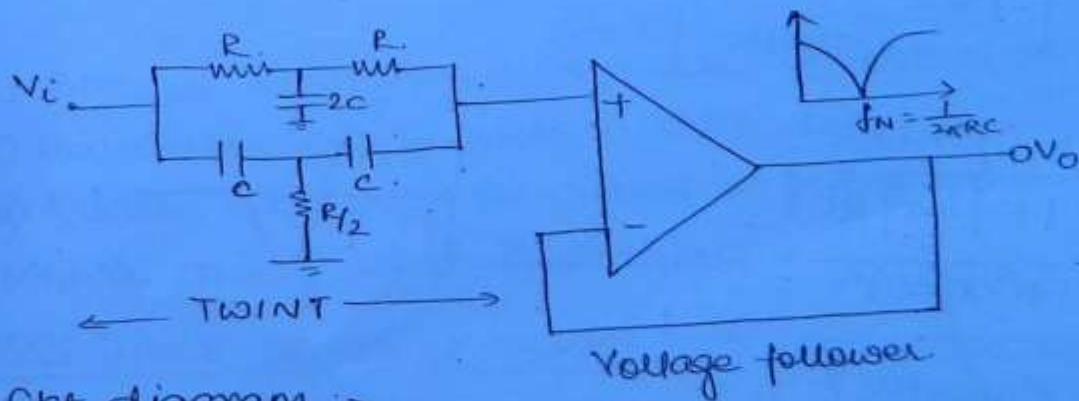


Band Reject →

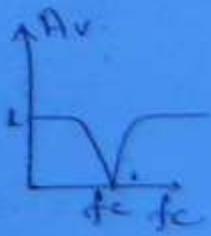
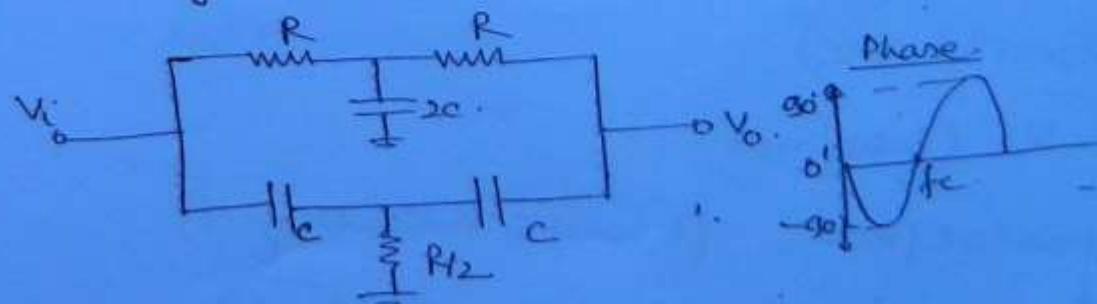
233



Notch filter →



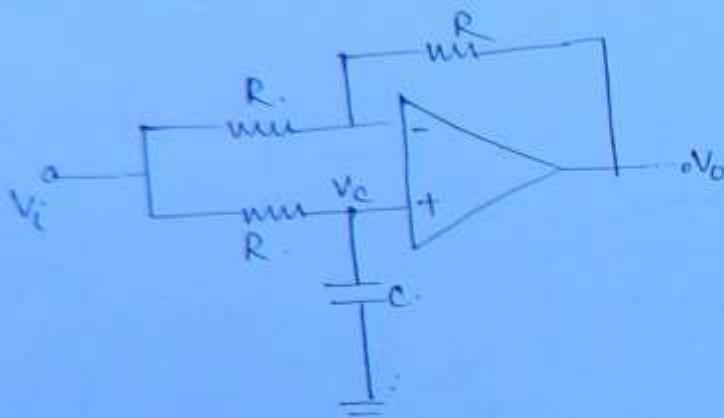
Ckt diagram →



A voltage follower n/w is added to the front n/w because to improve the quality factor of RC n/w.

All pass filter →

(Q34)



$$\begin{aligned}
 V_o &= -\frac{R}{R} V_i + \left(1 + \frac{R}{R}\right) V_c \\
 &= -V_i + 2V_i \left(\frac{-jX_C}{R-jX_C}\right) \\
 &= -V_i + \frac{2V_i}{1+j2\pi fRC} \\
 &= V_i \left[-1 + \frac{2}{1+j2\pi fRC} \right]
 \end{aligned}$$

$$\frac{V_o}{V_i} = \frac{1 - j2\pi fRC}{1 + j2\pi fRC}$$

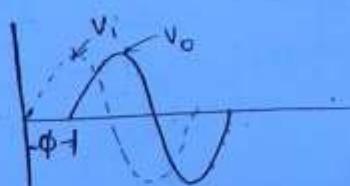
$$\left| \frac{V_o}{V_i} \right| = \frac{\sqrt{1^2 + (2\pi fRC)^2}}{\sqrt{1^2 + (2\pi fRC)^2}} = 1$$

$$\phi = -2\tan^{-1}(2\pi fRC)$$

V_o lags V_i (low pass)

$$\phi = +2\tan^{-1}(2\pi fRC) \quad (R \text{ and } C \text{ is interchanged})$$

V_o leads V_i (high pass)

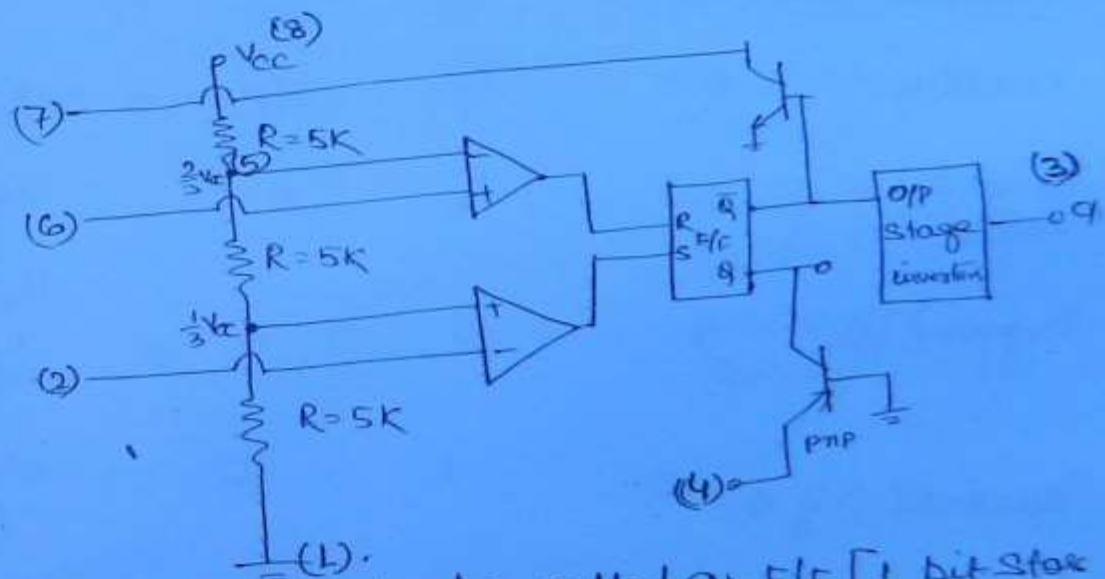
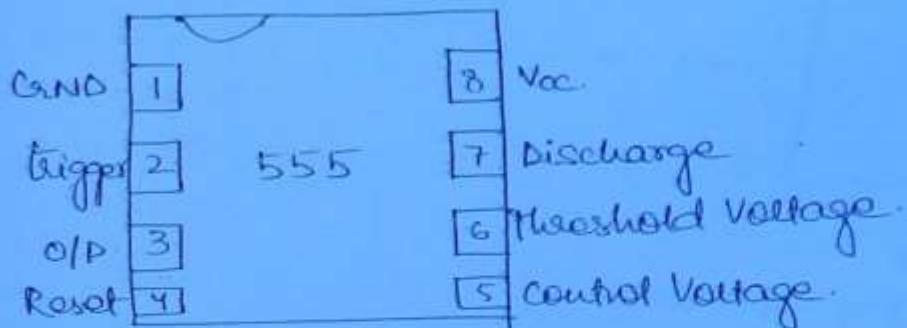


555 timer—

Whenever time delay is required.

Pin diagram →

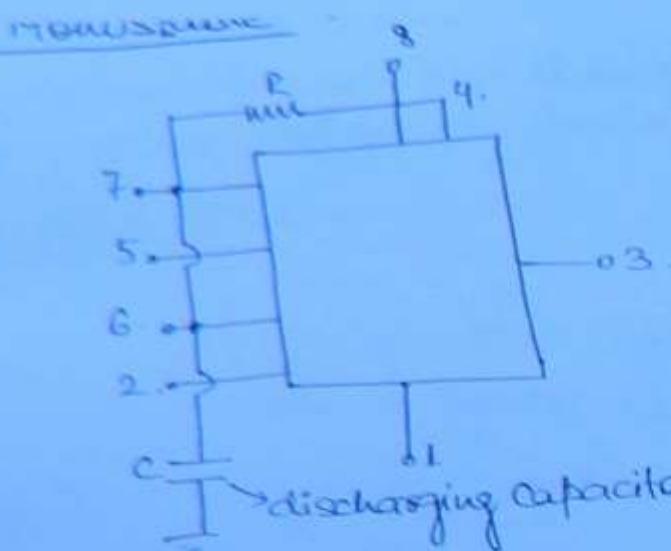
(285)



- 1) Bistable multivibrator can also be called as F/F [1 bit store]
- 2) Monostable can generate a pulse O/P.
- 3) Astable can also be called as free running oscillator which can generate oscillations.

555 timer operating modes :—

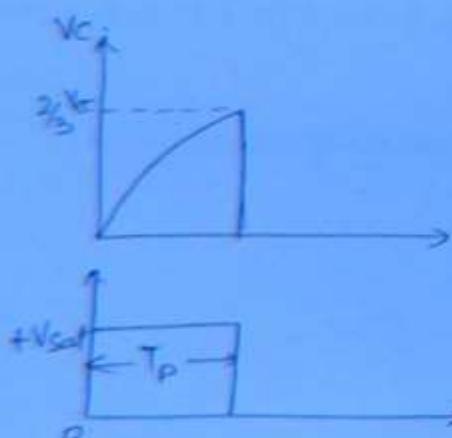
- monostable mode
- Astable mode



(236)

Tabular form →

Condition	Q	\bar{Q}	O/P	Capacitor position
Stand by mode	0	1	0	discharging (stable)
Trigger $< \frac{1}{3} V_{cc}$	1	0	1	[Because transistors are in sat.] charging (Quasi)
threshold $> \frac{2}{3} V_{cc}$	0	1	0	discharging (stable)

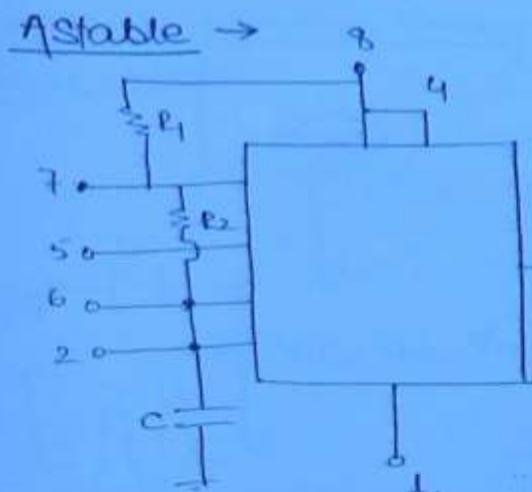


$$V_c = V(1 - e^{-t/RC})$$

$$\frac{2}{3} V_{cc} = V_{cc}(1 - e^{-t_p/RC})$$

$t_p = 1.1RC$

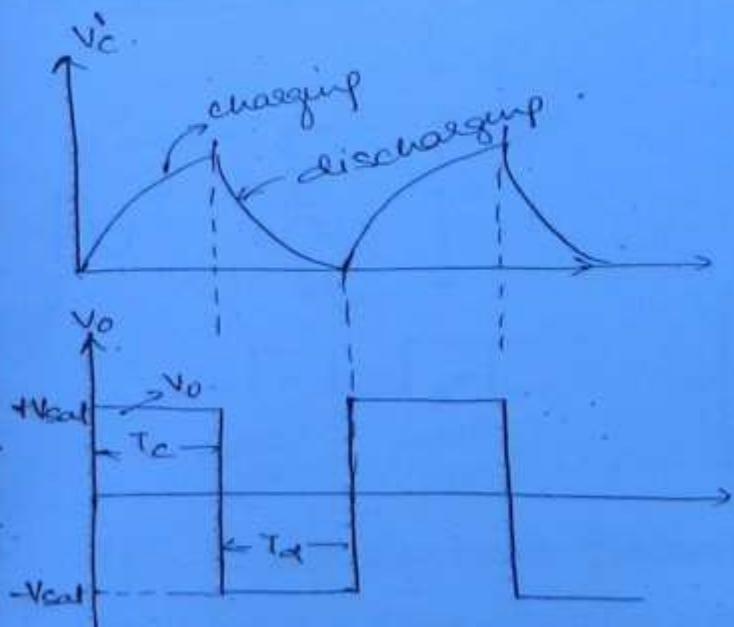
R will be fixed always = ?



(237)

tabular form \rightarrow

condition	Q	\bar{Q}	O/P	capacitor position
Standby	0	1	0	discharging (stable)
trigger $< \frac{1}{3} V_{cc}$ (capacitor)	1	0	1	charging (Quasi)
threshold $> \frac{2}{3} V_{cc}$	0	1	0	discharging (Quasi)



$$T_c = 0.69(R_1 + R_2)C.$$

$$T_d = 0.69 R_2 C.$$

$$T = T_c + T_d = 0.69(R_1 + 2R_2)C.$$

Duty cycle

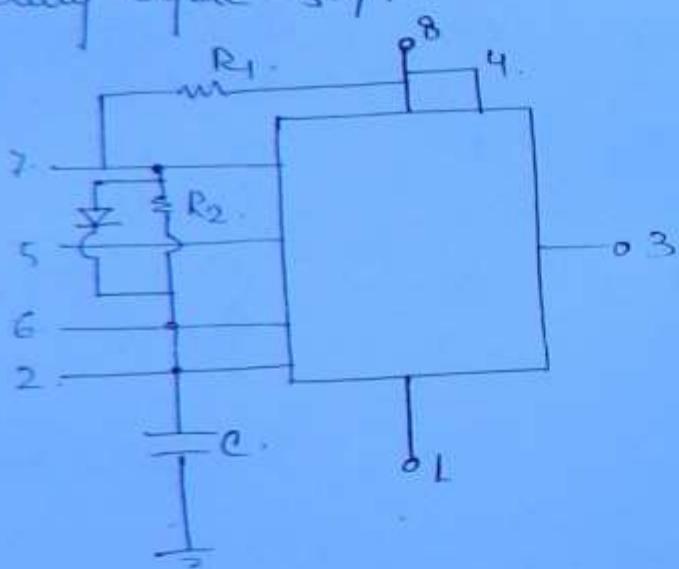
$$\begin{aligned}
 &= \frac{T_c + T_d}{T_c + T_d} \\
 &= \frac{0.69(R_1 + R_2)C}{0.69(R_1 + 2R_2)C} \\
 &= \frac{R_1 + R_2}{R_1 + 2R_2}
 \end{aligned}$$

(238)

$$f = \frac{1}{T} = \frac{1}{0.69(R_1 + 2R_2)C}$$

Q Design a stable multivibrator to generate square wave oscillation.

Ans duty cycle = 50%.



$$\text{D.C.} = \frac{R_1}{R_1 + R_2}$$

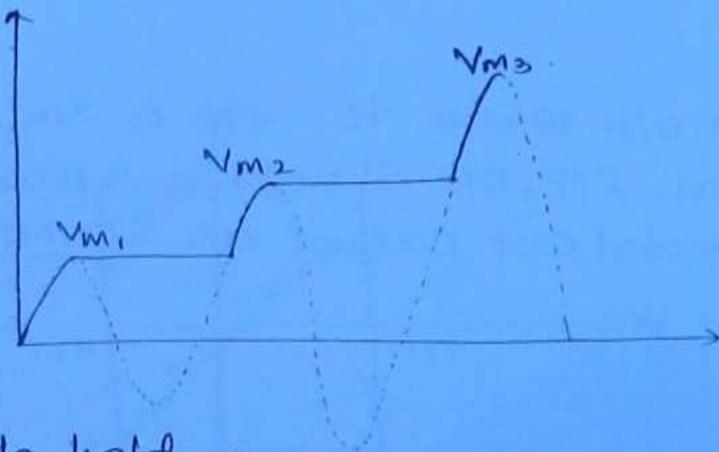
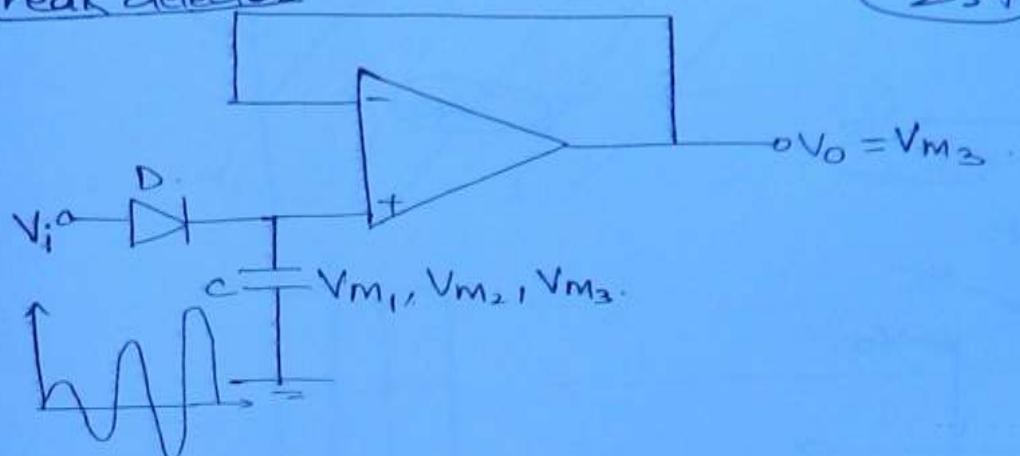
$$R_1 = R_2 = R$$

$$\text{D.C.} = 50\%$$

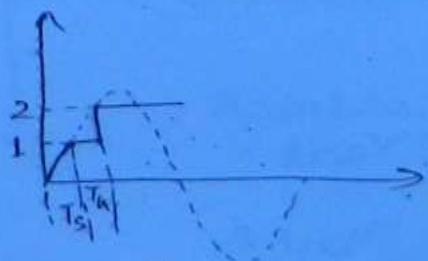
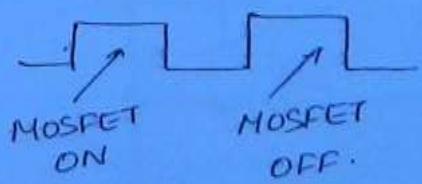
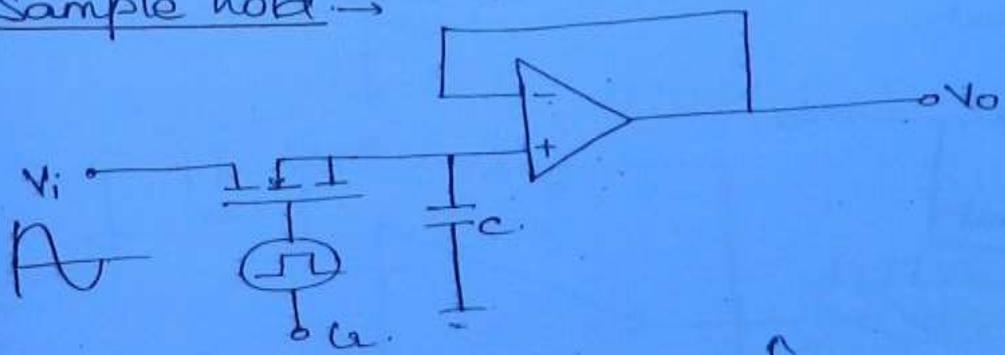
Special opamp design

Peak detector

(239)



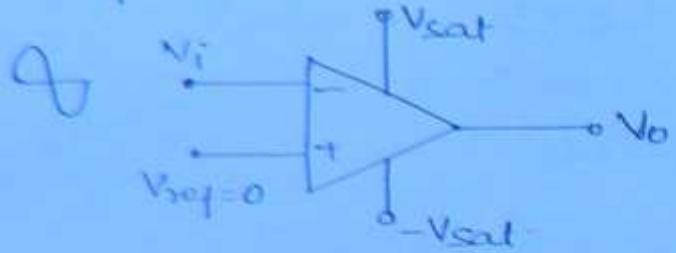
Sample hold →



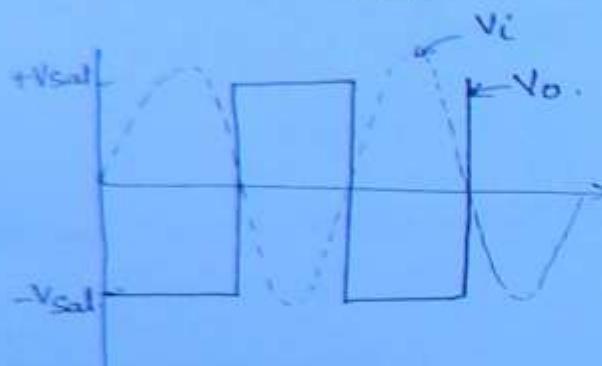
$T_s \rightarrow$ sampling time [MOSFET ON]

$T_h \rightarrow$ holding time [MOSFET OFF].

comparator \rightarrow ZCD \rightarrow zero crossing detector

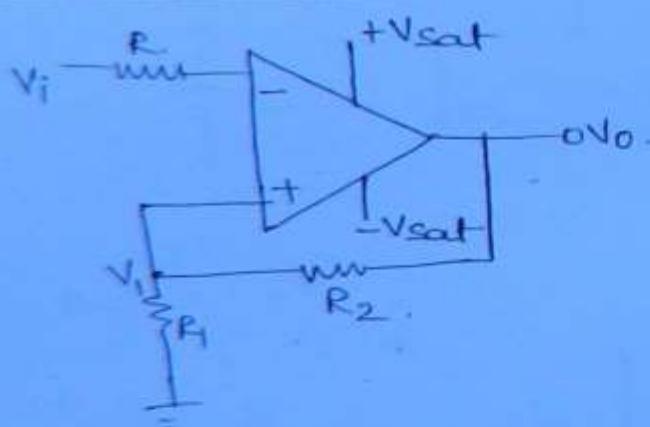


(240)



ZCD can give square wave o/p when the I/P is Sinusoidal signal. But for any irregular I/P, O/P should be square wave. It is possible with by special circuit called as SCHMITT TRIGGER.

SCHMITT TRIGGER \rightarrow



Assume $V_o = +Vsat$

$$[UTP] \quad V_i = \frac{Vsat \cdot R_1}{R_1 + R_2}$$

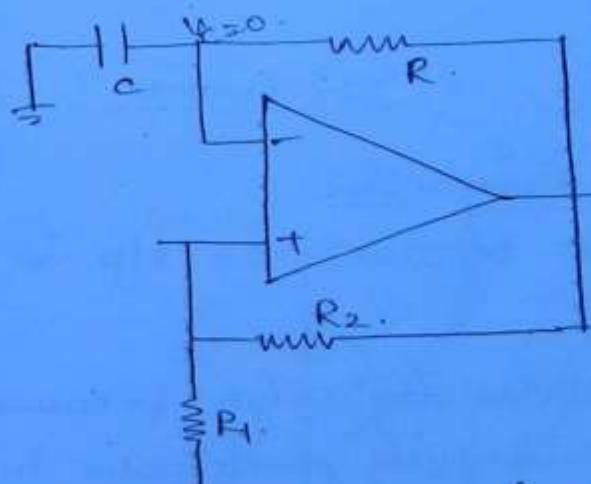
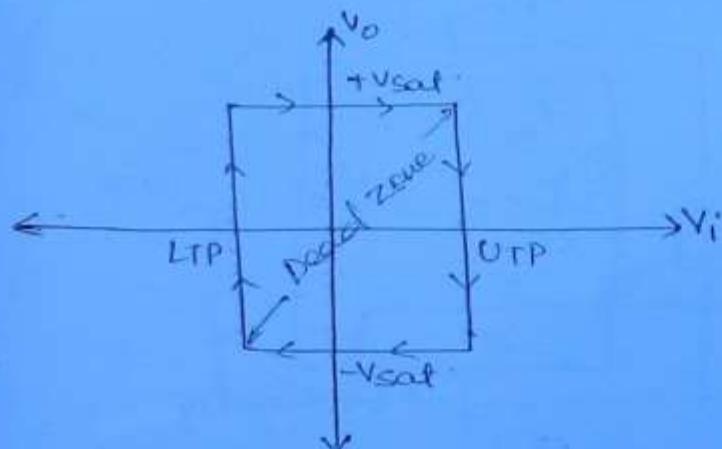
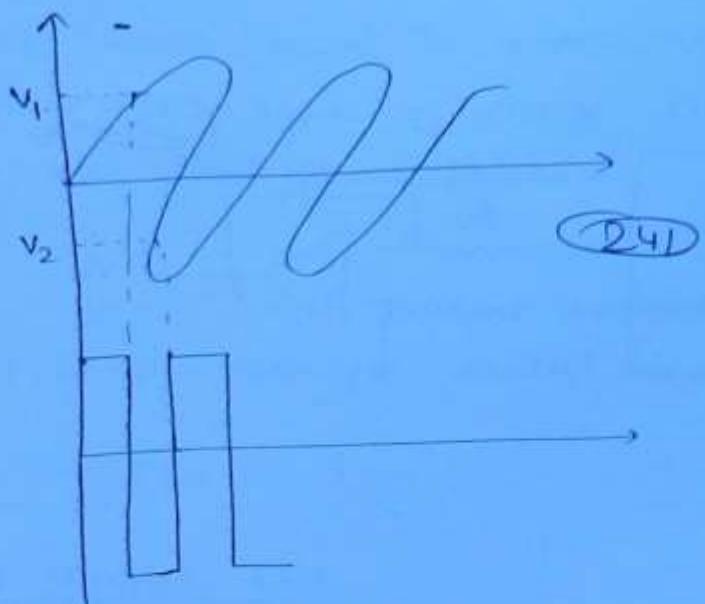
Upper \downarrow

trigger pt design

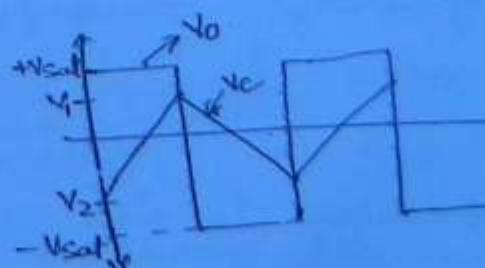
$$V_o = -Vsat$$

$$V_2 = -Vsat \cdot R_1$$

$$LTP = \frac{R_1 + R_2}{R_1 \cdot R_2}$$

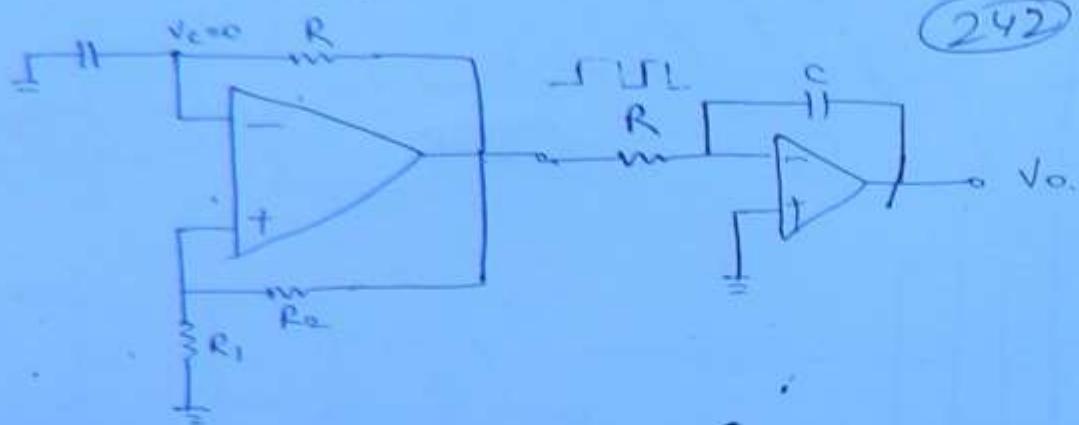


$V_C > UTP$, discharging.



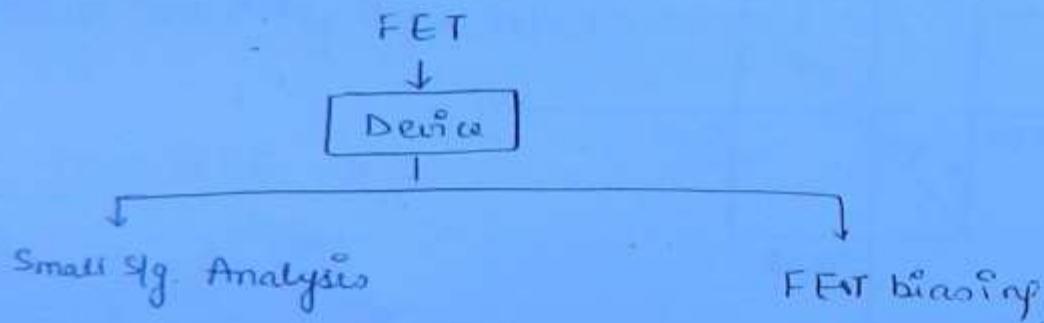
$$T = 2RC \ln \left(\frac{2R_1 + R_2}{R_2} \right)$$

$$f = \frac{1}{T}$$



17/1/2012

FET :-



Introduction :-

- ⇒ BJT is having following disadvantage.
- ⇒ The I_{FB} impedance is low because the I_{FB} is forward-bias.
- ⇒ The noise level is comparatively high because both type of charge carriers will participates in the conduction process.

The advantages of I_{FB} compared to BJT :-

- The I_{FB} impedance is high because the I_{FB} is always operated with reverse bias.

ii). The noise level is comparatively low because only one type of charge carrier will participate in the conduction process.

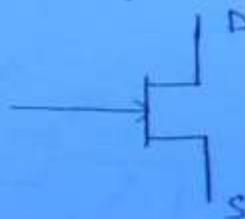
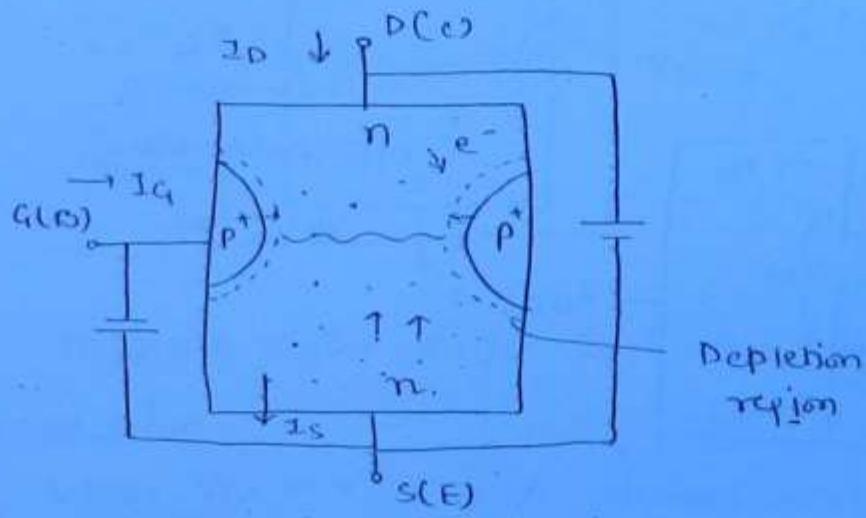
(243)

Note :-

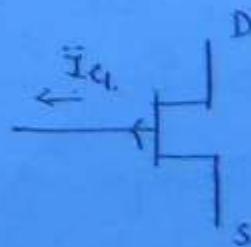
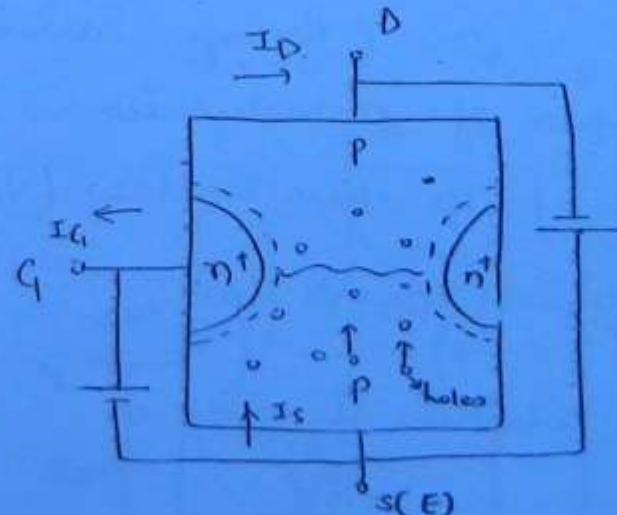
BJT is a current control device whereas FET is a voltage control device.

Types of FET :-

i) n channel FET.



ii) P channel FET :-



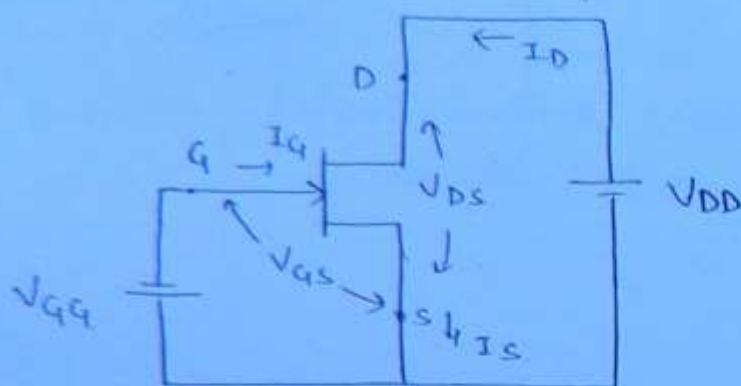
Note :-

Drain should be always R.B.

drain current and drain voltage :-

1) N-Channel FET

(244)



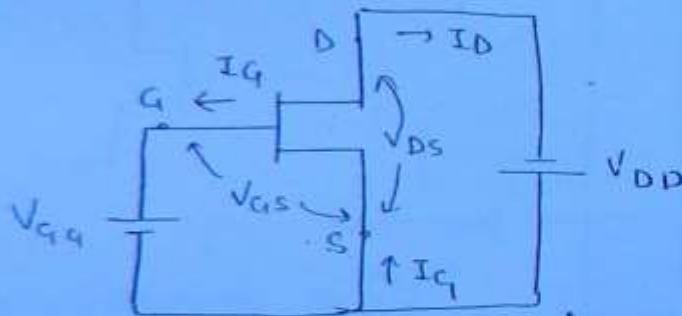
$$\begin{aligned}V_{GS} &= -ve \\I_D \quad \} &= +ve \\V_{DS} \quad \} &= +ve\end{aligned}$$

I/O parameters :-

$$V_{GS}, I_G = 0$$

O/I parameters

$$V_{DS}, I_D$$



Conclusion :-

- 1) There will be no I/O characteristics in FET, because I_S is approximately = 0. (Leakage current).
- 2) There are two types of characteristics.
 - i) Drain characteristics / O/I parameters ($-V_{DS}, I_D$) $|_{V_{GS}}$.
 - ii) Transfer characteristics $(V_{GS}, V_D, I_D) |_{V_{DS}}$.

In N-channel, the polarities are given as :

$$V_{GS} = -ve$$

$$\begin{aligned}I_D \quad \} &= +ve \\V_{DS} \quad \} &= +ve\end{aligned}$$

In P-channel the polarities are given as -

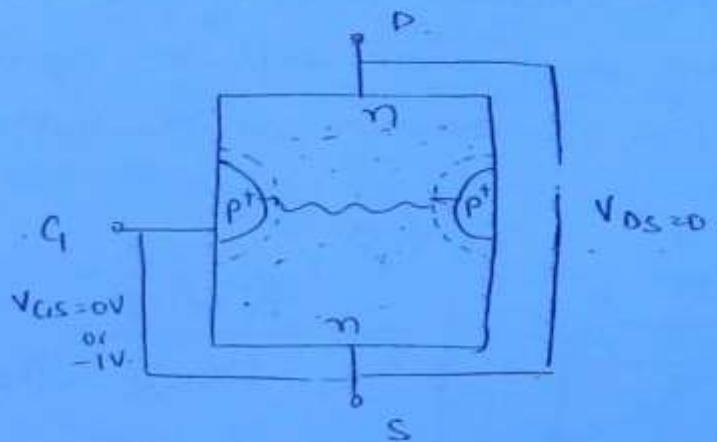
$$V_{GS} = +ve$$

$$\left. \begin{array}{l} I_D \\ V_{DS} \end{array} \right\} = -ve.$$

(245)

Working principle of FET :-

Case-1 :- $V_{GS} = 0V, V_{DS} = 0V$.



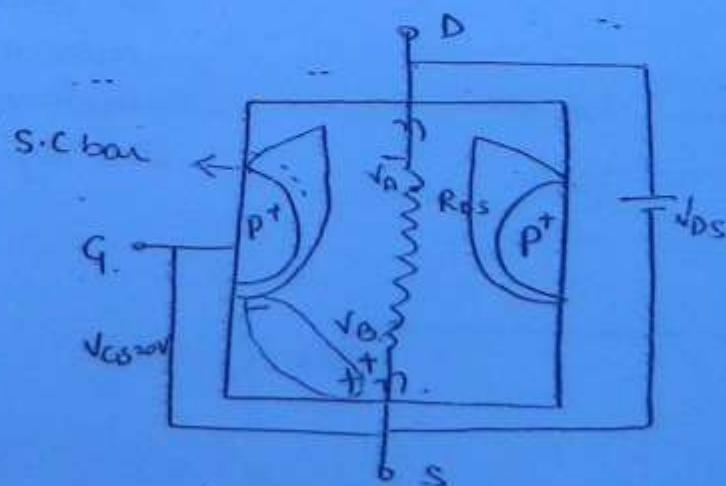
Depletion region layer is ↑, then region ↓

Conclusion :-

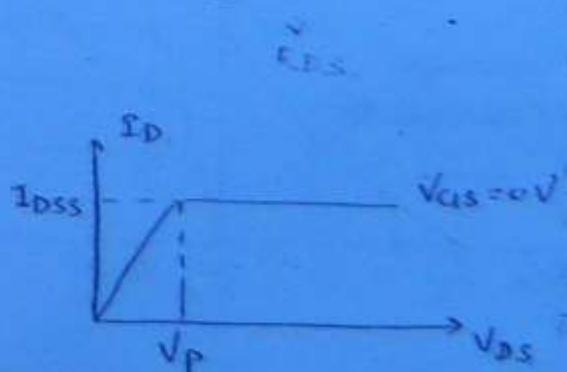
- 1) When $V_{GS} = 0V$ max. current can be achieved.
- 2) When $V_{DS} = 0V$ drain current becomes 0.

Case-2 :-

$$V_{GS} = 0V, V_{DS} \neq 0V.$$



$$V_{DS} \propto I_D$$

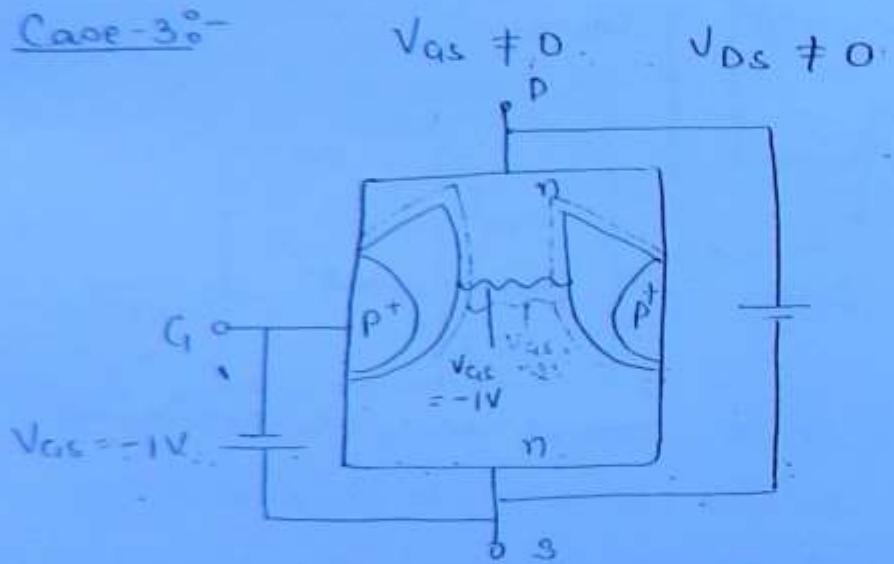


I_{DSS} = Short ckt. Drain current

Conclusions :-

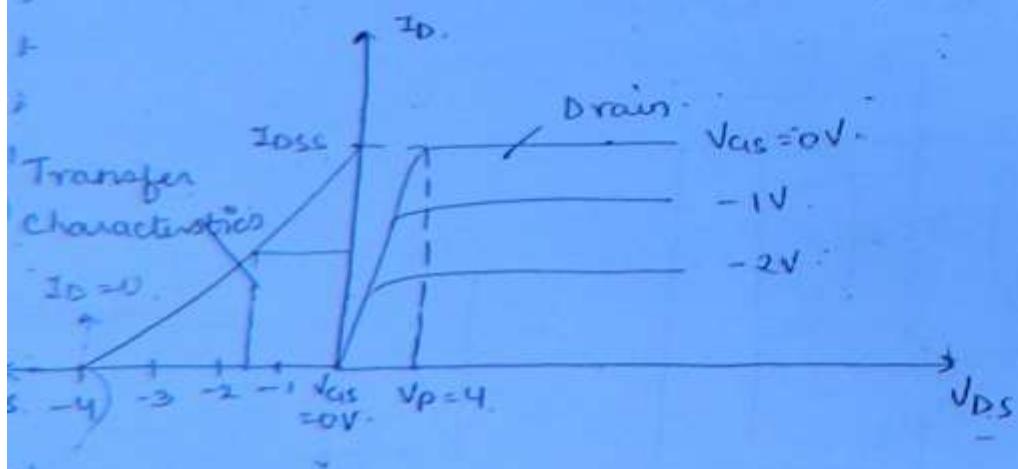
- 1) When $V_{DS} = 0V$ max. channel can be achieved.
- 2) When $V_{DS} \neq 0V$ the bar will act like a resistor ($V_{DS} \propto I_D$). (246)
- 3) The basic mechanism of FET is top side of the drain is covered with R. Bias & bottom side of the source is covered with F. Bias.
- 4) Due to the Internal Reverse bias of gate to source the depletion region penetration will be more at the top side & less penetration at the bottom side.

Case - 3 :-



Q point-

$$(V_{GS})_Q, (I_D)_Q$$



$(V_{GS})_{Q, \text{mean}}$
no channel
current is 0.
Both penetration
will together

$V_{GS}(Q, \text{mean})$
at state

V_{GS}
state

Transfer characteristics

$$I_D = I_{DS} \left[1 - \frac{V_{GS}}{V_P} \right]^2$$

(247)

$$| V_{GS} |_{off} = | V_P |$$

V_P = pinch off voltage & it depends on doping concentration.

- ⇒ For FET device analysis we have to concentrate on transfer characteristics but not drain characteristic.
- ⇒ In FET Biasing, Q point is defined as $(V_{GS})_Q (I_D)_Q$. FET is always thermally stable that means I_D is independent of temperature.

FET Parameters :-

ΔV_{GS} , ΔV_{DS} , ΔI_D

- 1). Ac drain resistance

$$r_d = \left. \frac{\Delta V_{DS}}{\Delta I_D} \right|_{V_{GS}}$$

- 2). Transconductance

$$g_m = \left. \frac{\Delta I_D}{\Delta V_{GS}} \right|_{V_{DS}}$$

- 3). Amplification factor

$$\mu = \left. \frac{\Delta V_{DS}}{\Delta V_{GS}} \right|_{I_D}$$

$$\mu = g_m r_d$$

$r_d > R_D$

Expression for transconductance

$$g_m = \frac{\Delta I_D}{\Delta V_{GS}} \quad (248)$$

$$= \frac{\partial I_{DSS}}{\partial V_{GS}} \left[1 - \frac{V_{GS}}{V_P} \right]^2$$

$$g_m = - \frac{\partial I_{DSS}}{V_P} \left[1 - \frac{V_{GS}}{V_P} \right]$$

$$g_m = g_{m0} \left[1 - \frac{V_{GS}}{V_P} \right]$$

$$g_{m0} = - \frac{\partial I_{DSS}}{V_P}$$

max. transconductance.

Prove $g_m = \frac{\partial}{|V_P|} \sqrt{I_D - I_{DSS}}$

$$g_m = - \frac{\partial I_{DSS}}{V_P} \left[1 - \frac{V_{GS}}{V_P} \right]$$

$$\sqrt{\frac{I_D}{I_{DSS}}} = \left[1 - \frac{V_{GS}}{V_P} \right]$$

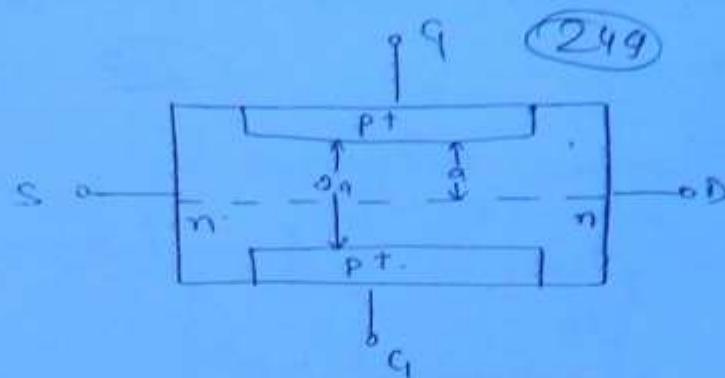
$$g_m = - \frac{\partial I_{DSS}}{V_P} \sqrt{\frac{I_D}{I_{DSS}}}$$

$$g_m = \frac{\partial}{|V_P|} \sqrt{I_D - I_{DSS}}$$

Pinch off voltage

$$V_P = \left| \frac{a^2 q N_A}{2e} \right| = \left| \frac{a^2 q N_D}{2e} \right|$$

↓
P channel
↓
n channel.



$a = \text{half channel height}$
 $2a = \text{full channel height}$

Problems:

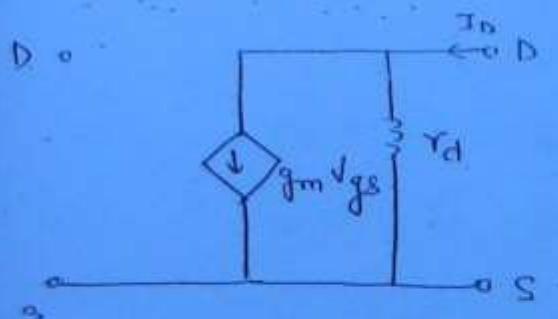
Small S/Ig. Analysis of FET

Low freq. Analysis

$$I_D = f(V_{GS}, V_{DS})$$

$$T_D = \frac{\partial I_D}{\partial V_{GS}} + \frac{\partial I_D}{\partial V_{DS}} \cdot V_{DS}$$

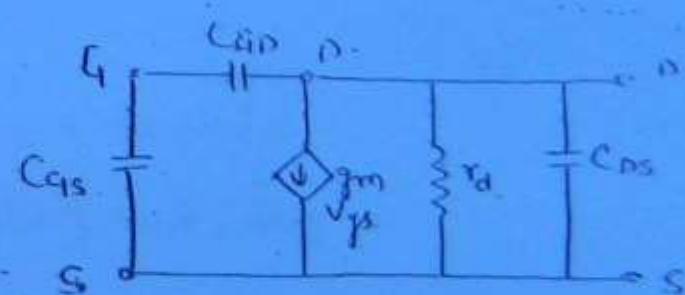
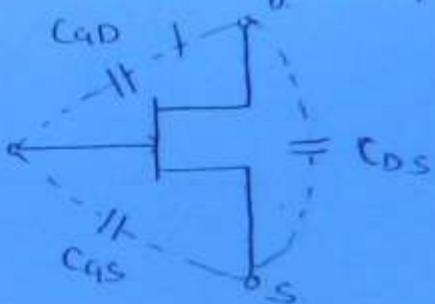
$$= g_m V_{GS} + \frac{V_{DS}}{r_d}$$



low freq.

High freq. Analysis

Input electrode Capacitance



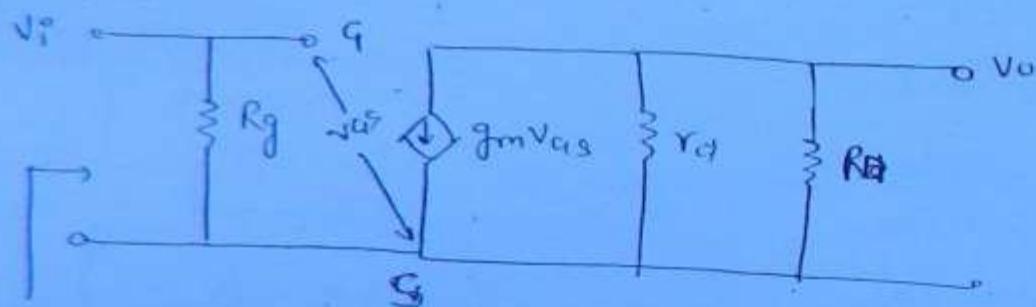
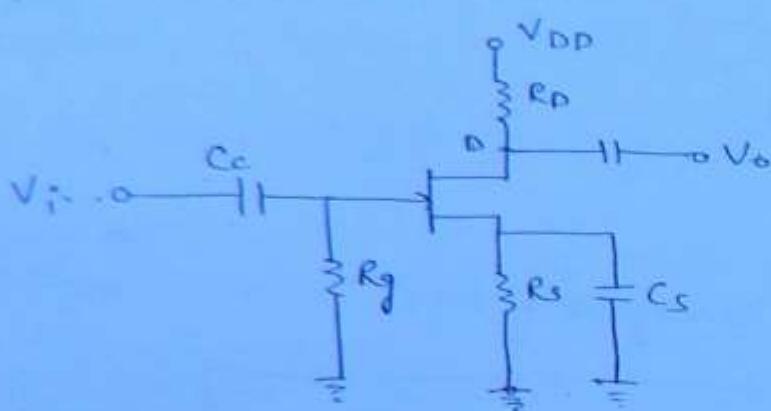
High freq.

Conclusion:-

⇒ Amp analysis should be done in mid band range
 therefore the high freq. model of FET when it is represented in the mid band range it converts

Like a low freq model. (All the Interelectrode capacitances are open). 250

Common Source Bypass Amplifier:



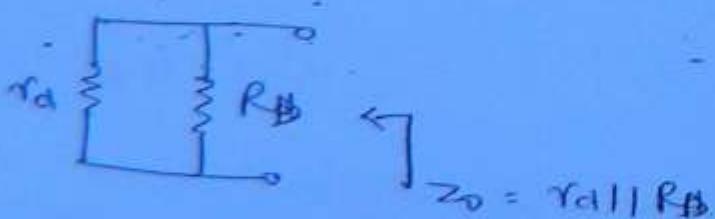
Z_0 :

$$V_i^o = 0$$

$$V_{GS} = 0$$

↓

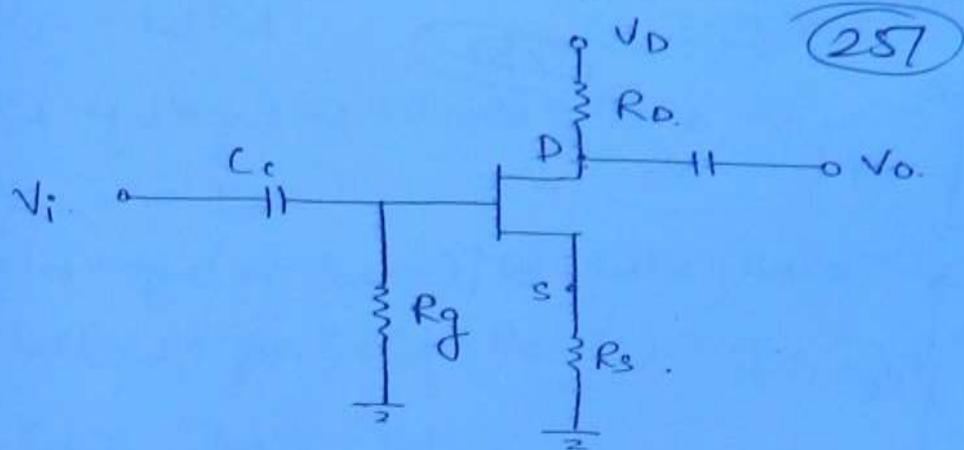
$$g_m V_{GS} = 0 \quad (\text{open})$$



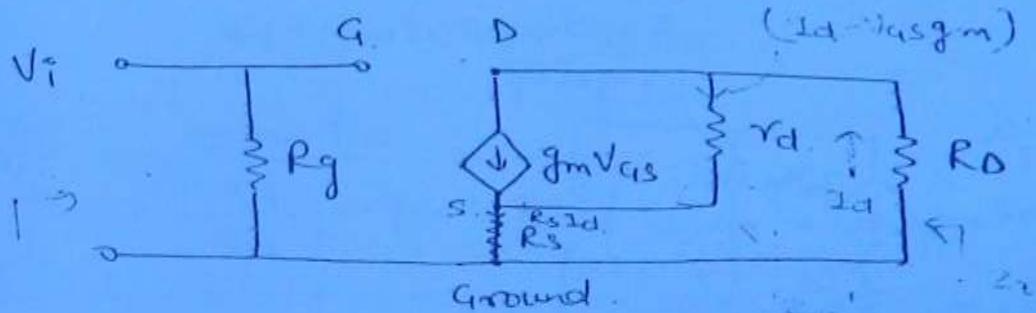
$$A_v = \frac{V_o}{V_i}$$

$$V_o = -g_m V_{GS} R_D \quad \Rightarrow \quad \frac{V_o}{V_i} = -g_m R_D$$

Common drain voltage gain



(257)



$$Z_1^o = R_g$$

$$Z_0^o = -$$

$$V_i^o = V_{gs} + I_D R_S$$

$$V_i^o = 0$$

$$V_{gs} = -I_D R_S$$

$$V_o = (I_d - V_{gs} g_m) r_d + R_S I_d$$

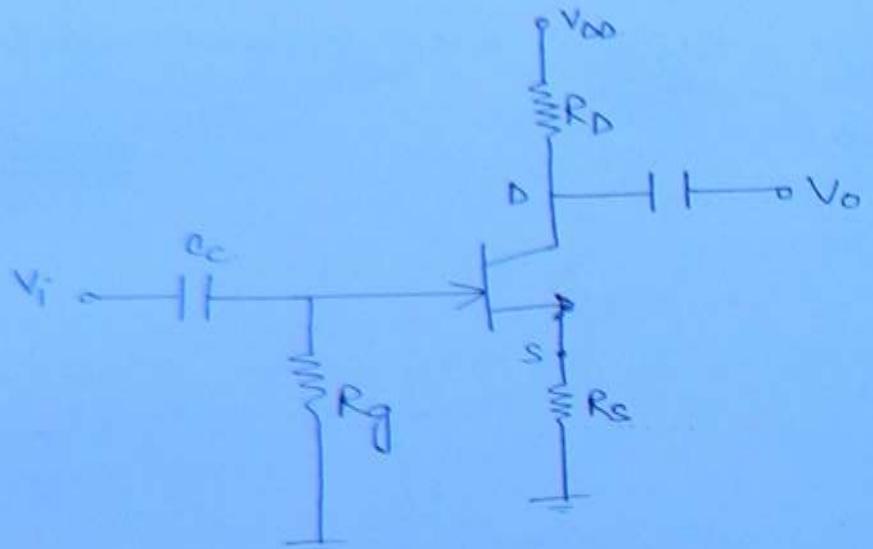
$$\begin{aligned} V_o &= \{I_d - g_m(-I_D R_S)\} r_d + R_S I_d \\ &= I_d (r_d + g_m R_S r_d + R_S) \end{aligned}$$

$$Z_0^o = \frac{V_o}{I_d} = r_d (1 + \mu) R_S$$

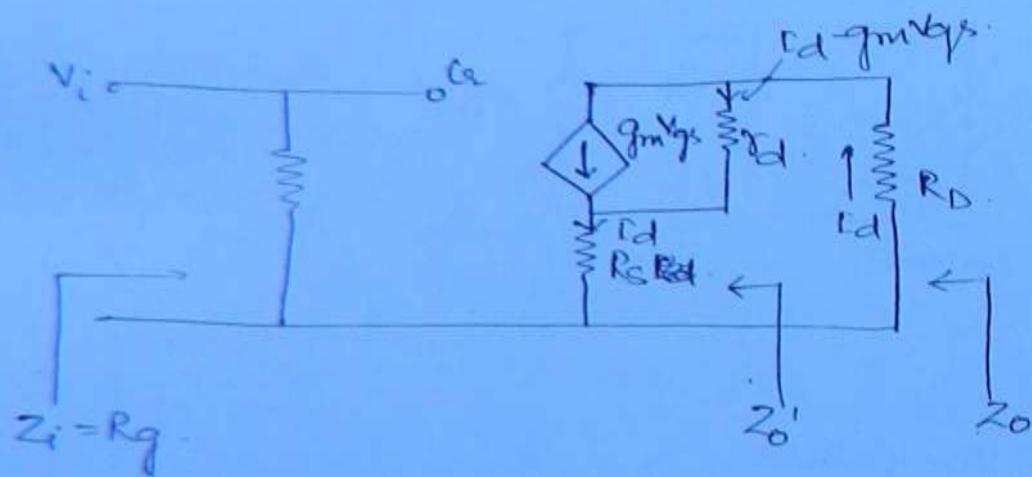
$$Z_0 = Z_0^o // R_D$$

$$= \{r_d + (1 + \mu) R_S\} // R_D$$

CS univexus -



(252)



$Z_o \rightarrow$

$$V_i = V_{GS} + I_D R_S$$

$$V_i^* = 0$$

$$V_{GS} = -I_D R_S$$

$$\begin{aligned} V_o &= (I_d - g_m V_{GS}) r_d + I_d R_S \\ &= \{I_d - g_m (-I_D R_S)\} r_d + I_d R_S \\ &= I_d \{r_d + R_S \parallel r_d\} + R_S \end{aligned}$$

$$Z'_o = \frac{V_o}{I_d} = r_d + (1 + u) R_S$$

$$Z_o = Z'_o \parallel R_d$$

$$A_V =$$

$$V_o = - I_d R_d$$

(283)

$$(I_d - g_m V_{gs}) \frac{V_d}{R_d} + I_d R_s + I_d R_D = 0$$

$$V_{GS} = V_i - I_d R_s$$

$$\{ I_d - g_m (V_i - I_d R_s) \} \frac{V_d}{R_d} + I_d R_s + I_d R_D = 0$$

$$\Rightarrow I_d (R_d + g_m R_s R_d + R_s + R_D) = g_m V_i R_d$$

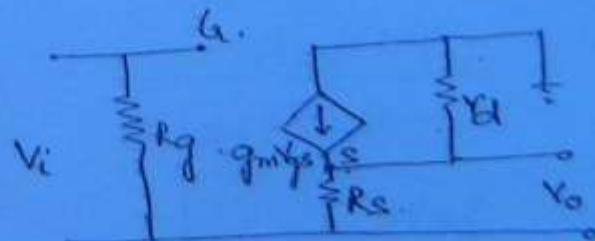
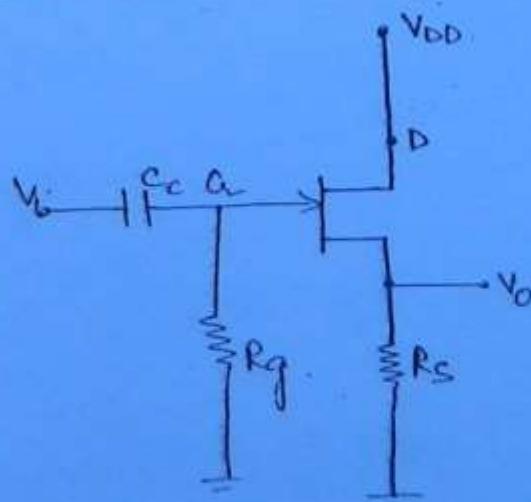
$$\Rightarrow I_d = \frac{g_m V_i + V_d}{R_d + g_m R_s R_d + R_s + R_D}$$

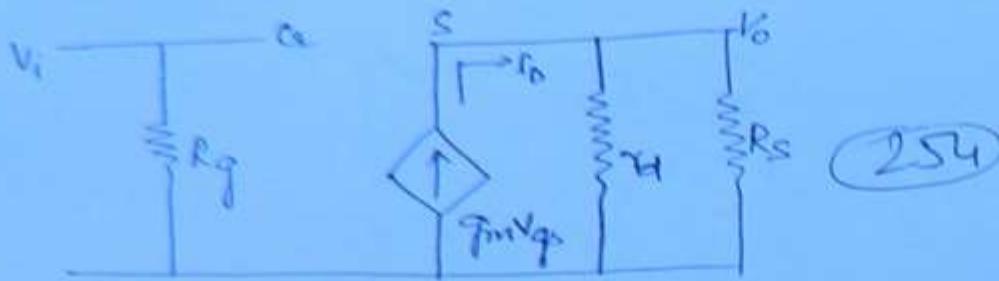
$$\frac{V_o}{V_i} = \frac{-g_m R_D}{\frac{R_d}{R_d} + g_m R_s \frac{R_d}{R_d} + \frac{R_s + R_D}{R_d}} \leftarrow \text{neglected}$$

$$A_V = \frac{-g_m R_D}{1 + g_m R_s}$$

$R_d \gg R_s + R_D$

Common drain amplifier :-





$$1) Z_i = R_g$$

$$2) Z_0 :=$$

$$V_i = -V_{cas} + V_o$$

$$\Rightarrow V_i + V_{cas} = V_o$$

$$4) V_i = 0$$

$$V_{cas} = V_o$$

source is at higher potential than gain

$$I_d = g_m V_{gs} \rightarrow V_o$$

$$Z_0' = \frac{V_o}{I_d} = \frac{1}{g_m}$$

$$Z_0 = Z_0' // R_s$$

$$= \frac{1}{g_m} // R_s$$

$$A_V = \frac{V_o}{V_i}$$

$$V_o = -g_m V_{gs} Z_d // R_s$$

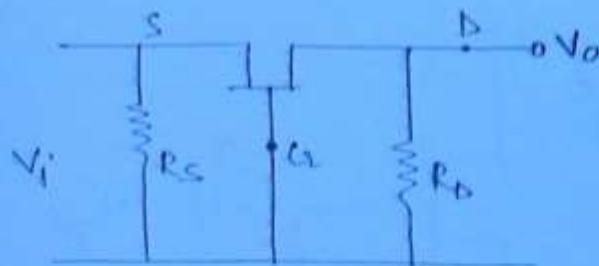
$$V_i = -V_{gs} + V_o$$

$$= -V_{gs} - g_m V_{gs} Z_d // R_s$$

$$\frac{V_o}{V_i} = \frac{-g_m V_{gs} R_s}{-V_{gs} (1 + g_m R_s)}$$

$$A_V = \frac{g_m R_s}{1 + g_m R_s}$$

Common gate amplifier



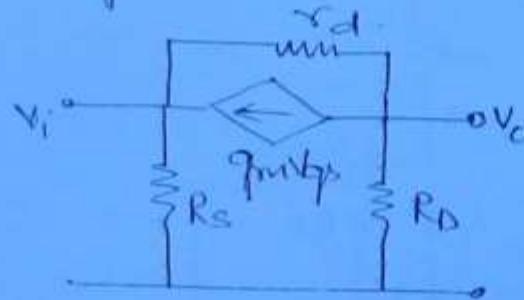
(255)

$$R_i = \frac{1}{g_m} \parallel R_s$$

$$R_o = R_d \parallel r_d$$

$$R_o =$$

$$A_v = g_m R_d$$



Conclusion →

	R_i	R_o	A_v
as by pass	R_g	$r_d \parallel R_d$	$-g_m R_d$
as Unby pass	R_g	$r_d + (1 + A) R_d / R_d$	$\frac{-g_m R_d}{1 + g_m R_g}$
CD	R_g	$\frac{1}{g_m} \parallel R_s$	$\frac{g_m R_s}{1 + g_m R_s}$
CC	$\frac{1}{g_m} \parallel R_s$	$r_d \parallel R_d$	$g_m R_d$

FET Biasing →

Condition

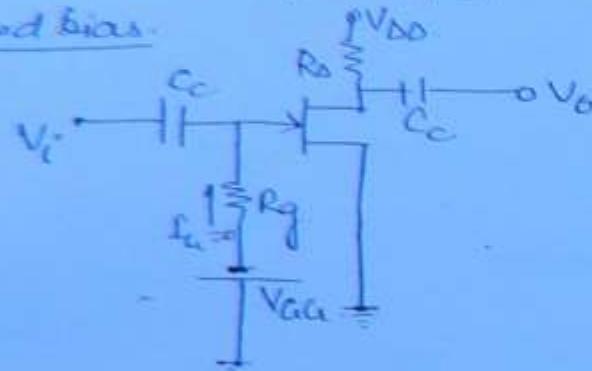
$$1) I_D = 0$$

$$2) I_D = I_S$$

$$3) I_D = I_{DSS} \left[1 - \frac{V_{GS}}{V_P} \right]^2$$

(256)

Ind bias



Calculations

$$(V_{GS})_Q = -V_{GS}$$

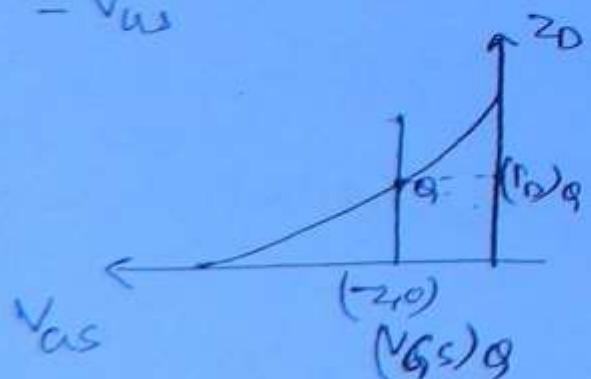
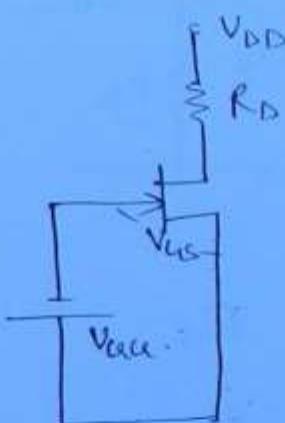
$$(I_D)_Q = I_{DSS} \left[1 - \frac{V_{GS}}{V_P} \right]^2$$

$$V_{DS} = V_{DD} - I_D R_D$$

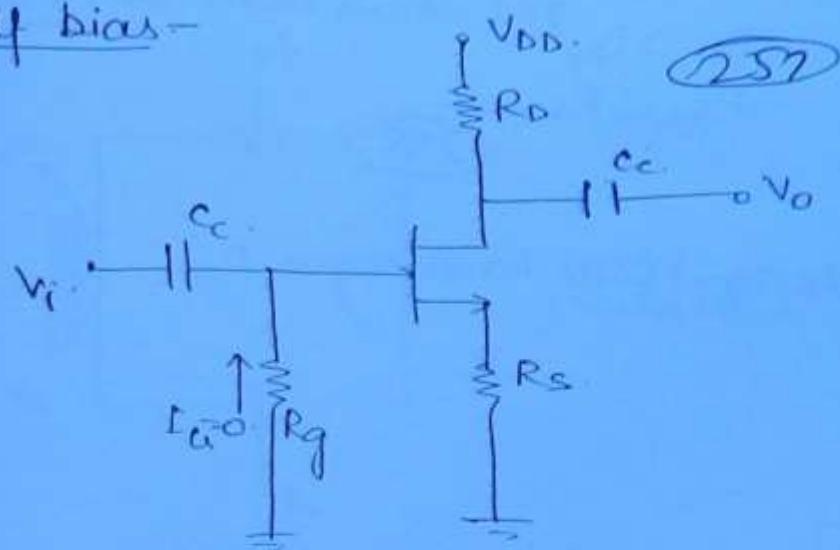
$$V_D = V_{DS}$$

$$V_S = 0$$

$$V_A = -V_{AS}$$

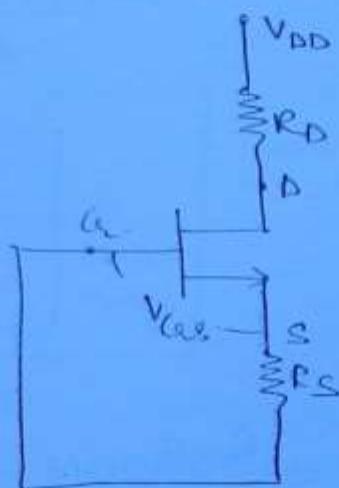


Self bias -



(257)

$$V_{GS} = -I_D R_S$$



$$V_{GS} = -1V$$

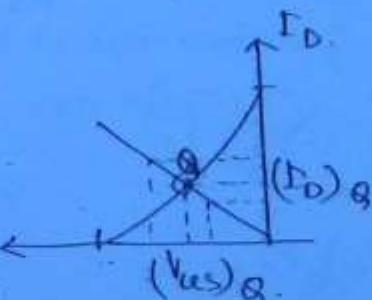
$$R_S = 1k\Omega$$

$$\left. \begin{array}{l} I_D = 1mA \\ \end{array} \right\}$$

$$V_{GS} = -2V$$

$$R_S = 1k\Omega$$

$$\left. \begin{array}{l} I_D = 2mA \\ V_{GS} \end{array} \right\}$$

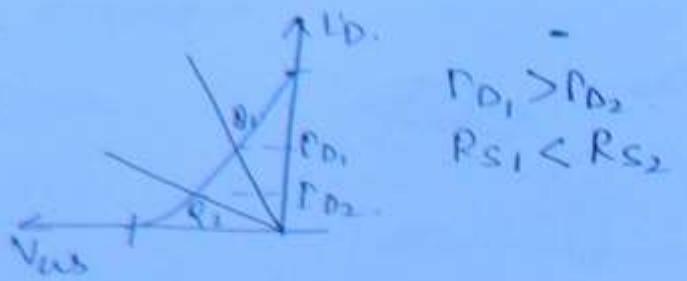


$$(I_D)_Q = P_{DSS} \left[1 - \frac{V_{GS}}{V_P} \right] \quad V_{GS} = -I_D R_S$$

$$(V_{GS})_Q = (I_D) R_S$$

$$V_{DS} = V_{DD} - I_D (R_D + R_S)$$

$$V_D = V_{DD} - I_D R_D, \quad V_S = I_D R_S$$

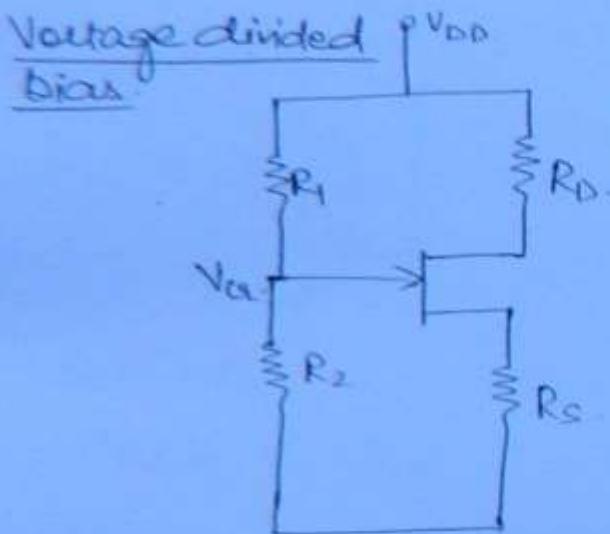


$$R_{D1} > R_{D2}$$

(258)

Q which transistor design will have more R_s .

Ans $R_{S2} \rightarrow Q_2$



$$V_G = V_{GS} + I_D R_S$$

$$V_{GS} = 0 \quad I_D = 0$$

$$V_{GS} = V_G - I_D R_S$$

$$I_D = \frac{V_G}{R_S} \quad V_{GS} = V_G$$

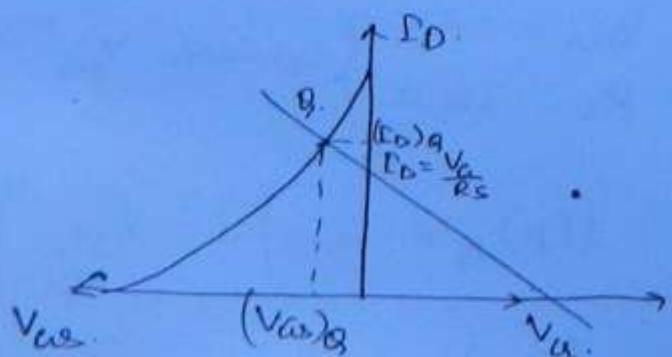
$$(I_D)_Q = I_{DSS} \left[1 - \frac{V_{GS}}{V_P} \right]^2$$

$$(V_{GS})_Q = V_G - (I_D)_Q R_S$$

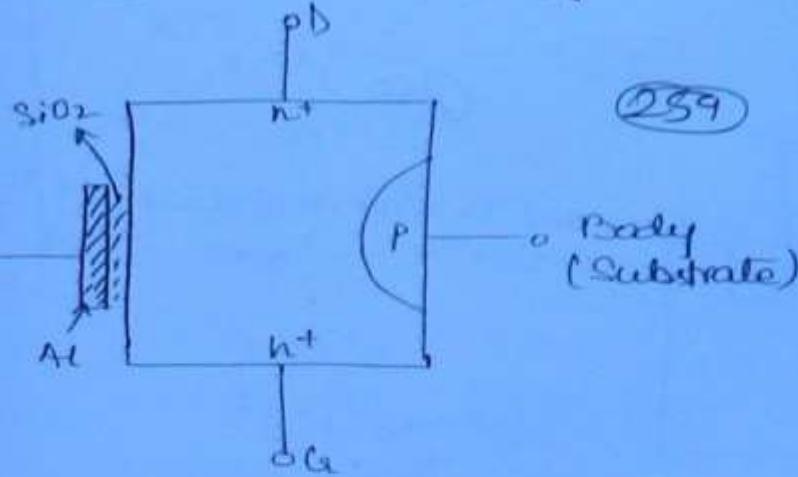
$$V_{DS} = V_{DD} - I_D (R_D + R_S)$$

$$V_D = V_{DD} - I_D R_D$$

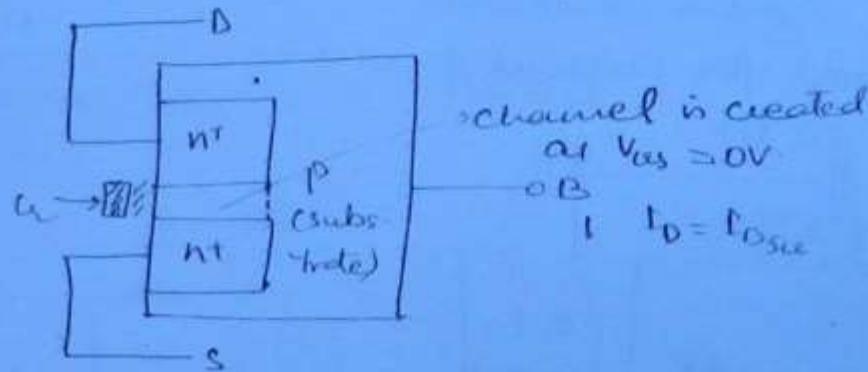
$$V_S = I_D R_S$$



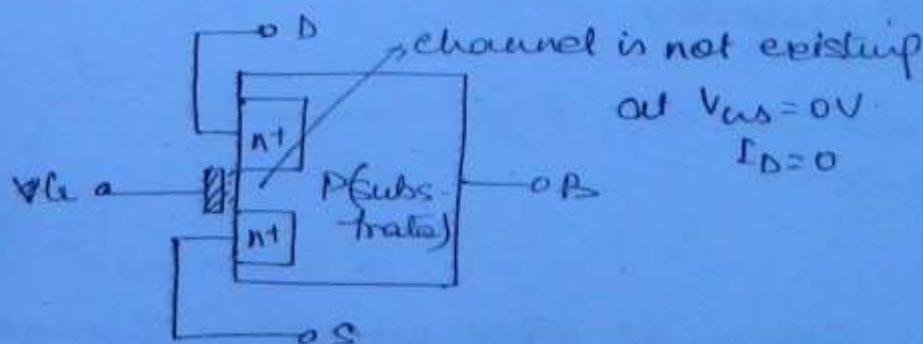
MOSFET \rightarrow Metal oxide FET.



Depletion MOSFET \rightarrow



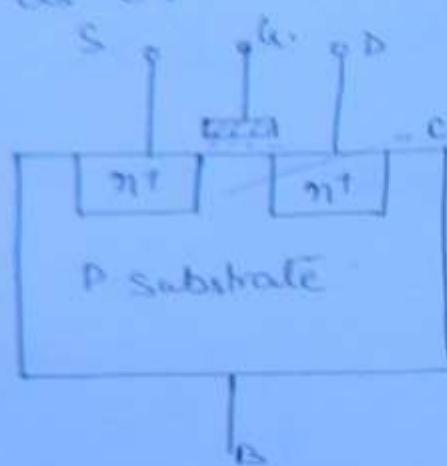
Enhancement MOSFET \rightarrow



- 1) Depletion MOSFET analysis is same as FET analysis because channel is m.p. at $V_{DS} = 0V$.
- 2) In enhancement MOSFET channel is not existing at $V_{DS} = 0V$, $I_D = 0$.
- 3) To analyse the MOSFET we always concentrate on enhancement mode, (ON state)

Case 1 :-

When $V_{GS} = 0V$:

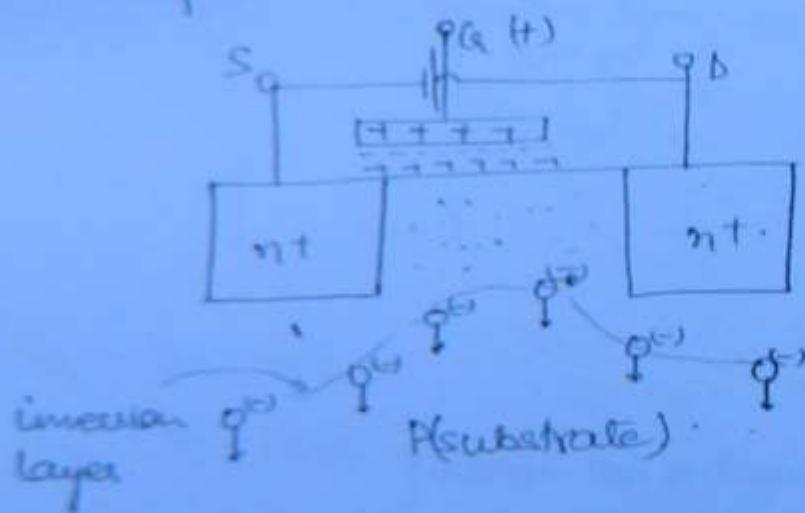


260

channel is not existing at $V_{GS} = 0V$
 $I_D = 0$

Case 2

Creating a channel for current flow :—



$V_T \rightarrow$ threshold Voltage = 0.5
 = Gate Voltage.

Threshold Voltage →

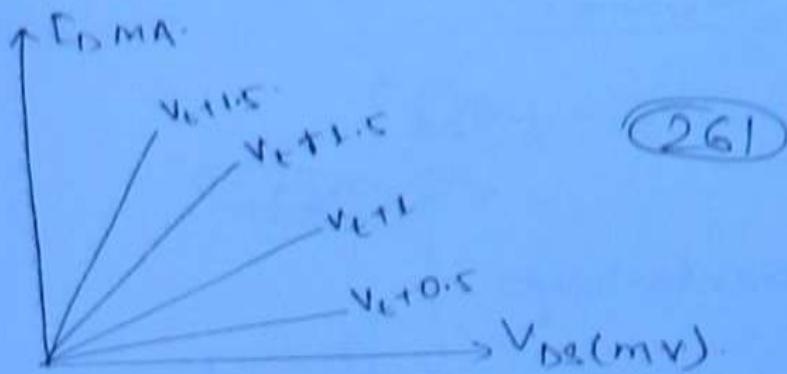
It is the min. V_{GS} voltage at which conducting channel will be formed.

Practically it lies b/w 0.5 to 1 V.

Case 3

Small V_{GS} (mv)

$V_{DS} < I_D$



(26)

$$V_{DS} \propto I_D$$

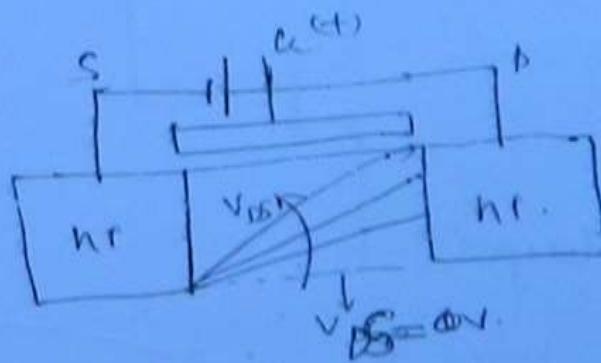
$$I_D \propto (V_{GS} - V_T)$$

effective Voltage

or
overdrive Voltage

Case 4:

large V_{DS} (v) is applied.



$$V_{DS} < V_{GS} - V_T$$

Saturation region

$$V_{DS} > V_{GS} - V_T$$

$$V_{DSsat} = V_{GS} - V_T$$

$$\boxed{V_{DS} < V_{GS} - V_T}$$

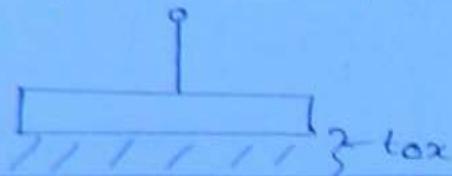
VI characteristics eq. of mosfet.

$$I_D = \mu n C_{ox} \left(\frac{w}{L} \right) \left\{ (V_{GS} - V_t) V_{DS} - \frac{1}{2} V_{DS}^2 \right\}$$

μn → mobility of e^-

C_{ox} → capacitance of oxide layer.

(262)



$$C_{ox} = \frac{C_{ox}}{t_{ox}}$$

C_{ox} → permittivity of oxide layer.

$$C_{ox} = 3.9 \epsilon_0$$

$$\epsilon_0 = 8.85 \times 10^{-12} \text{ F/m}$$

$$C_{ox} = 3.9 \times 8.85 \times 10^{-12}$$

$$= 3.45 \times 10^{-11} \text{ F/m}$$

t_{ox} → thickness of oxide layer.

$\frac{w}{L}$ → aspect ratio

$V_{GS} - V_t$ → effective voltage
'or'
Overdrive Voltage.

Triode region →

$$V_{GS} \geq V_t$$

$$V_{DS} < V_{GS} - V_t$$

$$I_D = \underbrace{\mu n C_{ox} \left(\frac{w}{L} \right)}_{k_n'} \left\{ (V_{GS} - V_t) V_{DS} \right\}$$

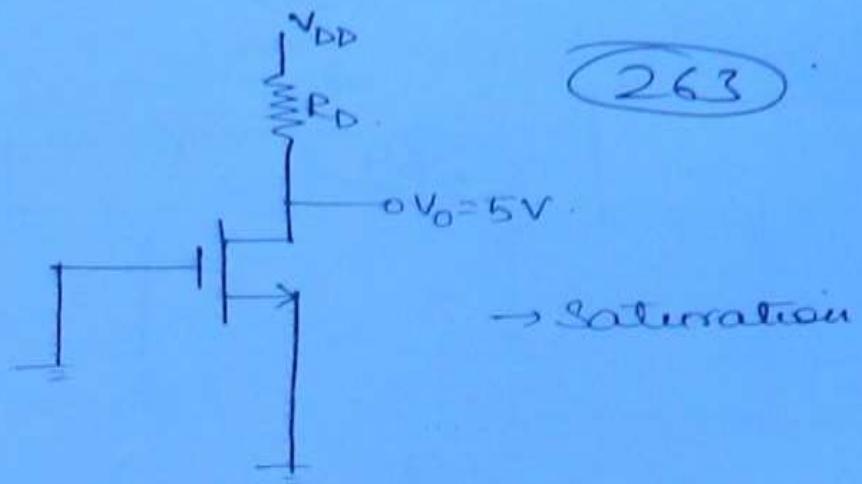
Saturation region →

$$V_{GS} \geq V_t$$

$$V_{DS} \geq V_{GS} - V_t$$

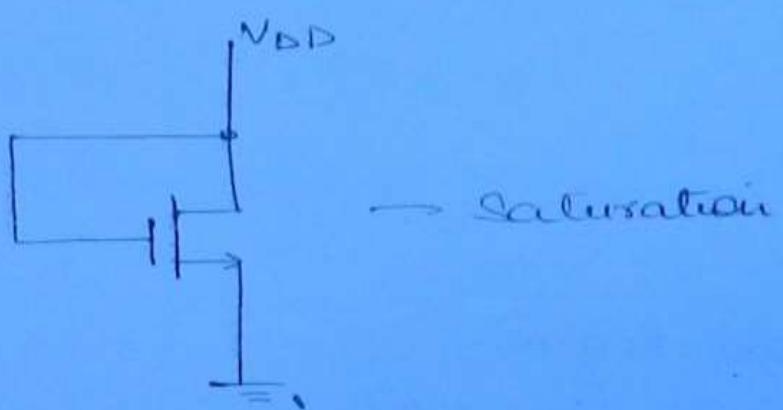
$$V_{DSat} = \underbrace{V_{GS} - V_t}_{\frac{1}{2} k_n} \quad I_D = \frac{1}{2} \mu n C_{ox} \left(\frac{w}{L} \right) (V_{GS} - V_t)^2$$

CKT - 1 →

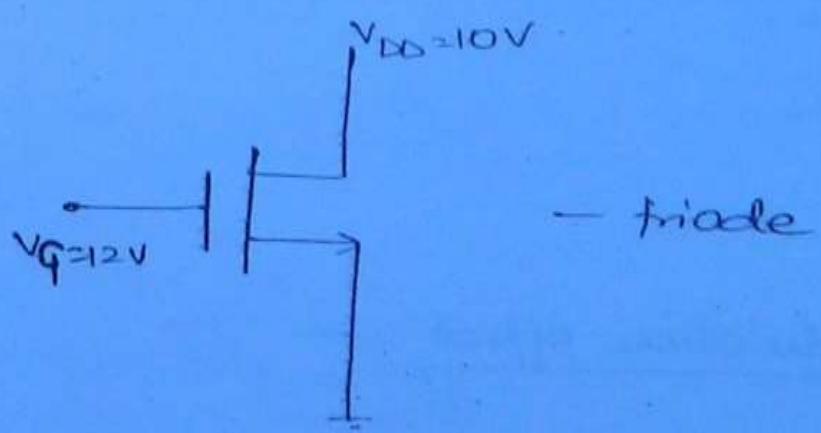


(263)

CKT-2 →



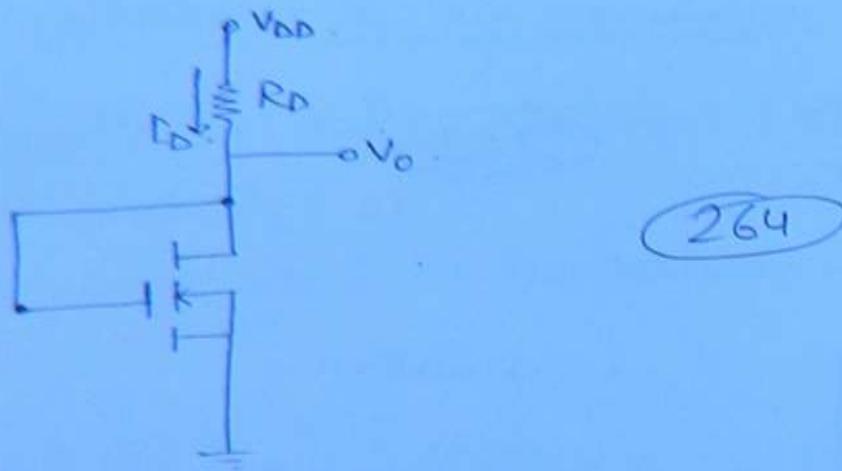
CKT-3 →



$$V_D > V_{ce} \quad \left. \begin{array}{l} \\ \end{array} \right\} \text{saturation}$$

$$V_D > V_{ce} \quad \left. \begin{array}{l} \\ \end{array} \right\} \text{saturation}$$

$$V_D < V_{ce} \quad \rightarrow \text{triode}$$



(264)

Given data →

I_{D_s}

$(\frac{W}{L})$

μ_n

C_{ox}

$\lambda = 0$

cal. V_o and R_d

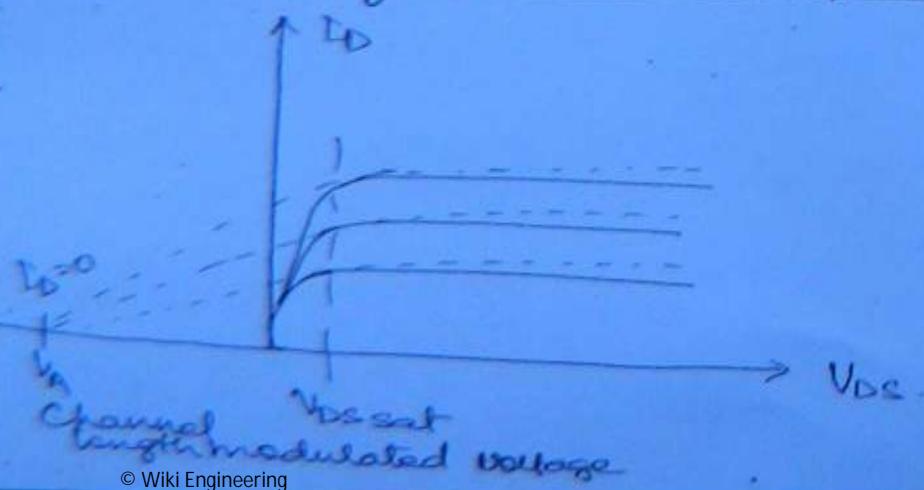
This is in saturation Region.

$$I_D = \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L} \right) (V_{GS} - V_t)^2$$

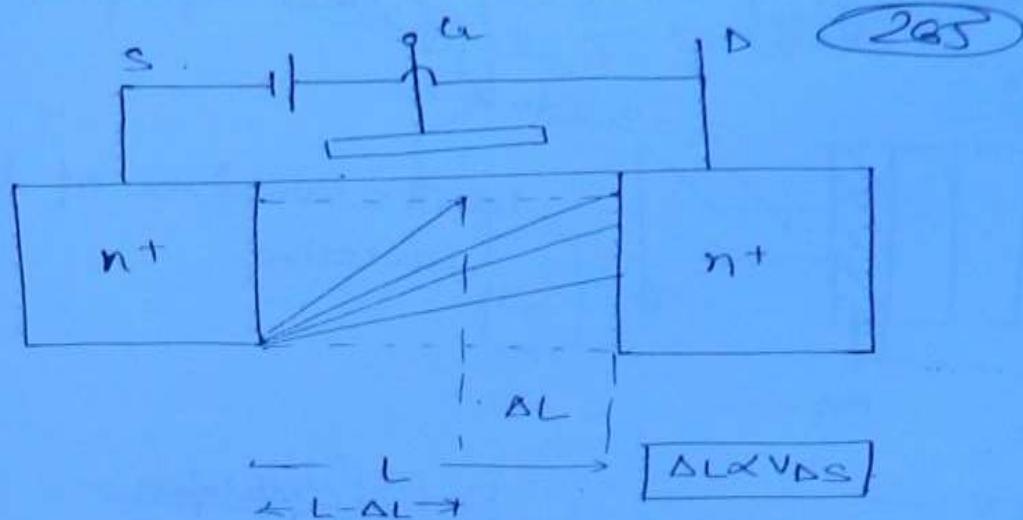
$$V_{GS} = V_o$$

$$R_d = \frac{V_{DD} - V_o}{I_D}$$

Channel length modulation effect :-



$$I_D = \frac{1}{2} \mu n C_{ox} \left(\frac{w}{L} \right) (V_{GS} - V_t)^2$$



$$\begin{aligned} I_D &= \frac{1}{2} \mu n C_{ox} \left(\frac{w}{L - \Delta L} \right) (V_{GS} - V_t)^2 \\ &= \frac{1}{2} \mu n C_{ox} \frac{w}{L} \left[1 + \frac{\Delta L}{L} \right] (V_{GS} - V_t)^2 \end{aligned}$$

$$\Delta L \propto V_{DS}$$

↓
λ

$$I_D = \frac{1}{2} \mu n C_{ox} \left(\frac{w}{L} \right) \left[1 + \left(\frac{\lambda}{L} \right) V_{DS} \right] (V_{GS} - V_t)^2$$

$$I_D = \frac{1}{2} \mu n C_{ox} \left(\frac{w}{L} \right) (V_{GS} - V_t)^2 (1 + \lambda V_{DS})$$

for $I_D = 0$

$$1 + \lambda V_{DS} = 0$$

$$\boxed{V_{DS} = -\frac{1}{\lambda} = V_A}$$

$$|V_A| = \frac{1}{\lambda}$$

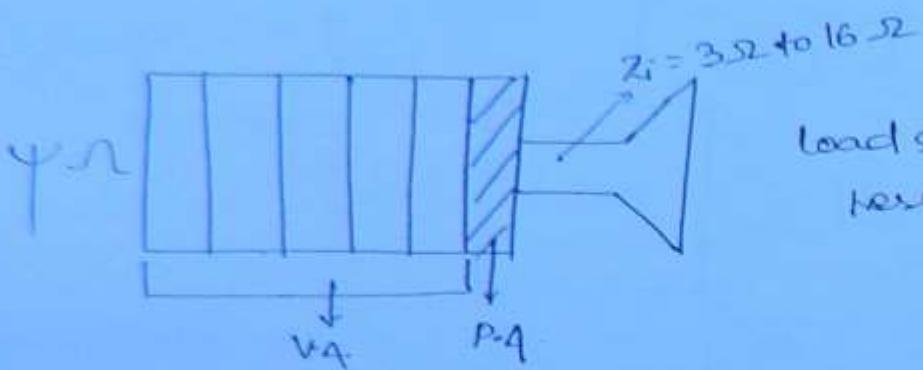
$$\lambda = 0, V_A = \infty$$

$$I_D = k_n (V_{GS} - V_t)^2 \left(1 + \frac{V_{DS}}{V_A} \right)$$

Power Amplifier :-

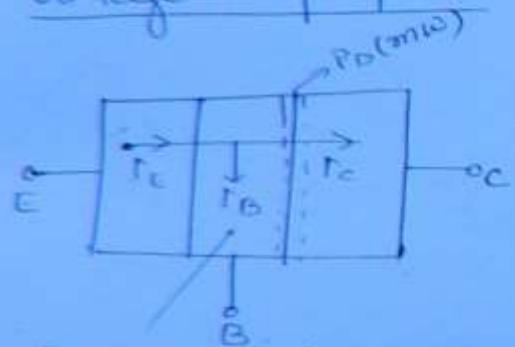
PAS → Public addressing system.

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Load should be of less resistive.

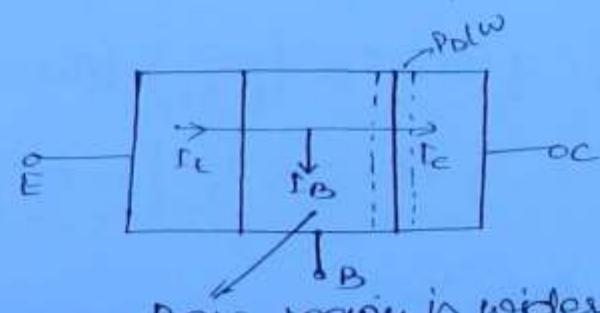
Voltage amplifier :-



Base region is narrower

$$\uparrow \beta = \frac{I_C \uparrow}{I_B}$$

Power amplifier :-



Base region is wider

$$\beta \downarrow = \frac{I_C \downarrow}{I_B \downarrow}$$

Diff b/w power ampifier and voltage amplifier :-

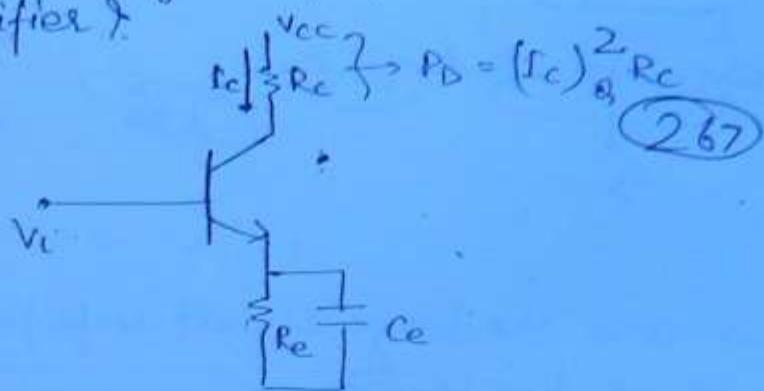
Parameter

V. A.

P. A

1) β	more	less
2) R_C	more	less
3) V_{CE}	Small	large
4) P_0	less	more
5) I_C	less	more
6) Coupling	Resistive coupling in med.	Inductive ab X-mee coupling 5 bar

Q. Why a Voltage amplifier can not be used as a power amplifier?



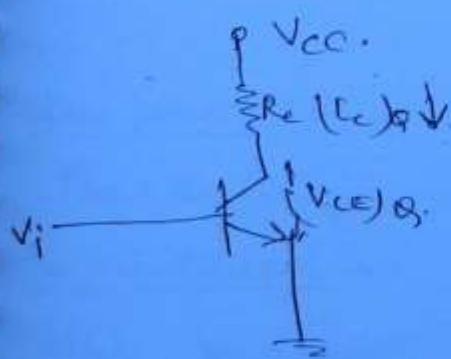
$$\frac{I_c}{Q_0} \downarrow \frac{V_{CC}}{R_P} \Rightarrow P_D = (I_c)^2 Q_0 R_P$$

$$\xrightarrow{\text{For } R_P = 0} \xrightarrow{\text{For } I_{dc} \text{ max}} \Rightarrow P_D = 0$$

For power amplifier, power dissipation should be negligible.

So, in case of resistive load inductive load is preferred.

Power diagram analysis:



$$P_{DC} \downarrow$$

$$(P_{RC})_{DC} \downarrow$$

$$(I_c)^2 Q_0 R_C \downarrow$$

$$\frac{1}{3} R_f \downarrow$$

$$(P_{CE})_{DC} \downarrow$$

$$(P_O)_{AC}$$

$$\xrightarrow{\text{Internal Power loss}} (P_C)_{DC} \rightarrow \text{Heat Sink}$$

$$P_{dc} = P_{ac} + \text{losses}$$

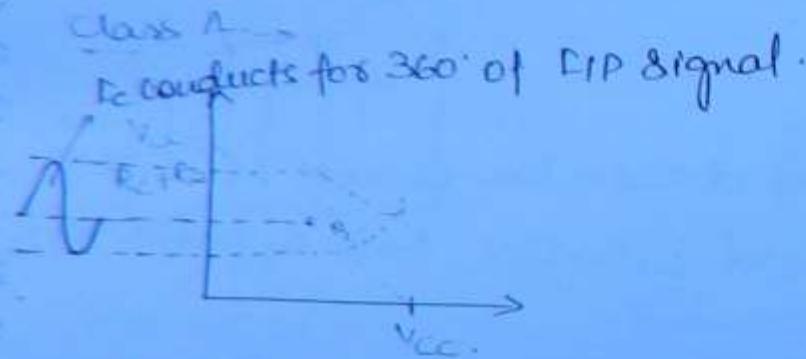
(268)

Definitions:-

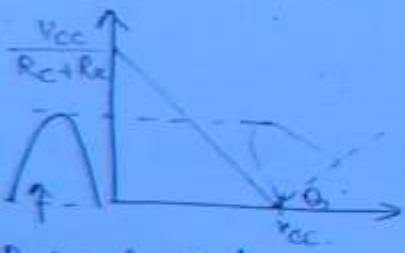
- Power amplifiers are the large signal amplifiers which rises the power level of the signals.
- It is a device which converts dc power into ac power and whose action is controlled by ac LIP signal.

Classes -

Class A -

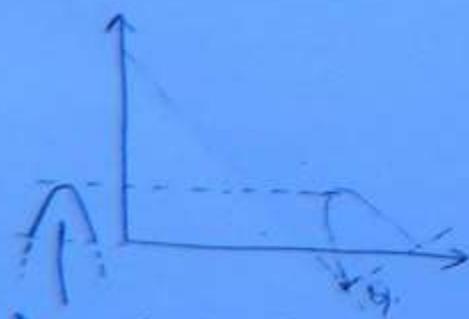


Class B -



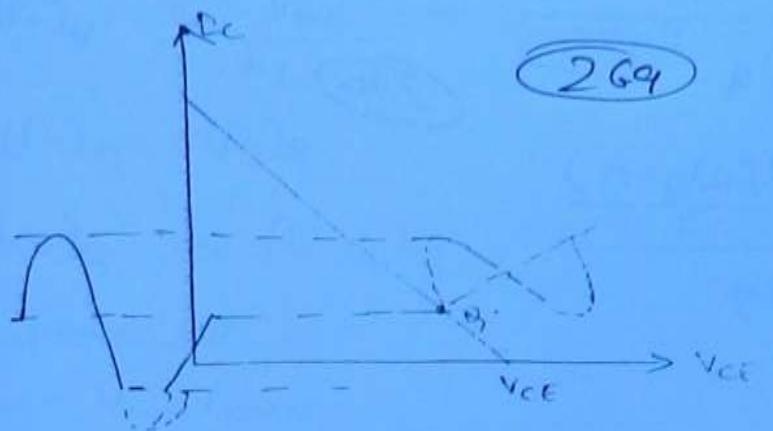
Ic conducts for 180° of LIP.

Class C -



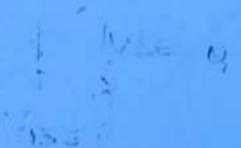
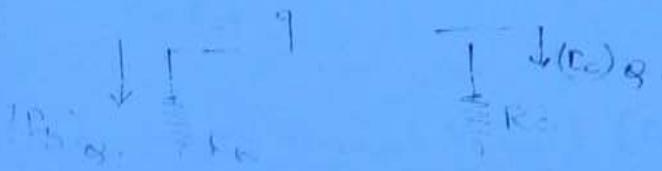
Ic conducts for less than 180°.

Class AB



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Class A series fed power amplifier :-



DC power D/P →

$$P_{DC} = V_{CC} (I_c)_Q.$$

DC conditions →

$$(I_b)_Q = \frac{V_{CC} - V_{BE}}{R_b}$$

$$(I_c)_Q = \beta (I_b)_Q.$$

$$(V_{CE})_Q = V_{CC} - (I_c)_Q R_C.$$

AC power O/P .

$$P_{AC} = V_{rms} I_{rms}$$

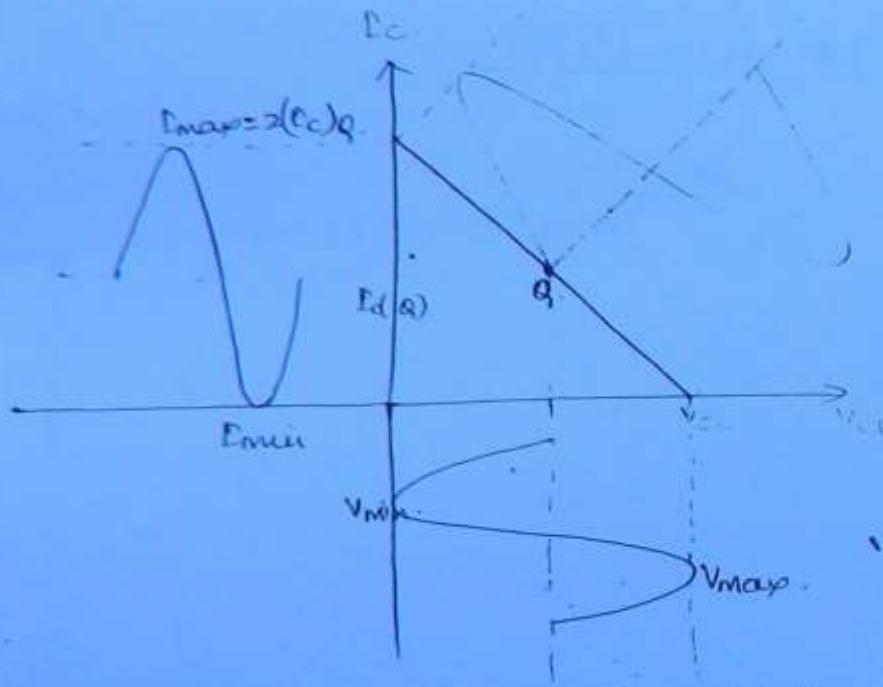
$$= \frac{V_m}{\sqrt{2}} \times \frac{I_m}{\sqrt{2}} = \frac{V_m I_m}{2}$$

$$\frac{P_{AC}}{P_{DC}} = \frac{\frac{1}{2} \left(\frac{V_{MAX} - V_{MIN}}{2} \right) \left(\frac{I_{MAX} - I_{MIN}}{2} \right)}{V_{CC}(I_C)_Q}$$

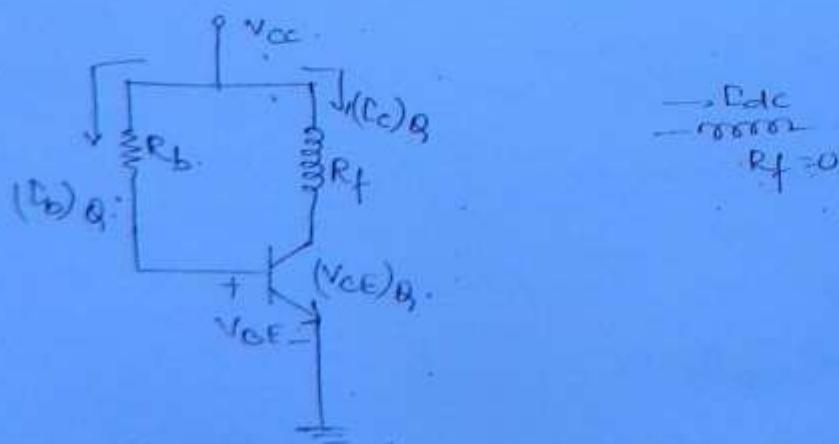
(270)

$$= \frac{\frac{1}{2} \left(\frac{V_{CC} - 0}{2} \right) \left(\frac{2(I_C)_Q - 0}{2} \right)}{V_{CC}(I_C)_Q}$$

$$= \frac{1}{4} = 25\%$$



Class A x-mic coupled power amplifier :-



Dc power DIP :-

$$P_{DC} = (V_{CC})(I_C)_Q.$$

DC condition →

$$(I_B)_Q = \frac{V_{CC} - V_{BE}}{R_B}$$

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$$(I_C)_Q = \beta(I_B)_Q$$

$$(V_{CE})_Q = V_{CC} - (I_C)_Q R_f$$

ac power O/P →

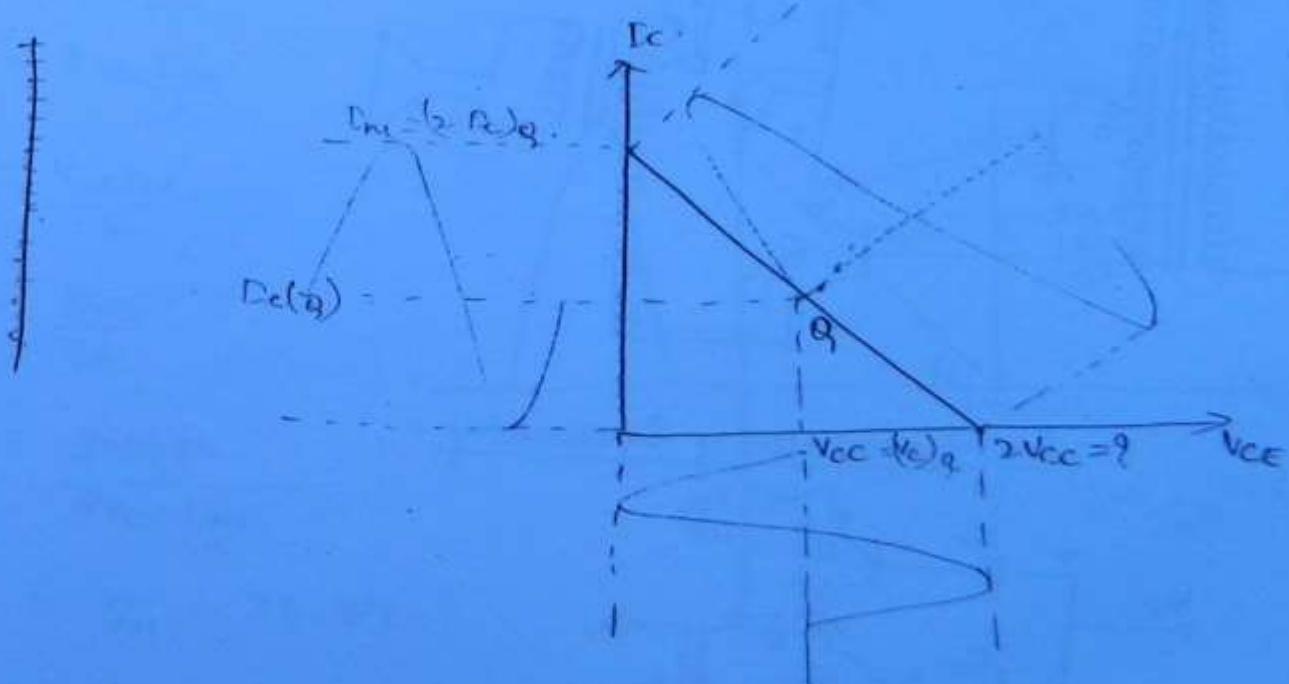
$$P_{AC} = V_{rms} I_{rms}$$

$$= \frac{V_m}{\sqrt{2}} \cdot \frac{I_m}{\sqrt{2}}$$

$$= \frac{V_m I_m}{2}$$

$$\frac{P_{AC}}{P_{DC}} = \frac{\frac{1}{2} \left(\frac{V_{max} - V_{min}}{2} \right) \left(\frac{I_{max} - I_{min}}{2} \right)}{V_{CC} (I_C)_Q}$$

$$= \frac{1}{2} = 50\%$$



Power consumption :-

$$P_{DC} = P_{AC} + P_D$$

$$P_D = P_{DC} - P_{AC}$$

$$= V_{CC}(I_C)_Q - \frac{V_m I_m}{2}$$

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At zero signal conditions :-

$$V_m = 0, I_m = 0$$

$$P_D = P_{DC}$$

When signal is applied,

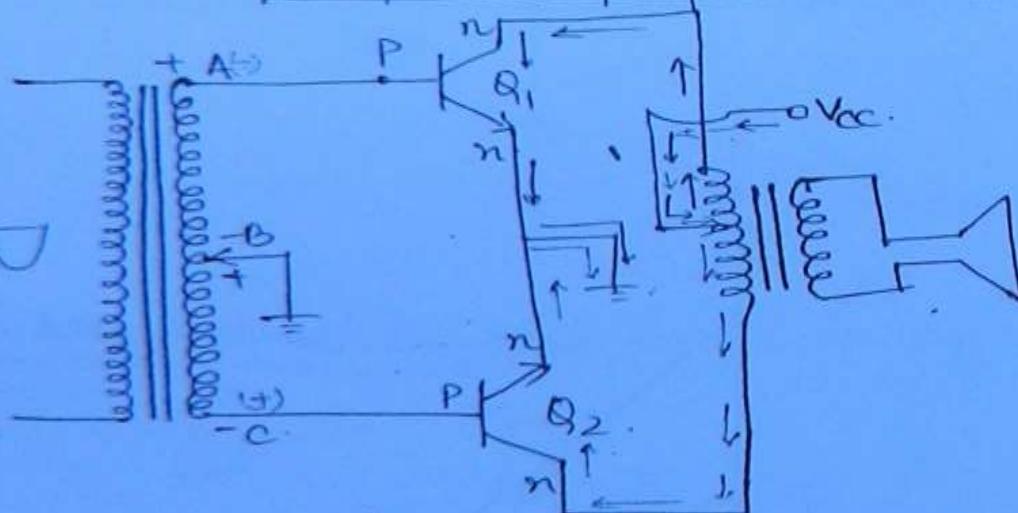
$$P_D = V_{CC}(I_C)_Q - \frac{V_m I_m}{2}$$



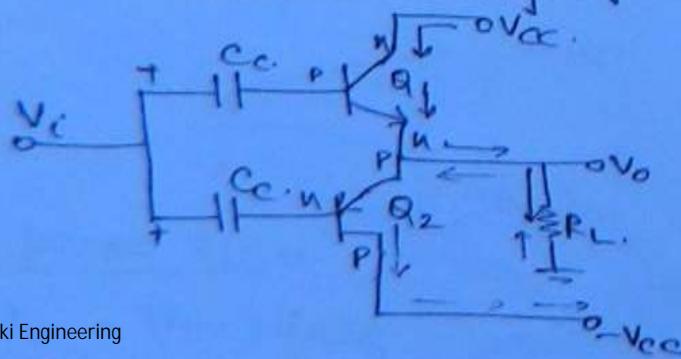
P_D decreases.

Class B Power amplifiers :-

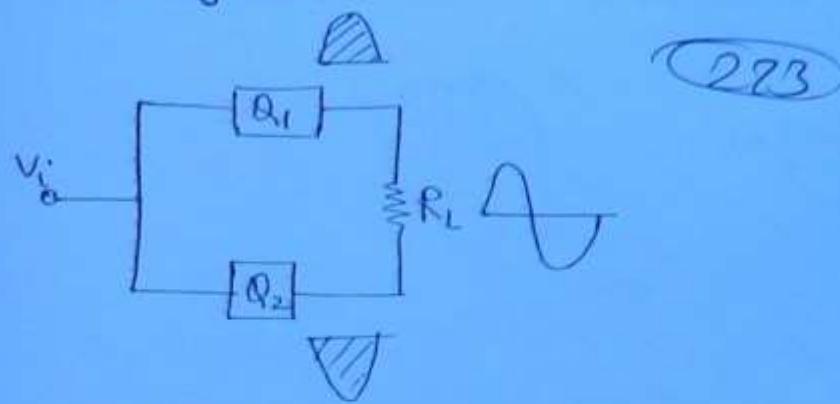
- Pushpull amplifier.



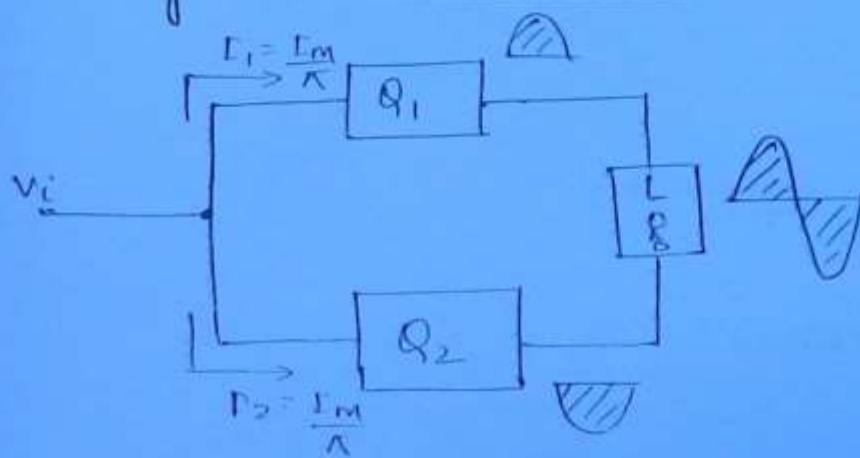
- Complementary Symmetry →



Block diagram →



Efficiency cal. in class B! —



$$P_{DC} = V_{CC} I_{DC}$$

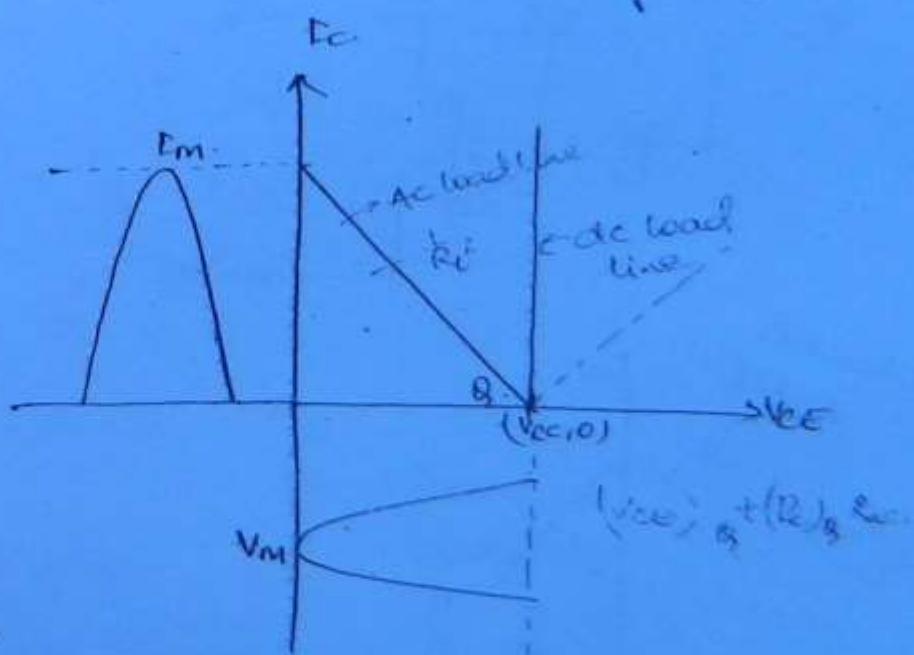
$$= 2V_{CC} \frac{I_m}{R}$$

$$P_{AC} = \frac{V_m I_m}{2}$$

$$\therefore \eta = \frac{P_{AC}}{P_{DC}}$$

$$= \frac{V_m I_m}{2V_{CC} \frac{I_m}{R}}$$

$$\therefore \eta = 28.5\%$$



$$\frac{1}{R_L} = \frac{I_{DC}}{V_m}$$

Power dissipation in class D :-

$$P_D = P_{DC} - P_{AC}$$

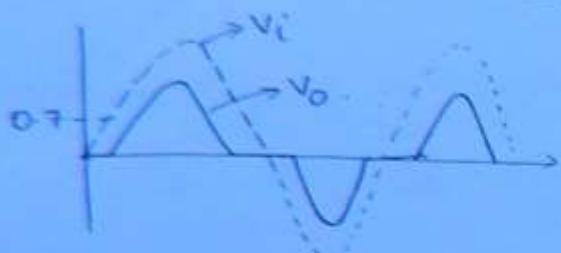
$$= \frac{2V_{CC}I_m}{2} V_m I_m$$

At 0 signal conditions

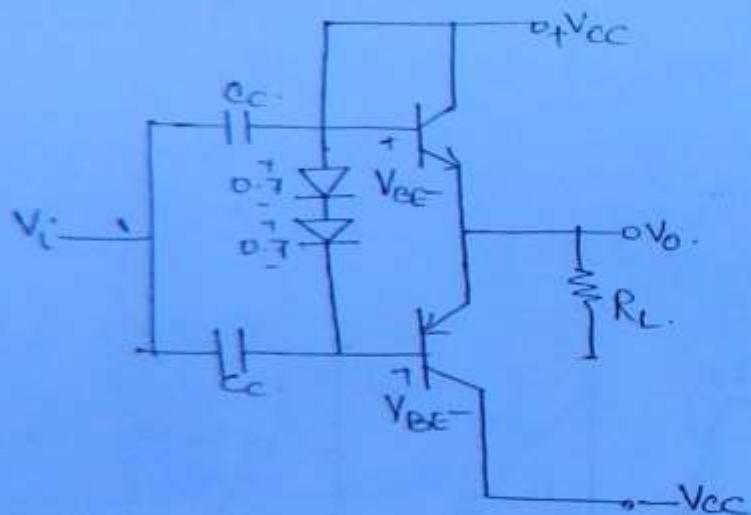
$$\boxed{P_D = 0}$$

(274)

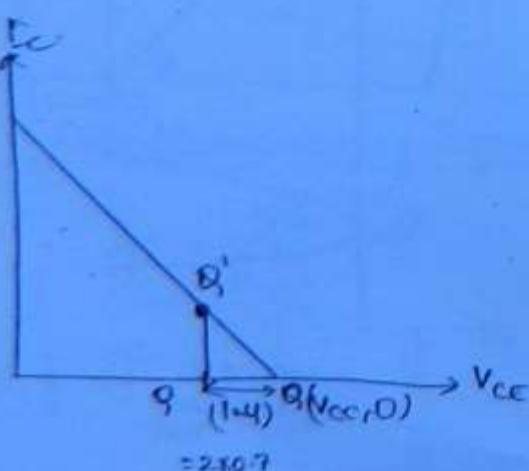
Cross over distortion :-



Class B complementary Symmetry :-



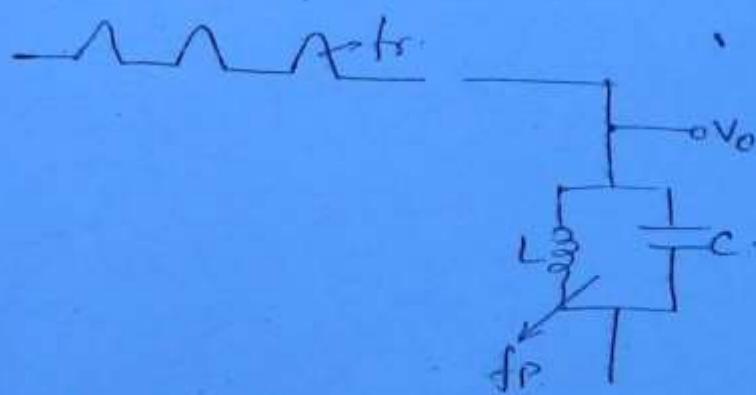
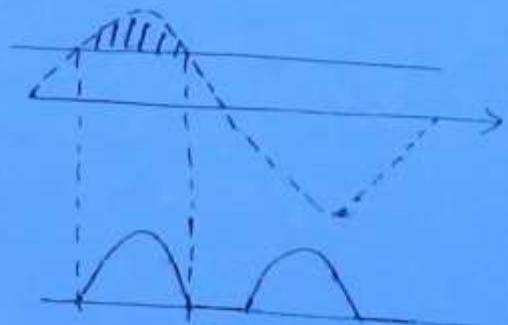
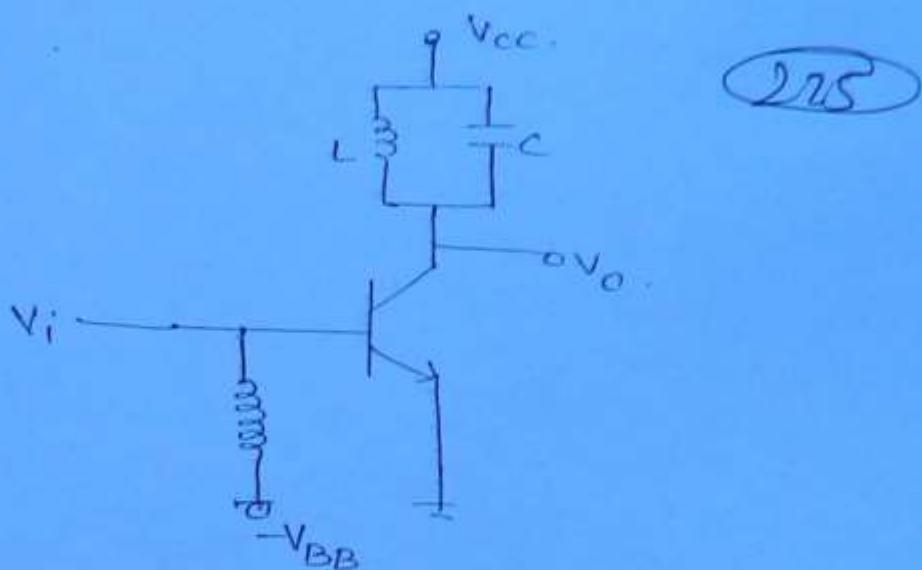
Class B
Amplifier



$$(V_{CC} - 1.4)$$

if 1 transistor is there then $(V_{CC} - 0.7)$

2ss C power amp →



$\text{~~~~~} \rightarrow f_r = f_p$ }
 $\text{~~~~~} \rightarrow f_r \neq f_p$ } → tunner
amplifier.

